Radiation Report

TPS7H1101-SP Total Ionizing Dose (TID)

ABSTRACT

This report discusses the results of the total-ionizing dose (TID) testing for the Texas Instruments TPS7H1101-SP, Radiation-hardened, 1.5-V to 7-V input, 3 Amp, Radiation Hardened Ultra-Low Dropout (LDO) regulator

The study was done to determine TID effects under high dose rate (HDR) up to 100krad(Si) and low dose rate(LDR) up to 100krad(Si). The results show that all samples passed within the specified limits up to 100krad(Si) for both HDR and LDR.

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Trademarks

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1 Device Information

1.1 Product Description

The TPS7H1101-SP is a radiation-hardened LDO linear regulator that uses a PMOS pass element configuration. This device operates over a wide range of input voltage, from 1.5 V to 7 V while offering excellent PSRR. The TPS7H1101-SP features a precise and programmable foldback current limit implementation with a very-wide adjustment range. To support the complex power requirements of FPGAs, DSPs, or microcontrollers, the TPS7H1101-SP provides enable on and off functionality, programmable SoftStart, current sharing capability, and a PowerGood open-drain output. The TPS7H1101-SP is available in a thermally-enhanced 16-pin ceramic flatpack package (CFP).

1.2 Device Details

Table 1-1 lists the device information and test conditions used in the TID HDR and LDR characterization.

Table 1-1. Device and Exposure Details

TID HDR and LDR Details	
TI Device	TPS7H1101-SP
TI Part Name	5962R1320201VXC
Device Function	Low Dropout Linear Regulator
Package	16-pin CFP (HKR)
Technology	LBC7 (Linear BiCMOS 7)
Assembly Lot Number	3003221(LTC: 1314B), 3003223(LTC: 1314C), 3003222(LTC: 1314D)
Quantity Tested	HDR: • 5 units biased at 3krad(Si) • 5 units biased at 10krad(Si) • 5 units biased at 30krad(Si) • 5 units biased at 50krad(Si) • 22 units biased at 100krad(Si) LDR: • 5 units biased and 5 units unbiased at 50krad(Si) • 5 units biased and 5 units unbiased at 100krad(Si)
HDR Dose rate	93.62-rad(Si)/s ioinizing radiation
HDR Radiation Facility	Texas Instruments Santa Clara, California
LDR Dose Rate	10-mrad(Si)/s ionizing radiation
LDR Radiation Facility	Aeroflex Radiation Assured Devices Colorado Springs, Colorado
Irradiation and Test Temperature	Ambient, room temperature controlled to 25°C ±6°C per MIL-STD-883J

2 Total Dose Test Setup

2.1 Test Overview

The TPS7H1101-SP was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Conditions A and D were used. For both HDR and LDR, the product was irradiated up to the target radiation level, and then put through full electrical parametric testing on the production automated test equipment (ATE).

2.2 Test Facility

The TPS7H1101-SP HDR exposure was performed on biased and unbiased at Texas Instruments Santa Clara, California. The dose rate for exposure was 93.62rad(Si)/s.

The TPS7H1101-SP LDR exposure was performed on biased and unbiased devices at Aeroflex Radiation Assured Devices Colorado Springs, Colorado. The dose rate for exposure was 10 mrad(Si)/s.

2.3 Test Setup Details

The devices under HDR and LDR exposure were tested in two conditions, biased and unbiased, as described in the following sections.

Unbiased

For the unbiased HDR and LDR conditions, the exposure was performed with all pins grounded.

Biased

Figure 2-1 shows the bias conditions used for HDR and LDR exposure.

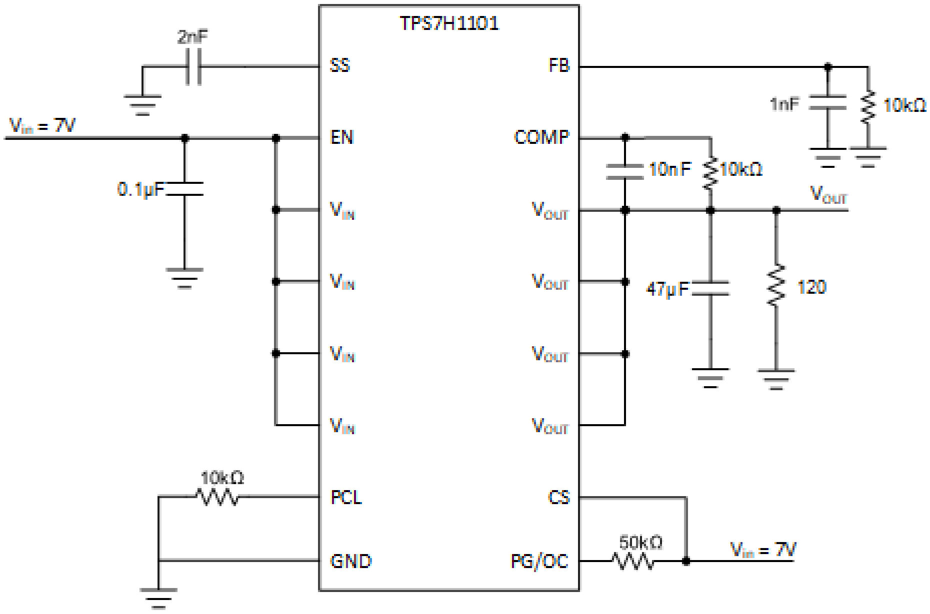


Figure 2-1. Bias Diagram Used in TID exposure

2.4 Test Configuration and Condition

HDR devices were stressed at 3 krad(Si), 10 krad(Si), 30 krad(Si), 50 krad(Si), and 100 krad(Si) for biased conditions.

LDR devices were stressed at 50 krad(Si) and 100krad(Si) for biased and unbiased conditions.

Table 2-1. HDR Biased Device Information (HDR)

Total Samples: 42				
Exposure Levels:				
3 krad(Si) (5 samples)	10 krad(Si) (5 samples)	30 krad(Si) (5 samples)	50 krad(Si) (5 samples)	100 krad(Si) (22 samples)
HDR_W5_D2_Bias, HDR_W5_D12_Bias, HDR_W6_D13_Bias, HDR_W6_D21_Bias, HDR_W7_D5_Bias	HDR_W5_D9_Bias, HDR_W6_D4_Bias, HDR_W6_D28_Bias, HDR_W7_D27_Bias, HDR_W7_D41_Bias	HDR_W5_D29_Bias, HDR_W6_D27_Bias, HDR_W6_D42_Bias, HDR_W7_D31_Bias, HDR_W7_D22_Bias	HDR_W5_D37_Bias, HDR_W5_D39_Bias, HDR_W6_D14_Bias, HDR_W7_D13_Bias, HDR_W7_D37_Bias	HDR_W5_D8_Bias, HDR_W5_D13_Bias, HDR_W5_D30_Bias, HDR_W5_D32_Bias, HDR_W5_D34_Bias, HDR_W5_D38_Bias, HDR_W5_D41_Bias, HDR_W6_D1_Bias, HDR_W6_D8_Bias, HDR_W6_D18_Bias, HDR_W6_D22_Bias, HDR_W6_D24_Bias, HDR_W6_D30_Bias, HDR_W6_D32_Bias, HDR_W6_D39_Bias, HDR_W7_D4_Bias, HDR_W7_D9_Bias, HDR_W7_D17_Bias, HDR_W7_D18_Bias, HDR_W7_D25_Bias, HDR_W7_D34_Bias, HDR_W7_D35_Bias

Table 2-2. LDR 10 mrad(Si)/s Biased Device Information (LDR)

Total Samples: 10	
Exposure Levels:	
50 krad(Si) (5 samples)	100 krad(Si) (5 samples)
LDR_Bias_50K_Q1_3, LDR_Bias_50K_Q2_65, LDR_Bias_50K_Q3_30, LDR_Bias_50K_Q4_76, LDR_Bias_50K_Q5_46	LDR_Bias_100K_Q1_5, LDR_Bias_100K_Q3_28, LDR_Bias_100K_Q5_45, LDR_Bias_100K_Q2_67, LDR_Bias_100K_Q2_68

Table 2-3. LDR 10 mrad(Si)/s Unbiased Device Information (LDR)

Total Samples: 10	
Exposure Levels:	
50 krad(Si) (5 samples)	100 krad(Si) (5 samples)
LDR_UnBias_50K_Q1_4, LDR_UnBias_50K_Q2_66, LDR_UnBias_50K_Q3_31, LDR_UnBias_50K_Q4_77, LDR_UnBias_50K_Q5_47	LDR_UnBias_100K_Q1_6, LDR_UnBias_100K_Q3_29, LDR_UnBias_100K_Q5_69, LDR_UnBias_100K_Q4_78, LDR_UnBias_100K_Q4_79

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The results show that all devices were fully functional and within specification limits up to 100krad (Si) LDR and 100krad (Si) HDR TID.

Overall, the TPS7H1101-SP showed a strong degree of hardness to irradiation for both biased and unbiased exposure conditions. The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level for both biased and unbiased conditions. All parameters were within the data sheet electrical specifications at 100krad(Si) LDR and 100krad(Si) HDR (see Section 3.2 for the electrical parameters).

3.2 Data Sheet Electrical Parameters and Associated Tests

1.5 V ≤ V_{IN} ≤ 7 V, $V_{OUT(target)}$ = V_{IN} – 0.35 V, I_{OUT} = 10 mA, V_{EN} = 1.1 V, C_{OUT} = 22 µF, PG terminal pulled up to V_{IN} with 50 kΩ, over operating temperature range (T_J = –55°C to 125°C), unless otherwise noted. Typical values are at T_J = 25°C.

Parameters		Test Conditions	TPS7H1101-SP Data Sheet SLVSD81A –January 2016–Revised February 2017				Test Number(s)
Symbol	Description		MIN	TYP	MAX	Unit	
V_{IN}	Input voltage range		1.5		7	V	13.1, 13.2
V_{FB}	Feedback pin voltage(1)	0 A ≤ I_{OUT} ≤ 3 A, 1.5 V ≤ V_{IN} ≤ 7 V	0.594	0.605	0.616	V	13.0, 13.16, 13.17
V_{OUT}	Output voltage range		0.8		V_{IN}	V	13.1, 13.2, 13.4
	Output voltage accuracy(1)	0 A ≤ I_{OUT} ≤ 3 A, 1.5 V ≤ V_{IN} ≤ 7 V, V_{OUT} = 0.8 V, 1.2 V, 1.8 V, 6.65 V	–2		2	%	13.1, 13.10, 13.11, 13.13, 13.14, 13.2, 13.4, 25.0, 25.1, 25.4, 25.5, 25.7, 25.8
$\Delta V_{OUT}\%$ / ΔV_{IN}	Line regulation	1.5 V ≤ V_{IN} ≤ 7 V	–0.07	0.01	0.07	% / V	13.3, 13.12, 13.15
V_{DO}	Dropout voltage(3)	I_{OUT} = 3 A, V_{OUT} = 1.3 V, V_{IN} = V_{OUT} + V_{DO}		210	335	mV	13.6
I_{CL}	Programmable output current limit range	V_{IN} = 1.5 V, V_{OUT} = 1.2 V , PCL resistance = 47 kΩ	500		750	mA	26.1
		V_{IN} = 1.5 V, V_{OUT} = 1.2 V , PCL resistance varies	200		3500(4)	mA	26.0
I_{GND}	GND pin current	V_{IN} = 1.5 V, V_{OUT} = 1.2 V, I_{OUT} = 2 A		10	16	mA	13.8
I_Q	Quiescent current (no load)	V_{IN} = V_{OUT} + 0.5 V, I_{OUT} = 0 A		7	10	mA	12.0, 12.1, 12.2, 12.3
I_{SHDN}	Shutdown current (IGND)	1.5 V ≤ V_{IN} ≤ 7 V		26	230	µA	11.0, 11.1, 11.2, 11.3
		1.5 V ≤ V_{IN} ≤ 7 V, post 100 kRads (si), TJ = 25°C (5)			1400	µA	
I_{SNS}, I_{FB}	FB/SNS pin current	V_{IN} = 7 V, V_{OUT} = 6.65 V		1	5	nA	19.0
I_{EN}	EN pin input current	V_{IN} = 7 V, V_{EN} = 7 V, V_{OUT} = 6.65 V		20	150	nA	14.3, 15.3, 25.2
V_{ILEN}	EN pin input low (disable)	3.5 V < V_{IN} < 7 V		0.30 × V_{IN}		V	14.0, 15.0, 16.0
V_{IHEN}	EN pin input high (enable)	3.5 V < V_{IN} < 7 V		0.75 × V_{IN}		V	14.1, 15.1, 16.1

1.5 V ≤ V_{IN} ≤ 7 V, $V_{OUT(target)}$ = V_{IN} – 0.35 V, I_{OUT} = 10 mA, V_{EN} = 1.1 V, C_{OUT} = 22 µF, PG terminal pulled up to V_{IN} with 50 kΩ, over operating temperature range (T_J = –55°C to 125°C), unless otherwise noted. Typical values are at T_J = 25°C.

Parameters		Test Conditions	TPS7H1101-SP Data Sheet SLVSD81A –January 2016–Revised February 2017				Test Number(s)
Symbol	Description		MIN	TYP	MAX	Unit	
Eprop Dly	Enable pin propagation delay	V_{IN} = 2.2 V, EN rise to I_{OUT} rise		650	1000	uS	20.1
T_{EN}	Enable pin turn-on delay	V_{IN} = 2.2 V, V_{OUT} = 1.8 V, I_{Load} = 1A, C_{OUT} = 220 µF, C_{SS} = 2 nF		1.4	1.6	mS	20.0
V_{THPG}	PG threshold on	No load, 0.8 V ≤ V_{OUT} ≤ 6.65 V	86	90		%	17.1, 17.5
$V_{THPGHYS}$	PG hysteresis	1.5 V ≤ V_{IN} ≤ 7 V		2		%	22.9
V_{OLPG}	PG pin output low	I_{PG} = –1 mA to 0 mA		120	300	mV	17.2, 17.3
I_{LKGPG}	PG pin leakage current	V_{OUT} > V_{THPG}, V_{PG} = 1.2 V		0.2	1.5	µA	23.0
		V_{OUT} > V_{THPG}, V_{PG} = 7 V		0.5	2.5	µA	
I_{SS}	SS pin charge current	V_{IN} = 1.5 V to 7 V		2.5	3.5	µA	21.0, 22.0
V_{SS}	SS terminal voltage (device enabled)(6)	V_{IN} = 1.5 V to 7 V			1.232	V	22.1

1. The output voltage accuracy of condition at IOUT = 2 A and IOUT = 3 A is specified by characterization, but not production tested.
2. Line and load regulations done under pulse condition for t < 10 ms.
3. The parameter is specified to the limit in characterization, but not production tested.
4. The maximum limit of the I_{CL} parameter is specified to the limit in characterization, but not production tested.
5. This maximum limit applies to SMD 5962R13202 post 100 kRads (Si) test at 25°C.
6. Any external pullup voltage should not exceed 1.188 V.

4 Applicable and Reference Documents

4.1 Applicable Documents

- TPS7H1101-SP Radiation Tolerant 1.5 -7V Input, 3 Amp, Ultra Low Dropout Regulator Data Sheet
- TPS7H1101-SP EVM User's Guide

4.2 Reference Documents

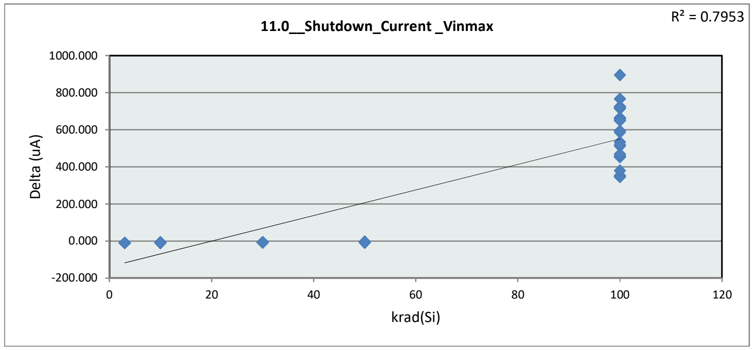
Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A Biased HDR TID Report Data

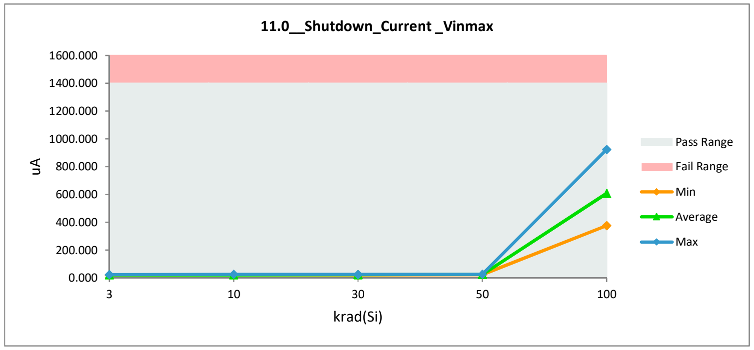
This appendix contains the Biased HDR TID report data.

HDR Report
TPS7H1101-SP

		11.0__Shutdown_Current _Vinm		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		uA	uA	
Max Limit		1400	1400	
Min Limit		0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	32.914	23.248	-9.666
3	HDR_W5_D12_Bias	32.919	22.667	-10.252
3	HDR_W6_D13_Bias	30.579	21.008	-9.571
3	HDR_W6_D21_Bias	29.882	20.215	-9.667
3	HDR_W7_D5_Bias	31.445	20.720	-10.725
10	HDR_W5_D9_Bias	32.966	26.072	-6.894
10	HDR_W6_D4_Bias	29.397	21.669	-7.728
10	HDR_W6_D28_Bias	29.545	20.767	-8.778
10	HDR_W7_D27_Bias	30.180	21.331	-8.849
10	HDR_W7_D41_Bias	31.660	21.116	-10.544
30	HDR_W5_D29_Bias	32.181	24.551	-7.630
30	HDR_W6_D27_Bias	29.287	23.004	-6.283
30	HDR_W6_D42_Bias	29.440	22.711	-6.729
30	HDR_W7_D31_Bias	30.541	23.425	-7.116
30	HDR_W7_D22_Bias	31.479	23.914	-7.565
50	HDR_W5_D37_Bias	33.122	26.840	-6.282
50	HDR_W5_D39_Bias	32.856	24.247	-8.609
50	HDR_W6_D14_Bias	29.256	24.623	-4.633
50	HDR_W7_D13_Bias	30.292	24.758	-5.534
50	HDR_W7_D37_Bias	30.746	27.013	-3.733
100	HDR_W5_D8_Bias	33.112	544.839	511.727
100	HDR_W5_D13_Bias	31.587	376.697	345.110
100	HDR_W5_D30_Bias	32.106	754.674	722.568
100	HDR_W5_D32_Bias	32.300	757.079	724.779
100	HDR_W5_D34_Bias	32.450	385.727	353.277
100	HDR_W5_D38_Bias	31.907	745.828	713.921
100	HDR_W5_D41_Bias	32.572	618.832	586.260
100	HDR_W6_D1_Bias	28.718	682.795	654.077
100	HDR_W6_D8_Bias	29.451	482.080	452.629
100	HDR_W6_D18_Bias	29.486	377.580	348.094
100	HDR_W6_D22_Bias	29.277	487.626	458.349
100	HDR_W6_D24_Bias	29.115	924.135	895.020
100	HDR_W6_D30_Bias	29.304	409.055	379.751
100	HDR_W6_D32_Bias	29.484	694.457	664.973
100	HDR_W6_D39_Bias	29.450	689.392	659.942
100	HDR_W7_D4_Bias	30.236	564.340	534.104
100	HDR_W7_D9_Bias	30.156	679.729	649.573
100	HDR_W7_D17_Bias	30.222	796.452	766.230
100	HDR_W7_D18_Bias	30.435	624.348	593.913
100	HDR_W7_D25_Bias	30.181	549.222	519.041
100	HDR_W7_D34_Bias	30.184	748.483	718.299
100	HDR_W7_D35_Bias	30.438	498.569	468.131
	Max	33.122	924.135	895.020
	Average	30.782	329.901	299.119
	Min	28.718	20.215	-10.725
	Std Dev	1.365	315.540	315.785

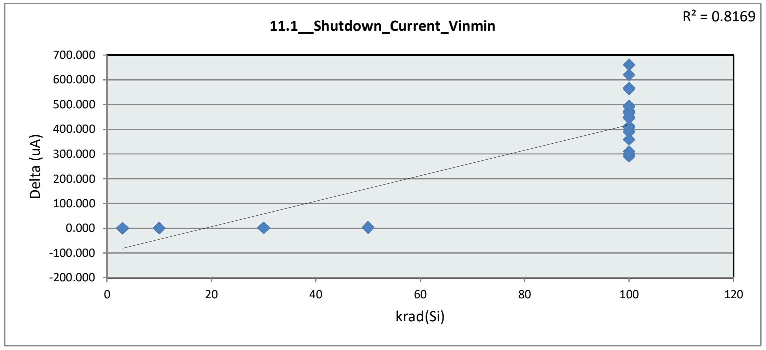


	11.0__Shutdown_Current _Vin				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1400	uA			
Min Limit	0.0005	uA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	20.215	20.767	22.711	24.247	376.697
Average	21.572	22.191	23.521	25.496	608.725
Max	23.248	26.072	24.551	27.013	924.135
UL	1400.000	1400.000	1400.000	1400.000	1400.000

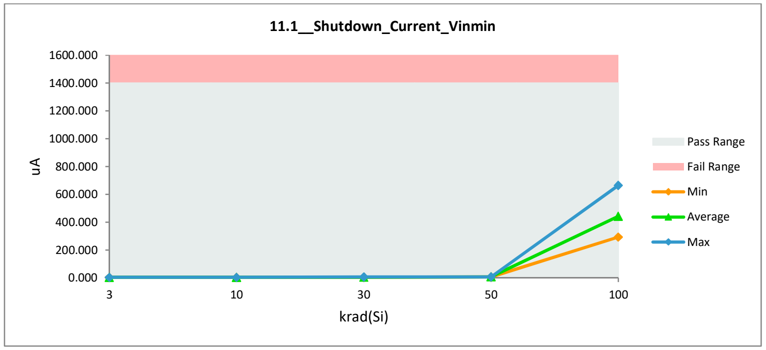


HDR Report
TPS7H1101-SP

		11.1__Shutdown_Current_Vinmi		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1400	1400	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	4.951	4.722	-0.229
3	HDR_W5_D12_Bias	4.941	4.673	-0.268
3	HDR_W6_D13_Bias	4.589	4.518	-0.071
3	HDR_W6_D21_Bias	4.562	4.455	-0.107
3	HDR_W7_D5_Bias	4.703	4.398	-0.305
10	HDR_W5_D9_Bias	4.826	4.740	-0.086
10	HDR_W6_D4_Bias	4.460	4.948	0.488
10	HDR_W6_D28_Bias	4.449	4.684	0.235
10	HDR_W7_D27_Bias	4.512	4.930	0.418
10	HDR_W7_D41_Bias	4.639	4.774	0.135
30	HDR_W5_D29_Bias	4.805	6.415	1.610
30	HDR_W6_D27_Bias	4.436	6.126	1.690
30	HDR_W6_D42_Bias	4.411	6.155	1.744
30	HDR_W7_D31_Bias	4.630	6.323	1.693
30	HDR_W7_D22_Bias	4.680	6.463	1.783
50	HDR_W5_D37_Bias	5.051	8.000	2.949
50	HDR_W5_D39_Bias	4.903	7.573	2.670
50	HDR_W6_D14_Bias	4.481	7.802	3.321
50	HDR_W7_D13_Bias	4.615	7.795	3.180
50	HDR_W7_D37_Bias	4.636	7.921	3.285
100	HDR_W5_D8_Bias	4.637	449.798	445.161
100	HDR_W5_D13_Bias	4.630	303.200	298.570
100	HDR_W5_D30_Bias	4.789	416.448	411.659
100	HDR_W5_D32_Bias	4.841	415.762	410.921
100	HDR_W5_D34_Bias	4.614	293.922	289.308
100	HDR_W5_D38_Bias	4.646	415.291	410.645
100	HDR_W5_D41_Bias	4.845	393.784	388.939
100	HDR_W6_D1_Bias	4.416	571.310	566.894
100	HDR_W6_D8_Bias	4.464	394.806	390.342
100	HDR_W6_D18_Bias	4.514	305.047	300.533
100	HDR_W6_D22_Bias	4.453	363.326	358.873
100	HDR_W6_D24_Bias	4.388	449.464	445.076
100	HDR_W6_D30_Bias	4.452	314.241	309.789
100	HDR_W6_D32_Bias	4.451	499.809	495.358
100	HDR_W6_D39_Bias	4.444	477.600	473.156
100	HDR_W7_D4_Bias	4.669	469.324	464.655
100	HDR_W7_D9_Bias	4.566	566.076	561.510
100	HDR_W7_D17_Bias	4.692	664.911	660.219
100	HDR_W7_D18_Bias	4.670	496.123	491.453
100	HDR_W7_D25_Bias	4.575	454.254	449.679
100	HDR_W7_D34_Bias	4.531	624.510	619.979
100	HDR_W7_D35_Bias	4.532	411.223	406.691
	Max	5.051	664.911	660.219
	Average	4.621	234.944	230.322
	Min	4.388	4.398	-0.305
	Std Dev	0.167	232.550	232.590

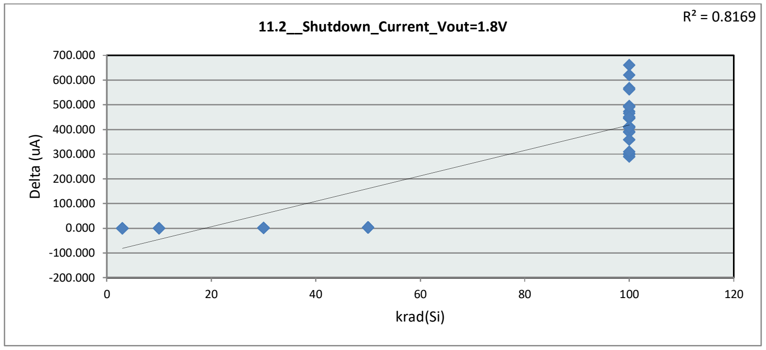


	11.1__Shutdown_Current_Vinr				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1400	uA			
Min Limit	0.0005	uA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	4.398	4.684	6.126	7.573	293.922
Average	4.553	4.815	6.296	7.818	443.192
Max	4.722	4.948	6.463	8.000	664.911
UL	1400.000	1400.000	1400.000	1400.000	1400.000



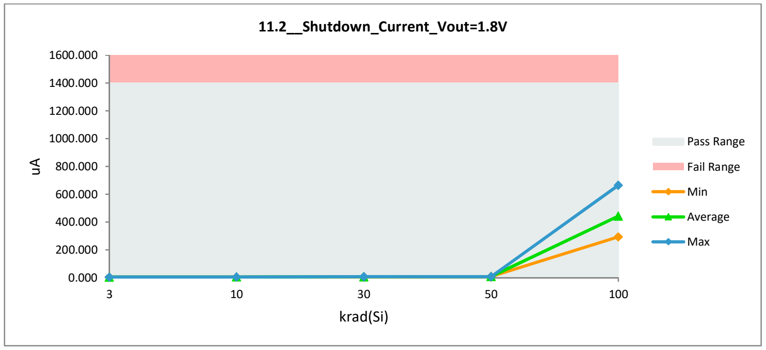
HDR Report
TPS7H1101-SP

		11.2__Shutdown_Current_Vout=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1400	1400	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	5.232	4.950	-0.282
3	HDR_W5_D12_Bias	5.196	4.852	-0.344
3	HDR_W6_D13_Bias	4.853	4.717	-0.136
3	HDR_W6_D21_Bias	4.830	4.645	-0.185
3	HDR_W7_D5_Bias	4.988	4.637	-0.351
10	HDR_W5_D9_Bias	5.099	5.007	-0.092
10	HDR_W6_D4_Bias	4.762	5.176	0.414
10	HDR_W6_D28_Bias	4.734	4.890	0.156
10	HDR_W7_D27_Bias	4.795	5.120	0.325
10	HDR_W7_D41_Bias	4.926	5.015	0.089
30	HDR_W5_D29_Bias	5.074	6.609	1.535
30	HDR_W6_D27_Bias	4.721	6.343	1.622
30	HDR_W6_D42_Bias	4.701	6.407	1.706
30	HDR_W7_D31_Bias	4.906	6.562	1.656
30	HDR_W7_D22_Bias	4.944	6.681	1.737
50	HDR_W5_D37_Bias	5.316	8.208	2.892
50	HDR_W5_D39_Bias	5.184	7.787	2.603
50	HDR_W6_D14_Bias	4.781	8.016	3.235
50	HDR_W7_D13_Bias	4.886	7.999	3.113
50	HDR_W7_D37_Bias	4.889	8.163	3.274
100	HDR_W5_D8_Bias	4.931	450.217	445.286
100	HDR_W5_D13_Bias	4.900	303.742	298.842
100	HDR_W5_D30_Bias	5.070	416.780	411.710
100	HDR_W5_D32_Bias	5.115	416.041	410.926
100	HDR_W5_D34_Bias	4.895	294.186	289.291
100	HDR_W5_D38_Bias	4.942	415.581	410.639
100	HDR_W5_D41_Bias	5.118	393.997	388.879
100	HDR_W6_D1_Bias	4.702	571.892	567.190
100	HDR_W6_D8_Bias	4.750	395.401	390.651
100	HDR_W6_D18_Bias	4.784	305.687	300.903
100	HDR_W6_D22_Bias	4.732	363.555	358.823
100	HDR_W6_D24_Bias	4.675	449.732	445.057
100	HDR_W6_D30_Bias	4.746	314.450	309.704
100	HDR_W6_D32_Bias	4.717	499.938	495.221
100	HDR_W6_D39_Bias	4.721	477.642	472.921
100	HDR_W7_D4_Bias	4.982	469.853	464.871
100	HDR_W7_D9_Bias	4.856	566.516	561.660
100	HDR_W7_D17_Bias	4.967	665.517	660.550
100	HDR_W7_D18_Bias	4.966	496.280	491.314
100	HDR_W7_D25_Bias	4.880	454.680	449.800
100	HDR_W7_D34_Bias	4.820	625.108	620.288
100	HDR_W7_D35_Bias	4.832	411.766	406.934
	Max	5.316	665.517	660.550
	Average	4.903	235.246	230.344
	Min	4.675	4.637	-0.351
	Std Dev	0.162	232.635	232.671


R² = 0.8169

11.2__Shutdown_Current_Vout=1.8V

	11.2__Shutdown_Current_Vou				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1400	uA			
Min Limit	0.0005	uA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	4.637	4.890	6.343	7.787	294.186
Average	4.760	5.042	6.520	8.035	443.571
Max	4.950	5.176	6.681	8.208	665.517
UL	1400.000	1400.000	1400.000	1400.000	1400.000


11.2__Shutdown_Current_Vout=1.8V

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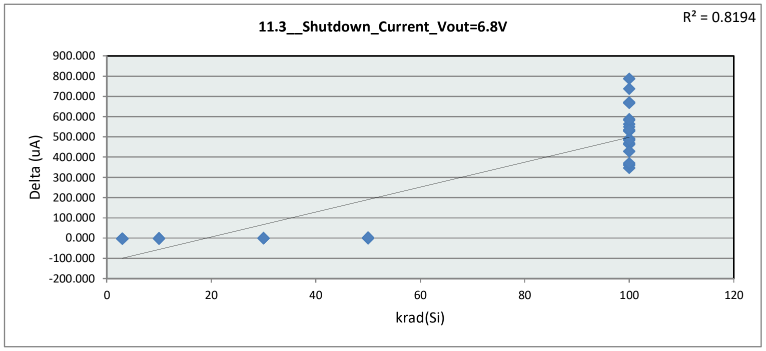
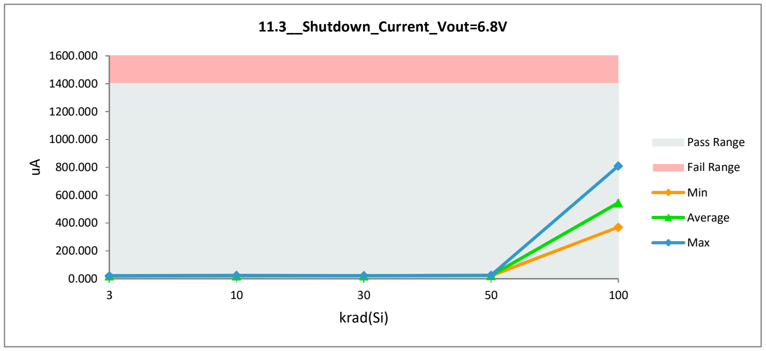
		11.3__Shutdown_Current_Vout=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1400	1400	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	23.772	20.580	-3.192
3	HDR_W5_D12_Bias	23.692	20.251	-3.441
3	HDR_W6_D13_Bias	21.303	18.425	-2.878
3	HDR_W6_D21_Bias	20.963	18.012	-2.951
3	HDR_W7_D5_Bias	21.918	18.255	-3.663
10	HDR_W5_D9_Bias	23.554	23.462	-0.092
10	HDR_W6_D4_Bias	20.706	19.070	-1.636
10	HDR_W6_D28_Bias	20.881	18.391	-2.490
10	HDR_W7_D27_Bias	21.255	18.951	-2.304
10	HDR_W7_D41_Bias	22.019	18.869	-3.150
30	HDR_W5_D29_Bias	23.004	22.051	-0.953
30	HDR_W6_D27_Bias	20.743	20.453	-0.290
30	HDR_W6_D42_Bias	20.808	20.220	-0.588
30	HDR_W7_D31_Bias	21.680	20.994	-0.686
30	HDR_W7_D22_Bias	21.968	21.271	-0.697
50	HDR_W5_D37_Bias	23.970	24.395	0.425
50	HDR_W5_D39_Bias	23.677	21.814	-1.863
50	HDR_W6_D14_Bias	20.758	22.555	1.797
50	HDR_W7_D13_Bias	21.560	22.374	0.814
50	HDR_W7_D37_Bias	21.643	24.435	2.792
100	HDR_W5_D8_Bias	23.191	551.234	528.043
100	HDR_W5_D13_Bias	22.850	382.192	359.342
100	HDR_W5_D30_Bias	23.272	511.632	488.360
100	HDR_W5_D32_Bias	23.387	513.671	490.284
100	HDR_W5_D34_Bias	22.716	369.194	346.478
100	HDR_W5_D38_Bias	22.858	511.300	488.442
100	HDR_W5_D41_Bias	23.413	486.059	462.646
100	HDR_W6_D1_Bias	20.334	690.374	670.040
100	HDR_W6_D8_Bias	20.951	488.399	467.448
100	HDR_W6_D18_Bias	20.933	383.306	362.373
100	HDR_W6_D22_Bias	20.644	448.456	427.812
100	HDR_W6_D24_Bias	20.481	549.647	529.166
100	HDR_W6_D30_Bias	20.658	390.639	369.981
100	HDR_W6_D32_Bias	20.884	608.046	587.162
100	HDR_W6_D39_Bias	20.706	583.235	562.529
100	HDR_W7_D4_Bias	21.442	571.106	549.664
100	HDR_W7_D9_Bias	21.458	688.026	666.568
100	HDR_W7_D17_Bias	21.383	808.498	787.115
100	HDR_W7_D18_Bias	21.563	604.409	582.846
100	HDR_W7_D25_Bias	21.265	555.186	533.921
100	HDR_W7_D34_Bias	21.423	758.080	736.657
100	HDR_W7_D35_Bias	21.622	504.820	483.198
	Max	23.970	808.498	787.115
	Average	21.841	294.579	272.739
	Min	20.334	18.012	-3.663
	Std Dev	1.105	277.517	277.716



	11.3__Shutdown_Current_Vou				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1400	uA			
Min Limit	0.0005	uA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	18.012	18.391	20.220	21.814	369.194
Average	19.105	19.749	20.998	23.115	543.523
Max	20.580	23.462	22.051	24.435	808.498
UL	1400.000	1400.000	1400.000	1400.000	1400.000



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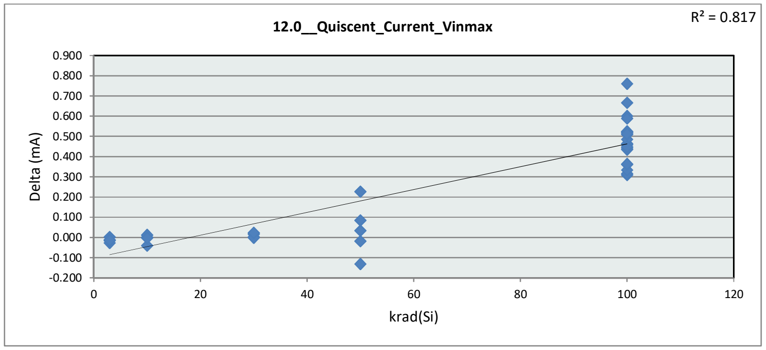
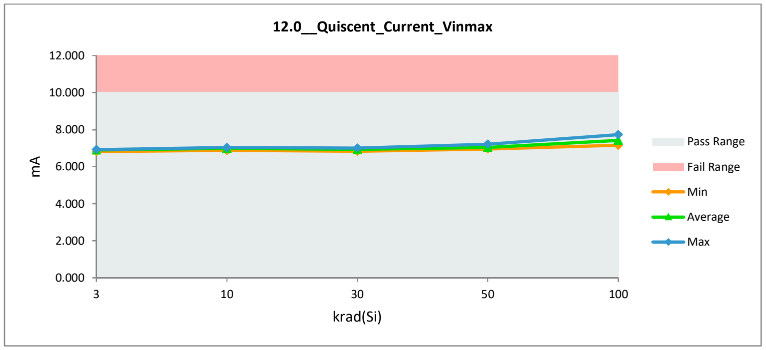
		12.0__Quiscent_Current_Vinmax		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	6.955	6.928	-0.027
3	HDR_W5_D12_Bias	6.944	6.929	-0.015
3	HDR_W6_D13_Bias	6.916	6.918	0.002
3	HDR_W6_D21_Bias	6.918	6.907	-0.011
3	HDR_W7_D5_Bias	6.833	6.819	-0.014
10	HDR_W5_D9_Bias	6.986	6.946	-0.040
10	HDR_W6_D4_Bias	7.028	7.039	0.011
10	HDR_W6_D28_Bias	6.883	6.884	0.001
10	HDR_W6_D27_Bias	7.034	7.047	0.013
10	HDR_W7_D41_Bias	7.020	7.018	-0.002
30	HDR_W5_D29_Bias	7.013	7.016	0.003
30	HDR_W6_D27_Bias	6.820	6.842	0.022
30	HDR_W6_D42_Bias	6.805	6.822	0.017
30	HDR_W7_D31_Bias	6.951	6.950	-0.001
30	HDR_W7_D22_Bias	6.984	7.007	0.023
50	HDR_W5_D37_Bias	6.986	7.020	0.034
50	HDR_W5_D39_Bias	6.978	6.960	-0.018
50	HDR_W6_D14_Bias	6.925	7.010	0.085
50	HDR_W7_D13_Bias	6.990	7.217	0.227
50	HDR_W7_D37_Bias	7.142	7.011	-0.131
100	HDR_W5_D8_Bias	6.923	7.448	0.525
100	HDR_W5_D13_Bias	7.032	7.341	0.309
100	HDR_W5_D30_Bias	6.959	7.404	0.445
100	HDR_W5_D32_Bias	6.979	7.439	0.460
100	HDR_W5_D34_Bias	7.080	7.395	0.315
100	HDR_W5_D38_Bias	6.987	7.422	0.435
100	HDR_W5_D41_Bias	6.917	7.381	0.464
100	HDR_W6_D1_Bias	6.948	7.549	0.601
100	HDR_W6_D8_Bias	6.955	7.393	0.438
100	HDR_W6_D18_Bias	6.922	7.255	0.333
100	HDR_W6_D22_Bias	6.801	7.162	0.361
100	HDR_W6_D24_Bias	6.865	7.350	0.485
100	HDR_W6_D30_Bias	6.798	7.162	0.364
100	HDR_W6_D32_Bias	6.896	7.414	0.518
100	HDR_W6_D39_Bias	6.898	7.420	0.522
100	HDR_W7_D4_Bias	6.960	7.481	0.521
100	HDR_W7_D9_Bias	7.016	7.605	0.589
100	HDR_W7_D17_Bias	6.979	7.739	0.760
100	HDR_W7_D18_Bias	6.956	7.466	0.510
100	HDR_W7_D25_Bias	7.035	7.548	0.513
100	HDR_W7_D34_Bias	6.977	7.643	0.666
100	HDR_W7_D35_Bias	6.950	7.399	0.449
	Max	7.142	7.739	0.760
	Average	6.951	7.207	0.256
	Min	6.798	6.819	-0.131
	Std Dev	0.074	0.262	0.255



	12.0__Quiscent_Current_Vinm				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	10	mA			
Min Limit	0.0005	mA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	6.819	6.884	6.822	6.960	7.162
Average	6.900	6.987	6.927	7.044	7.428
Max	6.929	7.047	7.016	7.217	7.739
UL	10.000	10.000	10.000	10.000	10.000



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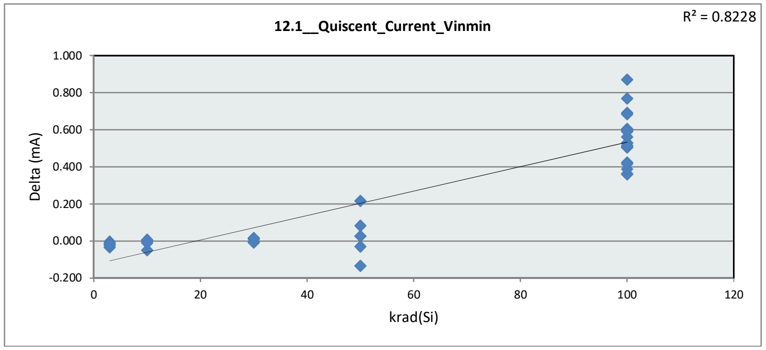
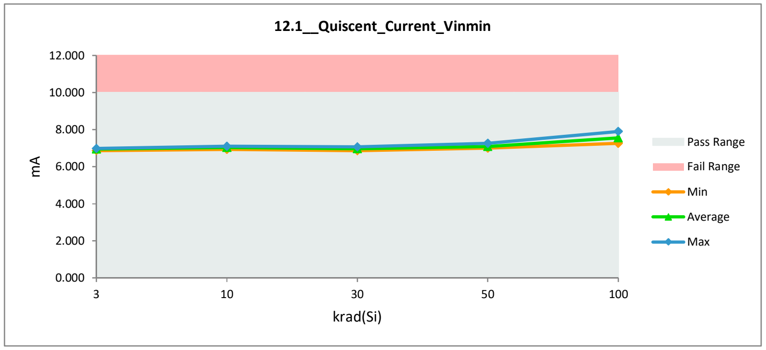
		12.1__Quiscent_Current_Vinmin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	7.013	6.980	-0.033
3	HDR_W5_D12_Bias	7.002	6.980	-0.022
3	HDR_W6_D13_Bias	6.966	6.963	-0.003
3	HDR_W6_D21_Bias	6.967	6.954	-0.013
3	HDR_W7_D5_Bias	6.888	6.868	-0.020
10	HDR_W5_D9_Bias	7.041	6.992	-0.049
10	HDR_W6_D4_Bias	7.078	7.082	0.004
10	HDR_W6_D28_Bias	6.934	6.931	-0.003
10	HDR_W7_D27_Bias	7.088	7.095	0.007
10	HDR_W7_D41_Bias	7.074	7.064	-0.010
30	HDR_W5_D29_Bias	7.067	7.063	-0.004
30	HDR_W6_D27_Bias	6.872	6.885	0.013
30	HDR_W6_D42_Bias	6.856	6.866	0.010
30	HDR_W7_D31_Bias	7.006	6.999	-0.007
30	HDR_W7_D22_Bias	7.039	7.055	0.016
50	HDR_W5_D37_Bias	7.042	7.069	0.027
50	HDR_W5_D39_Bias	7.034	7.005	-0.029
50	HDR_W6_D14_Bias	6.975	7.058	0.083
50	HDR_W7_D13_Bias	7.043	7.259	0.216
50	HDR_W7_D37_Bias	7.193	7.059	-0.134
100	HDR_W5_D8_Bias	6.982	7.578	0.596
100	HDR_W5_D13_Bias	7.086	7.449	0.363
100	HDR_W5_D30_Bias	7.016	7.527	0.511
100	HDR_W5_D32_Bias	7.036	7.565	0.529
100	HDR_W5_D34_Bias	7.132	7.492	0.360
100	HDR_W5_D38_Bias	7.042	7.547	0.505
100	HDR_W5_D41_Bias	6.973	7.502	0.529
100	HDR_W6_D1_Bias	6.997	7.688	0.691
100	HDR_W6_D8_Bias	7.006	7.512	0.506
100	HDR_W6_D18_Bias	6.972	7.360	0.388
100	HDR_W6_D22_Bias	6.852	7.275	0.423
100	HDR_W6_D24_Bias	6.915	7.477	0.562
100	HDR_W6_D30_Bias	6.850	7.267	0.417
100	HDR_W6_D32_Bias	6.946	7.548	0.602
100	HDR_W6_D39_Bias	6.948	7.552	0.604
100	HDR_W7_D4_Bias	7.015	7.614	0.599
100	HDR_W7_D9_Bias	7.070	7.754	0.684
100	HDR_W7_D17_Bias	7.035	7.905	0.870
100	HDR_W7_D18_Bias	7.011	7.605	0.594
100	HDR_W7_D25_Bias	7.087	7.677	0.590
100	HDR_W7_D34_Bias	7.033	7.802	0.769
100	HDR_W7_D35_Bias	7.005	7.520	0.515
	Max	7.193	7.905	0.870
	Average	7.004	7.296	0.292
	Min	6.850	6.866	-0.134
	Std Dev	0.075	0.302	0.297



	12.1__Quiscent_Current_Vinm				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	10	mA			
Min Limit	0.0005	mA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	6.868	6.931	6.866	7.005	7.267
Average	6.949	7.033	6.974	7.090	7.555
Max	6.980	7.095	7.063	7.259	7.905
UL	10.000	10.000	10.000	10.000	10.000



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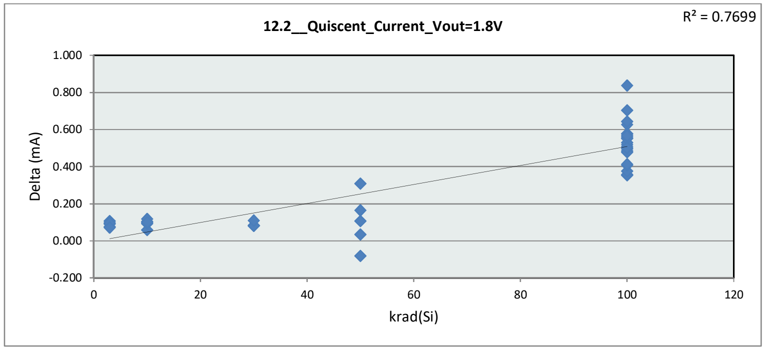
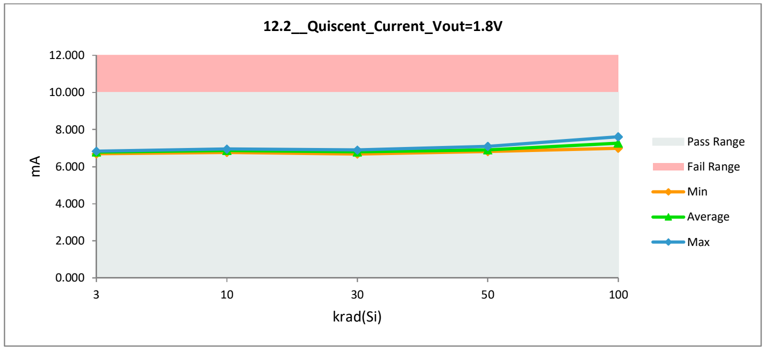
		12.2__Quiscent_Current_Vout=1		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	6.746	6.821	0.075
3	HDR_W5_D12_Bias	6.738	6.829	0.091
3	HDR_W6_D13_Bias	6.705	6.811	0.106
3	HDR_W6_D21_Bias	6.705	6.801	0.096
3	HDR_W7_D5_Bias	6.619	6.690	0.071
10	HDR_W5_D9_Bias	6.781	6.840	0.059
10	HDR_W6_D4_Bias	6.831	6.935	0.104
10	HDR_W6_D28_Bias	6.674	6.767	0.093
10	HDR_W7_D27_Bias	6.825	6.943	0.118
10	HDR_W7_D41_Bias	6.809	6.909	0.100
30	HDR_W5_D29_Bias	6.810	6.894	0.084
30	HDR_W6_D27_Bias	6.612	6.695	0.083
30	HDR_W6_D42_Bias	6.594	6.676	0.082
30	HDR_W7_D31_Bias	6.741	6.822	0.081
30	HDR_W7_D22_Bias	6.777	6.887	0.110
50	HDR_W5_D37_Bias	6.777	6.883	0.106
50	HDR_W5_D39_Bias	6.779	6.813	0.034
50	HDR_W6_D14_Bias	6.717	6.881	0.164
50	HDR_W7_D13_Bias	6.789	7.097	0.308
50	HDR_W7_D37_Bias	6.963	6.882	-0.081
100	HDR_W5_D8_Bias	6.722	7.297	0.575
100	HDR_W5_D13_Bias	6.848	7.202	0.354
100	HDR_W5_D30_Bias	6.757	7.252	0.495
100	HDR_W5_D32_Bias	6.778	7.286	0.508
100	HDR_W5_D34_Bias	6.887	7.244	0.357
100	HDR_W5_D38_Bias	6.782	7.266	0.484
100	HDR_W5_D41_Bias	6.708	7.226	0.518
100	HDR_W6_D1_Bias	6.747	7.374	0.627
100	HDR_W6_D8_Bias	6.750	7.228	0.478
100	HDR_W6_D18_Bias	6.714	7.089	0.375
100	HDR_W6_D22_Bias	6.590	6.997	0.407
100	HDR_W6_D24_Bias	6.654	7.184	0.530
100	HDR_W6_D30_Bias	6.587	7.000	0.413
100	HDR_W6_D32_Bias	6.687	7.242	0.555
100	HDR_W6_D39_Bias	6.688	7.253	0.565
100	HDR_W7_D4_Bias	6.754	7.331	0.577
100	HDR_W7_D9_Bias	6.815	7.458	0.643
100	HDR_W7_D17_Bias	6.770	7.607	0.837
100	HDR_W7_D18_Bias	6.746	7.297	0.551
100	HDR_W7_D25_Bias	6.830	7.396	0.566
100	HDR_W7_D34_Bias	6.769	7.472	0.703
100	HDR_W7_D35_Bias	6.742	7.243	0.501
	Max	6.963	7.607	0.837
	Average	6.746	7.067	0.322
	Min	6.587	6.676	-0.081
	Std Dev	0.079	0.247	0.239

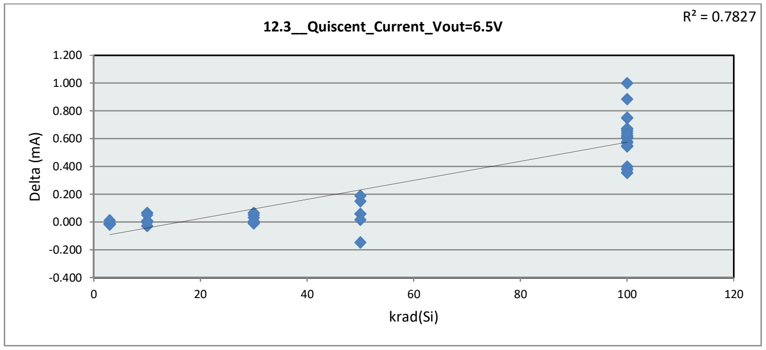


	12.2__Quiscent_Current_Vout=				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	10	mA			
Min Limit	0.0005	mA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	6.690	6.767	6.676	6.813	6.997
Average	6.790	6.879	6.795	6.911	7.270
Max	6.829	6.943	6.894	7.097	7.607
UL	10.000	10.000	10.000	10.000	10.000

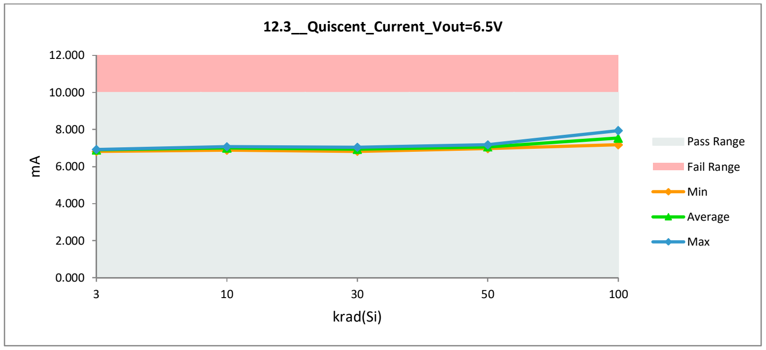


HDR Report
TPS7H1101-SP

		12.3__Quiscent_Current_Vout=6		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	6.934	6.922	-0.012
3	HDR_W5_D12_Bias	6.944	6.926	-0.018
3	HDR_W6_D13_Bias	6.913	6.903	-0.010
3	HDR_W6_D21_Bias	6.925	6.911	-0.014
3	HDR_W7_D5_Bias	6.802	6.815	0.013
10	HDR_W5_D9_Bias	6.959	6.931	-0.028
10	HDR_W6_D4_Bias	7.002	7.068	0.066
10	HDR_W6_D28_Bias	6.876	6.885	0.009
10	HDR_W7_D27_Bias	7.005	7.056	0.051
10	HDR_W7_D41_Bias	7.033	7.033	0.000
30	HDR_W5_D29_Bias	6.992	7.043	0.051
30	HDR_W6_D27_Bias	6.856	6.846	-0.010
30	HDR_W6_D42_Bias	6.819	6.823	0.004
30	HDR_W7_D31_Bias	6.918	6.950	0.032
30	HDR_W7_D22_Bias	6.950	7.017	0.067
50	HDR_W5_D37_Bias	6.995	7.055	0.060
50	HDR_W5_D39_Bias	6.956	6.973	0.017
50	HDR_W6_D14_Bias	6.896	7.046	0.150
50	HDR_W7_D13_Bias	6.990	7.179	0.189
50	HDR_W7_D37_Bias	7.177	7.031	-0.146
100	HDR_W5_D8_Bias	6.897	7.552	0.655
100	HDR_W5_D13_Bias	7.013	7.395	0.382
100	HDR_W5_D30_Bias	6.956	7.506	0.550
100	HDR_W5_D32_Bias	6.953	7.556	0.603
100	HDR_W5_D34_Bias	7.105	7.462	0.357
100	HDR_W5_D38_Bias	6.950	7.522	0.572
100	HDR_W5_D41_Bias	6.898	7.477	0.579
100	HDR_W6_D1_Bias	6.943	7.691	0.748
100	HDR_W6_D8_Bias	6.934	7.479	0.545
100	HDR_W6_D18_Bias	6.887	7.287	0.400
100	HDR_W6_D22_Bias	6.812	7.190	0.378
100	HDR_W6_D24_Bias	6.840	7.447	0.607
100	HDR_W6_D30_Bias	6.827	7.180	0.353
100	HDR_W6_D32_Bias	6.909	7.531	0.622
100	HDR_W6_D39_Bias	6.923	7.537	0.614
100	HDR_W7_D4_Bias	6.934	7.602	0.668
100	HDR_W7_D9_Bias	7.020	7.772	0.752
100	HDR_W7_D17_Bias	6.944	7.945	1.001
100	HDR_W7_D18_Bias	6.939	7.613	0.674
100	HDR_W7_D25_Bias	7.040	7.679	0.639
100	HDR_W7_D34_Bias	6.944	7.828	0.884
100	HDR_W7_D35_Bias	6.942	7.489	0.547
	Max	7.177	7.945	1.001
	Average	6.942	7.266	0.324
	Min	6.802	6.815	-0.146
	Std Dev	0.074	0.320	0.316



	12.3__Quiscent_Current_Vout=				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	10	mA			
Min Limit	0.0005	mA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	6.815	6.885	6.823	6.973	7.180
Average	6.895	6.995	6.936	7.057	7.534
Max	6.926	7.068	7.043	7.179	7.945
UL	10.000	10.000	10.000	10.000	10.000



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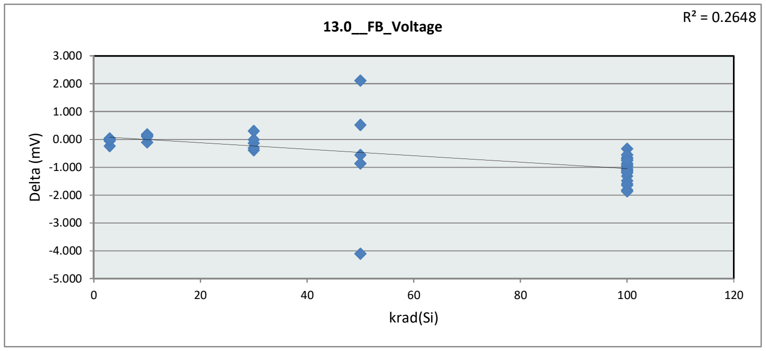
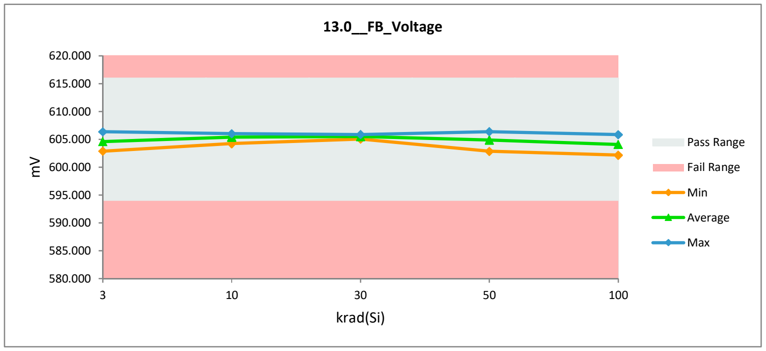
krad(Si)	Serial #	Pre	Post	Delta
		13.0__FB_Voltage		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	603.136	602.900	-0.236
3	HDR_W5_D12_Bias	604.987	605.018	0.031
3	HDR_W6_D13_Bias	606.439	606.386	-0.053
3	HDR_W6_D21_Bias	605.118	605.150	0.032
3	HDR_W7_D5_Bias	603.597	603.605	0.008
10	HDR_W5_D9_Bias	604.336	604.228	-0.108
10	HDR_W6_D4_Bias	605.717	605.848	0.131
10	HDR_W6_D28_Bias	605.846	606.029	0.183
10	HDR_W7_D27_Bias	605.921	606.013	0.092
10	HDR_W7_D41_Bias	604.691	604.842	0.151
30	HDR_W5_D29_Bias	606.193	605.804	-0.389
30	HDR_W6_D27_Bias	605.708	605.572	-0.136
30	HDR_W6_D42_Bias	605.250	605.240	-0.010
30	HDR_W7_D31_Bias	606.196	605.891	-0.305
30	HDR_W7_D22_Bias	604.756	605.055	0.299
50	HDR_W5_D37_Bias	604.781	604.221	-0.560
50	HDR_W5_D39_Bias	603.707	605.817	2.110
50	HDR_W6_D14_Bias	605.986	605.121	-0.865
50	HDR_W7_D13_Bias	605.891	606.414	0.523
50	HDR_W7_D37_Bias	606.968	602.862	-4.106
100	HDR_W5_D8_Bias	605.384	604.410	-0.974
100	HDR_W5_D13_Bias	605.192	604.336	-0.856
100	HDR_W5_D30_Bias	603.847	603.193	-0.654
100	HDR_W5_D32_Bias	602.903	602.171	-0.732
100	HDR_W5_D34_Bias	606.193	605.238	-0.955
100	HDR_W5_D38_Bias	603.732	602.831	-0.901
100	HDR_W5_D41_Bias	604.595	603.535	-1.060
100	HDR_W6_D1_Bias	606.107	604.291	-1.816
100	HDR_W6_D8_Bias	604.960	604.628	-0.332
100	HDR_W6_D18_Bias	607.180	605.860	-1.320
100	HDR_W6_D22_Bias	605.381	604.625	-0.756
100	HDR_W6_D24_Bias	604.527	603.421	-1.106
100	HDR_W6_D30_Bias	605.918	604.323	-1.595
100	HDR_W6_D32_Bias	605.887	605.210	-0.677
100	HDR_W6_D39_Bias	605.022	603.533	-1.489
100	HDR_W7_D4_Bias	605.871	604.716	-1.155
100	HDR_W7_D9_Bias	605.786	604.592	-1.194
100	HDR_W7_D17_Bias	604.763	604.200	-0.563
100	HDR_W7_D18_Bias	603.979	602.337	-1.642
100	HDR_W7_D25_Bias	607.288	605.425	-1.863
100	HDR_W7_D34_Bias	604.385	603.834	-0.551
100	HDR_W7_D35_Bias	604.287	603.533	-0.754
	Max	607.288	606.414	2.110
	Average	605.200	604.578	-0.623
	Min	602.903	602.171	-4.106
	Std Dev	1.047	1.118	0.919



	13.0__FB_Voltage				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	616	mV			
Min Limit	594	mV			
krad(Si)	3	10	30	50	100
LL	594.000	594.000	594.000	594.000	594.000
Min	602.900	604.228	605.055	602.862	602.171
Average	604.612	605.392	605.512	604.887	604.102
Max	606.386	606.029	605.891	606.414	605.860
UL	616.000	616.000	616.000	616.000	616.000



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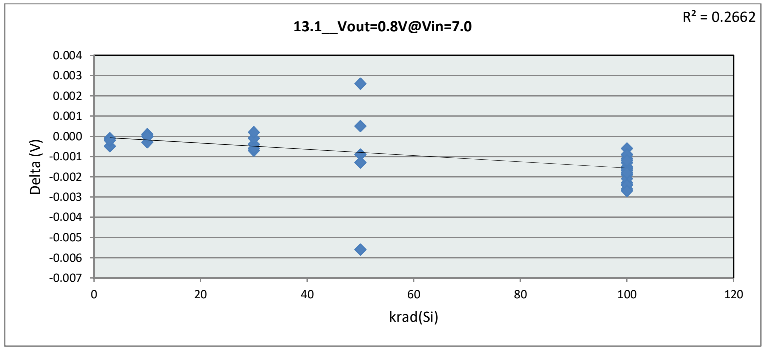
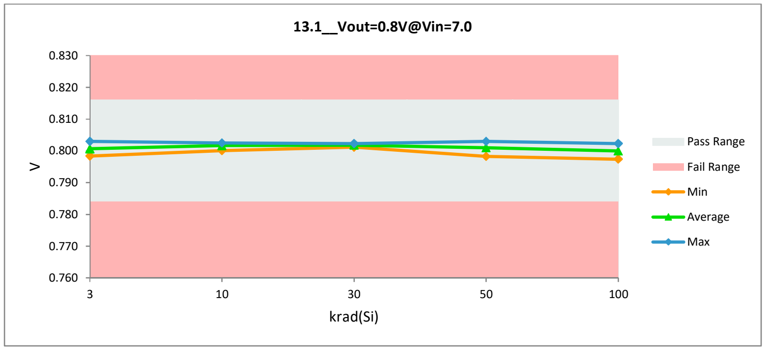
		13.1__Vout=0.8V@Vin=7.0		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.799	0.798	-0.001
3	HDR_W5_D12_Bias	0.801	0.801	0.000
3	HDR_W6_D13_Bias	0.803	0.803	0.000
3	HDR_W6_D21_Bias	0.802	0.801	0.000
3	HDR_W7_D5_Bias	0.799	0.799	0.000
10	HDR_W5_D9_Bias	0.800	0.800	0.000
10	HDR_W6_D4_Bias	0.802	0.802	0.000
10	HDR_W6_D28_Bias	0.802	0.803	0.000
10	HDR_W7_D27_Bias	0.803	0.803	0.000
10	HDR_W7_D41_Bias	0.801	0.801	0.000
30	HDR_W5_D29_Bias	0.803	0.802	-0.001
30	HDR_W6_D27_Bias	0.802	0.802	0.000
30	HDR_W6_D42_Bias	0.802	0.802	0.000
30	HDR_W7_D31_Bias	0.803	0.802	-0.001
30	HDR_W7_D22_Bias	0.801	0.801	0.000
50	HDR_W5_D37_Bias	0.801	0.800	-0.001
50	HDR_W5_D39_Bias	0.800	0.802	0.003
50	HDR_W6_D14_Bias	0.803	0.801	-0.001
50	HDR_W7_D13_Bias	0.803	0.803	0.000
50	HDR_W7_D37_Bias	0.804	0.798	-0.006
100	HDR_W5_D8_Bias	0.802	0.800	-0.002
100	HDR_W5_D13_Bias	0.802	0.800	-0.001
100	HDR_W5_D30_Bias	0.800	0.799	-0.001
100	HDR_W5_D32_Bias	0.799	0.797	-0.001
100	HDR_W5_D34_Bias	0.803	0.801	-0.002
100	HDR_W5_D38_Bias	0.800	0.798	-0.001
100	HDR_W5_D41_Bias	0.801	0.799	-0.002
100	HDR_W6_D1_Bias	0.803	0.800	-0.003
100	HDR_W6_D8_Bias	0.801	0.801	-0.001
100	HDR_W6_D18_Bias	0.804	0.802	-0.002
100	HDR_W6_D22_Bias	0.802	0.801	-0.001
100	HDR_W6_D24_Bias	0.801	0.799	-0.002
100	HDR_W6_D30_Bias	0.803	0.800	-0.002
100	HDR_W6_D32_Bias	0.803	0.801	-0.001
100	HDR_W6_D39_Bias	0.801	0.799	-0.002
100	HDR_W7_D4_Bias	0.803	0.801	-0.002
100	HDR_W7_D9_Bias	0.802	0.801	-0.002
100	HDR_W7_D17_Bias	0.801	0.800	-0.001
100	HDR_W7_D18_Bias	0.800	0.798	-0.002
100	HDR_W7_D25_Bias	0.804	0.802	-0.003
100	HDR_W7_D34_Bias	0.800	0.800	-0.001
100	HDR_W7_D35_Bias	0.800	0.799	-0.001
	Max	0.804	0.803	0.003
	Average	0.802	0.801	-0.001
	Min	0.799	0.797	-0.006
	Std Dev	0.001	0.001	0.001



	13.1__Vout=0.8V@Vin=7.0				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.816	V			
Min Limit	0.784	V			
krad(Si)	3	10	30	50	100
LL	0.784	0.784	0.784	0.784	0.784
Min	0.798	0.800	0.801	0.798	0.797
Average	0.801	0.802	0.802	0.801	0.800
Max	0.803	0.803	0.802	0.803	0.802
UL	0.816	0.816	0.816	0.816	0.816



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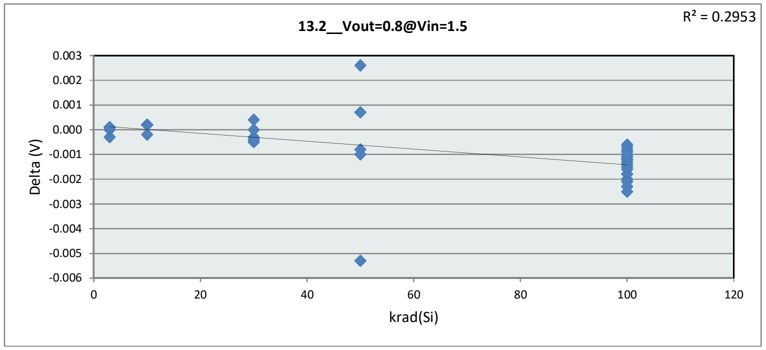
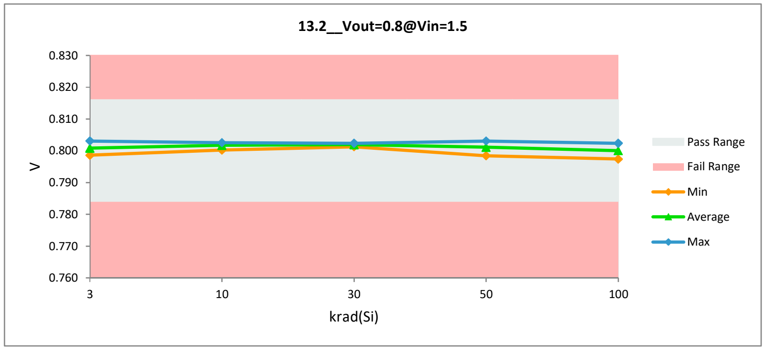
krad(Si)	Serial #	Pre	Post	Delta
		13.2__Vout=0.8@Vin=1.5		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
3	HDR_W5_D2_Bias	0.799	0.799	0.000
3	HDR_W5_D12_Bias	0.801	0.801	0.000
3	HDR_W6_D13_Bias	0.803	0.803	0.000
3	HDR_W6_D21_Bias	0.801	0.802	0.000
3	HDR_W7_D5_Bias	0.799	0.800	0.000
10	HDR_W5_D9_Bias	0.800	0.800	0.000
10	HDR_W6_D4_Bias	0.802	0.802	0.000
10	HDR_W6_D28_Bias	0.802	0.803	0.000
10	HDR_W7_D27_Bias	0.802	0.803	0.000
10	HDR_W7_D41_Bias	0.801	0.801	0.000
30	HDR_W5_D29_Bias	0.803	0.802	-0.001
30	HDR_W6_D27_Bias	0.802	0.802	0.000
30	HDR_W6_D42_Bias	0.802	0.802	0.000
30	HDR_W7_D31_Bias	0.803	0.802	0.000
30	HDR_W7_D22_Bias	0.801	0.801	0.000
50	HDR_W5_D37_Bias	0.801	0.800	-0.001
50	HDR_W5_D39_Bias	0.800	0.802	0.003
50	HDR_W6_D14_Bias	0.803	0.802	-0.001
50	HDR_W7_D13_Bias	0.802	0.803	0.001
50	HDR_W7_D37_Bias	0.804	0.799	-0.005
100	HDR_W5_D8_Bias	0.802	0.800	-0.001
100	HDR_W5_D13_Bias	0.802	0.800	-0.001
100	HDR_W5_D30_Bias	0.800	0.799	-0.001
100	HDR_W5_D32_Bias	0.799	0.797	-0.001
100	HDR_W5_D34_Bias	0.803	0.802	-0.001
100	HDR_W5_D38_Bias	0.799	0.798	-0.001
100	HDR_W5_D41_Bias	0.801	0.799	-0.001
100	HDR_W6_D1_Bias	0.803	0.800	-0.002
100	HDR_W6_D8_Bias	0.801	0.801	-0.001
100	HDR_W6_D18_Bias	0.804	0.802	-0.002
100	HDR_W6_D22_Bias	0.802	0.801	-0.001
100	HDR_W6_D24_Bias	0.801	0.799	-0.002
100	HDR_W6_D30_Bias	0.803	0.800	-0.002
100	HDR_W6_D32_Bias	0.802	0.802	-0.001
100	HDR_W6_D39_Bias	0.801	0.799	-0.002
100	HDR_W7_D4_Bias	0.802	0.801	-0.002
100	HDR_W7_D9_Bias	0.802	0.801	-0.001
100	HDR_W7_D17_Bias	0.801	0.800	-0.001
100	HDR_W7_D18_Bias	0.800	0.798	-0.002
100	HDR_W7_D25_Bias	0.804	0.802	-0.002
100	HDR_W7_D34_Bias	0.800	0.800	-0.001
100	HDR_W7_D35_Bias	0.800	0.799	-0.001
	Max	0.804	0.803	0.003
	Average	0.802	0.801	-0.001
	Min	0.799	0.797	-0.005
	Std Dev	0.001	0.001	0.001



krad(Si)	3	10	30	50	100
	13.2__Vout=0.8@Vin=1.5				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.816	V			
Min Limit	0.784	V			
LL	0.784	0.784	0.784	0.784	0.784
Min	0.799	0.800	0.801	0.799	0.797
Average	0.801	0.802	0.802	0.801	0.800
Max	0.803	0.803	0.802	0.803	0.802
UL	0.816	0.816	0.816	0.816	0.816



HDR Report
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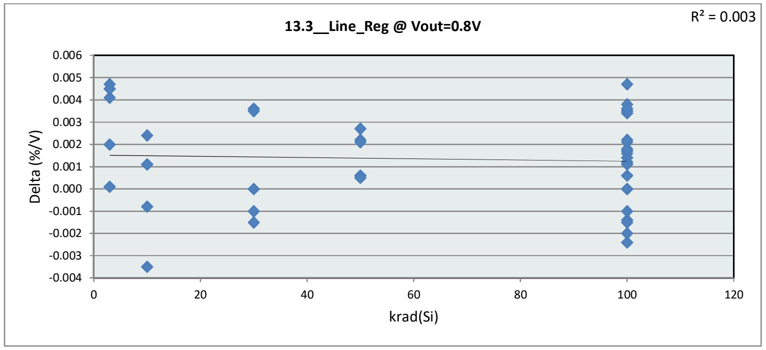
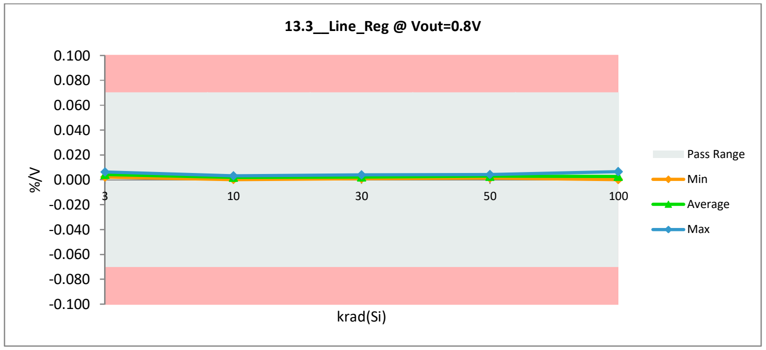
		13.3__Line_Reg @ Vout=0.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.000	0.004	0.004
3	HDR_W5_D12_Bias	0.001	0.005	0.005
3	HDR_W6_D13_Bias	0.002	0.002	0.000
3	HDR_W6_D21_Bias	0.001	0.003	0.002
3	HDR_W7_D5_Bias	0.002	0.006	0.005
10	HDR_W5_D9_Bias	0.001	0.002	0.001
10	HDR_W6_D4_Bias	0.002	0.003	0.001
10	HDR_W6_D28_Bias	0.004	0.000	-0.004
10	HDR_W7_D27_Bias	0.003	0.002	-0.001
10	HDR_W7_D41_Bias	0.001	0.003	0.002
30	HDR_W5_D29_Bias	0.000	0.004	0.004
30	HDR_W6_D27_Bias	0.000	0.004	0.003
30	HDR_W6_D42_Bias	0.002	0.001	-0.001
30	HDR_W7_D31_Bias	0.002	0.001	-0.002
30	HDR_W7_D22_Bias	0.002	0.002	0.000
50	HDR_W5_D37_Bias	0.001	0.003	0.003
50	HDR_W5_D39_Bias	0.001	0.002	0.001
50	HDR_W6_D14_Bias	0.002	0.004	0.002
50	HDR_W7_D13_Bias	0.001	0.002	0.000
50	HDR_W7_D37_Bias	0.002	0.004	0.002
100	HDR_W5_D8_Bias	0.000	0.004	0.004
100	HDR_W5_D13_Bias	0.000	0.004	0.004
100	HDR_W5_D30_Bias	0.000	0.005	0.005
100	HDR_W5_D32_Bias	0.001	0.001	0.000
100	HDR_W5_D34_Bias	0.001	0.001	0.001
100	HDR_W5_D38_Bias	0.002	0.001	-0.001
100	HDR_W5_D41_Bias	0.003	0.007	0.003
100	HDR_W6_D1_Bias	0.002	0.003	0.002
100	HDR_W6_D8_Bias	0.003	0.000	-0.002
100	HDR_W6_D18_Bias	0.000	0.002	0.002
100	HDR_W6_D22_Bias	0.003	0.001	-0.002
100	HDR_W6_D24_Bias	0.002	0.004	0.002
100	HDR_W6_D30_Bias	0.002	0.005	0.003
100	HDR_W6_D32_Bias	0.003	0.001	-0.001
100	HDR_W6_D39_Bias	0.002	0.003	0.001
100	HDR_W7_D4_Bias	0.001	0.003	0.001
100	HDR_W7_D9_Bias	0.002	0.003	0.002
100	HDR_W7_D17_Bias	0.000	0.004	0.004
100	HDR_W7_D18_Bias	0.003	0.001	-0.002
100	HDR_W7_D25_Bias	0.001	0.003	0.002
100	HDR_W7_D34_Bias	0.001	0.002	0.001
100	HDR_W7_D35_Bias	0.002	0.002	0.000
	Max	0.004	0.007	0.005
	Average	0.001	0.003	0.001
	Min	0.000	0.000	-0.004
	Std Dev	0.001	0.002	0.002



	13.3__Line_Reg @ Vout=0.8V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.07	%/V			
Min Limit	-0.07	%/V			
krad(Si)	3	10	30	50	100
LL	-0.070	-0.070	-0.070	-0.070	-0.070
Min	0.002	0.000	0.001	0.002	0.000
Average	0.004	0.002	0.002	0.003	0.003
Max	0.006	0.003	0.004	0.004	0.007
UL	0.070	0.070	0.070	0.070	0.070



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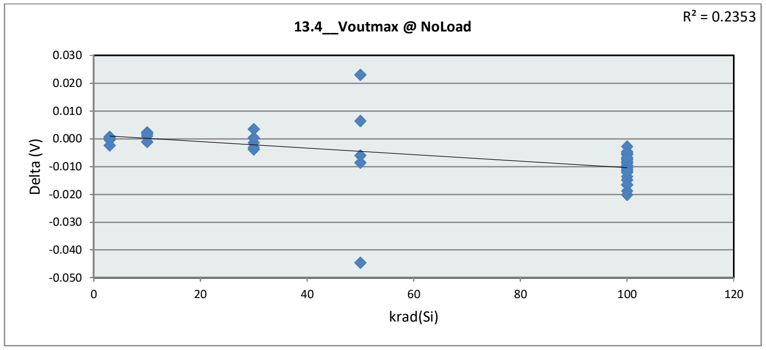
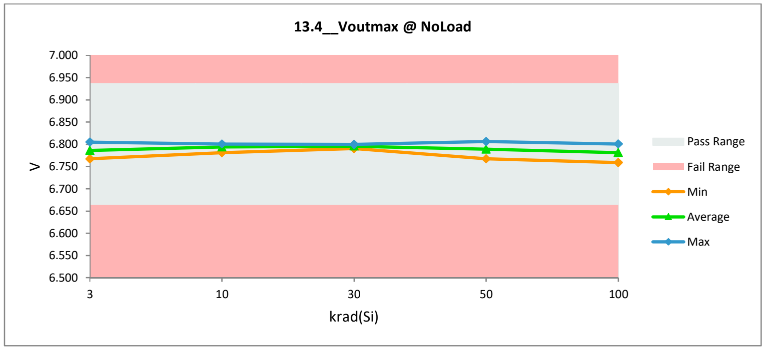
		13.4__Voutmax @ NoLoad		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	6.936	6.936	
	Min Limit	6.664	6.664	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	6.769	6.767	-0.002
3	HDR_W5_D12_Bias	6.790	6.791	0.001
3	HDR_W6_D13_Bias	6.806	6.805	0.000
3	HDR_W6_D21_Bias	6.791	6.792	0.001
3	HDR_W7_D5_Bias	6.775	6.776	0.000
10	HDR_W5_D9_Bias	6.782	6.781	-0.001
10	HDR_W6_D4_Bias	6.798	6.799	0.002
10	HDR_W6_D28_Bias	6.798	6.801	0.002
10	HDR_W7_D27_Bias	6.800	6.801	0.001
10	HDR_W7_D41_Bias	6.787	6.788	0.002
30	HDR_W5_D29_Bias	6.804	6.800	-0.004
30	HDR_W6_D27_Bias	6.798	6.797	-0.001
30	HDR_W6_D42_Bias	6.792	6.793	0.000
30	HDR_W7_D31_Bias	6.803	6.800	-0.003
30	HDR_W7_D22_Bias	6.787	6.791	0.003
50	HDR_W5_D37_Bias	6.788	6.782	-0.006
50	HDR_W5_D39_Bias	6.776	6.799	0.023
50	HDR_W6_D14_Bias	6.801	6.792	-0.009
50	HDR_W7_D13_Bias	6.800	6.806	0.006
50	HDR_W7_D37_Bias	6.812	6.767	-0.045
100	HDR_W5_D8_Bias	6.795	6.785	-0.010
100	HDR_W5_D13_Bias	6.793	6.784	-0.008
100	HDR_W5_D30_Bias	6.777	6.772	-0.005
100	HDR_W5_D32_Bias	6.766	6.759	-0.007
100	HDR_W5_D34_Bias	6.804	6.793	-0.010
100	HDR_W5_D38_Bias	6.775	6.767	-0.009
100	HDR_W5_D41_Bias	6.787	6.776	-0.011
100	HDR_W6_D1_Bias	6.802	6.783	-0.019
100	HDR_W6_D8_Bias	6.789	6.786	-0.003
100	HDR_W6_D18_Bias	6.815	6.801	-0.014
100	HDR_W6_D22_Bias	6.793	6.786	-0.007
100	HDR_W6_D24_Bias	6.786	6.774	-0.011
100	HDR_W6_D30_Bias	6.801	6.785	-0.016
100	HDR_W6_D32_Bias	6.799	6.794	-0.006
100	HDR_W6_D39_Bias	6.790	6.775	-0.015
100	HDR_W7_D4_Bias	6.799	6.788	-0.011
100	HDR_W7_D9_Bias	6.799	6.787	-0.012
100	HDR_W7_D17_Bias	6.788	6.782	-0.005
100	HDR_W7_D18_Bias	6.778	6.761	-0.017
100	HDR_W7_D25_Bias	6.816	6.796	-0.020
100	HDR_W7_D34_Bias	6.783	6.778	-0.005
100	HDR_W7_D35_Bias	6.782	6.775	-0.007
	Max	6.816	6.806	0.023
	Average	6.792	6.786	-0.006
	Min	6.766	6.759	-0.045
	Std Dev	0.012	0.012	0.010



	13.4__Voutmax @ NoLoad				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	6.936	V			
Min Limit	6.664	V			
krad(Si)	3	10	30	50	100
LL	6.664	6.664	6.664	6.664	6.664
Min	6.767	6.781	6.791	6.767	6.759
Average	6.786	6.794	6.796	6.789	6.781
Max	6.805	6.801	6.800	6.806	6.801
UL	6.936	6.936	6.936	6.936	6.936



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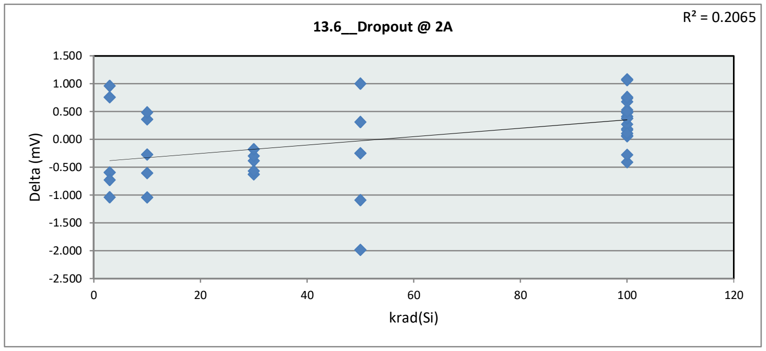
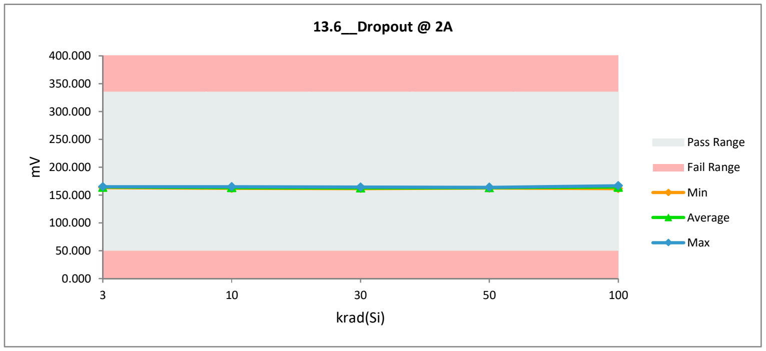
		13.6__Dropout @ 2A		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	335	335	
	Min Limit	50	50	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	165.042	164.004	-1.038
3	HDR_W5_D12_Bias	165.436	164.841	-0.595
3	HDR_W6_D13_Bias	162.586	163.548	0.962
3	HDR_W6_D21_Bias	163.447	164.204	0.757
3	HDR_W7_D5_Bias	165.970	165.242	-0.728
10	HDR_W5_D9_Bias	164.900	163.860	-1.040
10	HDR_W6_D4_Bias	162.192	162.555	0.363
10	HDR_W6_D28_Bias	164.146	163.878	-0.268
10	HDR_W7_D27_Bias	164.888	165.373	0.485
10	HDR_W7_D41_Bias	162.918	162.316	-0.602
30	HDR_W5_D29_Bias	162.385	161.758	-0.627
30	HDR_W6_D27_Bias	162.137	161.755	-0.382
30	HDR_W6_D42_Bias	164.936	164.640	-0.296
30	HDR_W7_D31_Bias	163.375	162.808	-0.567
30	HDR_W7_D22_Bias	163.840	163.663	-0.177
50	HDR_W5_D37_Bias	164.046	162.955	-1.091
50	HDR_W5_D39_Bias	164.600	162.619	-1.981
50	HDR_W6_D14_Bias	163.004	162.755	-0.249
50	HDR_W7_D13_Bias	162.422	163.426	1.004
50	HDR_W7_D37_Bias	163.852	164.164	0.312
100	HDR_W5_D8_Bias	164.651	164.719	0.068
100	HDR_W5_D13_Bias	163.768	164.263	0.495
100	HDR_W5_D30_Bias	165.186	165.374	0.188
100	HDR_W5_D32_Bias	162.587	162.644	0.057
100	HDR_W5_D34_Bias	164.144	163.737	-0.407
100	HDR_W5_D38_Bias	163.188	163.600	0.412
100	HDR_W5_D41_Bias	165.013	165.495	0.482
100	HDR_W6_D1_Bias	162.609	163.139	0.530
100	HDR_W6_D8_Bias	162.150	161.873	-0.277
100	HDR_W6_D18_Bias	162.064	162.233	0.169
100	HDR_W6_D22_Bias	163.984	164.255	0.271
100	HDR_W6_D24_Bias	162.784	163.546	0.762
100	HDR_W6_D30_Bias	163.480	163.856	0.376
100	HDR_W6_D32_Bias	163.094	163.585	0.491
100	HDR_W6_D39_Bias	163.043	163.722	0.679
100	HDR_W7_D4_Bias	166.586	166.695	0.109
100	HDR_W7_D9_Bias	165.067	165.447	0.380
100	HDR_W7_D17_Bias	165.855	166.935	1.080
100	HDR_W7_D18_Bias	165.048	165.546	0.498
100	HDR_W7_D25_Bias	164.023	165.089	1.066
100	HDR_W7_D34_Bias	164.716	165.454	0.738
100	HDR_W7_D35_Bias	162.206	162.962	0.756
	Max	166.586	166.935	1.080
	Average	163.842	163.917	0.075
	Min	162.064	161.755	-1.981
	Std Dev	1.208	1.273	0.679



	13.6__Dropout @ 2A				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	335	mV			
Min Limit	50	mV			
krad(Si)	3	10	30	50	100
LL	50.000	50.000	50.000	50.000	50.000
Min	163.548	162.316	161.755	162.619	161.873
Average	164.368	163.596	162.925	163.184	164.280
Max	165.242	165.373	164.640	164.164	166.935
UL	335.000	335.000	335.000	335.000	335.000



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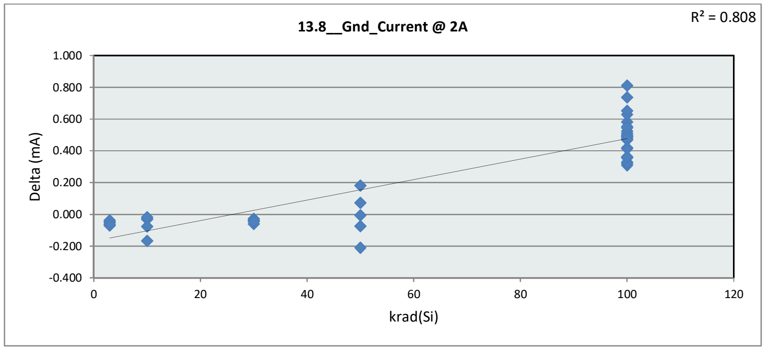
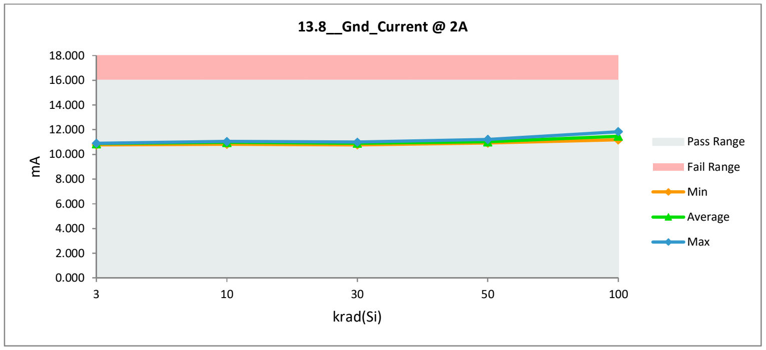
		13.8__Gnd_Current @ 2A		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	10.966	10.896	-0.070
3	HDR_W5_D12_Bias	10.949	10.902	-0.047
3	HDR_W6_D13_Bias	10.949	10.897	-0.052
3	HDR_W6_D21_Bias	10.930	10.892	-0.038
3	HDR_W7_D5_Bias	10.843	10.779	-0.064
10	HDR_W5_D9_Bias	10.989	10.822	-0.167
10	HDR_W6_D4_Bias	11.058	11.028	-0.030
10	HDR_W6_D28_Bias	10.907	10.876	-0.031
10	HDR_W7_D27_Bias	11.105	11.029	-0.076
10	HDR_W7_D41_Bias	11.060	11.042	-0.018
30	HDR_W5_D29_Bias	11.055	10.994	-0.061
30	HDR_W6_D27_Bias	10.824	10.796	-0.028
30	HDR_W6_D42_Bias	10.810	10.772	-0.038
30	HDR_W7_D31_Bias	10.991	10.949	-0.042
30	HDR_W7_D22_Bias	11.022	10.977	-0.045
50	HDR_W5_D37_Bias	11.019	11.013	-0.006
50	HDR_W5_D39_Bias	10.998	10.924	-0.074
50	HDR_W6_D14_Bias	10.942	11.014	0.072
50	HDR_W7_D13_Bias	11.037	11.218	0.181
50	HDR_W7_D37_Bias	11.179	10.969	-0.210
100	HDR_W5_D8_Bias	10.934	11.516	0.582
100	HDR_W5_D13_Bias	11.074	11.383	0.309
100	HDR_W5_D30_Bias	10.971	11.459	0.488
100	HDR_W5_D32_Bias	10.968	11.465	0.497
100	HDR_W5_D34_Bias	11.054	11.374	0.320
100	HDR_W5_D38_Bias	11.007	11.476	0.469
100	HDR_W5_D41_Bias	10.932	11.421	0.489
100	HDR_W6_D1_Bias	10.950	11.579	0.629
100	HDR_W6_D8_Bias	10.984	11.403	0.419
100	HDR_W6_D18_Bias	10.990	11.319	0.329
100	HDR_W6_D22_Bias	10.829	11.185	0.356
100	HDR_W6_D24_Bias	10.846	11.355	0.509
100	HDR_W6_D30_Bias	10.842	11.204	0.362
100	HDR_W6_D32_Bias	10.907	11.459	0.552
100	HDR_W6_D39_Bias	10.942	11.466	0.524
100	HDR_W7_D4_Bias	11.017	11.562	0.545
100	HDR_W7_D9_Bias	11.076	11.727	0.651
100	HDR_W7_D17_Bias	11.031	11.842	0.811
100	HDR_W7_D18_Bias	10.990	11.485	0.495
100	HDR_W7_D25_Bias	11.120	11.597	0.477
100	HDR_W7_D34_Bias	11.022	11.758	0.736
100	HDR_W7_D35_Bias	10.999	11.413	0.414
	Max	11.179	11.842	0.811
	Average	10.979	11.220	0.241
	Min	10.810	10.772	-0.210
	Std Dev	0.084	0.303	0.293



	13.8__Gnd_Current @ 2A				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	16	mA			
Min Limit	0.0005	mA			
krad(Si)	3	10	30	50	100
LL	0.001	0.001	0.001	0.001	0.001
Min	10.779	10.822	10.772	10.924	11.185
Average	10.873	10.959	10.898	11.028	11.475
Max	10.902	11.042	10.994	11.218	11.842
UL	16.000	16.000	16.000	16.000	16.000



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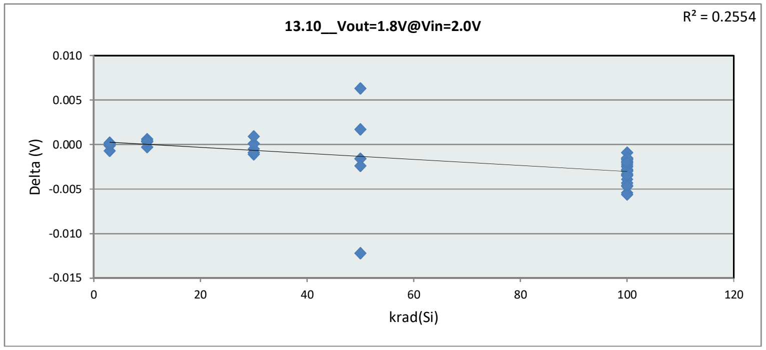
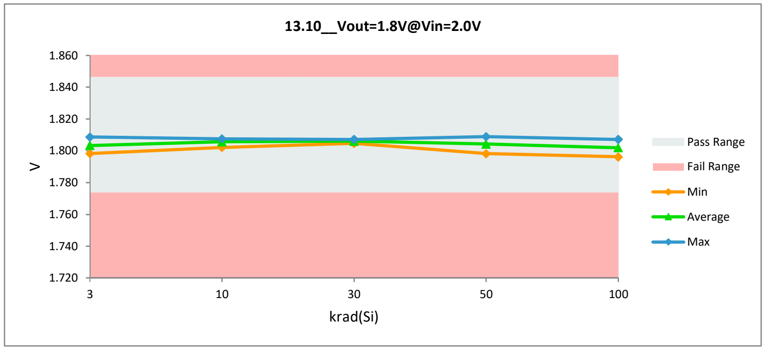
		13.10__Vout=1.8V@Vin=2.0V		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		1.8462	1.8462	
Min Limit		1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.799	1.798	-0.001
3	HDR_W5_D12_Bias	1.804	1.805	0.000
3	HDR_W6_D13_Bias	1.809	1.809	0.000
3	HDR_W6_D21_Bias	1.805	1.805	0.000
3	HDR_W7_D5_Bias	1.800	1.801	0.000
10	HDR_W5_D9_Bias	1.803	1.802	0.000
10	HDR_W6_D4_Bias	1.807	1.807	0.000
10	HDR_W6_D28_Bias	1.807	1.808	0.001
10	HDR_W7_D27_Bias	1.807	1.808	0.000
10	HDR_W7_D41_Bias	1.804	1.804	0.000
30	HDR_W5_D29_Bias	1.808	1.807	-0.001
30	HDR_W6_D27_Bias	1.807	1.806	0.000
30	HDR_W6_D42_Bias	1.805	1.805	0.000
30	HDR_W7_D31_Bias	1.808	1.807	-0.001
30	HDR_W7_D22_Bias	1.804	1.805	0.001
50	HDR_W5_D37_Bias	1.804	1.802	-0.002
50	HDR_W5_D39_Bias	1.801	1.807	0.006
50	HDR_W6_D14_Bias	1.807	1.805	-0.002
50	HDR_W7_D13_Bias	1.807	1.809	0.002
50	HDR_W7_D37_Bias	1.810	1.798	-0.012
100	HDR_W5_D8_Bias	1.806	1.803	-0.003
100	HDR_W5_D13_Bias	1.805	1.803	-0.002
100	HDR_W5_D30_Bias	1.801	1.799	-0.002
100	HDR_W5_D32_Bias	1.798	1.796	-0.002
100	HDR_W5_D34_Bias	1.808	1.805	-0.003
100	HDR_W5_D38_Bias	1.801	1.798	-0.002
100	HDR_W5_D41_Bias	1.803	1.800	-0.003
100	HDR_W6_D1_Bias	1.808	1.802	-0.005
100	HDR_W6_D8_Bias	1.804	1.804	-0.001
100	HDR_W6_D18_Bias	1.811	1.807	-0.004
100	HDR_W6_D22_Bias	1.806	1.803	-0.002
100	HDR_W6_D24_Bias	1.803	1.800	-0.003
100	HDR_W6_D30_Bias	1.807	1.803	-0.005
100	HDR_W6_D32_Bias	1.807	1.805	-0.002
100	HDR_W6_D39_Bias	1.805	1.800	-0.004
100	HDR_W7_D4_Bias	1.807	1.804	-0.003
100	HDR_W7_D9_Bias	1.807	1.803	-0.003
100	HDR_W7_D17_Bias	1.804	1.802	-0.002
100	HDR_W7_D18_Bias	1.801	1.797	-0.005
100	HDR_W7_D25_Bias	1.811	1.806	-0.006
100	HDR_W7_D34_Bias	1.803	1.801	-0.002
100	HDR_W7_D35_Bias	1.802	1.800	-0.002
	Max	1.811	1.809	0.006
	Average	1.805	1.803	-0.002
	Min	1.798	1.796	-0.012
	Std Dev	0.003	0.003	0.003

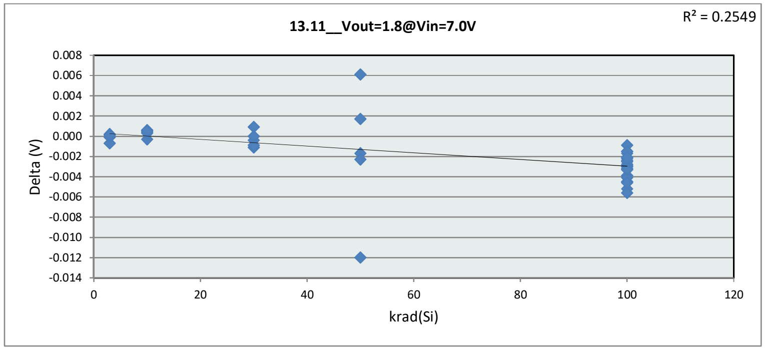


	13.10__Vout=1.8V@Vin=2.0V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.8462	V			
Min Limit	1.7738	V			
krad(Si)	3	10	30	50	100
LL	1.774	1.774	1.774	1.774	1.774
Min	1.798	1.802	1.805	1.798	1.796
Average	1.803	1.806	1.806	1.804	1.802
Max	1.809	1.808	1.807	1.809	1.807
UL	1.846	1.846	1.846	1.846	1.846

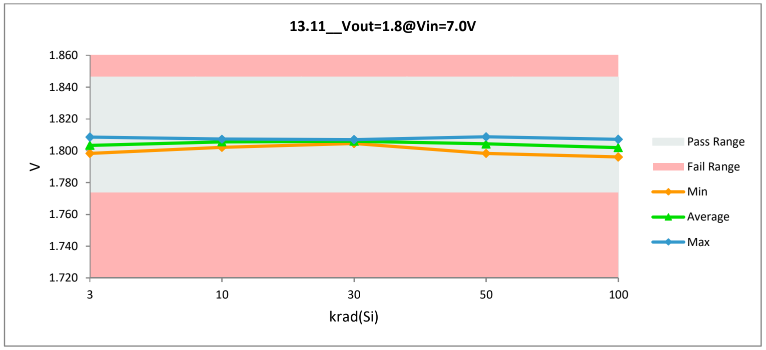


HDR Report
TPS7H1101-SP

		13.11__Vout=1.8@Vin=7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.799	1.798	-0.001
3	HDR_W5_D12_Bias	1.805	1.805	0.000
3	HDR_W6_D13_Bias	1.809	1.809	0.000
3	HDR_W6_D21_Bias	1.805	1.805	0.000
3	HDR_W7_D5_Bias	1.801	1.801	0.000
10	HDR_W5_D9_Bias	1.802	1.802	0.000
10	HDR_W6_D4_Bias	1.807	1.807	0.000
10	HDR_W6_D28_Bias	1.807	1.807	0.001
10	HDR_W7_D27_Bias	1.807	1.807	0.000
10	HDR_W7_D41_Bias	1.804	1.804	0.001
30	HDR_W5_D29_Bias	1.808	1.807	-0.001
30	HDR_W6_D27_Bias	1.807	1.806	0.000
30	HDR_W6_D42_Bias	1.805	1.805	0.000
30	HDR_W7_D31_Bias	1.808	1.807	-0.001
30	HDR_W7_D22_Bias	1.804	1.805	0.001
50	HDR_W5_D37_Bias	1.804	1.802	-0.002
50	HDR_W5_D39_Bias	1.801	1.807	0.006
50	HDR_W6_D14_Bias	1.807	1.805	-0.002
50	HDR_W7_D13_Bias	1.807	1.809	0.002
50	HDR_W7_D37_Bias	1.810	1.798	-0.012
100	HDR_W5_D8_Bias	1.806	1.803	-0.003
100	HDR_W5_D13_Bias	1.805	1.803	-0.002
100	HDR_W5_D30_Bias	1.801	1.800	-0.002
100	HDR_W5_D32_Bias	1.798	1.796	-0.002
100	HDR_W5_D34_Bias	1.808	1.805	-0.003
100	HDR_W5_D38_Bias	1.801	1.798	-0.003
100	HDR_W5_D41_Bias	1.804	1.801	-0.003
100	HDR_W6_D1_Bias	1.808	1.803	-0.005
100	HDR_W6_D8_Bias	1.804	1.803	-0.001
100	HDR_W6_D18_Bias	1.811	1.807	-0.004
100	HDR_W6_D22_Bias	1.805	1.803	-0.002
100	HDR_W6_D24_Bias	1.803	1.800	-0.003
100	HDR_W6_D30_Bias	1.807	1.803	-0.005
100	HDR_W6_D32_Bias	1.807	1.805	-0.002
100	HDR_W6_D39_Bias	1.804	1.800	-0.004
100	HDR_W7_D4_Bias	1.807	1.804	-0.003
100	HDR_W7_D9_Bias	1.807	1.803	-0.003
100	HDR_W7_D17_Bias	1.804	1.802	-0.002
100	HDR_W7_D18_Bias	1.801	1.797	-0.005
100	HDR_W7_D25_Bias	1.811	1.806	-0.006
100	HDR_W7_D34_Bias	1.803	1.801	-0.002
100	HDR_W7_D35_Bias	1.802	1.800	-0.002
	Max	1.811	1.809	0.006
	Average	1.805	1.803	-0.002
	Min	1.798	1.796	-0.012
	Std Dev	0.003	0.003	0.003

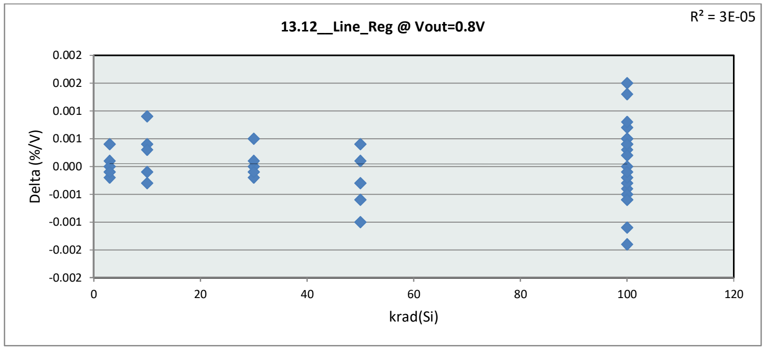


	13.11__Vout=1.8@Vin=7.0V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.8462 V				
Min Limit	1.7738 V				
krad(Si)	3	10	30	50	100
LL	1.774	1.774	1.774	1.774	1.774
Min	1.798	1.802	1.805	1.798	1.796
Average	1.803	1.806	1.806	1.804	1.802
Max	1.809	1.807	1.807	1.809	1.807
UL	1.846	1.846	1.846	1.846	1.846

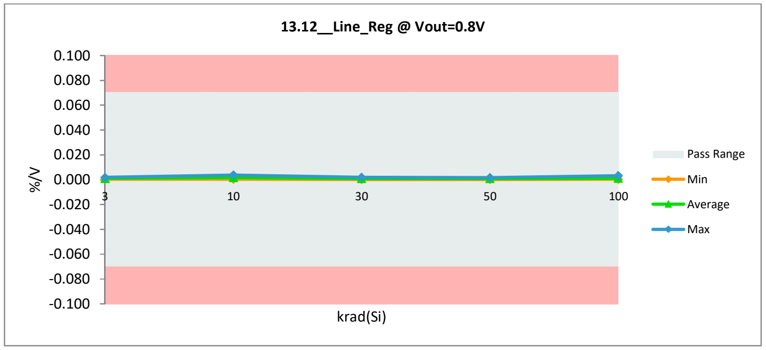


HDR Report
TPS7H1101-SP

		13.12__Line_Reg @ Vout=0.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.001	0.000	0.000
3	HDR_W5_D12_Bias	0.001	0.001	0.000
3	HDR_W6_D13_Bias	0.002	0.002	0.000
3	HDR_W6_D21_Bias	0.000	0.000	0.000
3	HDR_W7_D5_Bias	0.002	0.002	0.000
10	HDR_W5_D9_Bias	0.001	0.001	0.000
10	HDR_W6_D4_Bias	0.001	0.001	0.000
10	HDR_W6_D28_Bias	0.003	0.004	0.001
10	HDR_W7_D27_Bias	0.002	0.002	0.000
10	HDR_W7_D41_Bias	0.001	0.001	0.000
30	HDR_W5_D29_Bias	0.000	0.000	0.000
30	HDR_W6_D27_Bias	0.000	0.000	0.000
30	HDR_W6_D42_Bias	0.001	0.001	0.000
30	HDR_W7_D31_Bias	0.002	0.002	0.001
30	HDR_W7_D22_Bias	0.001	0.001	0.000
50	HDR_W5_D37_Bias	0.001	0.000	-0.001
50	HDR_W5_D39_Bias	0.002	0.002	0.000
50	HDR_W6_D14_Bias	0.001	0.000	-0.001
50	HDR_W7_D13_Bias	0.001	0.001	0.000
50	HDR_W7_D37_Bias	0.002	0.001	0.000
100	HDR_W5_D8_Bias	0.001	0.001	0.000
100	HDR_W5_D13_Bias	0.001	0.001	0.000
100	HDR_W5_D30_Bias	0.001	0.002	0.002
100	HDR_W5_D32_Bias	0.001	0.001	0.001
100	HDR_W5_D34_Bias	0.000	0.002	0.001
100	HDR_W5_D38_Bias	0.002	0.001	0.000
100	HDR_W5_D41_Bias	0.003	0.003	0.000
100	HDR_W6_D1_Bias	0.001	0.001	0.000
100	HDR_W6_D8_Bias	0.002	0.002	0.000
100	HDR_W6_D18_Bias	0.000	0.001	0.000
100	HDR_W6_D22_Bias	0.002	0.002	0.000
100	HDR_W6_D24_Bias	0.002	0.002	0.000
100	HDR_W6_D30_Bias	0.002	0.002	0.000
100	HDR_W6_D32_Bias	0.002	0.001	-0.001
100	HDR_W6_D39_Bias	0.001	0.001	0.000
100	HDR_W7_D4_Bias	0.001	0.000	0.000
100	HDR_W7_D9_Bias	0.001	0.000	-0.001
100	HDR_W7_D17_Bias	0.000	0.001	0.001
100	HDR_W7_D18_Bias	0.001	0.001	-0.001
100	HDR_W7_D25_Bias	0.001	0.000	0.000
100	HDR_W7_D34_Bias	0.001	0.000	-0.001
100	HDR_W7_D35_Bias	0.001	0.001	0.000
	Max	0.003	0.004	0.002
	Average	0.001	0.001	0.000
	Min	0.000	0.000	-0.001
	Std Dev	0.001	0.001	0.001

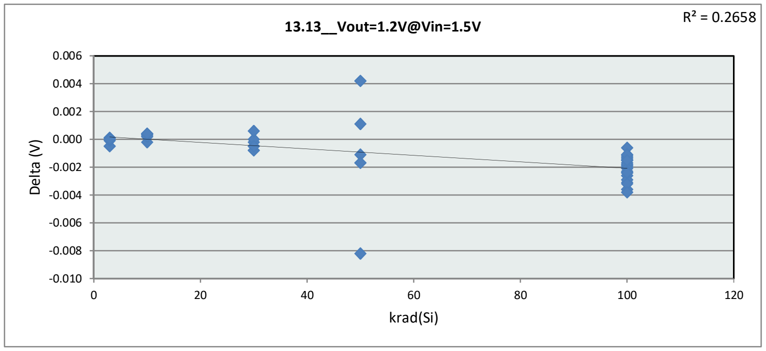


	13.12__Line_Reg @ Vout=0.8V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.07	%/V			
Min Limit	-0.07	%/V			
krad(Si)	3	10	30	50	100
LL	-0.070	-0.070	-0.070	-0.070	-0.070
Min	0.000	0.001	0.000	0.000	0.000
Average	0.001	0.002	0.001	0.001	0.001
Max	0.002	0.004	0.002	0.002	0.003
UL	0.070	0.070	0.070	0.070	0.070

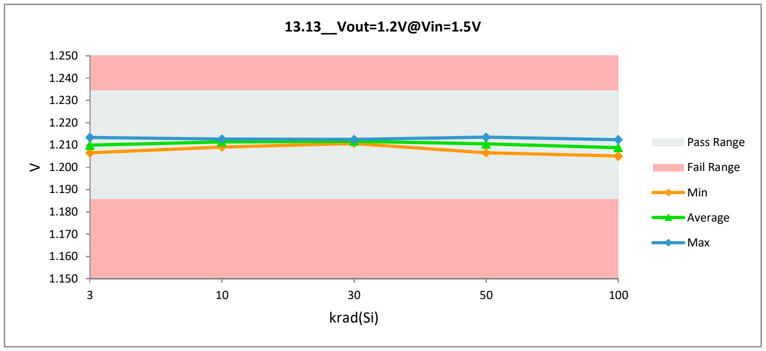


HDR Report
TPS7H1101-SP

		13.13__Vout=1.2V@Vin=1.5V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.207	1.206	0.000
3	HDR_W5_D12_Bias	1.211	1.211	0.000
3	HDR_W6_D13_Bias	1.214	1.213	0.000
3	HDR_W6_D21_Bias	1.211	1.211	0.000
3	HDR_W7_D5_Bias	1.208	1.208	0.000
10	HDR_W5_D9_Bias	1.209	1.209	0.000
10	HDR_W6_D4_Bias	1.212	1.212	0.000
10	HDR_W6_D28_Bias	1.212	1.213	0.000
10	HDR_W7_D27_Bias	1.212	1.213	0.000
10	HDR_W7_D41_Bias	1.210	1.210	0.000
30	HDR_W5_D29_Bias	1.213	1.212	-0.001
30	HDR_W6_D27_Bias	1.212	1.212	0.000
30	HDR_W6_D42_Bias	1.211	1.211	0.000
30	HDR_W7_D31_Bias	1.213	1.212	-0.001
30	HDR_W7_D22_Bias	1.210	1.211	0.001
50	HDR_W5_D37_Bias	1.210	1.209	-0.001
50	HDR_W5_D39_Bias	1.208	1.212	0.004
50	HDR_W6_D14_Bias	1.213	1.211	-0.002
50	HDR_W7_D13_Bias	1.212	1.214	0.001
50	HDR_W7_D37_Bias	1.215	1.206	-0.008
100	HDR_W5_D8_Bias	1.211	1.209	-0.002
100	HDR_W5_D13_Bias	1.211	1.209	-0.002
100	HDR_W5_D30_Bias	1.208	1.207	-0.001
100	HDR_W5_D32_Bias	1.206	1.205	-0.001
100	HDR_W5_D34_Bias	1.213	1.211	-0.002
100	HDR_W5_D38_Bias	1.208	1.206	-0.002
100	HDR_W5_D41_Bias	1.210	1.208	-0.002
100	HDR_W6_D1_Bias	1.213	1.209	-0.004
100	HDR_W6_D8_Bias	1.211	1.210	-0.001
100	HDR_W6_D18_Bias	1.215	1.212	-0.003
100	HDR_W6_D22_Bias	1.211	1.210	-0.002
100	HDR_W6_D24_Bias	1.210	1.207	-0.002
100	HDR_W6_D30_Bias	1.212	1.209	-0.003
100	HDR_W6_D32_Bias	1.212	1.211	-0.001
100	HDR_W6_D39_Bias	1.211	1.208	-0.003
100	HDR_W7_D4_Bias	1.212	1.210	-0.002
100	HDR_W7_D9_Bias	1.212	1.210	-0.002
100	HDR_W7_D17_Bias	1.210	1.209	-0.001
100	HDR_W7_D18_Bias	1.209	1.205	-0.003
100	HDR_W7_D25_Bias	1.215	1.211	-0.004
100	HDR_W7_D34_Bias	1.209	1.208	-0.001
100	HDR_W7_D35_Bias	1.209	1.208	-0.002
	Max	1.215	1.214	0.004
	Average	1.211	1.210	-0.001
	Min	1.206	1.205	-0.008
	Std Dev	0.002	0.002	0.002

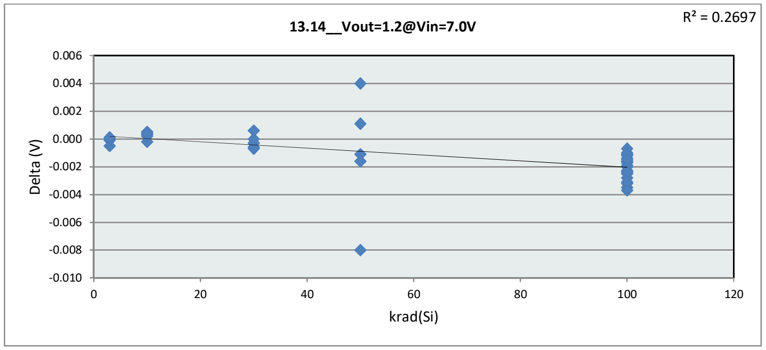


	13.13__Vout=1.2V@Vin=1.5V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.2342	V			
Min Limit	1.1858	V			
krad(Si)	3	10	30	50	100
LL	1.186	1.186	1.186	1.186	1.186
Min	1.206	1.209	1.211	1.206	1.205
Average	1.210	1.211	1.212	1.210	1.209
Max	1.213	1.213	1.213	1.214	1.212
UL	1.234	1.234	1.234	1.234	1.234

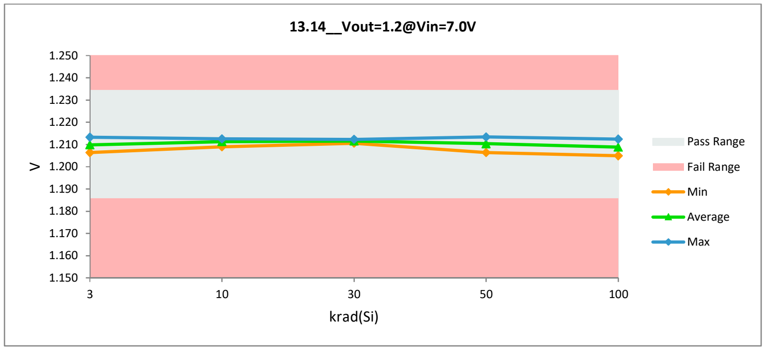


HDR Report
TPS7H1101-SP

		13.14__Vout=1.2@Vin=7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.207	1.206	0.000
3	HDR_W5_D12_Bias	1.211	1.211	0.000
3	HDR_W6_D13_Bias	1.213	1.213	0.000
3	HDR_W6_D21_Bias	1.211	1.211	0.000
3	HDR_W7_D5_Bias	1.208	1.208	0.000
10	HDR_W5_D9_Bias	1.209	1.209	0.000
10	HDR_W6_D4_Bias	1.212	1.212	0.000
10	HDR_W6_D28_Bias	1.212	1.212	0.000
10	HDR_W7_D27_Bias	1.212	1.212	0.000
10	HDR_W7_D41_Bias	1.210	1.210	0.000
30	HDR_W5_D29_Bias	1.213	1.212	-0.001
30	HDR_W6_D27_Bias	1.212	1.212	0.000
30	HDR_W6_D42_Bias	1.211	1.211	0.000
30	HDR_W7_D31_Bias	1.213	1.212	-0.001
30	HDR_W7_D22_Bias	1.210	1.211	0.001
50	HDR_W5_D37_Bias	1.210	1.209	-0.001
50	HDR_W5_D39_Bias	1.208	1.212	0.004
50	HDR_W6_D14_Bias	1.212	1.211	-0.002
50	HDR_W7_D13_Bias	1.212	1.213	0.001
50	HDR_W7_D37_Bias	1.214	1.206	-0.008
100	HDR_W5_D8_Bias	1.211	1.209	-0.002
100	HDR_W5_D13_Bias	1.211	1.209	-0.002
100	HDR_W5_D30_Bias	1.208	1.207	-0.001
100	HDR_W5_D32_Bias	1.206	1.205	-0.001
100	HDR_W5_D34_Bias	1.213	1.211	-0.002
100	HDR_W5_D38_Bias	1.208	1.206	-0.002
100	HDR_W5_D41_Bias	1.210	1.208	-0.002
100	HDR_W6_D1_Bias	1.213	1.209	-0.003
100	HDR_W6_D8_Bias	1.210	1.210	-0.001
100	HDR_W6_D18_Bias	1.215	1.212	-0.003
100	HDR_W6_D22_Bias	1.211	1.210	-0.002
100	HDR_W6_D24_Bias	1.210	1.207	-0.002
100	HDR_W6_D30_Bias	1.213	1.209	-0.003
100	HDR_W6_D32_Bias	1.212	1.211	-0.001
100	HDR_W6_D39_Bias	1.211	1.208	-0.003
100	HDR_W7_D4_Bias	1.212	1.210	-0.002
100	HDR_W7_D9_Bias	1.212	1.210	-0.002
100	HDR_W7_D17_Bias	1.210	1.209	-0.001
100	HDR_W7_D18_Bias	1.208	1.205	-0.003
100	HDR_W7_D25_Bias	1.215	1.211	-0.004
100	HDR_W7_D34_Bias	1.209	1.208	-0.001
100	HDR_W7_D35_Bias	1.209	1.208	-0.002
	Max	1.215	1.213	0.004
	Average	1.211	1.210	-0.001
	Min	1.206	1.205	-0.008
	Std Dev	0.002	0.002	0.002

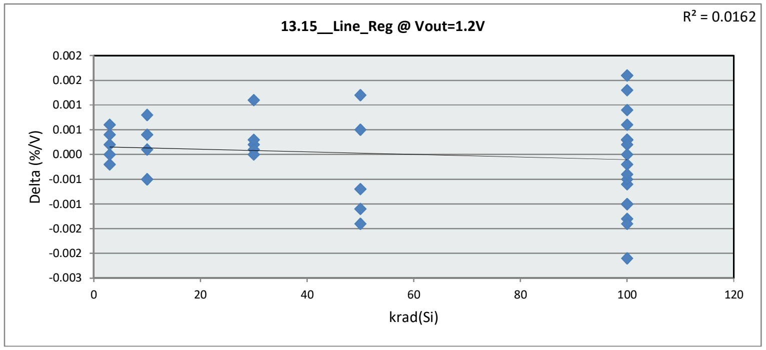


	13.14__Vout=1.2@Vin=7.0V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.2342 V				
Min Limit	1.1858 V				
krad(Si)	3	10	30	50	100
LL	1.186	1.186	1.186	1.186	1.186
Min	1.206	1.209	1.211	1.206	1.205
Average	1.210	1.211	1.212	1.210	1.209
Max	1.213	1.213	1.212	1.213	1.212
UL	1.234	1.234	1.234	1.234	1.234

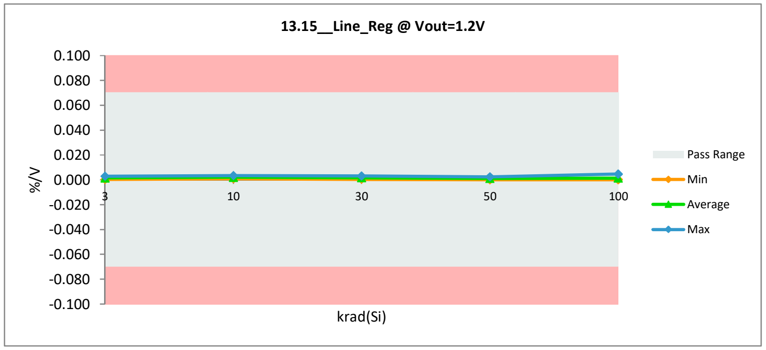


HDR Report
TPS7H1101-SP

		13.15__Line_Reg @ Vout=1.2V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.000	0.000	0.000
3	HDR_W5_D12_Bias	0.001	0.001	0.001
3	HDR_W6_D13_Bias	0.002	0.002	0.000
3	HDR_W6_D21_Bias	0.001	0.001	0.000
3	HDR_W7_D5_Bias	0.002	0.003	0.000
10	HDR_W5_D9_Bias	0.001	0.002	0.001
10	HDR_W6_D4_Bias	0.001	0.002	0.000
10	HDR_W6_D28_Bias	0.004	0.003	0.000
10	HDR_W7_D27_Bias	0.003	0.002	-0.001
10	HDR_W7_D41_Bias	0.001	0.001	0.000
30	HDR_W5_D29_Bias	0.000	0.001	0.000
30	HDR_W6_D27_Bias	0.000	0.000	0.000
30	HDR_W6_D42_Bias	0.002	0.002	0.000
30	HDR_W7_D31_Bias	0.002	0.003	0.001
30	HDR_W7_D22_Bias	0.002	0.002	0.000
50	HDR_W5_D37_Bias	0.001	0.000	-0.001
50	HDR_W5_D39_Bias	0.001	0.002	0.001
50	HDR_W6_D14_Bias	0.001	0.000	-0.001
50	HDR_W7_D13_Bias	0.001	0.002	0.000
50	HDR_W7_D37_Bias	0.002	0.001	-0.001
100	HDR_W5_D8_Bias	0.000	0.000	0.000
100	HDR_W5_D13_Bias	0.000	0.001	0.000
100	HDR_W5_D30_Bias	0.000	0.002	0.002
100	HDR_W5_D32_Bias	0.001	0.001	0.001
100	HDR_W5_D34_Bias	0.001	0.002	0.001
100	HDR_W5_D38_Bias	0.002	0.002	0.000
100	HDR_W5_D41_Bias	0.003	0.005	0.002
100	HDR_W6_D1_Bias	0.001	0.000	-0.001
100	HDR_W6_D8_Bias	0.002	0.002	0.000
100	HDR_W6_D18_Bias	0.000	0.001	0.000
100	HDR_W6_D22_Bias	0.003	0.003	0.000
100	HDR_W6_D24_Bias	0.002	0.001	-0.001
100	HDR_W6_D30_Bias	0.002	0.002	0.000
100	HDR_W6_D32_Bias	0.003	0.001	-0.002
100	HDR_W6_D39_Bias	0.001	0.000	-0.001
100	HDR_W7_D4_Bias	0.002	0.000	-0.001
100	HDR_W7_D9_Bias	0.002	0.000	-0.001
100	HDR_W7_D17_Bias	0.000	0.001	0.001
100	HDR_W7_D18_Bias	0.002	0.002	-0.001
100	HDR_W7_D25_Bias	0.001	0.000	-0.001
100	HDR_W7_D34_Bias	0.001	0.001	0.000
100	HDR_W7_D35_Bias	0.001	0.001	0.000
	Max	0.004	0.005	0.002
	Average	0.001	0.001	0.000
	Min	0.000	0.000	-0.002
	Std Dev	0.001	0.001	0.001



	13.15__Line_Reg @ Vout=1.2V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.07	%/V			
Min Limit	-0.07	%/V			
krad(Si)	3	10	30	50	100
LL	-0.070	-0.070	-0.070	-0.070	-0.070
Min	0.000	0.001	0.000	0.000	0.000
Average	0.001	0.002	0.002	0.001	0.001
Max	0.003	0.003	0.003	0.003	0.005
UL	0.070	0.070	0.070	0.070	0.070



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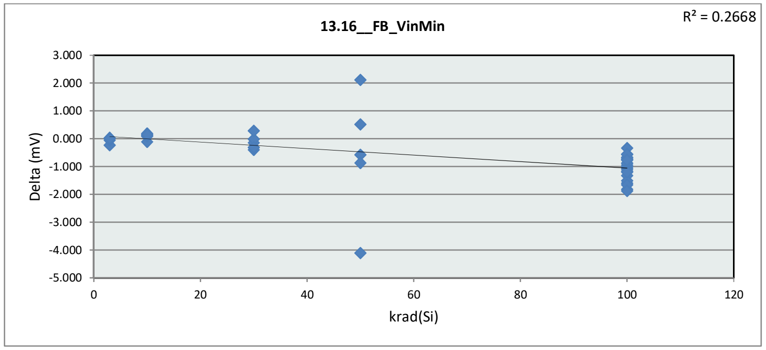
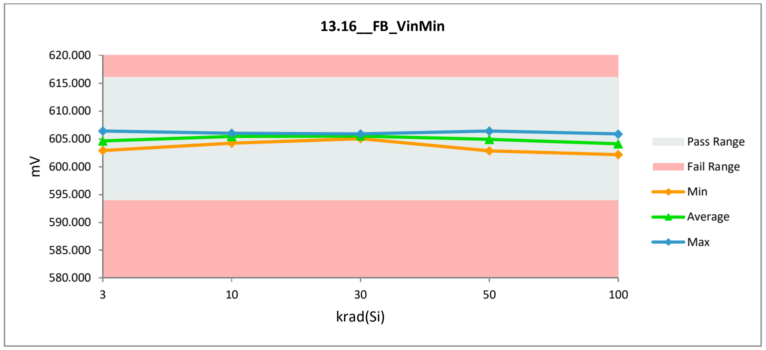
		13.16__FB_VinMin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	603.135	602.904	-0.231
3	HDR_W5_D12_Bias	604.981	605.013	0.032
3	HDR_W6_D13_Bias	606.440	606.385	-0.055
3	HDR_W6_D21_Bias	605.119	605.150	0.031
3	HDR_W7_D5_Bias	603.598	603.610	0.012
10	HDR_W5_D9_Bias	604.334	604.226	-0.108
10	HDR_W6_D4_Bias	605.718	605.840	0.122
10	HDR_W6_D28_Bias	605.846	606.031	0.185
10	HDR_W7_D27_Bias	605.919	606.011	0.092
10	HDR_W7_D41_Bias	604.693	604.842	0.149
30	HDR_W5_D29_Bias	606.195	605.797	-0.398
30	HDR_W6_D27_Bias	605.710	605.566	-0.144
30	HDR_W6_D42_Bias	605.249	605.238	-0.011
30	HDR_W7_D31_Bias	606.197	605.887	-0.310
30	HDR_W7_D22_Bias	604.758	605.046	0.288
50	HDR_W5_D37_Bias	604.788	604.210	-0.578
50	HDR_W5_D39_Bias	603.708	605.819	2.111
50	HDR_W6_D14_Bias	605.987	605.119	-0.868
50	HDR_W7_D13_Bias	605.890	606.408	0.518
50	HDR_W7_D37_Bias	606.967	602.862	-4.105
100	HDR_W5_D8_Bias	605.390	604.387	-1.003
100	HDR_W5_D13_Bias	605.193	604.326	-0.867
100	HDR_W5_D30_Bias	603.851	603.183	-0.668
100	HDR_W5_D32_Bias	602.907	602.173	-0.734
100	HDR_W5_D34_Bias	606.193	605.228	-0.965
100	HDR_W5_D38_Bias	603.731	602.830	-0.901
100	HDR_W5_D41_Bias	604.597	603.538	-1.059
100	HDR_W6_D1_Bias	606.107	604.287	-1.820
100	HDR_W6_D8_Bias	604.959	604.623	-0.336
100	HDR_W6_D18_Bias	607.181	605.860	-1.321
100	HDR_W6_D22_Bias	605.384	604.628	-0.756
100	HDR_W6_D24_Bias	604.531	603.419	-1.112
100	HDR_W6_D30_Bias	605.917	604.319	-1.598
100	HDR_W6_D32_Bias	605.889	605.204	-0.685
100	HDR_W6_D39_Bias	605.022	603.513	-1.509
100	HDR_W7_D4_Bias	605.869	604.698	-1.171
100	HDR_W7_D9_Bias	605.786	604.589	-1.197
100	HDR_W7_D17_Bias	604.760	604.197	-0.563
100	HDR_W7_D18_Bias	603.982	602.330	-1.652
100	HDR_W7_D25_Bias	607.291	605.416	-1.875
100	HDR_W7_D34_Bias	604.384	603.836	-0.548
100	HDR_W7_D35_Bias	604.288	603.526	-0.762
	Max	607.291	606.408	2.111
	Average	605.201	604.573	-0.628
	Min	602.907	602.173	-4.105
	Std Dev	1.047	1.117	0.921



	13.16__FB_VinMin				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	616 mV				
Min Limit	594 mV				
krad(Si)	3	10	30	50	100
LL	594.000	594.000	594.000	594.000	594.000
Min	602.904	604.226	605.046	602.862	602.173
Average	604.612	605.390	605.507	604.884	604.096
Max	606.385	606.031	605.887	606.408	605.860
UL	616.000	616.000	616.000	616.000	616.000



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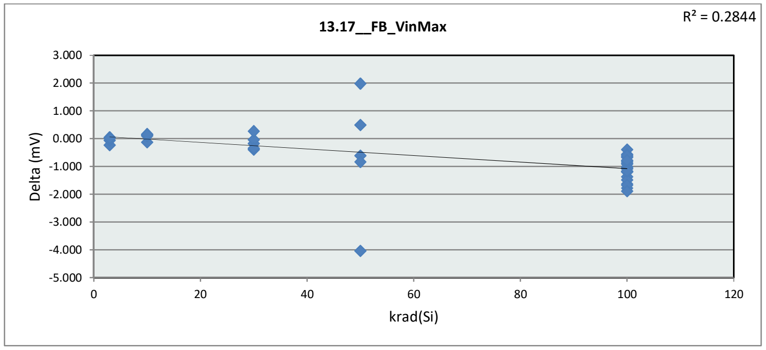
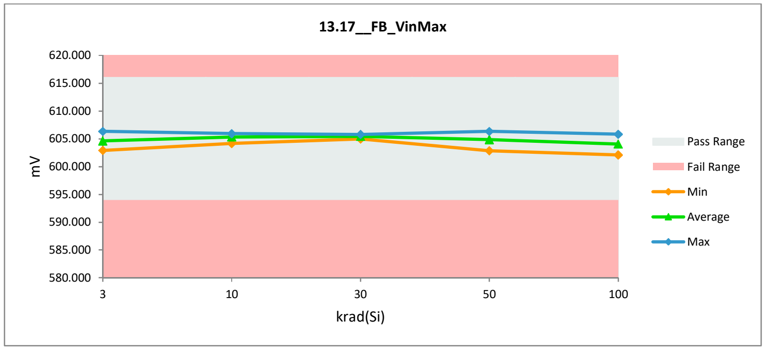
		13.17__FB_VinMax		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	603.146	602.911	-0.235
3	HDR_W5_D12_Bias	605.003	605.054	0.051
3	HDR_W6_D13_Bias	606.378	606.319	-0.059
3	HDR_W6_D21_Bias	605.084	605.116	0.032
3	HDR_W7_D5_Bias	603.657	603.679	0.022
10	HDR_W5_D9_Bias	604.292	604.165	-0.127
10	HDR_W6_D4_Bias	605.666	605.795	0.129
10	HDR_W6_D28_Bias	605.729	605.897	0.168
10	HDR_W7_D27_Bias	605.831	605.932	0.101
10	HDR_W7_D41_Bias	604.668	604.813	0.145
30	HDR_W5_D29_Bias	606.182	605.794	-0.388
30	HDR_W6_D27_Bias	605.714	605.546	-0.168
30	HDR_W6_D42_Bias	605.180	605.146	-0.034
30	HDR_W7_D31_Bias	606.121	605.775	-0.346
30	HDR_W7_D22_Bias	604.696	604.968	0.272
50	HDR_W5_D37_Bias	604.808	604.195	-0.613
50	HDR_W5_D39_Bias	603.747	605.731	1.984
50	HDR_W6_D14_Bias	605.934	605.098	-0.836
50	HDR_W7_D13_Bias	605.851	606.343	0.492
50	HDR_W7_D37_Bias	606.895	602.861	-4.034
100	HDR_W5_D8_Bias	605.388	604.380	-1.008
100	HDR_W5_D13_Bias	605.204	604.319	-0.885
100	HDR_W5_D30_Bias	603.850	603.205	-0.645
100	HDR_W5_D32_Bias	602.870	602.076	-0.794
100	HDR_W5_D34_Bias	606.167	605.122	-1.045
100	HDR_W5_D38_Bias	603.653	602.736	-0.917
100	HDR_W5_D41_Bias	604.699	603.619	-1.080
100	HDR_W6_D1_Bias	606.053	604.272	-1.781
100	HDR_W6_D8_Bias	604.875	604.484	-0.391
100	HDR_W6_D18_Bias	607.174	605.800	-1.374
100	HDR_W6_D22_Bias	605.284	604.454	-0.830
100	HDR_W6_D24_Bias	604.601	603.405	-1.196
100	HDR_W6_D30_Bias	605.977	604.350	-1.627
100	HDR_W6_D32_Bias	605.796	605.126	-0.670
100	HDR_W6_D39_Bias	604.968	603.486	-1.482
100	HDR_W7_D4_Bias	605.824	604.653	-1.171
100	HDR_W7_D9_Bias	605.736	604.567	-1.169
100	HDR_W7_D17_Bias	604.749	604.187	-0.562
100	HDR_W7_D18_Bias	603.892	602.227	-1.665
100	HDR_W7_D25_Bias	607.269	605.383	-1.886
100	HDR_W7_D34_Bias	604.355	603.759	-0.596
100	HDR_W7_D35_Bias	604.238	603.460	-0.778
	Max	607.269	606.343	1.984
	Average	605.172	604.529	-0.643
	Min	602.870	602.076	-4.034
	Std Dev	1.035	1.105	0.905



	13.17__FB_VinMax				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	616	mV			
Min Limit	594	mV			
krad(Si)	3	10	30	50	100
LL	594.000	594.000	594.000	594.000	594.000
Min	602.911	604.165	604.968	602.861	602.076
Average	604.616	605.320	605.446	604.846	604.049
Max	606.319	605.932	605.794	606.343	605.800
UL	616.000	616.000	616.000	616.000	616.000



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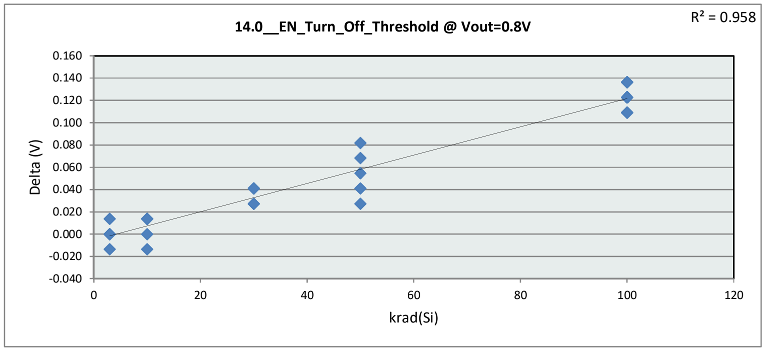
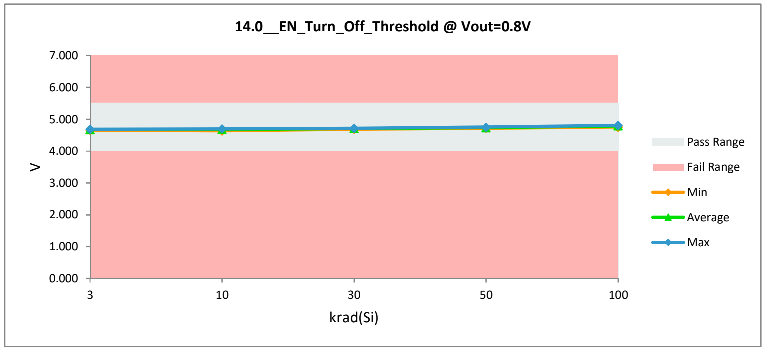
		14.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	5.5	5.5	
	Min Limit	4	4	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	4.674	4.661	-0.014
3	HDR_W5_D12_Bias	4.661	4.661	0.000
3	HDR_W6_D13_Bias	4.688	4.688	0.000
3	HDR_W6_D21_Bias	4.674	4.688	0.014
3	HDR_W7_D5_Bias	4.674	4.674	0.000
10	HDR_W5_D9_Bias	4.647	4.633	-0.014
10	HDR_W6_D4_Bias	4.688	4.701	0.014
10	HDR_W6_D28_Bias	4.674	4.688	0.014
10	HDR_W7_D27_Bias	4.674	4.688	0.014
10	HDR_W7_D41_Bias	4.688	4.688	0.000
30	HDR_W5_D29_Bias	4.647	4.688	0.041
30	HDR_W6_D27_Bias	4.688	4.715	0.027
30	HDR_W6_D42_Bias	4.674	4.715	0.041
30	HDR_W7_D31_Bias	4.688	4.715	0.027
30	HDR_W7_D22_Bias	4.674	4.715	0.041
50	HDR_W5_D37_Bias	4.674	4.729	0.055
50	HDR_W5_D39_Bias	4.661	4.729	0.068
50	HDR_W6_D14_Bias	4.674	4.756	0.082
50	HDR_W7_D13_Bias	4.701	4.742	0.041
50	HDR_W7_D37_Bias	4.688	4.715	0.027
100	HDR_W5_D8_Bias	4.633	4.756	0.123
100	HDR_W5_D13_Bias	4.647	4.769	0.123
100	HDR_W5_D30_Bias	4.647	4.783	0.136
100	HDR_W5_D32_Bias	4.647	4.783	0.136
100	HDR_W5_D34_Bias	4.661	4.783	0.123
100	HDR_W5_D38_Bias	4.633	4.756	0.123
100	HDR_W5_D41_Bias	4.647	4.783	0.136
100	HDR_W6_D1_Bias	4.688	4.810	0.123
100	HDR_W6_D8_Bias	4.701	4.810	0.109
100	HDR_W6_D18_Bias	4.701	4.810	0.109
100	HDR_W6_D22_Bias	4.688	4.810	0.123
100	HDR_W6_D24_Bias	4.688	4.810	0.123
100	HDR_W6_D30_Bias	4.674	4.797	0.123
100	HDR_W6_D32_Bias	4.688	4.810	0.123
100	HDR_W6_D39_Bias	4.688	4.810	0.123
100	HDR_W7_D4_Bias	4.674	4.783	0.109
100	HDR_W7_D9_Bias	4.688	4.797	0.109
100	HDR_W7_D17_Bias	4.701	4.810	0.109
100	HDR_W7_D18_Bias	4.661	4.797	0.136
100	HDR_W7_D25_Bias	4.674	4.797	0.123
100	HDR_W7_D34_Bias	4.674	4.797	0.123
100	HDR_W7_D35_Bias	4.674	4.797	0.123
	Max	4.701	4.810	0.136
	Average	4.673	4.749	0.075
	Min	4.633	4.633	-0.014
	Std Dev	0.018	0.053	0.053



	14.0__EN_Turn_Off_Threshold				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	5.5	V			
Min Limit	4	V			
krad(Si)	3	10	30	50	100
LL	4.000	4.000	4.000	4.000	4.000
Min	4.661	4.633	4.688	4.715	4.756
Average	4.674	4.680	4.710	4.734	4.794
Max	4.688	4.701	4.715	4.756	4.810
UL	5.500	5.500	5.500	5.500	5.500



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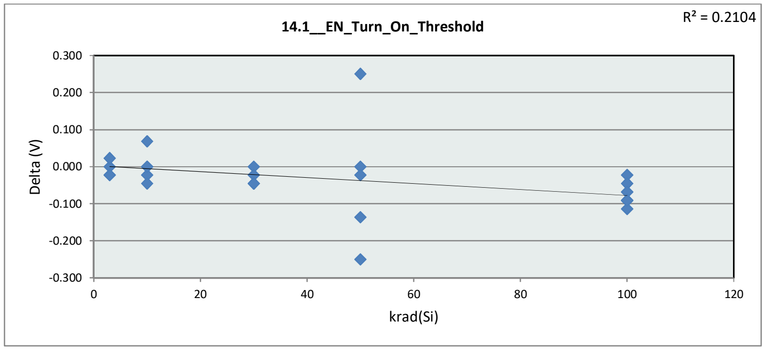
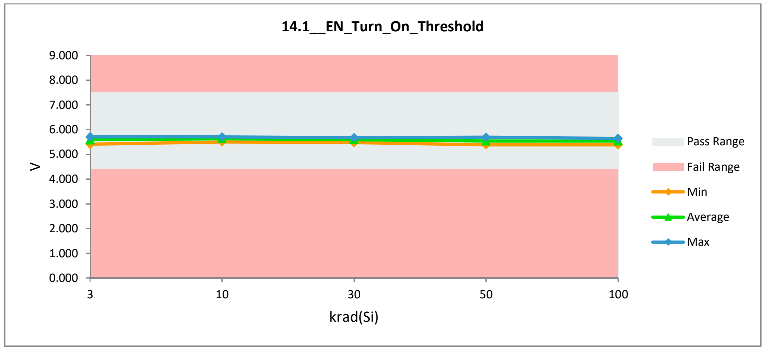
		14.1__EN_Turn_On_Threshold		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	7.5	7.5	
	Min Limit	4.4	4.4	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	5.413	5.436	0.023
3	HDR_W5_D12_Bias	5.413	5.413	0.000
3	HDR_W6_D13_Bias	5.708	5.686	-0.023
3	HDR_W6_D21_Bias	5.731	5.708	-0.023
3	HDR_W7_D5_Bias	5.663	5.686	0.023
10	HDR_W5_D9_Bias	5.436	5.504	0.068
10	HDR_W6_D4_Bias	5.686	5.663	-0.023
10	HDR_W6_D28_Bias	5.708	5.708	0.000
10	HDR_W7_D27_Bias	5.708	5.663	-0.045
10	HDR_W7_D41_Bias	5.640	5.640	0.000
30	HDR_W5_D29_Bias	5.481	5.481	0.000
30	HDR_W6_D27_Bias	5.663	5.640	-0.023
30	HDR_W6_D42_Bias	5.708	5.663	-0.045
30	HDR_W7_D31_Bias	5.663	5.617	-0.045
30	HDR_W7_D22_Bias	5.640	5.595	-0.045
50	HDR_W5_D37_Bias	5.390	5.390	0.000
50	HDR_W5_D39_Bias	5.436	5.686	0.250
50	HDR_W6_D14_Bias	5.731	5.595	-0.136
50	HDR_W7_D13_Bias	5.640	5.617	-0.023
50	HDR_W7_D37_Bias	5.663	5.413	-0.250
100	HDR_W5_D8_Bias	5.504	5.436	-0.068
100	HDR_W5_D13_Bias	5.436	5.390	-0.046
100	HDR_W5_D30_Bias	5.436	5.413	-0.023
100	HDR_W5_D32_Bias	5.413	5.390	-0.023
100	HDR_W5_D34_Bias	5.549	5.481	-0.068
100	HDR_W5_D38_Bias	5.481	5.436	-0.045
100	HDR_W5_D41_Bias	5.436	5.390	-0.046
100	HDR_W6_D1_Bias	5.686	5.595	-0.091
100	HDR_W6_D8_Bias	5.708	5.640	-0.068
100	HDR_W6_D18_Bias	5.708	5.617	-0.091
100	HDR_W6_D22_Bias	5.731	5.640	-0.091
100	HDR_W6_D24_Bias	5.708	5.617	-0.091
100	HDR_W6_D30_Bias	5.731	5.617	-0.114
100	HDR_W6_D32_Bias	5.686	5.595	-0.091
100	HDR_W6_D39_Bias	5.731	5.617	-0.114
100	HDR_W7_D4_Bias	5.663	5.572	-0.091
100	HDR_W7_D9_Bias	5.663	5.572	-0.091
100	HDR_W7_D17_Bias	5.663	5.572	-0.091
100	HDR_W7_D18_Bias	5.663	5.572	-0.091
100	HDR_W7_D25_Bias	5.686	5.595	-0.091
100	HDR_W7_D34_Bias	5.663	5.572	-0.091
100	HDR_W7_D35_Bias	5.640	5.549	-0.091
	Max	5.731	5.708	0.250
	Average	5.612	5.564	-0.048
	Min	5.390	5.390	-0.250
	Std Dev	0.117	0.101	0.071



	14.1__EN_Turn_On_Threshold				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	7.5	V			
Min Limit	4.4	V			
krad(Si)	3	10	30	50	100
LL	4.400	4.400	4.400	4.400	4.400
Min	5.413	5.504	5.481	5.390	5.390
Average	5.586	5.636	5.599	5.540	5.540
Max	5.708	5.708	5.663	5.686	5.640
UL	7.500	7.500	7.500	7.500	7.500



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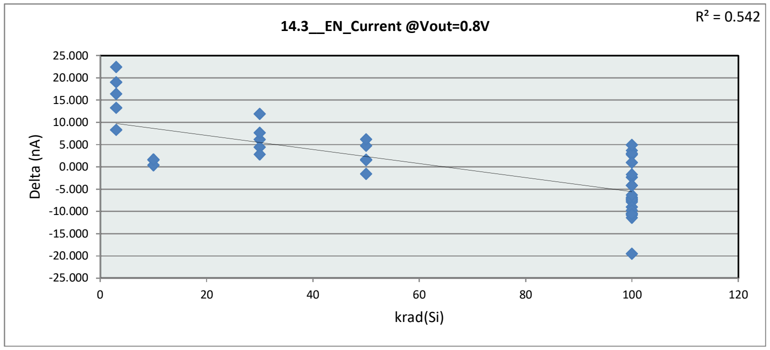
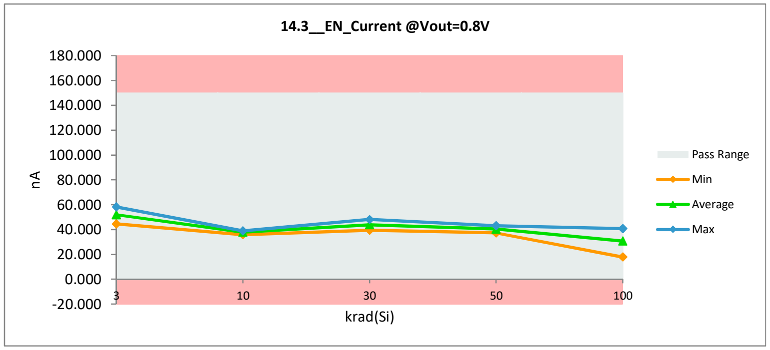
	14.3__EN_Current @Vout=0.8V	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	nA	nA
Max Limit	150	150
Min Limit	-0.0001	-0.0001

krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	36.209	44.475	8.266
3	HDR_W5_D12_Bias	35.887	58.299	22.412
3	HDR_W6_D13_Bias	33.797	47.046	13.249
3	HDR_W6_D21_Bias	35.525	51.906	16.381
3	HDR_W7_D5_Bias	38.872	57.890	19.018
10	HDR_W5_D9_Bias	35.580	35.914	0.334
10	HDR_W6_D4_Bias	36.515	38.074	1.559
10	HDR_W6_D28_Bias	38.000	38.381	0.381
10	HDR_W7_D27_Bias	37.403	38.986	1.583
10	HDR_W7_D41_Bias	36.554	38.161	1.607
30	HDR_W5_D29_Bias	36.704	42.808	6.104
30	HDR_W6_D27_Bias	39.115	43.500	4.385
30	HDR_W6_D42_Bias	37.748	45.356	7.608
30	HDR_W7_D31_Bias	36.594	39.403	2.809
30	HDR_W7_D22_Bias	36.201	48.092	11.891
50	HDR_W5_D37_Bias	37.717	42.470	4.753
50	HDR_W5_D39_Bias	37.010	43.178	6.168
50	HDR_W6_D14_Bias	38.809	37.201	-1.608
50	HDR_W7_D13_Bias	38.118	39.702	1.584
50	HDR_W7_D37_Bias	37.788	39.277	1.489
100	HDR_W5_D8_Bias	36.444	25.547	-10.897
100	HDR_W5_D13_Bias	34.826	32.475	-2.351
100	HDR_W5_D30_Bias	37.450	17.896	-19.554
100	HDR_W5_D32_Bias	35.698	39.364	3.666
100	HDR_W5_D34_Bias	35.407	24.910	-10.497
100	HDR_W5_D38_Bias	38.267	36.517	-1.750
100	HDR_W5_D41_Bias	38.133	40.826	2.693
100	HDR_W6_D1_Bias	35.227	28.363	-6.864
100	HDR_W6_D8_Bias	36.099	24.659	-11.440
100	HDR_W6_D18_Bias	35.243	28.032	-7.211
100	HDR_W6_D22_Bias	35.808	31.594	-4.214
100	HDR_W6_D24_Bias	36.586	29.078	-7.508
100	HDR_W6_D30_Bias	35.117	27.222	-7.895
100	HDR_W6_D32_Bias	35.942	28.685	-7.257
100	HDR_W6_D39_Bias	37.756	40.716	2.960
100	HDR_W7_D4_Bias	35.942	40.842	4.900
100	HDR_W7_D9_Bias	36.295	27.262	-9.033
100	HDR_W7_D17_Bias	35.989	29.660	-6.329
100	HDR_W7_D18_Bias	38.031	33.843	-4.188
100	HDR_W7_D25_Bias	36.083	26.279	-9.804
100	HDR_W7_D34_Bias	37.379	26.711	-10.668
100	HDR_W7_D35_Bias	35.227	36.155	0.928
	Max	39.115	58.299	22.412
	Average	36.645	36.827	0.182
	Min	33.797	17.896	-19.554
	Std Dev	1.227	8.956	8.774



	14.3__EN_Current @Vout=0.8V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	150	nA			
Min Limit	-0.0001	nA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	44.475	35.914	39.403	37.201	17.896
Average	51.923	37.903	43.832	40.366	30.756
Max	58.299	38.986	48.092	43.178	40.842
UL	150.000	150.000	150.000	150.000	150.000



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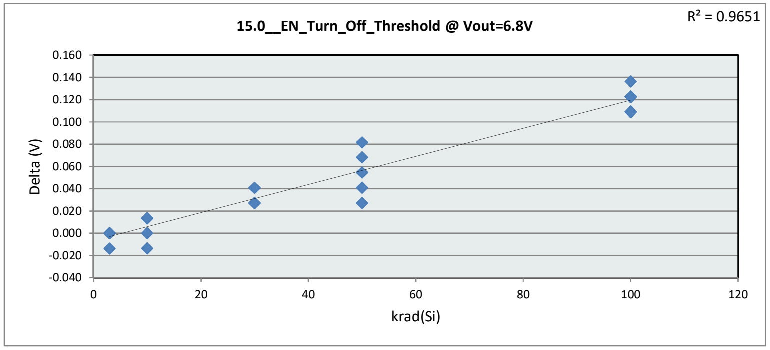
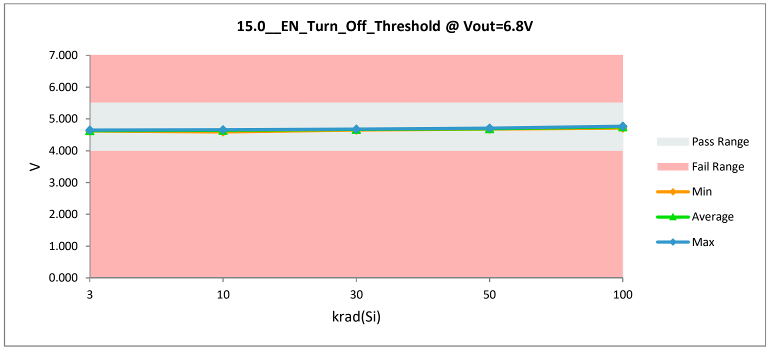
krad(Si)		15.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	5.5	5.5	
	Min Limit	4	4	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	4.633	4.620	-0.014
3	HDR_W5_D12_Bias	4.620	4.620	0.000
3	HDR_W6_D13_Bias	4.647	4.647	0.000
3	HDR_W6_D21_Bias	4.647	4.647	0.000
3	HDR_W7_D5_Bias	4.633	4.633	0.000
10	HDR_W5_D9_Bias	4.606	4.592	-0.014
10	HDR_W6_D4_Bias	4.647	4.661	0.014
10	HDR_W6_D28_Bias	4.633	4.647	0.014
10	HDR_W7_D27_Bias	4.633	4.647	0.014
10	HDR_W7_D41_Bias	4.647	4.647	0.000
30	HDR_W5_D29_Bias	4.620	4.647	0.027
30	HDR_W6_D27_Bias	4.647	4.674	0.027
30	HDR_W6_D42_Bias	4.633	4.674	0.041
30	HDR_W7_D31_Bias	4.647	4.674	0.027
30	HDR_W7_D22_Bias	4.633	4.674	0.041
50	HDR_W5_D37_Bias	4.633	4.688	0.055
50	HDR_W5_D39_Bias	4.620	4.688	0.068
50	HDR_W6_D14_Bias	4.633	4.715	0.082
50	HDR_W7_D13_Bias	4.661	4.701	0.041
50	HDR_W7_D37_Bias	4.647	4.674	0.027
100	HDR_W5_D8_Bias	4.592	4.715	0.123
100	HDR_W5_D13_Bias	4.606	4.729	0.123
100	HDR_W5_D30_Bias	4.606	4.742	0.136
100	HDR_W5_D32_Bias	4.606	4.729	0.123
100	HDR_W5_D34_Bias	4.620	4.742	0.123
100	HDR_W5_D38_Bias	4.592	4.715	0.123
100	HDR_W5_D41_Bias	4.620	4.742	0.123
100	HDR_W6_D1_Bias	4.647	4.769	0.123
100	HDR_W6_D8_Bias	4.661	4.769	0.109
100	HDR_W6_D18_Bias	4.661	4.769	0.109
100	HDR_W6_D22_Bias	4.647	4.769	0.123
100	HDR_W6_D24_Bias	4.647	4.769	0.123
100	HDR_W6_D30_Bias	4.647	4.756	0.109
100	HDR_W6_D32_Bias	4.647	4.769	0.123
100	HDR_W6_D39_Bias	4.647	4.769	0.123
100	HDR_W7_D4_Bias	4.633	4.742	0.109
100	HDR_W7_D9_Bias	4.647	4.756	0.109
100	HDR_W7_D17_Bias	4.661	4.769	0.109
100	HDR_W7_D18_Bias	4.633	4.756	0.123
100	HDR_W7_D25_Bias	4.633	4.756	0.123
100	HDR_W7_D34_Bias	4.633	4.756	0.123
100	HDR_W7_D35_Bias	4.633	4.756	0.123
	Max	4.661	4.769	0.136
	Average	4.634	4.708	0.073
	Min	4.592	4.592	-0.014
	Std Dev	0.018	0.053	0.052



	15.0__EN_Turn_Off_Threshold				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	5.5	V			
Min Limit	4	V			
krad(Si)	3	10	30	50	100
LL	4.000	4.000	4.000	4.000	4.000
Min	4.620	4.592	4.647	4.674	4.715
Average	4.633	4.639	4.669	4.693	4.752
Max	4.647	4.661	4.674	4.715	4.770
UL	5.500	5.500	5.500	5.500	5.500



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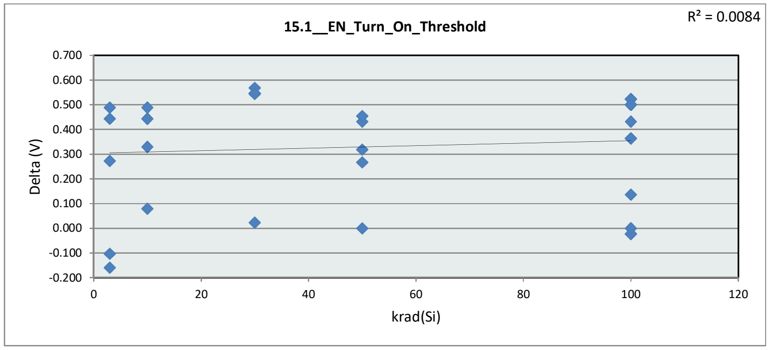
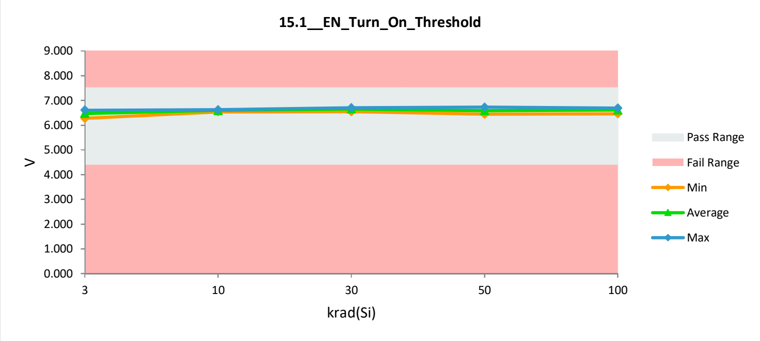
	15.1__EN_Turn_On_Threshold	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	V	V
Max Limit	7.5	7.5
Min Limit	4.4	4.4

krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	6.436	6.334	-0.102
3	HDR_W5_D12_Bias	6.436	6.277	-0.159
3	HDR_W6_D13_Bias	6.163	6.607	0.444
3	HDR_W6_D21_Bias	6.300	6.573	0.273
3	HDR_W7_D5_Bias	6.095	6.584	0.489
10	HDR_W5_D9_Bias	6.459	6.538	0.080
10	HDR_W6_D4_Bias	6.163	6.607	0.444
10	HDR_W6_D28_Bias	6.300	6.629	0.330
10	HDR_W7_D27_Bias	6.163	6.607	0.444
10	HDR_W7_D41_Bias	6.095	6.584	0.489
30	HDR_W5_D29_Bias	6.527	6.550	0.023
30	HDR_W6_D27_Bias	6.118	6.663	0.546
30	HDR_W6_D42_Bias	6.163	6.707	0.544
30	HDR_W7_D31_Bias	6.118	6.686	0.569
30	HDR_W7_D22_Bias	6.095	6.641	0.546
50	HDR_W5_D37_Bias	6.436	6.436	0.000
50	HDR_W5_D39_Bias	6.459	6.726	0.267
50	HDR_W6_D14_Bias	6.209	6.641	0.432
50	HDR_W7_D13_Bias	6.231	6.686	0.455
50	HDR_W7_D37_Bias	6.141	6.459	0.318
100	HDR_W5_D8_Bias	6.527	6.504	-0.023
100	HDR_W5_D13_Bias	6.482	6.459	-0.023
100	HDR_W5_D30_Bias	6.459	6.459	0.000
100	HDR_W5_D32_Bias	6.436	6.573	0.136
100	HDR_W5_D34_Bias	6.141	6.573	0.432
100	HDR_W5_D38_Bias	6.504	6.482	-0.023
100	HDR_W5_D41_Bias	6.459	6.459	0.000
100	HDR_W6_D1_Bias	6.300	6.663	0.364
100	HDR_W6_D8_Bias	6.186	6.686	0.500
100	HDR_W6_D18_Bias	6.186	6.686	0.500
100	HDR_W6_D22_Bias	6.186	6.686	0.500
100	HDR_W6_D24_Bias	6.300	6.663	0.364
100	HDR_W6_D30_Bias	6.186	6.686	0.500
100	HDR_W6_D32_Bias	6.163	6.663	0.500
100	HDR_W6_D39_Bias	6.186	6.686	0.500
100	HDR_W7_D4_Bias	6.118	6.641	0.523
100	HDR_W7_D9_Bias	6.141	6.663	0.523
100	HDR_W7_D17_Bias	6.141	6.663	0.523
100	HDR_W7_D18_Bias	6.118	6.618	0.500
100	HDR_W7_D25_Bias	6.300	6.663	0.364
100	HDR_W7_D34_Bias	6.141	6.663	0.523
100	HDR_W7_D35_Bias	6.095	6.595	0.500
	Max	6.527	6.726	0.569
	Average	6.259	6.595	0.336
	Min	6.095	6.277	-0.159
	Std Dev	0.147	0.102	0.223



	15.1__EN_Turn_On_Threshold	
Test Site	Dallas	
Tester	ETS-364	
Test Number	EF5069	
Max Limit	7.5	V
Min Limit	4.4	V

krad(Si)	3	10	30	50	100
LL	4.400	4.400	4.400	4.400	4.400
Min	6.277	6.539	6.550	6.436	6.459
Average	6.475	6.593	6.649	6.590	6.611
Max	6.607	6.629	6.707	6.726	6.686
UL	7.500	7.500	7.500	7.500	7.500



HDR Report
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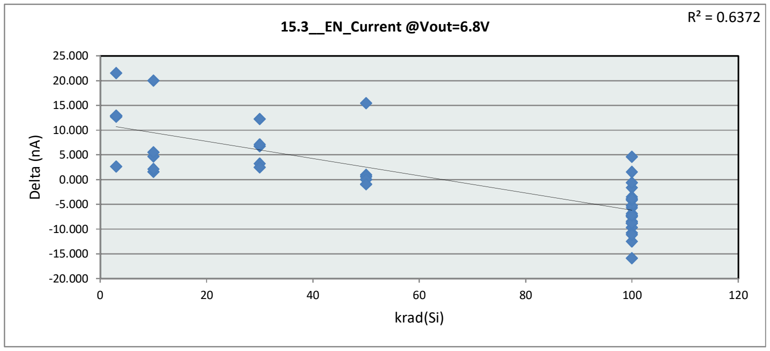
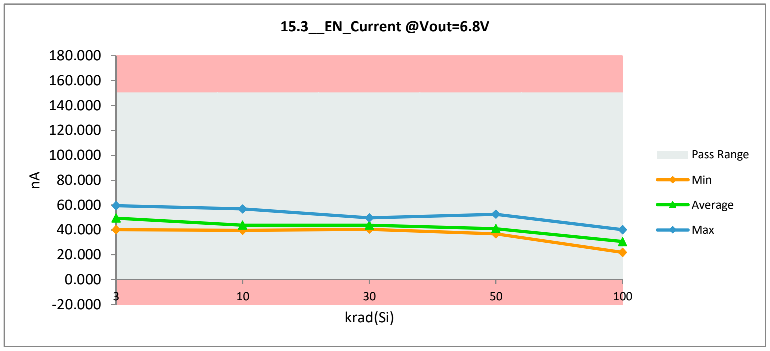
		15.3__EN_Current @Vout=6.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	37.458	40.119	2.661
3	HDR_W5_D12_Bias	36.279	49.170	12.891
3	HDR_W6_D13_Bias	35.926	48.635	12.709
3	HDR_W6_D21_Bias	37.206	50.121	12.915
3	HDR_W7_D5_Bias	37.898	59.416	21.518
10	HDR_W5_D9_Bias	36.798	56.808	20.010
10	HDR_W6_D4_Bias	38.063	39.663	1.600
10	HDR_W6_D28_Bias	37.858	40.024	2.166
10	HDR_W7_D27_Bias	37.576	42.265	4.689
10	HDR_W7_D41_Bias	35.093	40.614	5.521
30	HDR_W5_D29_Bias	34.583	41.353	6.770
30	HDR_W6_D27_Bias	39.869	43.083	3.214
30	HDR_W6_D42_Bias	37.403	49.657	12.254
30	HDR_W7_D31_Bias	38.031	40.543	2.512
30	HDR_W7_D22_Bias	37.261	44.365	7.104
50	HDR_W5_D37_Bias	38.966	39.953	0.987
50	HDR_W5_D39_Bias	36.303	36.942	0.639
50	HDR_W6_D14_Bias	38.298	38.349	0.051
50	HDR_W7_D13_Bias	38.667	37.760	-0.907
50	HDR_W7_D37_Bias	37.238	52.692	15.454
100	HDR_W5_D8_Bias	36.075	27.230	-8.845
100	HDR_W5_D13_Bias	34.999	33.395	-1.604
100	HDR_W5_D30_Bias	37.709	21.867	-15.842
100	HDR_W5_D32_Bias	35.792	26.153	-9.639
100	HDR_W5_D34_Bias	37.796	25.319	-12.477
100	HDR_W5_D38_Bias	39.013	35.102	-3.911
100	HDR_W5_D41_Bias	38.353	31.154	-7.199
100	HDR_W6_D1_Bias	35.525	40.142	4.617
100	HDR_W6_D8_Bias	35.093	26.648	-8.445
100	HDR_W6_D18_Bias	36.342	30.659	-5.683
100	HDR_W6_D22_Bias	37.136	38.687	1.551
100	HDR_W6_D24_Bias	36.814	29.338	-7.476
100	HDR_W6_D30_Bias	36.397	25.642	-10.755
100	HDR_W6_D32_Bias	36.114	30.863	-5.251
100	HDR_W6_D39_Bias	36.931	28.182	-8.749
100	HDR_W7_D4_Bias	36.279	32.137	-4.142
100	HDR_W7_D9_Bias	37.379	33.899	-3.480
100	HDR_W7_D17_Bias	36.869	30.030	-6.839
100	HDR_W7_D18_Bias	39.037	31.854	-7.183
100	HDR_W7_D25_Bias	37.395	26.287	-11.108
100	HDR_W7_D34_Bias	36.460	32.601	-3.859
100	HDR_W7_D35_Bias	36.947	36.336	-0.611
	Max	39.869	59.416	21.518
	Average	37.077	37.263	0.186
	Min	34.583	21.867	-15.842
	Std Dev	1.196	8.958	8.895



	15.3__EN_Current @Vout=6.8V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	150	nA			
Min Limit	-0.0001	nA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	40.119	39.663	40.543	36.942	21.867
Average	49.492	43.875	43.800	41.139	30.615
Max	59.416	56.808	49.657	52.692	40.142
UL	150.000	150.000	150.000	150.000	150.000



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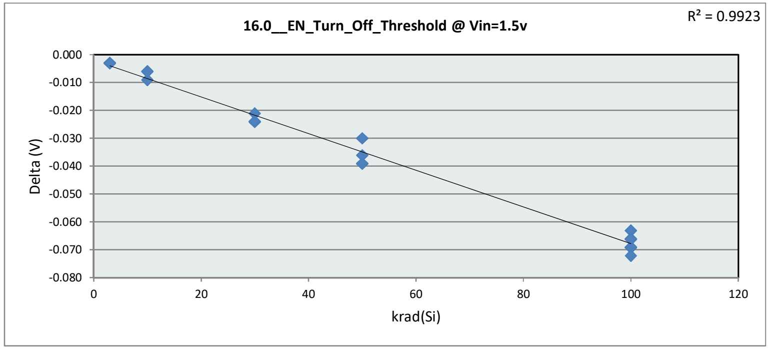
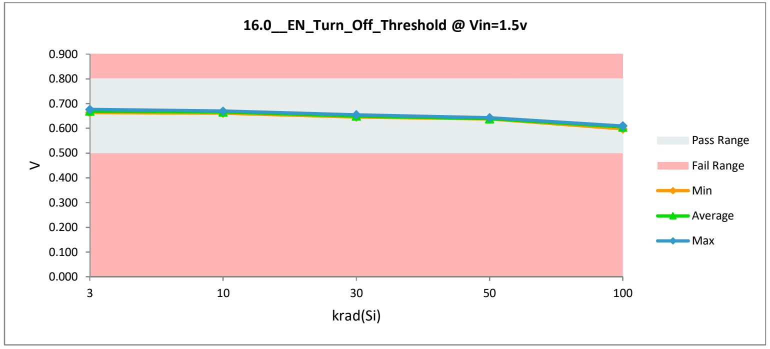
		16.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.8	0.8	
	Min Limit	0.5	0.5	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.679	0.676	-0.003
3	HDR_W5_D12_Bias	0.676	0.673	-0.003
3	HDR_W6_D13_Bias	0.667	0.664	-0.003
3	HDR_W6_D21_Bias	0.667	0.664	-0.003
3	HDR_W7_D5_Bias	0.673	0.670	-0.003
10	HDR_W5_D9_Bias	0.676	0.670	-0.006
10	HDR_W6_D4_Bias	0.670	0.661	-0.009
10	HDR_W6_D28_Bias	0.670	0.664	-0.006
10	HDR_W7_D27_Bias	0.676	0.667	-0.009
10	HDR_W7_D41_Bias	0.673	0.667	-0.006
30	HDR_W5_D29_Bias	0.676	0.655	-0.021
30	HDR_W6_D27_Bias	0.670	0.646	-0.024
30	HDR_W6_D42_Bias	0.670	0.646	-0.024
30	HDR_W7_D31_Bias	0.676	0.652	-0.024
30	HDR_W7_D22_Bias	0.673	0.649	-0.024
50	HDR_W5_D37_Bias	0.679	0.643	-0.036
50	HDR_W5_D39_Bias	0.676	0.637	-0.039
50	HDR_W6_D14_Bias	0.670	0.640	-0.030
50	HDR_W7_D13_Bias	0.676	0.637	-0.039
50	HDR_W7_D37_Bias	0.676	0.637	-0.039
100	HDR_W5_D8_Bias	0.676	0.607	-0.069
100	HDR_W5_D13_Bias	0.676	0.610	-0.066
100	HDR_W5_D30_Bias	0.676	0.610	-0.066
100	HDR_W5_D32_Bias	0.679	0.610	-0.069
100	HDR_W5_D34_Bias	0.676	0.607	-0.069
100	HDR_W5_D38_Bias	0.670	0.601	-0.069
100	HDR_W5_D41_Bias	0.679	0.610	-0.069
100	HDR_W6_D1_Bias	0.670	0.601	-0.069
100	HDR_W6_D8_Bias	0.673	0.610	-0.063
100	HDR_W6_D18_Bias	0.673	0.607	-0.066
100	HDR_W6_D22_Bias	0.670	0.604	-0.066
100	HDR_W6_D24_Bias	0.664	0.598	-0.066
100	HDR_W6_D30_Bias	0.667	0.604	-0.063
100	HDR_W6_D32_Bias	0.670	0.601	-0.069
100	HDR_W6_D39_Bias	0.667	0.601	-0.066
100	HDR_W7_D4_Bias	0.670	0.601	-0.069
100	HDR_W7_D9_Bias	0.673	0.604	-0.069
100	HDR_W7_D17_Bias	0.676	0.610	-0.066
100	HDR_W7_D18_Bias	0.673	0.604	-0.069
100	HDR_W7_D25_Bias	0.670	0.604	-0.066
100	HDR_W7_D34_Bias	0.673	0.601	-0.072
100	HDR_W7_D35_Bias	0.670	0.604	-0.066
	Max	0.679	0.676	-0.003
	Average	0.673	0.629	-0.044
	Min	0.664	0.598	-0.072
	Std Dev	0.004	0.027	0.027



	16.0__EN_Turn_Off_Threshold				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.8	V			
Min Limit	0.5	V			
krad(Si)	3	10	30	50	100
LL	0.500	0.500	0.500	0.500	0.500
Min	0.664	0.661	0.646	0.637	0.598
Average	0.670	0.666	0.650	0.639	0.605
Max	0.676	0.670	0.655	0.643	0.610
UL	0.800	0.800	0.800	0.800	0.800



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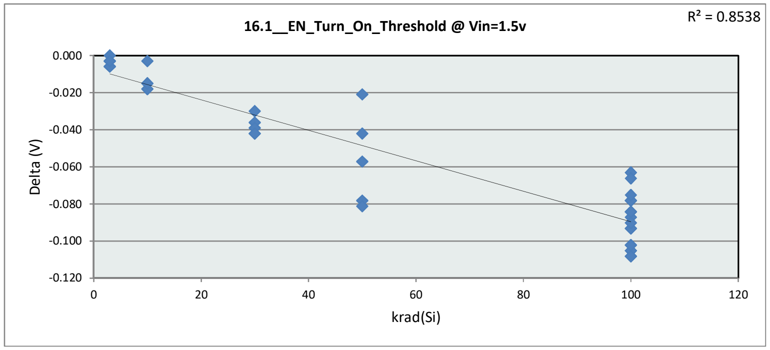
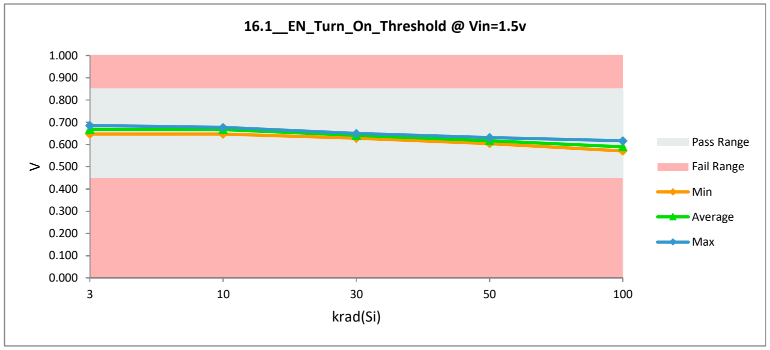
		16.1__EN_Turn_On_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.85	0.85	
	Min Limit	0.45	0.45	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.649	0.649	0.000
3	HDR_W5_D12_Bias	0.649	0.646	-0.003
3	HDR_W6_D13_Bias	0.688	0.682	-0.006
3	HDR_W6_D21_Bias	0.691	0.685	-0.006
3	HDR_W7_D5_Bias	0.679	0.676	-0.003
10	HDR_W5_D9_Bias	0.649	0.646	-0.003
10	HDR_W6_D4_Bias	0.688	0.670	-0.018
10	HDR_W6_D28_Bias	0.691	0.676	-0.015
10	HDR_W7_D27_Bias	0.694	0.676	-0.018
10	HDR_W7_D41_Bias	0.682	0.667	-0.015
30	HDR_W5_D29_Bias	0.658	0.628	-0.030
30	HDR_W6_D27_Bias	0.682	0.646	-0.036
30	HDR_W6_D42_Bias	0.691	0.649	-0.042
30	HDR_W7_D31_Bias	0.682	0.643	-0.039
30	HDR_W7_D22_Bias	0.676	0.634	-0.042
50	HDR_W5_D37_Bias	0.649	0.607	-0.042
50	HDR_W5_D39_Bias	0.652	0.631	-0.021
50	HDR_W6_D14_Bias	0.697	0.619	-0.078
50	HDR_W7_D13_Bias	0.679	0.622	-0.057
50	HDR_W7_D37_Bias	0.685	0.604	-0.081
100	HDR_W5_D8_Bias	0.658	0.574	-0.084
100	HDR_W5_D13_Bias	0.652	0.589	-0.063
100	HDR_W5_D30_Bias	0.652	0.574	-0.078
100	HDR_W5_D32_Bias	0.652	0.589	-0.063
100	HDR_W5_D34_Bias	0.664	0.586	-0.078
100	HDR_W5_D38_Bias	0.655	0.571	-0.084
100	HDR_W5_D41_Bias	0.652	0.574	-0.078
100	HDR_W6_D1_Bias	0.688	0.595	-0.093
100	HDR_W6_D8_Bias	0.694	0.589	-0.105
100	HDR_W6_D18_Bias	0.691	0.589	-0.102
100	HDR_W6_D22_Bias	0.700	0.592	-0.108
100	HDR_W6_D24_Bias	0.685	0.580	-0.105
100	HDR_W6_D30_Bias	0.691	0.616	-0.075
100	HDR_W6_D32_Bias	0.691	0.586	-0.105
100	HDR_W6_D39_Bias	0.697	0.604	-0.093
100	HDR_W7_D4_Bias	0.682	0.595	-0.087
100	HDR_W7_D9_Bias	0.685	0.595	-0.090
100	HDR_W7_D17_Bias	0.682	0.616	-0.066
100	HDR_W7_D18_Bias	0.682	0.592	-0.090
100	HDR_W7_D25_Bias	0.694	0.610	-0.084
100	HDR_W7_D34_Bias	0.688	0.580	-0.108
100	HDR_W7_D35_Bias	0.682	0.580	-0.102
	Max	0.700	0.685	0.000
	Average	0.677	0.618	-0.060
	Min	0.649	0.571	-0.108
	Std Dev	0.017	0.035	0.036



	16.1__EN_Turn_On_Threshold				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.85	V			
Min Limit	0.45	V			
krad(Si)	3	10	30	50	100
LL	0.450	0.450	0.450	0.450	0.450
Min	0.646	0.646	0.628	0.604	0.571
Average	0.668	0.667	0.640	0.617	0.590
Max	0.685	0.676	0.649	0.631	0.616
UL	0.850	0.850	0.850	0.850	0.850



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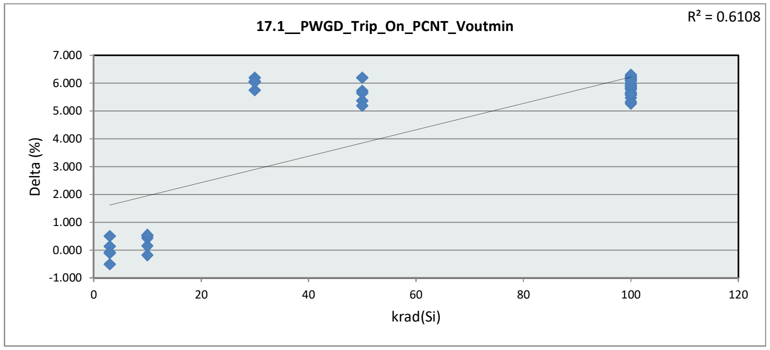
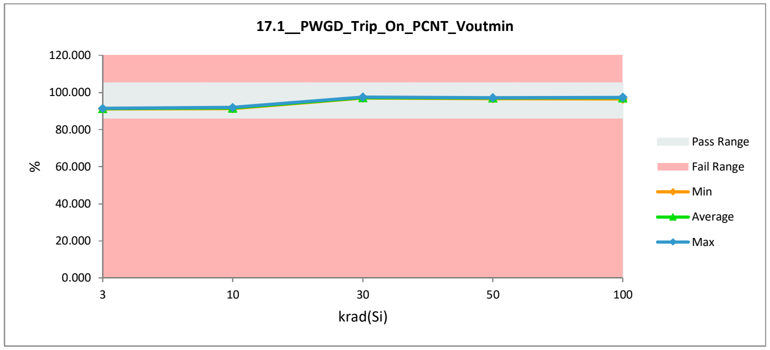
		17.1__PWGD_Trip_On_PCNT_Vo		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%	%	
	Max Limit	105	105	
	Min Limit	86	86	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	91.281	91.417	0.136
3	HDR_W5_D12_Bias	91.710	91.196	-0.514
3	HDR_W6_D13_Bias	91.303	91.221	-0.082
3	HDR_W6_D21_Bias	91.268	91.160	-0.108
3	HDR_W7_D5_Bias	90.869	91.369	0.500
10	HDR_W5_D9_Bias	91.495	91.312	-0.183
10	HDR_W6_D4_Bias	91.349	91.496	0.147
10	HDR_W6_D28_Bias	91.193	91.619	0.426
10	HDR_W7_D27_Bias	91.219	91.722	0.503
10	HDR_W7_D41_Bias	91.350	91.896	0.546
30	HDR_W5_D29_Bias	91.699	97.443	5.744
30	HDR_W6_D27_Bias	90.892	96.952	6.060
30	HDR_W6_D42_Bias	91.074	97.270	6.196
30	HDR_W7_D31_Bias	90.976	97.038	6.062
30	HDR_W7_D22_Bias	91.162	97.199	6.037
50	HDR_W5_D37_Bias	91.488	96.850	5.362
50	HDR_W5_D39_Bias	91.500	97.223	5.723
50	HDR_W6_D14_Bias	91.318	96.961	5.643
50	HDR_W7_D13_Bias	91.028	97.218	6.190
50	HDR_W7_D37_Bias	91.509	96.697	5.188
100	HDR_W5_D8_Bias	91.042	97.283	6.241
100	HDR_W5_D13_Bias	91.462	97.379	5.917
100	HDR_W5_D30_Bias	91.204	97.028	5.824
100	HDR_W5_D32_Bias	91.038	96.881	5.843
100	HDR_W5_D34_Bias	91.392	97.063	5.671
100	HDR_W5_D38_Bias	91.114	97.321	6.207
100	HDR_W5_D41_Bias	91.579	96.841	5.262
100	HDR_W6_D1_Bias	91.341	96.911	5.570
100	HDR_W6_D8_Bias	91.165	97.049	5.884
100	HDR_W6_D18_Bias	90.891	97.045	6.154
100	HDR_W6_D22_Bias	91.255	97.238	5.983
100	HDR_W6_D24_Bias	91.107	96.439	5.332
100	HDR_W6_D30_Bias	90.923	96.701	5.778
100	HDR_W6_D32_Bias	90.804	96.929	6.125
100	HDR_W6_D39_Bias	91.359	96.828	5.469
100	HDR_W7_D4_Bias	91.265	97.046	5.781
100	HDR_W7_D9_Bias	91.704	97.332	5.628
100	HDR_W7_D17_Bias	91.473	97.059	5.586
100	HDR_W7_D18_Bias	91.062	97.162	6.100
100	HDR_W7_D25_Bias	90.884	97.183	6.299
100	HDR_W7_D34_Bias	90.821	96.753	5.932
100	HDR_W7_D35_Bias	90.902	96.978	6.076
	Max	91.710	97.443	6.299
	Average	91.225	95.707	4.482
	Min	90.804	91.160	-0.514
	Std Dev	0.252	2.425	2.478



	17.1__PWGD_Trip_On_PCNT_V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	105	%			
Min Limit	86	%			
krad(Si)	3	10	30	50	100
LL	86.000	86.000	86.000	86.000	86.000
Min	91.160	91.312	96.952	96.697	96.439
Average	91.273	91.609	97.180	96.990	97.020
Max	91.417	91.896	97.443	97.223	97.379
UL	105.000	105.000	105.000	105.000	105.000



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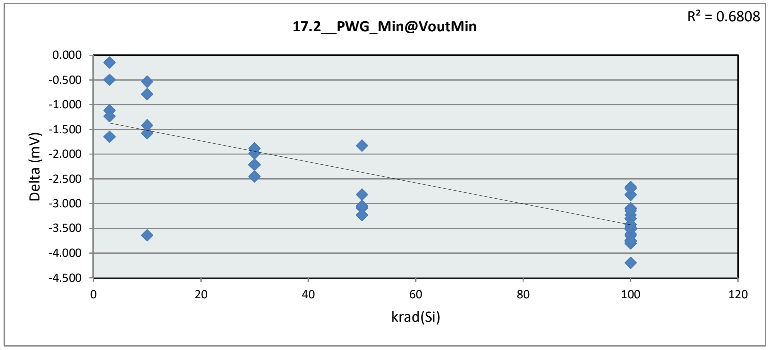
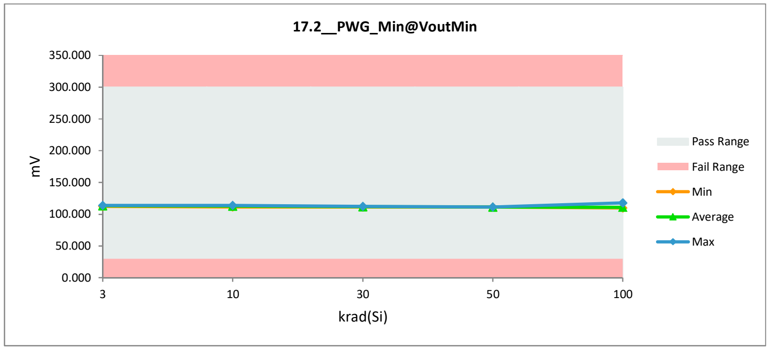
		17.2__PWG_Min@VoutMin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	300	300	
	Min Limit	30	30	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	114.080	112.432	-1.648
3	HDR_W5_D12_Bias	114.226	113.108	-1.118
3	HDR_W6_D13_Bias	114.045	113.895	-0.150
3	HDR_W6_D21_Bias	113.775	113.276	-0.499
3	HDR_W7_D5_Bias	114.558	113.323	-1.235
10	HDR_W5_D9_Bias	115.163	111.521	-3.642
10	HDR_W6_D4_Bias	113.549	112.757	-0.792
10	HDR_W6_D28_Bias	114.031	112.612	-1.419
10	HDR_W7_D27_Bias	114.202	113.668	-0.534
10	HDR_W7_D41_Bias	113.828	112.248	-1.580
30	HDR_W5_D29_Bias	114.309	111.856	-2.453
30	HDR_W6_D27_Bias	114.050	111.840	-2.210
30	HDR_W6_D42_Bias	114.146	112.162	-1.984
30	HDR_W7_D31_Bias	113.767	111.547	-2.220
30	HDR_W7_D22_Bias	113.077	111.191	-1.886
50	HDR_W5_D37_Bias	114.042	110.958	-3.084
50	HDR_W5_D39_Bias	114.356	111.309	-3.047
50	HDR_W6_D14_Bias	114.250	111.019	-3.231
50	HDR_W7_D13_Bias	113.356	111.527	-1.829
50	HDR_W7_D37_Bias	114.211	111.395	-2.816
100	HDR_W5_D8_Bias	113.852	110.748	-3.104
100	HDR_W5_D13_Bias	114.032	110.800	-3.232
100	HDR_W5_D30_Bias	114.022	110.264	-3.758
100	HDR_W5_D32_Bias	114.363	110.618	-3.745
100	HDR_W5_D34_Bias	114.421	110.223	-4.198
100	HDR_W5_D38_Bias	113.794	110.143	-3.651
100	HDR_W5_D41_Bias	114.342	110.727	-3.615
100	HDR_W6_D1_Bias	113.772	110.461	-3.311
100	HDR_W6_D8_Bias	113.643	109.842	-3.801
100	HDR_W6_D18_Bias	114.003	110.482	-3.521
100	HDR_W6_D22_Bias	113.917	110.159	-3.758
100	HDR_W6_D24_Bias	114.082	110.582	-3.500
100	HDR_W6_D30_Bias	114.050	110.627	-3.423
100	HDR_W6_D32_Bias	113.831	110.355	-3.476
100	HDR_W6_D39_Bias	113.938	110.638	-3.300
100	HDR_W7_D4_Bias	114.014	111.193	-2.821
100	HDR_W7_D9_Bias	113.526	110.434	-3.092
100	HDR_W7_D17_Bias	120.590	117.765	-2.825
100	HDR_W7_D18_Bias	113.506	110.087	-3.419
100	HDR_W7_D25_Bias	113.904	111.240	-2.664
100	HDR_W7_D34_Bias	113.628	110.482	-3.146
100	HDR_W7_D35_Bias	113.003	110.311	-2.692
	Max	120.590	117.765	-0.150
	Average	114.125	111.472	-2.653
	Min	113.003	109.842	-4.198
	Std Dev	1.091	1.463	1.050



	17.2__PWG_Min@VoutMin				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	300	mV			
Min Limit	30	mV			
krad(Si)	3	10	30	50	100
LL	30.000	30.000	30.000	30.000	30.000
Min	112.432	111.521	111.191	110.958	109.842
Average	113.207	112.561	111.719	111.242	110.826
Max	113.895	113.668	112.162	111.527	117.765
UL	300.000	300.000	300.000	300.000	300.000



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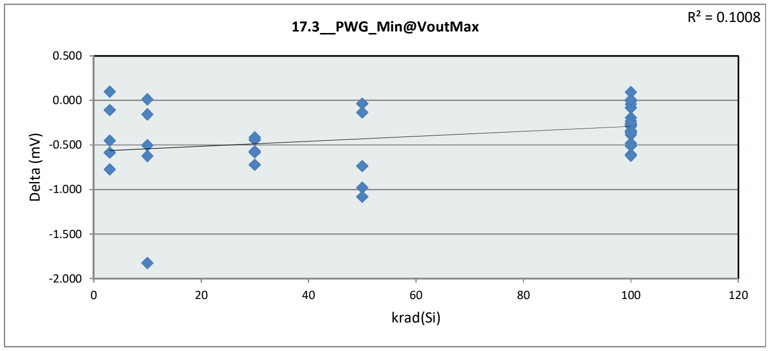
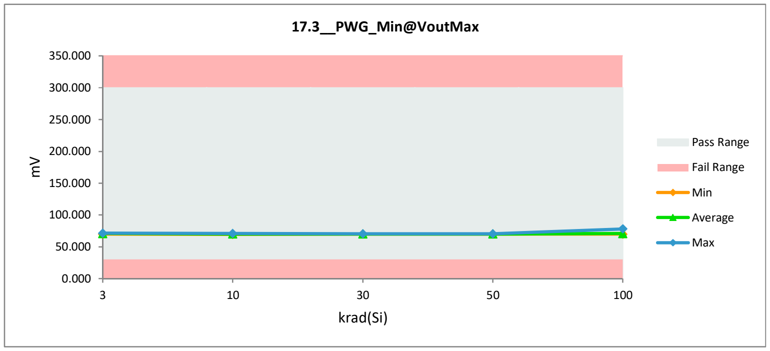
		17.3__PWG_Min@VoutMax		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	300	300	
	Min Limit	30	30	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	70.558	69.782	-0.776
3	HDR_W5_D12_Bias	70.618	70.166	-0.452
3	HDR_W6_D13_Bias	71.257	71.354	0.097
3	HDR_W6_D21_Bias	71.541	71.432	-0.109
3	HDR_W7_D5_Bias	71.708	71.122	-0.586
10	HDR_W5_D9_Bias	71.148	69.323	-1.825
10	HDR_W6_D4_Bias	70.766	70.610	-0.156
10	HDR_W6_D28_Bias	70.851	70.348	-0.503
10	HDR_W7_D27_Bias	71.125	71.135	0.010
10	HDR_W7_D41_Bias	70.711	70.087	-0.624
30	HDR_W5_D29_Bias	70.769	70.045	-0.724
30	HDR_W6_D27_Bias	70.766	70.182	-0.584
30	HDR_W6_D42_Bias	70.961	70.518	-0.443
30	HDR_W7_D31_Bias	70.750	70.178	-0.572
30	HDR_W7_D22_Bias	70.689	70.273	-0.416
50	HDR_W5_D37_Bias	70.562	69.826	-0.736
50	HDR_W5_D39_Bias	70.738	70.602	-0.136
50	HDR_W6_D14_Bias	71.276	70.297	-0.979
50	HDR_W7_D13_Bias	70.684	70.648	-0.036
50	HDR_W7_D37_Bias	71.139	70.058	-1.081
100	HDR_W5_D8_Bias	70.359	70.276	-0.083
100	HDR_W5_D13_Bias	70.712	70.447	-0.265
100	HDR_W5_D30_Bias	70.544	70.156	-0.388
100	HDR_W5_D32_Bias	70.564	70.211	-0.353
100	HDR_W5_D34_Bias	70.607	69.999	-0.608
100	HDR_W5_D38_Bias	70.469	70.118	-0.351
100	HDR_W5_D41_Bias	70.664	70.375	-0.289
100	HDR_W6_D1_Bias	70.769	70.481	-0.288
100	HDR_W6_D8_Bias	70.699	70.079	-0.620
100	HDR_W6_D18_Bias	71.047	70.565	-0.482
100	HDR_W6_D22_Bias	71.242	70.732	-0.510
100	HDR_W6_D24_Bias	71.425	71.084	-0.341
100	HDR_W6_D30_Bias	71.272	70.907	-0.365
100	HDR_W6_D32_Bias	70.851	70.577	-0.274
100	HDR_W6_D39_Bias	70.925	70.729	-0.196
100	HDR_W7_D4_Bias	71.329	71.286	-0.043
100	HDR_W7_D9_Bias	70.889	70.657	-0.232
100	HDR_W7_D17_Bias	78.302	78.299	-0.003
100	HDR_W7_D18_Bias	71.186	70.928	-0.258
100	HDR_W7_D25_Bias	71.080	71.172	0.092
100	HDR_W7_D34_Bias	70.772	70.691	-0.081
100	HDR_W7_D35_Bias	70.428	70.435	0.007
	Max	78.302	78.299	0.097
	Average	71.066	70.671	-0.394
	Min	70.359	69.323	-1.825
	Std Dev	1.187	1.289	0.359



	17.3__PWG_Min@VoutMax				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	300	mV			
Min Limit	30	mV			
krad(Si)	3	10	30	50	100
LL	30.000	30.000	30.000	30.000	30.000
Min	69.782	69.323	70.045	69.826	69.999
Average	70.771	70.301	70.239	70.286	70.918
Max	71.432	71.135	70.518	70.648	78.299
UL	300.000	300.000	300.000	300.000	300.000



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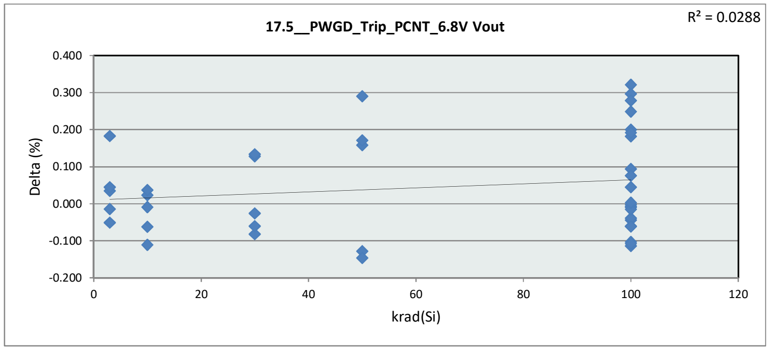
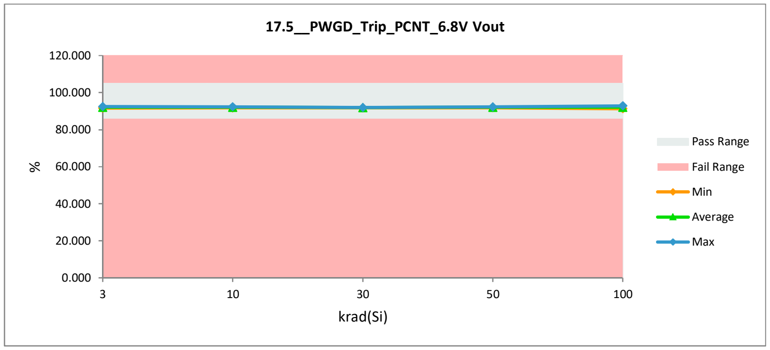
		17.5__PWGD_Trip_PCNT_6.8V V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%	%	
	Max Limit	105	105	
	Min Limit	86	86	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	92.486	92.435	-0.051
3	HDR_W5_D12_Bias	92.000	92.035	0.035
3	HDR_W6_D13_Bias	91.862	92.045	0.183
3	HDR_W6_D21_Bias	91.654	91.699	0.045
3	HDR_W7_D5_Bias	92.058	92.044	-0.014
10	HDR_W5_D9_Bias	92.304	92.242	-0.062
10	HDR_W6_D4_Bias	92.123	92.114	-0.009
10	HDR_W6_D28_Bias	91.896	91.785	-0.111
10	HDR_W7_D27_Bias	91.879	91.902	0.023
10	HDR_W7_D41_Bias	92.317	92.354	0.037
30	HDR_W5_D29_Bias	91.873	92.001	0.128
30	HDR_W6_D27_Bias	91.687	91.821	0.134
30	HDR_W6_D42_Bias	91.974	91.892	-0.082
30	HDR_W7_D31_Bias	92.025	91.999	-0.026
30	HDR_W7_D22_Bias	91.827	91.767	-0.060
50	HDR_W5_D37_Bias	92.084	91.956	-0.128
50	HDR_W5_D39_Bias	91.831	92.121	0.290
50	HDR_W6_D14_Bias	91.873	92.031	0.158
50	HDR_W7_D13_Bias	92.069	92.240	0.171
50	HDR_W7_D37_Bias	91.977	91.831	-0.146
100	HDR_W5_D8_Bias	92.202	92.195	-0.007
100	HDR_W5_D13_Bias	92.572	92.528	-0.044
100	HDR_W5_D30_Bias	91.949	91.889	-0.060
100	HDR_W5_D32_Bias	92.381	92.342	-0.039
100	HDR_W5_D34_Bias	91.795	91.793	-0.002
100	HDR_W5_D38_Bias	92.405	92.726	0.321
100	HDR_W5_D41_Bias	92.032	92.022	-0.010
100	HDR_W6_D1_Bias	91.505	91.802	0.297
100	HDR_W6_D8_Bias	91.833	91.772	-0.061
100	HDR_W6_D18_Bias	91.891	91.985	0.094
100	HDR_W6_D22_Bias	91.841	92.120	0.279
100	HDR_W6_D24_Bias	91.111	91.311	0.200
100	HDR_W6_D30_Bias	91.531	91.780	0.249
100	HDR_W6_D32_Bias	91.900	91.797	-0.103
100	HDR_W6_D39_Bias	92.019	91.905	-0.114
100	HDR_W7_D4_Bias	92.155	92.337	0.182
100	HDR_W7_D9_Bias	92.299	92.284	-0.015
100	HDR_W7_D17_Bias	91.904	91.949	0.045
100	HDR_W7_D18_Bias	92.774	92.850	0.076
100	HDR_W7_D25_Bias	91.650	91.842	0.192
100	HDR_W7_D34_Bias	91.551	91.444	-0.107
100	HDR_W7_D35_Bias	92.333	92.336	0.003
	Max	92.774	92.850	0.321
	Average	91.986	92.031	0.045
	Min	91.111	91.311	-0.146
	Std Dev	0.313	0.303	0.130



	17.5__PWGD_Trip_PCNT_6.8V	
Test Site	Dallas	
Tester	ETS-364	
Test Number	EF5069	
Max Limit	105	%
Min Limit	86	%

krad(Si)	3	10	30	50	100
LL	86.000	86.000	86.000	86.000	86.000
Min	91.699	91.785	91.767	91.831	91.311
Average	92.052	92.079	91.896	92.036	92.046
Max	92.435	92.354	92.001	92.240	92.850
UL	105.000	105.000	105.000	105.000	105.000



HDR Report
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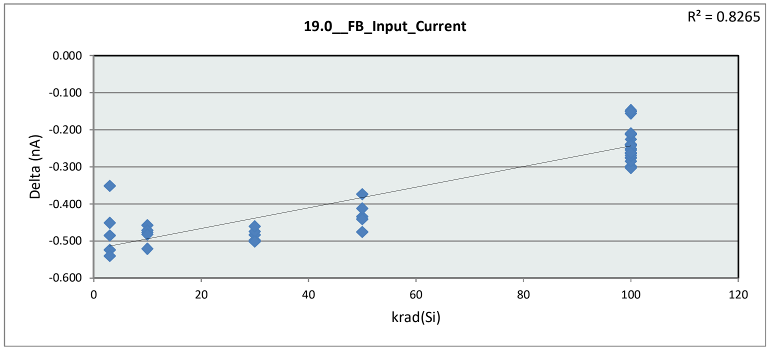
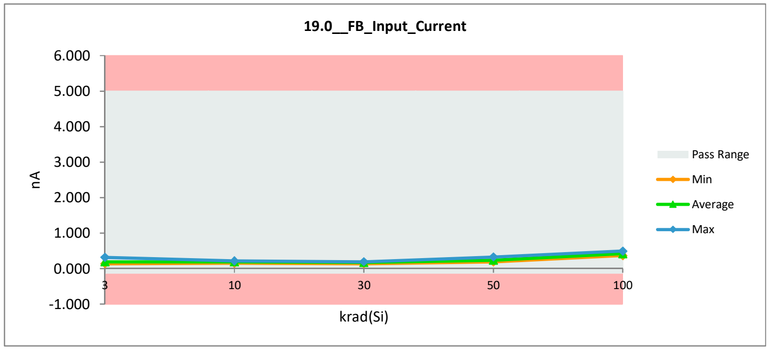
		19.0__FB_Input_Current		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	5	5	
	Min Limit	-0.15	-0.15	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.667	0.316	-0.351
3	HDR_W5_D12_Bias	0.661	0.137	-0.524
3	HDR_W6_D13_Bias	0.698	0.158	-0.540
3	HDR_W6_D21_Bias	0.651	0.166	-0.485
3	HDR_W7_D5_Bias	0.631	0.180	-0.451
10	HDR_W5_D9_Bias	0.668	0.191	-0.477
10	HDR_W6_D4_Bias	0.672	0.215	-0.457
10	HDR_W6_D28_Bias	0.676	0.155	-0.521
10	HDR_W7_D27_Bias	0.662	0.191	-0.471
10	HDR_W7_D41_Bias	0.665	0.183	-0.482
30	HDR_W5_D29_Bias	0.664	0.181	-0.483
30	HDR_W6_D27_Bias	0.634	0.136	-0.498
30	HDR_W6_D42_Bias	0.664	0.190	-0.474
30	HDR_W7_D31_Bias	0.669	0.168	-0.501
30	HDR_W7_D22_Bias	0.638	0.178	-0.460
50	HDR_W5_D37_Bias	0.652	0.218	-0.434
50	HDR_W5_D39_Bias	0.664	0.189	-0.475
50	HDR_W6_D14_Bias	0.629	0.217	-0.412
50	HDR_W7_D13_Bias	0.677	0.236	-0.441
50	HDR_W7_D37_Bias	0.700	0.326	-0.374
100	HDR_W5_D8_Bias	0.638	0.412	-0.226
100	HDR_W5_D13_Bias	0.664	0.365	-0.299
100	HDR_W5_D30_Bias	0.627	0.480	-0.147
100	HDR_W5_D32_Bias	0.625	0.474	-0.151
100	HDR_W5_D34_Bias	0.684	0.422	-0.262
100	HDR_W5_D38_Bias	0.647	0.491	-0.156
100	HDR_W5_D41_Bias	0.663	0.387	-0.276
100	HDR_W6_D1_Bias	0.658	0.407	-0.251
100	HDR_W6_D8_Bias	0.657	0.417	-0.240
100	HDR_W6_D18_Bias	0.689	0.386	-0.303
100	HDR_W6_D22_Bias	0.637	0.373	-0.264
100	HDR_W6_D24_Bias	0.647	0.435	-0.212
100	HDR_W6_D30_Bias	0.664	0.389	-0.275
100	HDR_W6_D32_Bias	0.652	0.413	-0.239
100	HDR_W6_D39_Bias	0.662	0.407	-0.255
100	HDR_W7_D4_Bias	0.670	0.427	-0.243
100	HDR_W7_D9_Bias	0.666	0.453	-0.213
100	HDR_W7_D17_Bias	0.657	0.447	-0.210
100	HDR_W7_D18_Bias	0.638	0.487	-0.151
100	HDR_W7_D25_Bias	0.693	0.408	-0.285
100	HDR_W7_D34_Bias	0.659	0.389	-0.270
100	HDR_W7_D35_Bias	0.665	0.403	-0.262
	Max	0.700	0.491	-0.147
	Average	0.660	0.314	-0.345
	Min	0.625	0.136	-0.540
	Std Dev	0.019	0.122	0.125



	19.0__FB_Input_Current				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	5	nA			
Min Limit	-0.15	nA			
krad(Si)	3	10	30	50	100
LL	-0.150	-0.150	-0.150	-0.150	-0.150
Min	0.137	0.155	0.136	0.189	0.365
Average	0.191	0.187	0.171	0.237	0.421
Max	0.316	0.215	0.190	0.326	0.491
UL	5.000	5.000	5.000	5.000	5.000



HDR Report
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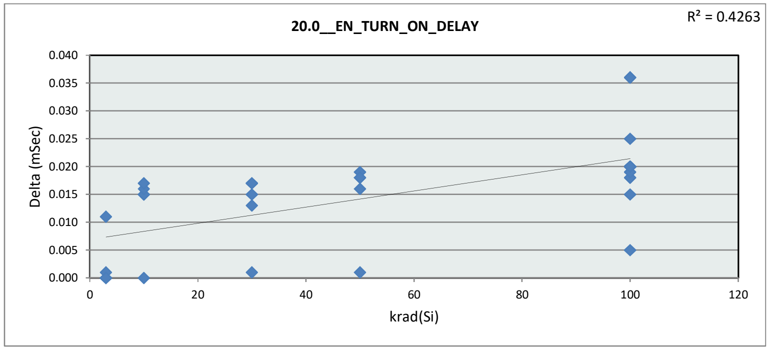
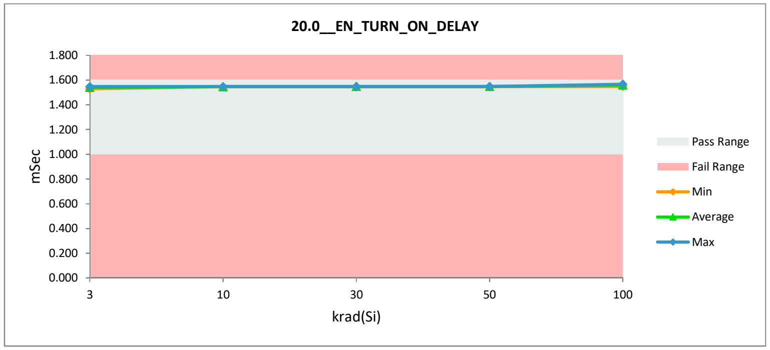
		20.0__EN_TURN_ON_DELAY		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mSec	mSec	
	Max Limit	1.6	1.6	
	Min Limit	1	1	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.529	1.529	0.000
3	HDR_W5_D12_Bias	1.530	1.531	0.001
3	HDR_W6_D13_Bias	1.547	1.547	0.000
3	HDR_W6_D21_Bias	1.547	1.547	0.000
3	HDR_W7_D5_Bias	1.536	1.547	0.011
10	HDR_W5_D9_Bias	1.532	1.547	0.015
10	HDR_W6_D4_Bias	1.532	1.547	0.015
10	HDR_W6_D28_Bias	1.547	1.547	0.000
10	HDR_W7_D27_Bias	1.531	1.547	0.016
10	HDR_W7_D41_Bias	1.530	1.547	0.017
30	HDR_W5_D29_Bias	1.530	1.547	0.017
30	HDR_W6_D27_Bias	1.533	1.548	0.015
30	HDR_W6_D42_Bias	1.547	1.548	0.001
30	HDR_W7_D31_Bias	1.530	1.547	0.017
30	HDR_W7_D22_Bias	1.535	1.548	0.013
50	HDR_W5_D37_Bias	1.529	1.548	0.019
50	HDR_W5_D39_Bias	1.532	1.548	0.016
50	HDR_W6_D14_Bias	1.547	1.548	0.001
50	HDR_W7_D13_Bias	1.530	1.548	0.018
50	HDR_W7_D37_Bias	1.530	1.548	0.018
100	HDR_W5_D8_Bias	1.547	1.567	0.020
100	HDR_W5_D13_Bias	1.531	1.551	0.020
100	HDR_W5_D30_Bias	1.531	1.567	0.036
100	HDR_W5_D32_Bias	1.529	1.549	0.020
100	HDR_W5_D34_Bias	1.531	1.567	0.036
100	HDR_W5_D38_Bias	1.547	1.567	0.020
100	HDR_W5_D41_Bias	1.529	1.549	0.020
100	HDR_W6_D1_Bias	1.547	1.567	0.020
100	HDR_W6_D8_Bias	1.531	1.549	0.018
100	HDR_W6_D18_Bias	1.532	1.550	0.018
100	HDR_W6_D22_Bias	1.547	1.567	0.020
100	HDR_W6_D24_Bias	1.547	1.567	0.020
100	HDR_W6_D30_Bias	1.547	1.567	0.020
100	HDR_W6_D32_Bias	1.547	1.567	0.020
100	HDR_W6_D39_Bias	1.547	1.567	0.020
100	HDR_W7_D4_Bias	1.547	1.567	0.020
100	HDR_W7_D9_Bias	1.531	1.556	0.025
100	HDR_W7_D17_Bias	1.530	1.549	0.019
100	HDR_W7_D18_Bias	1.537	1.552	0.015
100	HDR_W7_D25_Bias	1.547	1.567	0.020
100	HDR_W7_D34_Bias	1.531	1.567	0.036
100	HDR_W7_D35_Bias	1.547	1.552	0.005
	Max	1.547	1.567	0.036
	Average	1.537	1.553	0.016
	Min	1.529	1.529	0.000
	Std Dev	0.008	0.010	0.009



	20.0__EN_TURN_ON_DELAY				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.6	mSec			
Min Limit	1	mSec			
krad(Si)	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000
Min	1.529	1.547	1.547	1.548	1.549
Average	1.540	1.547	1.548	1.548	1.560
Max	1.547	1.547	1.548	1.548	1.567
UL	1.600	1.600	1.600	1.600	1.600



HDR Report
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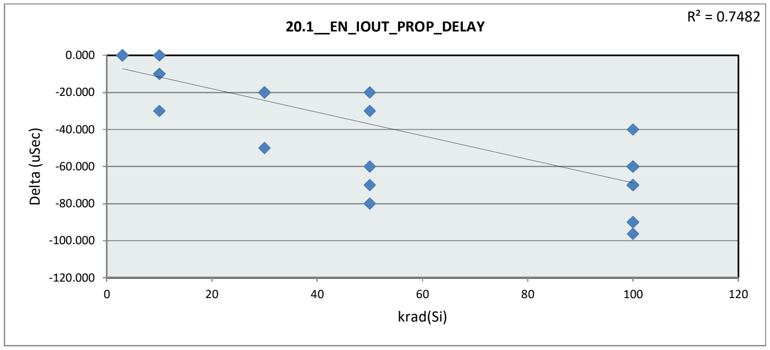
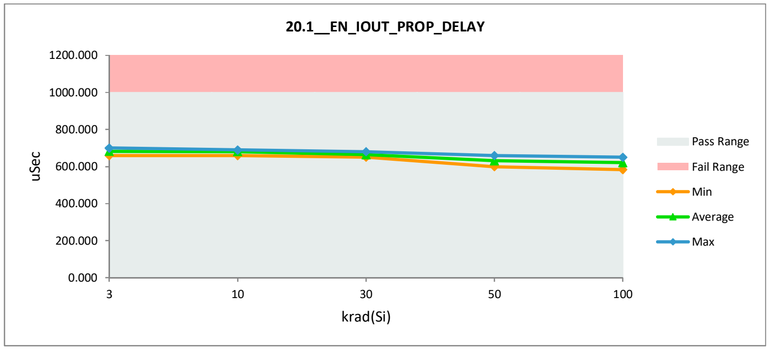
		20.1__EN_IOUT_PROP_DELAY		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uSec	uSec	
	Max Limit	1000	1000	
	Min Limit	1	1	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	660.000	660.000	0.000
3	HDR_W5_D12_Bias	660.000	660.000	0.000
3	HDR_W6_D13_Bias	700.000	700.000	0.000
3	HDR_W6_D21_Bias	700.000	700.000	0.000
3	HDR_W7_D5_Bias	690.000	690.000	0.000
10	HDR_W5_D9_Bias	660.000	660.000	0.000
10	HDR_W6_D4_Bias	700.000	690.000	-10.000
10	HDR_W6_D28_Bias	700.000	670.000	-30.000
10	HDR_W7_D27_Bias	700.000	690.000	-10.000
10	HDR_W7_D41_Bias	690.000	690.000	0.000
30	HDR_W5_D29_Bias	670.000	650.000	-20.000
30	HDR_W6_D27_Bias	700.000	650.000	-50.000
30	HDR_W6_D42_Bias	700.000	680.000	-20.000
30	HDR_W7_D31_Bias	690.000	670.000	-20.000
30	HDR_W7_D22_Bias	690.000	670.000	-20.000
50	HDR_W5_D37_Bias	660.000	600.000	-60.000
50	HDR_W5_D39_Bias	660.000	640.000	-20.000
50	HDR_W6_D14_Bias	710.000	630.000	-80.000
50	HDR_W7_D13_Bias	690.000	660.000	-30.000
50	HDR_W7_D37_Bias	700.000	630.000	-70.000
100	HDR_W5_D8_Bias	670.000	610.000	-60.000
100	HDR_W5_D13_Bias	660.000	600.000	-60.000
100	HDR_W5_D30_Bias	640.000	600.000	-40.000
100	HDR_W5_D32_Bias	660.000	600.000	-60.000
100	HDR_W5_D34_Bias	680.000	583.660	-96.340
100	HDR_W5_D38_Bias	670.000	610.000	-60.000
100	HDR_W5_D41_Bias	660.000	600.000	-60.000
100	HDR_W6_D1_Bias	700.000	640.000	-60.000
100	HDR_W6_D8_Bias	700.000	640.000	-60.000
100	HDR_W6_D18_Bias	700.000	640.000	-60.000
100	HDR_W6_D22_Bias	710.000	650.000	-60.000
100	HDR_W6_D24_Bias	700.000	640.000	-60.000
100	HDR_W6_D30_Bias	700.000	640.000	-60.000
100	HDR_W6_D32_Bias	700.000	610.000	-90.000
100	HDR_W6_D39_Bias	710.000	640.000	-70.000
100	HDR_W7_D4_Bias	700.000	630.000	-70.000
100	HDR_W7_D9_Bias	700.000	630.000	-70.000
100	HDR_W7_D17_Bias	690.000	600.000	-90.000
100	HDR_W7_D18_Bias	700.000	630.000	-70.000
100	HDR_W7_D25_Bias	700.000	610.000	-90.000
100	HDR_W7_D34_Bias	700.000	630.000	-70.000
100	HDR_W7_D35_Bias	690.000	630.000	-60.000
	Max	710.000	700.000	0.000
	Average	687.381	641.754	-45.627
	Min	640.000	583.660	-96.340
	Std Dev	18.354	31.369	29.977



	20.1__EN_IOUT_PROP_DELAY				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1000	uSec			
Min Limit	1	uSec			
krad(Si)	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000
Min	660.000	660.000	650.000	600.000	583.660
Average	682.000	680.000	664.000	632.000	621.075
Max	700.000	690.000	680.000	660.000	650.000
UL	1000.000	1000.000	1000.000	1000.000	1000.000



HDR Report
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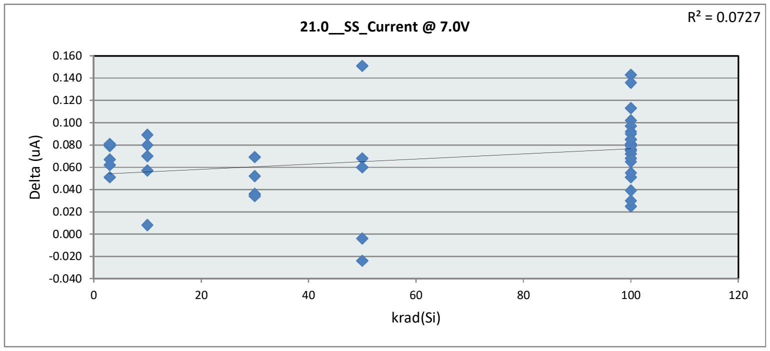
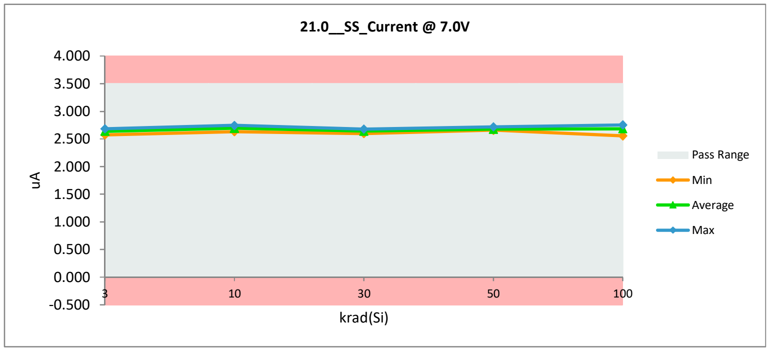
		21.0__SS_Current @ 7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	3.5	3.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	2.634	2.685	0.051
3	HDR_W5_D12_Bias	2.549	2.628	0.079
3	HDR_W6_D13_Bias	2.600	2.681	0.081
3	HDR_W6_D21_Bias	2.567	2.634	0.067
3	HDR_W7_D5_Bias	2.511	2.573	0.062
10	HDR_W5_D9_Bias	2.608	2.688	0.080
10	HDR_W6_D4_Bias	2.633	2.703	0.070
10	HDR_W6_D28_Bias	2.545	2.634	0.089
10	HDR_W7_D27_Bias	2.692	2.700	0.008
10	HDR_W7_D41_Bias	2.689	2.746	0.057
30	HDR_W5_D29_Bias	2.643	2.679	0.036
30	HDR_W6_D27_Bias	2.562	2.598	0.036
30	HDR_W6_D42_Bias	2.586	2.638	0.052
30	HDR_W7_D31_Bias	2.595	2.664	0.069
30	HDR_W7_D22_Bias	2.589	2.623	0.034
50	HDR_W5_D37_Bias	2.595	2.663	0.068
50	HDR_W5_D39_Bias	2.616	2.676	0.060
50	HDR_W6_D14_Bias	2.663	2.659	-0.004
50	HDR_W7_D13_Bias	2.568	2.719	0.151
50	HDR_W7_D37_Bias	2.682	2.658	-0.024
100	HDR_W5_D8_Bias	2.627	2.666	0.039
100	HDR_W5_D13_Bias	2.638	2.713	0.075
100	HDR_W5_D30_Bias	2.649	2.674	0.025
100	HDR_W5_D32_Bias	2.629	2.714	0.085
100	HDR_W5_D34_Bias	2.624	2.705	0.081
100	HDR_W5_D38_Bias	2.607	2.679	0.072
100	HDR_W5_D41_Bias	2.622	2.673	0.051
100	HDR_W6_D1_Bias	2.689	2.754	0.065
100	HDR_W6_D8_Bias	2.608	2.688	0.080
100	HDR_W6_D18_Bias	2.592	2.694	0.102
100	HDR_W6_D22_Bias	2.565	2.633	0.068
100	HDR_W6_D24_Bias	2.551	2.648	0.097
100	HDR_W6_D30_Bias	2.502	2.557	0.055
100	HDR_W6_D32_Bias	2.652	2.682	0.030
100	HDR_W6_D39_Bias	2.598	2.690	0.092
100	HDR_W7_D4_Bias	2.613	2.689	0.076
100	HDR_W7_D9_Bias	2.598	2.711	0.113
100	HDR_W7_D17_Bias	2.590	2.733	0.143
100	HDR_W7_D18_Bias	2.555	2.634	0.079
100	HDR_W7_D25_Bias	2.649	2.739	0.090
100	HDR_W7_D34_Bias	2.588	2.724	0.136
100	HDR_W7_D35_Bias	2.638	2.723	0.085
	Max	2.692	2.754	0.151
	Average	2.607	2.676	0.068
	Min	2.502	2.557	-0.024
	Std Dev	0.045	0.044	0.035

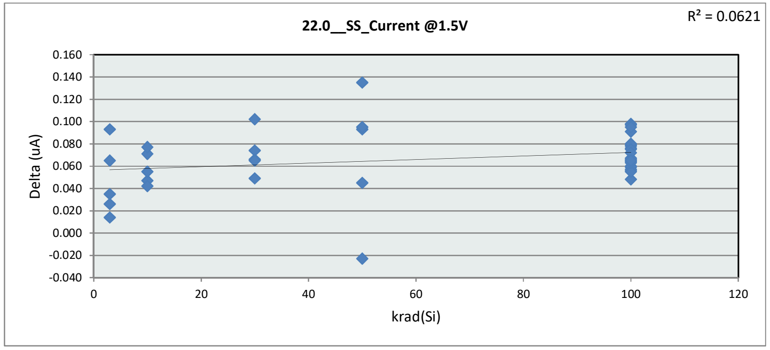


	21.0__SS_Current @ 7.0V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	3.5	uA			
Min Limit	-0.0001	uA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	2.573	2.634	2.598	2.658	2.557
Average	2.640	2.694	2.640	2.675	2.687
Max	2.685	2.746	2.679	2.719	2.754
UL	3.500	3.500	3.500	3.500	3.500

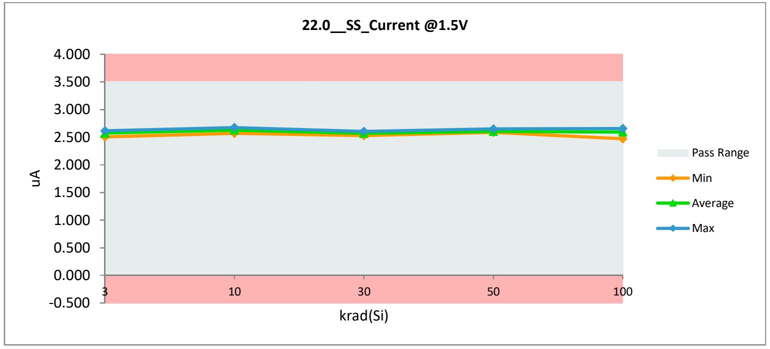


HDR Report
TPS7H1101-SP

		22.0__SS_Current @1.5V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	3.5	3.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	2.590	2.616	0.026
3	HDR_W5_D12_Bias	2.495	2.560	0.065
3	HDR_W6_D13_Bias	2.597	2.611	0.014
3	HDR_W6_D21_Bias	2.471	2.564	0.093
3	HDR_W7_D5_Bias	2.471	2.506	0.035
10	HDR_W5_D9_Bias	2.565	2.636	0.071
10	HDR_W6_D4_Bias	2.586	2.633	0.047
10	HDR_W6_D28_Bias	2.526	2.568	0.042
10	HDR_W6_D27_Bias	2.552	2.629	0.077
10	HDR_W7_D41_Bias	2.621	2.676	0.055
30	HDR_W5_D29_Bias	2.505	2.607	0.102
30	HDR_W6_D27_Bias	2.480	2.529	0.049
30	HDR_W6_D42_Bias	2.495	2.569	0.074
30	HDR_W7_D31_Bias	2.527	2.593	0.066
30	HDR_W7_D22_Bias	2.491	2.556	0.065
50	HDR_W5_D37_Bias	2.501	2.594	0.093
50	HDR_W5_D39_Bias	2.511	2.606	0.095
50	HDR_W6_D14_Bias	2.545	2.590	0.045
50	HDR_W7_D13_Bias	2.513	2.648	0.135
50	HDR_W7_D37_Bias	2.609	2.586	-0.023
100	HDR_W5_D8_Bias	2.506	2.582	0.076
100	HDR_W5_D13_Bias	2.566	2.632	0.066
100	HDR_W5_D30_Bias	2.513	2.591	0.078
100	HDR_W5_D32_Bias	2.531	2.587	0.056
100	HDR_W5_D34_Bias	2.575	2.632	0.057
100	HDR_W5_D38_Bias	2.531	2.590	0.059
100	HDR_W5_D41_Bias	2.528	2.593	0.065
100	HDR_W6_D1_Bias	2.577	2.656	0.079
100	HDR_W6_D8_Bias	2.525	2.605	0.080
100	HDR_W6_D18_Bias	2.557	2.617	0.060
100	HDR_W6_D22_Bias	2.507	2.555	0.048
100	HDR_W6_D24_Bias	2.482	2.557	0.075
100	HDR_W6_D30_Bias	2.418	2.473	0.055
100	HDR_W6_D32_Bias	2.508	2.599	0.091
100	HDR_W6_D39_Bias	2.529	2.593	0.064
100	HDR_W7_D4_Bias	2.540	2.607	0.067
100	HDR_W7_D9_Bias	2.522	2.594	0.072
100	HDR_W7_D17_Bias	2.524	2.622	0.098
100	HDR_W7_D18_Bias	2.467	2.530	0.063
100	HDR_W7_D25_Bias	2.541	2.638	0.097
100	HDR_W7_D34_Bias	2.535	2.600	0.065
100	HDR_W7_D35_Bias	2.534	2.629	0.095
	Max	2.621	2.676	0.135
	Average	2.528	2.594	0.066
	Min	2.418	2.473	-0.023
	Std Dev	0.041	0.040	0.026

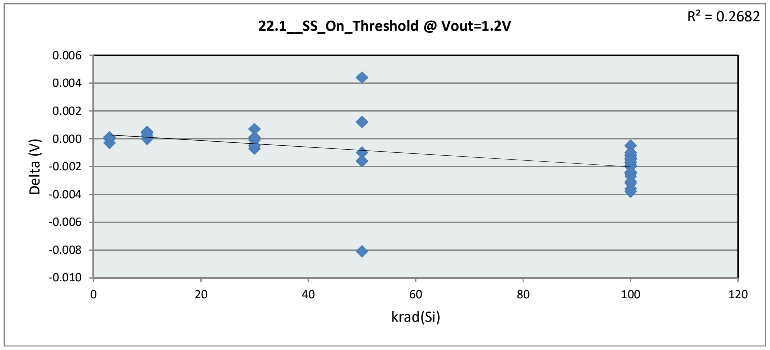


	22.0__SS_Current @1.5V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	3.5	uA			
Min Limit	-0.0001	uA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	2.506	2.568	2.529	2.586	2.473
Average	2.571	2.628	2.571	2.605	2.595
Max	2.616	2.676	2.607	2.648	2.656
UL	3.500	3.500	3.500	3.500	3.500

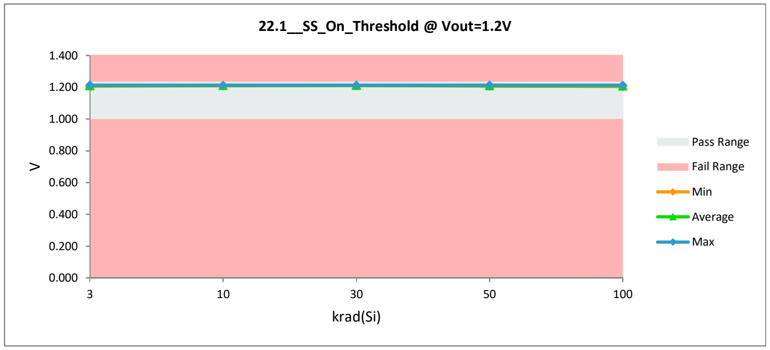


HDR Report
TPS7H1101-SP

		22.1__SS_On_Threshold @ Vout=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.232	1.232	
	Min Limit	1	1	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.207	1.206	0.000
3	HDR_W5_D12_Bias	1.211	1.211	0.000
3	HDR_W6_D13_Bias	1.213	1.213	0.000
3	HDR_W6_D21_Bias	1.211	1.211	0.000
3	HDR_W7_D5_Bias	1.208	1.208	0.000
10	HDR_W5_D9_Bias	1.209	1.209	0.000
10	HDR_W6_D4_Bias	1.212	1.212	0.000
10	HDR_W6_D28_Bias	1.212	1.213	0.000
10	HDR_W7_D27_Bias	1.212	1.213	0.000
10	HDR_W7_D41_Bias	1.210	1.210	0.000
30	HDR_W5_D29_Bias	1.213	1.212	-0.001
30	HDR_W6_D27_Bias	1.212	1.212	0.000
30	HDR_W6_D42_Bias	1.211	1.211	0.000
30	HDR_W7_D31_Bias	1.213	1.212	-0.001
30	HDR_W7_D22_Bias	1.210	1.211	0.001
50	HDR_W5_D37_Bias	1.210	1.209	-0.001
50	HDR_W5_D39_Bias	1.208	1.212	0.004
50	HDR_W6_D14_Bias	1.212	1.211	-0.002
50	HDR_W7_D13_Bias	1.212	1.214	0.001
50	HDR_W7_D37_Bias	1.214	1.206	-0.008
100	HDR_W5_D8_Bias	1.211	1.209	-0.002
100	HDR_W5_D13_Bias	1.211	1.209	-0.002
100	HDR_W5_D30_Bias	1.208	1.207	-0.001
100	HDR_W5_D32_Bias	1.206	1.205	-0.001
100	HDR_W5_D34_Bias	1.213	1.211	-0.002
100	HDR_W5_D38_Bias	1.208	1.206	-0.002
100	HDR_W5_D41_Bias	1.210	1.208	-0.002
100	HDR_W6_D1_Bias	1.213	1.209	-0.004
100	HDR_W6_D8_Bias	1.210	1.210	0.000
100	HDR_W6_D18_Bias	1.215	1.212	-0.003
100	HDR_W6_D22_Bias	1.211	1.210	-0.001
100	HDR_W6_D24_Bias	1.209	1.207	-0.002
100	HDR_W6_D30_Bias	1.212	1.209	-0.003
100	HDR_W6_D32_Bias	1.212	1.211	-0.001
100	HDR_W6_D39_Bias	1.211	1.208	-0.003
100	HDR_W7_D4_Bias	1.212	1.210	-0.002
100	HDR_W7_D9_Bias	1.212	1.210	-0.002
100	HDR_W7_D17_Bias	1.210	1.209	-0.001
100	HDR_W7_D18_Bias	1.209	1.205	-0.003
100	HDR_W7_D25_Bias	1.215	1.211	-0.004
100	HDR_W7_D34_Bias	1.209	1.208	-0.001
100	HDR_W7_D35_Bias	1.209	1.208	-0.002
	Max	1.215	1.214	0.004
	Average	1.211	1.210	-0.001
	Min	1.206	1.205	-0.008
	Std Dev	0.002	0.002	0.002

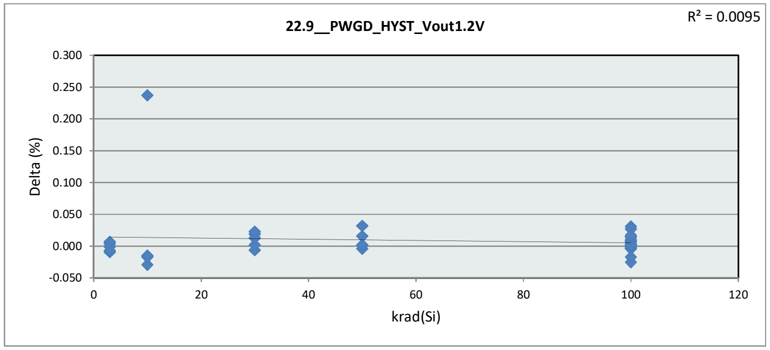


	22.1__SS_On_Threshold @ Vou				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.232	V			
Min Limit	1	V			
krad(Si)	3	10	30	50	100
LL	1.000	1.000	1.000	1.000	1.000
Min	1.206	1.209	1.211	1.206	1.205
Average	1.210	1.211	1.212	1.210	1.209
Max	1.213	1.213	1.212	1.214	1.212
UL	1.232	1.232	1.232	1.232	1.232

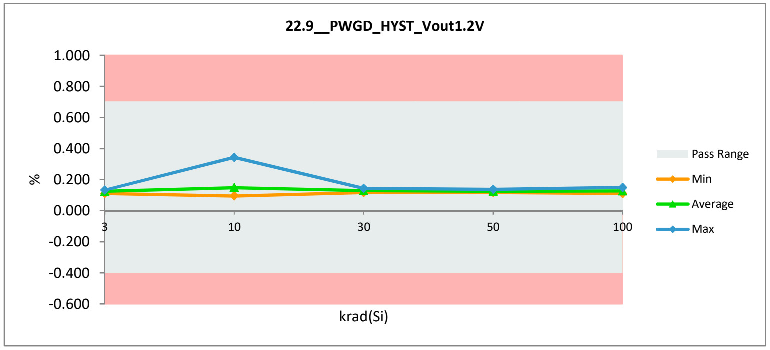


HDR Report
TPS7H1101-SP

		22.9__PWGD_HYST_Vout1.2V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%	%	
	Max Limit	0.7	0.7	
	Min Limit	-0.4	-0.4	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.119	0.123	0.004
3	HDR_W5_D12_Bias	0.132	0.131	-0.001
3	HDR_W6_D13_Bias	0.119	0.110	-0.009
3	HDR_W6_D21_Bias	0.139	0.132	-0.007
3	HDR_W7_D5_Bias	0.119	0.126	0.007
10	HDR_W5_D9_Bias	0.129	0.100	-0.029
10	HDR_W6_D4_Bias	0.115	0.099	-0.016
10	HDR_W6_D28_Bias	0.106	0.343	0.237
10	HDR_W7_D27_Bias	0.112	0.095	-0.017
10	HDR_W7_D41_Bias	0.120	0.105	-0.015
30	HDR_W5_D29_Bias	0.122	0.116	-0.006
30	HDR_W6_D27_Bias	0.125	0.144	0.019
30	HDR_W6_D42_Bias	0.123	0.125	0.002
30	HDR_W7_D31_Bias	0.106	0.119	0.013
30	HDR_W7_D22_Bias	0.117	0.140	0.023
50	HDR_W5_D37_Bias	0.116	0.117	0.001
50	HDR_W5_D39_Bias	0.120	0.116	-0.004
50	HDR_W6_D14_Bias	0.122	0.124	0.002
50	HDR_W7_D13_Bias	0.115	0.131	0.016
50	HDR_W7_D37_Bias	0.106	0.138	0.032
100	HDR_W5_D8_Bias	0.116	0.118	0.002
100	HDR_W5_D13_Bias	0.110	0.114	0.004
100	HDR_W5_D30_Bias	0.118	0.127	0.009
100	HDR_W5_D32_Bias	0.132	0.133	0.001
100	HDR_W5_D34_Bias	0.129	0.136	0.007
100	HDR_W5_D38_Bias	0.117	0.113	-0.004
100	HDR_W5_D41_Bias	0.099	0.130	0.031
100	HDR_W6_D1_Bias	0.135	0.149	0.014
100	HDR_W6_D8_Bias	0.124	0.120	-0.004
100	HDR_W6_D18_Bias	0.130	0.138	0.008
100	HDR_W6_D22_Bias	0.123	0.121	-0.002
100	HDR_W6_D24_Bias	0.139	0.136	-0.003
100	HDR_W6_D30_Bias	0.127	0.137	0.010
100	HDR_W6_D32_Bias	0.125	0.125	0.000
100	HDR_W6_D39_Bias	0.137	0.139	0.002
100	HDR_W7_D4_Bias	0.103	0.118	0.015
100	HDR_W7_D9_Bias	0.112	0.122	0.010
100	HDR_W7_D17_Bias	0.115	0.129	0.014
100	HDR_W7_D18_Bias	0.094	0.121	0.027
100	HDR_W7_D25_Bias	0.116	0.133	0.017
100	HDR_W7_D34_Bias	0.149	0.124	-0.025
100	HDR_W7_D35_Bias	0.127	0.110	-0.017
	Max	0.149	0.343	0.237
	Average	0.120	0.129	0.009
	Min	0.094	0.095	-0.029
	Std Dev	0.011	0.036	0.039

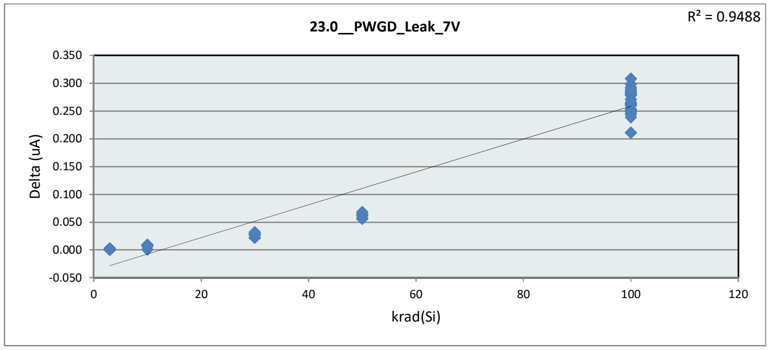


	22.9__PWGD_HYST_Vout1.2V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.7	%			
Min Limit	-0.4	%			
krad(Si)	3	10	30	50	100
LL	-0.400	-0.400	-0.400	-0.400	-0.400
Min	0.110	0.095	0.116	0.116	0.110
Average	0.124	0.148	0.129	0.125	0.127
Max	0.132	0.343	0.144	0.138	0.149
UL	0.700	0.700	0.700	0.700	0.700

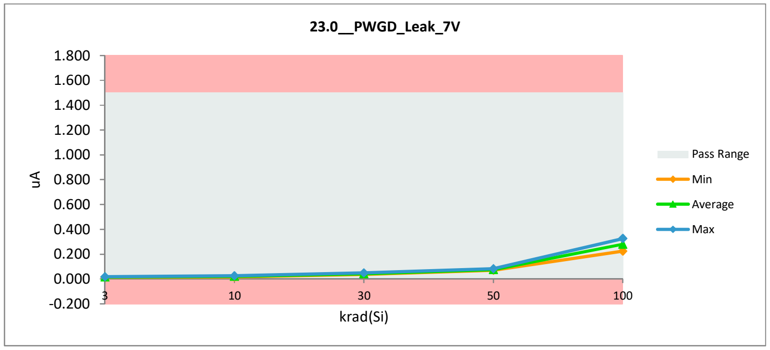


HDR Report
TPS7H1101-SP

		23.0__PWGD_Leak_7V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1.5	1.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.014	0.014	0.000
3	HDR_W5_D12_Bias	0.014	0.015	0.001
3	HDR_W6_D13_Bias	0.016	0.018	0.002
3	HDR_W6_D21_Bias	0.015	0.018	0.003
3	HDR_W7_D5_Bias	0.015	0.016	0.001
10	HDR_W5_D9_Bias	0.015	0.016	0.001
10	HDR_W6_D4_Bias	0.016	0.025	0.009
10	HDR_W6_D28_Bias	0.015	0.022	0.007
10	HDR_W7_D27_Bias	0.014	0.023	0.009
10	HDR_W7_D41_Bias	0.014	0.021	0.007
30	HDR_W5_D29_Bias	0.015	0.037	0.022
30	HDR_W6_D27_Bias	0.016	0.043	0.027
30	HDR_W6_D42_Bias	0.015	0.044	0.029
30	HDR_W7_D31_Bias	0.015	0.043	0.028
30	HDR_W7_D22_Bias	0.016	0.048	0.032
50	HDR_W5_D37_Bias	0.015	0.072	0.057
50	HDR_W5_D39_Bias	0.014	0.076	0.062
50	HDR_W6_D14_Bias	0.016	0.080	0.064
50	HDR_W7_D13_Bias	0.014	0.082	0.068
50	HDR_W7_D37_Bias	0.014	0.070	0.056
100	HDR_W5_D8_Bias	0.013	0.274	0.261
100	HDR_W5_D13_Bias	0.014	0.225	0.211
100	HDR_W5_D30_Bias	0.014	0.265	0.251
100	HDR_W5_D32_Bias	0.014	0.258	0.244
100	HDR_W5_D34_Bias	0.013	0.262	0.249
100	HDR_W5_D38_Bias	0.015	0.268	0.253
100	HDR_W5_D41_Bias	0.013	0.258	0.245
100	HDR_W6_D1_Bias	0.015	0.293	0.278
100	HDR_W6_D8_Bias	0.017	0.280	0.263
100	HDR_W6_D18_Bias	0.015	0.265	0.250
100	HDR_W6_D22_Bias	0.016	0.278	0.262
100	HDR_W6_D24_Bias	0.016	0.296	0.280
100	HDR_W6_D30_Bias	0.017	0.288	0.271
100	HDR_W6_D32_Bias	0.015	0.300	0.285
100	HDR_W6_D39_Bias	0.015	0.298	0.283
100	HDR_W7_D4_Bias	0.015	0.254	0.239
100	HDR_W7_D9_Bias	0.015	0.275	0.260
100	HDR_W7_D17_Bias	0.018	0.326	0.308
100	HDR_W7_D18_Bias	0.016	0.308	0.292
100	HDR_W7_D25_Bias	0.016	0.314	0.298
100	HDR_W7_D34_Bias	0.014	0.302	0.288
100	HDR_W7_D35_Bias	0.015	0.280	0.265
	Max	0.018	0.326	0.308
	Average	0.015	0.165	0.150
	Min	0.013	0.014	0.000
	Std Dev	0.001	0.124	0.124

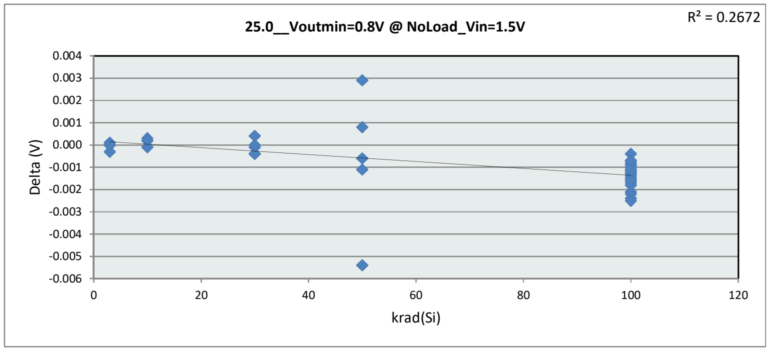


	23.0__PWGD_Leak_7V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.5	uA			
Min Limit	-0.0001	uA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	0.014	0.016	0.037	0.070	0.225
Average	0.016	0.021	0.043	0.076	0.280
Max	0.018	0.025	0.048	0.082	0.326
UL	1.500	1.500	1.500	1.500	1.500

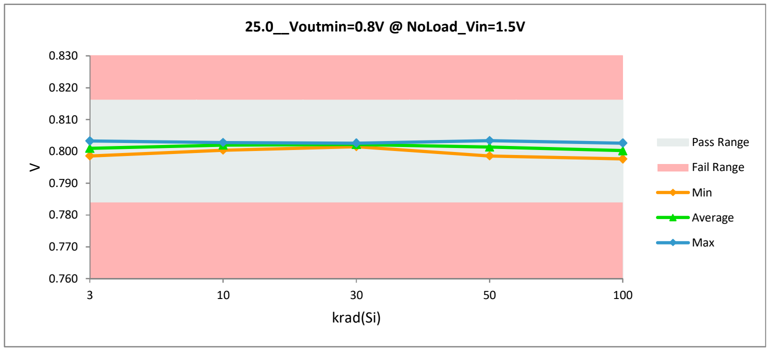


HDR Report
TPS7H1101-SP

		25.0__Voutmin=0.8V @ NoLoad_		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.799	0.799	0.000
3	HDR_W5_D12_Bias	0.801	0.802	0.000
3	HDR_W6_D13_Bias	0.803	0.803	0.000
3	HDR_W6_D21_Bias	0.802	0.802	0.000
3	HDR_W7_D5_Bias	0.800	0.800	0.000
10	HDR_W5_D9_Bias	0.800	0.800	0.000
10	HDR_W6_D4_Bias	0.802	0.803	0.000
10	HDR_W6_D28_Bias	0.803	0.803	0.000
10	HDR_W7_D27_Bias	0.803	0.803	0.000
10	HDR_W7_D41_Bias	0.801	0.801	0.000
30	HDR_W5_D29_Bias	0.803	0.803	0.000
30	HDR_W6_D27_Bias	0.802	0.802	0.000
30	HDR_W6_D42_Bias	0.802	0.802	0.000
30	HDR_W7_D31_Bias	0.803	0.803	0.000
30	HDR_W7_D22_Bias	0.801	0.802	0.000
50	HDR_W5_D37_Bias	0.801	0.800	-0.001
50	HDR_W5_D39_Bias	0.800	0.803	0.003
50	HDR_W6_D14_Bias	0.803	0.802	-0.001
50	HDR_W7_D13_Bias	0.803	0.803	0.001
50	HDR_W7_D37_Bias	0.804	0.799	-0.005
100	HDR_W5_D8_Bias	0.802	0.801	-0.001
100	HDR_W5_D13_Bias	0.802	0.800	-0.001
100	HDR_W5_D30_Bias	0.800	0.799	-0.001
100	HDR_W5_D32_Bias	0.799	0.798	-0.001
100	HDR_W5_D34_Bias	0.803	0.802	-0.001
100	HDR_W5_D38_Bias	0.800	0.799	-0.001
100	HDR_W5_D41_Bias	0.801	0.799	-0.001
100	HDR_W6_D1_Bias	0.803	0.800	-0.002
100	HDR_W6_D8_Bias	0.801	0.801	0.000
100	HDR_W6_D18_Bias	0.804	0.803	-0.002
100	HDR_W6_D22_Bias	0.802	0.801	-0.001
100	HDR_W6_D24_Bias	0.801	0.799	-0.002
100	HDR_W6_D30_Bias	0.803	0.800	-0.002
100	HDR_W6_D32_Bias	0.803	0.802	-0.001
100	HDR_W6_D39_Bias	0.801	0.800	-0.002
100	HDR_W7_D4_Bias	0.803	0.801	-0.002
100	HDR_W7_D9_Bias	0.802	0.801	-0.002
100	HDR_W7_D17_Bias	0.801	0.800	-0.001
100	HDR_W7_D18_Bias	0.800	0.798	-0.002
100	HDR_W7_D25_Bias	0.804	0.802	-0.002
100	HDR_W7_D34_Bias	0.801	0.800	-0.001
100	HDR_W7_D35_Bias	0.800	0.799	-0.001
	Max	0.804	0.803	0.003
	Average	0.802	0.801	-0.001
	Min	0.799	0.798	-0.005
	Std Dev	0.001	0.002	0.001



	25.0__Voutmin=0.8V @ NoLoad				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.816	V			
Min Limit	0.784	V			
krad(Si)	3	10	30	50	100
LL	0.784	0.784	0.784	0.784	0.784
Min	0.799	0.800	0.802	0.799	0.798
Average	0.801	0.802	0.802	0.801	0.800
Max	0.803	0.803	0.803	0.803	0.803
UL	0.816	0.816	0.816	0.816	0.816



HDR Report
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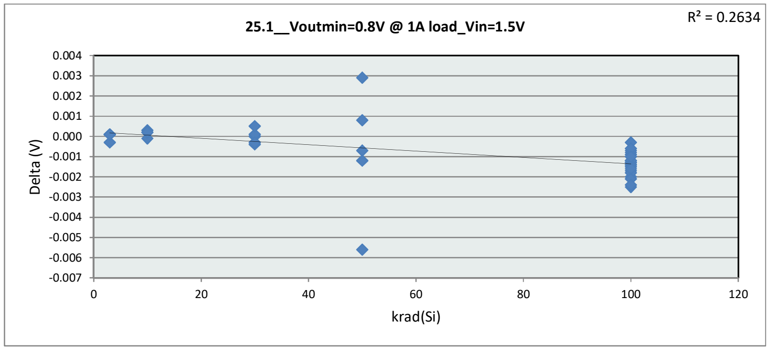
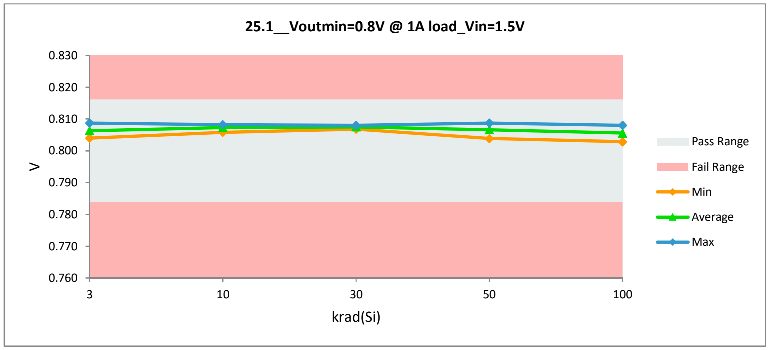
		25.1__Voutmin=0.8V @ 1A load_		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		0.816	0.816	
Min Limit		0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	0.804	0.804	0.000
3	HDR_W5_D12_Bias	0.807	0.807	0.000
3	HDR_W6_D13_Bias	0.809	0.809	0.000
3	HDR_W6_D21_Bias	0.807	0.807	0.000
3	HDR_W7_D5_Bias	0.805	0.805	0.000
10	HDR_W5_D9_Bias	0.806	0.806	0.000
10	HDR_W6_D4_Bias	0.808	0.808	0.000
10	HDR_W6_D28_Bias	0.808	0.808	0.000
10	HDR_W7_D27_Bias	0.808	0.808	0.000
10	HDR_W7_D41_Bias	0.806	0.807	0.000
30	HDR_W5_D29_Bias	0.808	0.808	0.000
30	HDR_W6_D27_Bias	0.808	0.808	0.000
30	HDR_W6_D42_Bias	0.807	0.807	0.000
30	HDR_W7_D31_Bias	0.808	0.808	0.000
30	HDR_W7_D22_Bias	0.806	0.807	0.001
50	HDR_W5_D37_Bias	0.806	0.806	-0.001
50	HDR_W5_D39_Bias	0.805	0.808	0.003
50	HDR_W6_D14_Bias	0.808	0.807	-0.001
50	HDR_W7_D13_Bias	0.808	0.809	0.001
50	HDR_W7_D37_Bias	0.809	0.804	-0.006
100	HDR_W5_D8_Bias	0.807	0.806	-0.001
100	HDR_W5_D13_Bias	0.807	0.806	-0.001
100	HDR_W5_D30_Bias	0.805	0.804	-0.001
100	HDR_W5_D32_Bias	0.804	0.803	-0.001
100	HDR_W5_D34_Bias	0.808	0.807	-0.001
100	HDR_W5_D38_Bias	0.805	0.804	-0.001
100	HDR_W5_D41_Bias	0.806	0.805	-0.001
100	HDR_W6_D1_Bias	0.808	0.806	-0.002
100	HDR_W6_D8_Bias	0.807	0.806	0.000
100	HDR_W6_D18_Bias	0.810	0.808	-0.002
100	HDR_W6_D22_Bias	0.807	0.806	-0.001
100	HDR_W6_D24_Bias	0.806	0.805	-0.001
100	HDR_W6_D30_Bias	0.808	0.806	-0.002
100	HDR_W6_D32_Bias	0.808	0.807	-0.001
100	HDR_W6_D39_Bias	0.807	0.805	-0.002
100	HDR_W7_D4_Bias	0.808	0.806	-0.002
100	HDR_W7_D9_Bias	0.808	0.806	-0.002
100	HDR_W7_D17_Bias	0.806	0.806	-0.001
100	HDR_W7_D18_Bias	0.805	0.803	-0.002
100	HDR_W7_D25_Bias	0.810	0.807	-0.002
100	HDR_W7_D34_Bias	0.806	0.805	-0.001
100	HDR_W7_D35_Bias	0.806	0.805	-0.001
	Max	0.810	0.809	0.003
	Average	0.807	0.806	-0.001
	Min	0.804	0.803	-0.006
	Std Dev	0.001	0.002	0.001



	25.1__Voutmin=0.8V @ 1A loa				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	0.816	V			
Min Limit	0.784	V			
krad(Si)	3	10	30	50	100
LL	0.784	0.784	0.784	0.784	0.784
Min	0.804	0.806	0.807	0.804	0.803
Average	0.806	0.807	0.808	0.807	0.806
Max	0.809	0.808	0.808	0.809	0.808
UL	0.816	0.816	0.816	0.816	0.816



HDR Report
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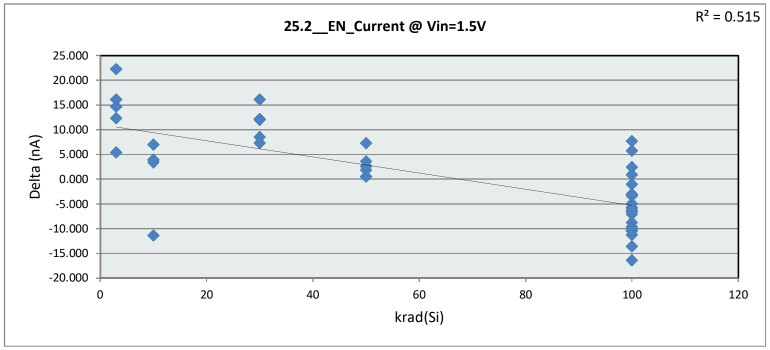
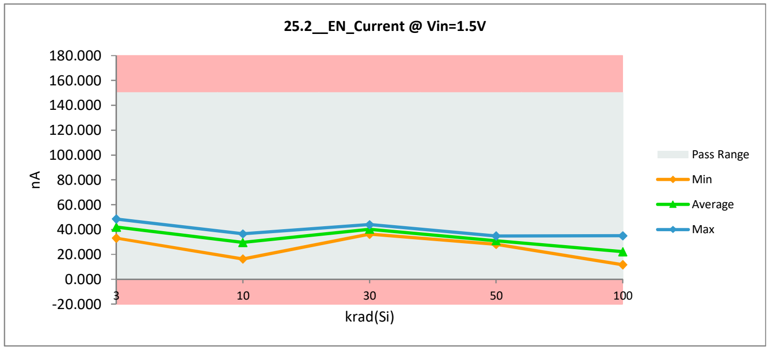
		25.2__EN_Current @ Vin=1.5V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	27.678	33.081	5.403
3	HDR_W5_D12_Bias	26.264	48.525	22.261
3	HDR_W6_D13_Bias	27.756	40.087	12.331
3	HDR_W6_D21_Bias	27.010	41.715	14.705
3	HDR_W7_D5_Bias	30.333	46.449	16.116
10	HDR_W5_D9_Bias	27.717	16.342	-11.375
10	HDR_W6_D4_Bias	29.532	36.525	6.993
10	HDR_W6_D28_Bias	27.733	31.642	3.909
10	HDR_W7_D27_Bias	27.364	30.777	3.413
10	HDR_W7_D41_Bias	28.440	32.373	3.933
30	HDR_W5_D29_Bias	27.804	43.948	16.144
30	HDR_W6_D27_Bias	28.958	36.273	7.315
30	HDR_W6_D42_Bias	30.309	42.493	12.184
30	HDR_W7_D31_Bias	29.092	37.594	8.502
30	HDR_W7_D22_Bias	28.778	40.779	12.001
50	HDR_W5_D37_Bias	28.000	31.571	3.571
50	HDR_W5_D39_Bias	26.201	28.056	1.855
50	HDR_W6_D14_Bias	28.346	30.950	2.604
50	HDR_W7_D13_Bias	28.833	29.338	0.505
50	HDR_W7_D37_Bias	27.536	34.795	7.259
100	HDR_W5_D8_Bias	30.231	18.981	-11.250
100	HDR_W5_D13_Bias	26.892	32.664	5.772
100	HDR_W5_D30_Bias	28.047	11.629	-16.418
100	HDR_W5_D32_Bias	28.298	14.743	-13.555
100	HDR_W5_D34_Bias	26.138	17.393	-8.745
100	HDR_W5_D38_Bias	28.605	29.526	0.921
100	HDR_W5_D41_Bias	28.982	27.954	-1.028
100	HDR_W6_D1_Bias	25.675	18.604	-7.071
100	HDR_W6_D8_Bias	26.994	16.481	-10.513
100	HDR_W6_D18_Bias	27.701	22.732	-4.969
100	HDR_W6_D22_Bias	26.020	19.988	-6.032
100	HDR_W6_D24_Bias	27.725	30.155	2.430
100	HDR_W6_D30_Bias	27.348	17.723	-9.625
100	HDR_W6_D32_Bias	27.144	20.570	-6.574
100	HDR_W6_D39_Bias	25.800	22.599	-3.201
100	HDR_W7_D4_Bias	29.414	26.397	-3.017
100	HDR_W7_D9_Bias	28.141	21.694	-6.447
100	HDR_W7_D17_Bias	27.269	34.992	7.723
100	HDR_W7_D18_Bias	26.963	23.597	-3.366
100	HDR_W7_D25_Bias	27.741	17.755	-9.986
100	HDR_W7_D34_Bias	28.306	17.943	-10.363
100	HDR_W7_D35_Bias	28.723	22.968	-5.755
	Max	30.333	48.525	22.261
	Average	27.901	28.581	0.680
	Min	25.675	11.629	-16.418
	Std Dev	1.174	9.532	9.287



	25.2__EN_Current @ Vin=1.5V				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	150	nA			
Min Limit	-0.0001	nA			
krad(Si)	3	10	30	50	100
LL	0.000	0.000	0.000	0.000	0.000
Min	33.081	16.342	36.273	28.056	11.629
Average	41.971	29.532	40.217	30.942	22.140
Max	48.525	36.525	43.948	34.795	34.992
UL	150.000	150.000	150.000	150.000	150.000



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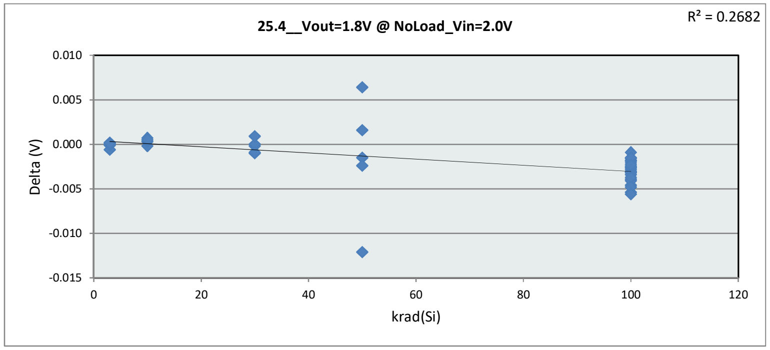
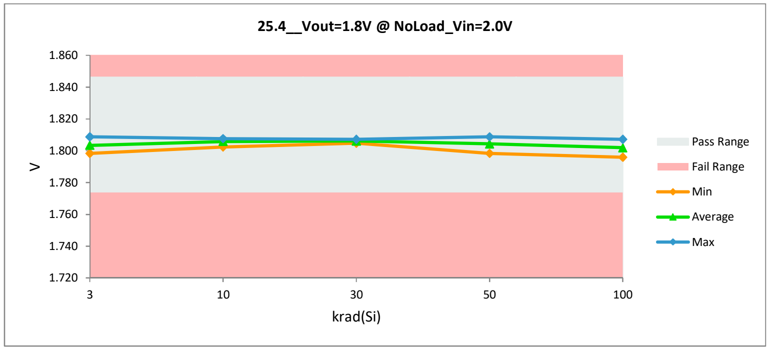
		25.4__Vout=1.8V @ NoLoad_Vin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.799	1.798	-0.001
3	HDR_W5_D12_Bias	1.804	1.805	0.000
3	HDR_W6_D13_Bias	1.809	1.809	0.000
3	HDR_W6_D21_Bias	1.805	1.805	0.000
3	HDR_W7_D5_Bias	1.800	1.801	0.000
10	HDR_W5_D9_Bias	1.803	1.802	0.000
10	HDR_W6_D4_Bias	1.807	1.807	0.000
10	HDR_W6_D28_Bias	1.807	1.808	0.001
10	HDR_W7_D27_Bias	1.807	1.808	0.000
10	HDR_W7_D41_Bias	1.804	1.804	0.001
30	HDR_W5_D29_Bias	1.808	1.807	-0.001
30	HDR_W6_D27_Bias	1.807	1.806	0.000
30	HDR_W6_D42_Bias	1.805	1.805	0.000
30	HDR_W7_D31_Bias	1.808	1.807	-0.001
30	HDR_W7_D22_Bias	1.804	1.805	0.001
50	HDR_W5_D37_Bias	1.804	1.802	-0.002
50	HDR_W5_D39_Bias	1.801	1.807	0.006
50	HDR_W6_D14_Bias	1.807	1.805	-0.002
50	HDR_W7_D13_Bias	1.807	1.809	0.002
50	HDR_W7_D37_Bias	1.810	1.798	-0.012
100	HDR_W5_D8_Bias	1.806	1.803	-0.003
100	HDR_W5_D13_Bias	1.805	1.803	-0.002
100	HDR_W5_D30_Bias	1.801	1.799	-0.002
100	HDR_W5_D32_Bias	1.798	1.796	-0.002
100	HDR_W5_D34_Bias	1.808	1.805	-0.003
100	HDR_W5_D38_Bias	1.801	1.798	-0.003
100	HDR_W5_D41_Bias	1.803	1.800	-0.003
100	HDR_W6_D1_Bias	1.808	1.802	-0.005
100	HDR_W6_D8_Bias	1.804	1.804	-0.001
100	HDR_W6_D18_Bias	1.811	1.807	-0.004
100	HDR_W6_D22_Bias	1.806	1.804	-0.002
100	HDR_W6_D24_Bias	1.803	1.800	-0.003
100	HDR_W6_D30_Bias	1.807	1.803	-0.005
100	HDR_W6_D32_Bias	1.807	1.805	-0.002
100	HDR_W6_D39_Bias	1.804	1.800	-0.004
100	HDR_W7_D4_Bias	1.807	1.804	-0.003
100	HDR_W7_D9_Bias	1.807	1.803	-0.004
100	HDR_W7_D17_Bias	1.804	1.802	-0.002
100	HDR_W7_D18_Bias	1.801	1.797	-0.005
100	HDR_W7_D25_Bias	1.811	1.806	-0.006
100	HDR_W7_D34_Bias	1.803	1.801	-0.002
100	HDR_W7_D35_Bias	1.802	1.800	-0.002
	Max	1.811	1.809	0.006
	Average	1.805	1.803	-0.002
	Min	1.798	1.796	-0.012
	Std Dev	0.003	0.003	0.003



	25.4__Vout=1.8V @ NoLoad_Vi				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.8462 V				
Min Limit	1.7738 V				
krad(Si)	3	10	30	50	100
LL	1.774	1.774	1.774	1.774	1.774
Min	1.798	1.802	1.805	1.798	1.796
Average	1.803	1.806	1.806	1.804	1.802
Max	1.809	1.808	1.807	1.809	1.807
UL	1.846	1.846	1.846	1.846	1.846



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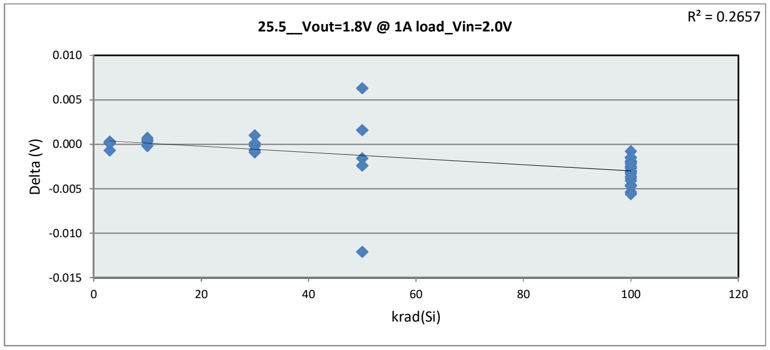
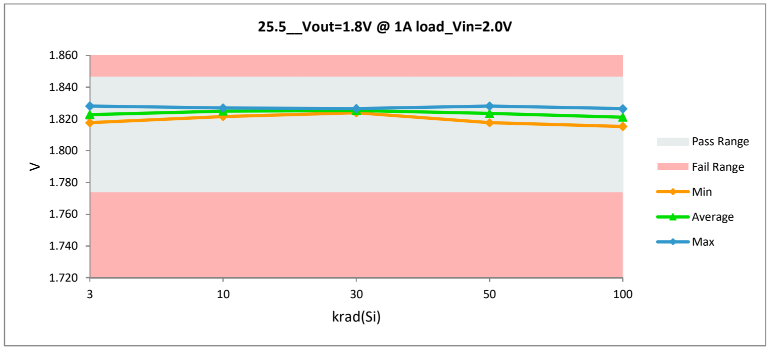
		25.5__Vout=1.8V @ 1A load_Vin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.818	1.817	-0.001
3	HDR_W5_D12_Bias	1.824	1.824	0.000
3	HDR_W6_D13_Bias	1.828	1.828	0.000
3	HDR_W6_D21_Bias	1.824	1.824	0.000
3	HDR_W7_D5_Bias	1.819	1.820	0.000
10	HDR_W5_D9_Bias	1.822	1.821	0.000
10	HDR_W6_D4_Bias	1.826	1.826	0.001
10	HDR_W6_D28_Bias	1.826	1.827	0.001
10	HDR_W7_D27_Bias	1.827	1.827	0.000
10	HDR_W7_D41_Bias	1.823	1.823	0.000
30	HDR_W5_D29_Bias	1.827	1.826	-0.001
30	HDR_W6_D27_Bias	1.826	1.826	0.000
30	HDR_W6_D42_Bias	1.824	1.824	0.000
30	HDR_W7_D31_Bias	1.827	1.827	-0.001
30	HDR_W7_D22_Bias	1.823	1.824	0.001
50	HDR_W5_D37_Bias	1.823	1.821	-0.002
50	HDR_W5_D39_Bias	1.820	1.826	0.006
50	HDR_W6_D14_Bias	1.827	1.824	-0.002
50	HDR_W7_D13_Bias	1.826	1.828	0.002
50	HDR_W7_D37_Bias	1.830	1.817	-0.012
100	HDR_W5_D8_Bias	1.825	1.822	-0.003
100	HDR_W5_D13_Bias	1.824	1.822	-0.002
100	HDR_W5_D30_Bias	1.820	1.818	-0.002
100	HDR_W5_D32_Bias	1.817	1.815	-0.002
100	HDR_W5_D34_Bias	1.827	1.825	-0.003
100	HDR_W5_D38_Bias	1.820	1.817	-0.003
100	HDR_W5_D41_Bias	1.823	1.820	-0.003
100	HDR_W6_D1_Bias	1.827	1.821	-0.005
100	HDR_W6_D8_Bias	1.824	1.823	-0.001
100	HDR_W6_D18_Bias	1.830	1.826	-0.004
100	HDR_W6_D22_Bias	1.825	1.823	-0.002
100	HDR_W6_D24_Bias	1.822	1.819	-0.003
100	HDR_W6_D30_Bias	1.826	1.822	-0.005
100	HDR_W6_D32_Bias	1.826	1.825	-0.002
100	HDR_W6_D39_Bias	1.824	1.820	-0.004
100	HDR_W7_D4_Bias	1.826	1.823	-0.003
100	HDR_W7_D9_Bias	1.826	1.822	-0.004
100	HDR_W7_D17_Bias	1.823	1.821	-0.002
100	HDR_W7_D18_Bias	1.821	1.816	-0.005
100	HDR_W7_D25_Bias	1.831	1.825	-0.006
100	HDR_W7_D34_Bias	1.822	1.820	-0.002
100	HDR_W7_D35_Bias	1.821	1.819	-0.002
	Max	1.831	1.828	0.006
	Average	1.824	1.823	-0.002
	Min	1.817	1.815	-0.012
	Std Dev	0.003	0.003	0.003



	25.5__Vout=1.8V @ 1A load_Vi				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.8462	V			
Min Limit	1.7738	V			
krad(Si)	3	10	30	50	100
LL	1.774	1.774	1.774	1.774	1.774
Min	1.818	1.822	1.824	1.818	1.815
Average	1.823	1.825	1.825	1.823	1.821
Max	1.828	1.827	1.827	1.828	1.826
UL	1.846	1.846	1.846	1.846	1.846



HDR Report
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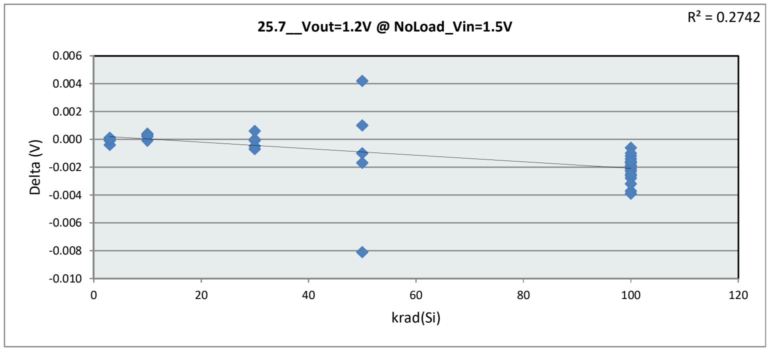
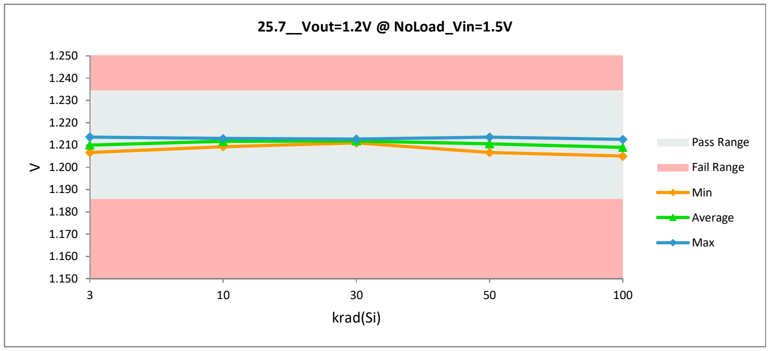
		25.7__Vout=1.2V @ NoLoad_Vin=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.207	1.207	0.000
3	HDR_W5_D12_Bias	1.211	1.211	0.000
3	HDR_W6_D13_Bias	1.214	1.214	0.000
3	HDR_W6_D21_Bias	1.211	1.211	0.000
3	HDR_W7_D5_Bias	1.208	1.208	0.000
10	HDR_W5_D9_Bias	1.209	1.209	0.000
10	HDR_W6_D4_Bias	1.212	1.212	0.000
10	HDR_W6_D28_Bias	1.212	1.213	0.000
10	HDR_W7_D27_Bias	1.213	1.213	0.000
10	HDR_W7_D41_Bias	1.210	1.211	0.000
30	HDR_W5_D29_Bias	1.213	1.212	-0.001
30	HDR_W6_D27_Bias	1.212	1.212	0.000
30	HDR_W6_D42_Bias	1.211	1.211	0.000
30	HDR_W7_D31_Bias	1.213	1.213	0.000
30	HDR_W7_D22_Bias	1.210	1.211	0.001
50	HDR_W5_D37_Bias	1.210	1.209	-0.001
50	HDR_W5_D39_Bias	1.208	1.212	0.004
50	HDR_W6_D14_Bias	1.213	1.211	-0.002
50	HDR_W7_D13_Bias	1.213	1.214	0.001
50	HDR_W7_D37_Bias	1.215	1.207	-0.008
100	HDR_W5_D8_Bias	1.212	1.210	-0.002
100	HDR_W5_D13_Bias	1.211	1.209	-0.002
100	HDR_W5_D30_Bias	1.209	1.207	-0.001
100	HDR_W5_D32_Bias	1.207	1.205	-0.002
100	HDR_W5_D34_Bias	1.213	1.211	-0.002
100	HDR_W5_D38_Bias	1.208	1.207	-0.002
100	HDR_W5_D41_Bias	1.210	1.208	-0.002
100	HDR_W6_D1_Bias	1.213	1.209	-0.004
100	HDR_W6_D8_Bias	1.211	1.210	-0.001
100	HDR_W6_D18_Bias	1.215	1.212	-0.003
100	HDR_W6_D22_Bias	1.212	1.210	-0.001
100	HDR_W6_D24_Bias	1.210	1.208	-0.002
100	HDR_W6_D30_Bias	1.213	1.209	-0.003
100	HDR_W6_D32_Bias	1.212	1.211	-0.001
100	HDR_W6_D39_Bias	1.211	1.208	-0.003
100	HDR_W7_D4_Bias	1.212	1.210	-0.002
100	HDR_W7_D9_Bias	1.212	1.210	-0.002
100	HDR_W7_D17_Bias	1.210	1.209	-0.001
100	HDR_W7_D18_Bias	1.209	1.206	-0.003
100	HDR_W7_D25_Bias	1.215	1.212	-0.004
100	HDR_W7_D34_Bias	1.209	1.209	-0.001
100	HDR_W7_D35_Bias	1.209	1.208	-0.002
	Max	1.215	1.214	0.004
	Average	1.211	1.210	-0.001
	Min	1.207	1.205	-0.008
	Std Dev	0.002	0.002	0.002

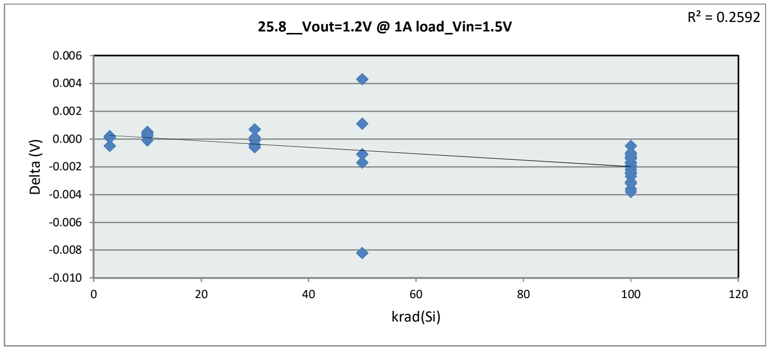


	25.7__Vout=1.2V @ NoLoad_Vi				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.2342	V			
Min Limit	1.1858	V			
krad(Si)	3	10	30	50	100
LL	1.186	1.186	1.186	1.186	1.186
Min	1.207	1.209	1.211	1.207	1.205
Average	1.210	1.212	1.212	1.211	1.209
Max	1.214	1.213	1.213	1.214	1.213
UL	1.234	1.234	1.234	1.234	1.234

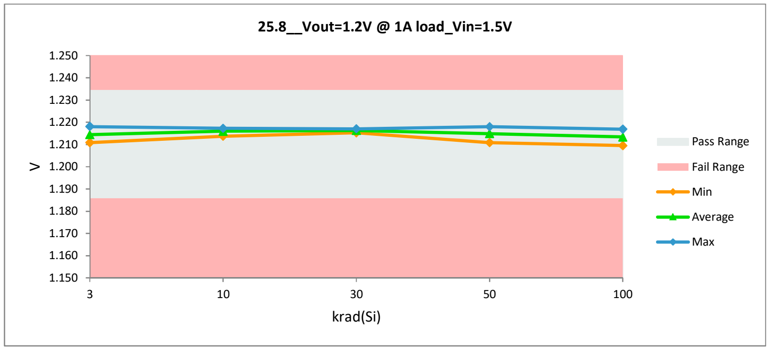


HDR Report
TPS7H1101-SP

		25.8__Vout=1.2V @ 1A load_Vin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	1.211	1.211	0.000
3	HDR_W5_D12_Bias	1.215	1.215	0.000
3	HDR_W6_D13_Bias	1.218	1.218	0.000
3	HDR_W6_D21_Bias	1.215	1.215	0.000
3	HDR_W7_D5_Bias	1.212	1.212	0.000
10	HDR_W5_D9_Bias	1.214	1.214	0.000
10	HDR_W6_D4_Bias	1.216	1.217	0.000
10	HDR_W6_D28_Bias	1.217	1.217	0.001
10	HDR_W7_D27_Bias	1.217	1.217	0.000
10	HDR_W7_D41_Bias	1.214	1.215	0.000
30	HDR_W5_D29_Bias	1.217	1.217	-0.001
30	HDR_W6_D27_Bias	1.216	1.216	0.000
30	HDR_W6_D42_Bias	1.216	1.216	0.000
30	HDR_W7_D31_Bias	1.217	1.217	0.000
30	HDR_W7_D22_Bias	1.215	1.215	0.001
50	HDR_W5_D37_Bias	1.215	1.214	-0.001
50	HDR_W5_D39_Bias	1.212	1.217	0.004
50	HDR_W6_D14_Bias	1.217	1.215	-0.002
50	HDR_W7_D13_Bias	1.217	1.218	0.001
50	HDR_W7_D37_Bias	1.219	1.211	-0.008
100	HDR_W5_D8_Bias	1.216	1.214	-0.002
100	HDR_W5_D13_Bias	1.216	1.214	-0.002
100	HDR_W5_D30_Bias	1.213	1.211	-0.001
100	HDR_W5_D32_Bias	1.211	1.209	-0.001
100	HDR_W5_D34_Bias	1.217	1.216	-0.002
100	HDR_W5_D38_Bias	1.213	1.211	-0.002
100	HDR_W5_D41_Bias	1.214	1.212	-0.002
100	HDR_W6_D1_Bias	1.217	1.214	-0.004
100	HDR_W6_D8_Bias	1.215	1.214	-0.001
100	HDR_W6_D18_Bias	1.219	1.217	-0.003
100	HDR_W6_D22_Bias	1.216	1.214	-0.001
100	HDR_W6_D24_Bias	1.214	1.212	-0.002
100	HDR_W6_D30_Bias	1.217	1.214	-0.003
100	HDR_W6_D32_Bias	1.217	1.216	-0.001
100	HDR_W6_D39_Bias	1.215	1.212	-0.003
100	HDR_W7_D4_Bias	1.217	1.215	-0.002
100	HDR_W7_D9_Bias	1.217	1.214	-0.002
100	HDR_W7_D17_Bias	1.215	1.214	-0.001
100	HDR_W7_D18_Bias	1.213	1.210	-0.003
100	HDR_W7_D25_Bias	1.220	1.216	-0.004
100	HDR_W7_D34_Bias	1.214	1.213	-0.001
100	HDR_W7_D35_Bias	1.214	1.212	-0.001
	Max	1.220	1.218	0.004
	Average	1.215	1.214	-0.001
	Min	1.211	1.209	-0.008
	Std Dev	0.002	0.002	0.002

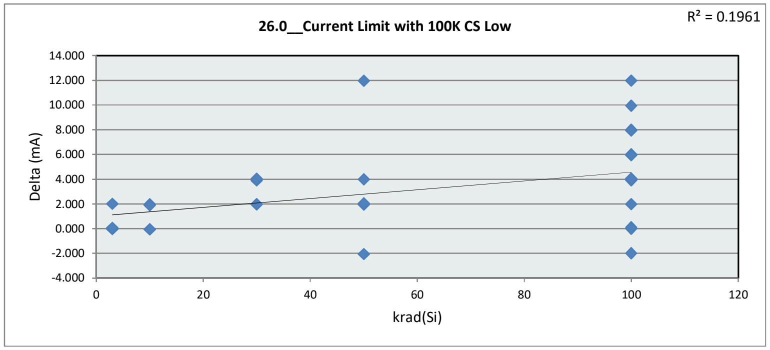


	25.8__Vout=1.2V @ 1A load_Vi				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	1.2342 V				
Min Limit	1.1858 V				
krad(Si)	3	10	30	50	100
LL	1.186	1.186	1.186	1.186	1.186
Min	1.211	1.214	1.215	1.211	1.209
Average	1.214	1.216	1.216	1.215	1.213
Max	1.218	1.217	1.217	1.218	1.217
UL	1.234	1.234	1.234	1.234	1.234

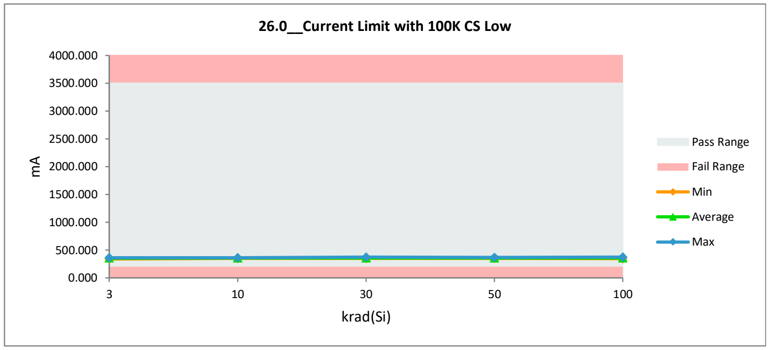


HDR Report
TPS7H1101-SP

		26.0__Current Limit with 100K C		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	3500	3500	
	Min Limit	200	200	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	364.851	364.837	-0.014
3	HDR_W5_D12_Bias	364.821	364.813	-0.008
3	HDR_W6_D13_Bias	340.704	342.710	2.006
3	HDR_W6_D21_Bias	352.754	352.728	-0.026
3	HDR_W7_D5_Bias	350.775	350.851	0.076
10	HDR_W5_D9_Bias	360.840	360.796	-0.044
10	HDR_W6_D4_Bias	358.790	358.728	-0.062
10	HDR_W6_D28_Bias	362.855	364.837	1.982
10	HDR_W7_D27_Bias	346.741	348.687	1.946
10	HDR_W7_D41_Bias	350.787	352.686	1.899
30	HDR_W5_D29_Bias	372.866	374.848	1.982
30	HDR_W6_D27_Bias	350.757	352.740	1.983
30	HDR_W6_D42_Bias	348.791	350.767	1.976
30	HDR_W7_D31_Bias	360.822	364.729	3.907
30	HDR_W7_D22_Bias	350.721	354.760	4.039
50	HDR_W5_D37_Bias	366.817	368.770	1.953
50	HDR_W5_D39_Bias	346.789	358.746	11.957
50	HDR_W6_D14_Bias	354.750	356.810	2.060
50	HDR_W7_D13_Bias	354.738	358.734	3.996
50	HDR_W7_D37_Bias	352.754	350.719	-2.035
100	HDR_W5_D8_Bias	354.869	360.820	5.951
100	HDR_W5_D13_Bias	366.883	370.796	3.913
100	HDR_W5_D30_Bias	360.882	372.864	11.982
100	HDR_W5_D32_Bias	358.862	362.853	3.991
100	HDR_W5_D34_Bias	350.692	354.748	4.056
100	HDR_W5_D38_Bias	362.837	366.821	3.984
100	HDR_W5_D41_Bias	368.861	372.828	3.967
100	HDR_W6_D1_Bias	354.756	362.763	8.007
100	HDR_W6_D8_Bias	364.869	370.862	5.993
100	HDR_W6_D18_Bias	358.820	362.787	3.967
100	HDR_W6_D22_Bias	348.743	348.753	0.010
100	HDR_W6_D24_Bias	344.810	348.789	3.979
100	HDR_W6_D30_Bias	354.822	356.810	1.988
100	HDR_W6_D32_Bias	348.815	356.762	7.947
100	HDR_W6_D39_Bias	348.737	354.760	6.023
100	HDR_W7_D4_Bias	352.760	350.779	-1.981
100	HDR_W7_D9_Bias	360.840	370.784	9.944
100	HDR_W7_D17_Bias	344.673	344.790	0.117
100	HDR_W7_D18_Bias	354.792	358.800	4.008
100	HDR_W7_D25_Bias	356.776	362.751	5.975
100	HDR_W7_D34_Bias	362.801	366.833	4.032
100	HDR_W7_D35_Bias	354.774	354.778	0.004
	Max	372.866	374.848	11.982
	Average	355.938	359.210	3.272
	Min	340.704	342.710	-2.035
	Std Dev	7.367	8.155	3.292

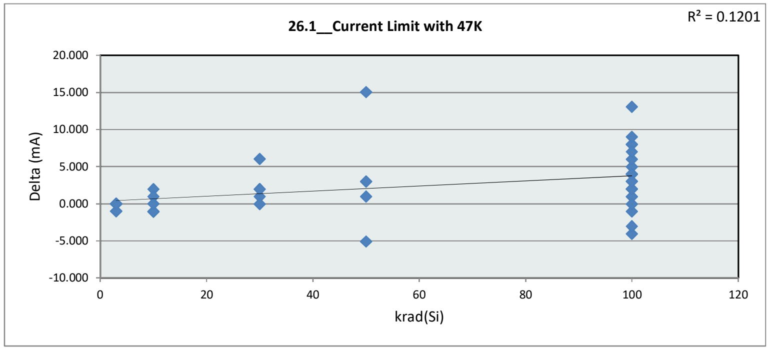


	26.0__Current Limit with 100K				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	3500	mA			
Min Limit	200	mA			
krad(Si)	3	10	30	50	100
LL	200.000	200.000	200.000	200.000	200.000
Min	342.710	348.687	350.767	350.719	344.790
Average	355.188	357.147	359.569	358.756	360.615
Max	364.837	364.837	374.848	368.770	372.864
UL	3500.000	3500.000	3500.000	3500.000	3500.000

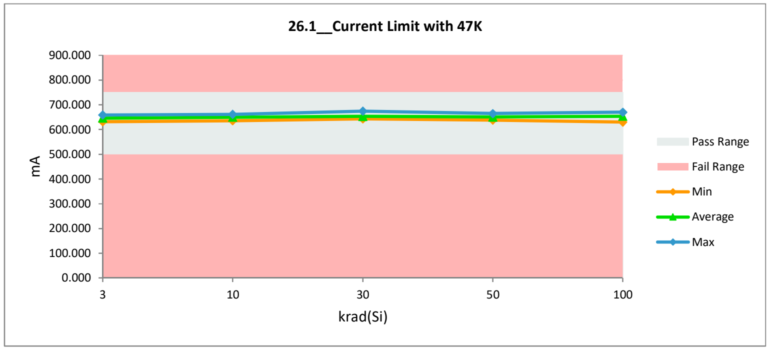


HDR Report
TPS7H1101-SP

		26.1__Current Limit with 47K		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	750	750	
	Min Limit	500	500	
krad(Si)	Serial #	Pre	Post	Delta
3	HDR_W5_D2_Bias	659.298	659.255	-0.043
3	HDR_W5_D12_Bias	659.298	658.275	-1.023
3	HDR_W6_D13_Bias	632.151	632.156	0.005
3	HDR_W6_D21_Bias	644.201	643.201	-1.000
3	HDR_W7_D5_Bias	639.204	639.209	0.005
10	HDR_W5_D9_Bias	655.288	654.247	-1.041
10	HDR_W6_D4_Bias	655.300	654.217	-1.083
10	HDR_W6_D28_Bias	659.292	661.251	1.959
10	HDR_W7_D27_Bias	635.169	636.142	0.973
10	HDR_W7_D41_Bias	642.174	642.173	-0.001
30	HDR_W5_D29_Bias	673.374	674.335	0.961
30	HDR_W6_D27_Bias	643.220	643.183	-0.037
30	HDR_W6_D42_Bias	641.218	643.159	1.941
30	HDR_W7_D31_Bias	656.274	658.233	1.959
30	HDR_W7_D22_Bias	640.178	646.208	6.030
50	HDR_W5_D37_Bias	661.313	664.306	2.993
50	HDR_W5_D39_Bias	636.180	651.234	15.054
50	HDR_W6_D14_Bias	647.225	650.218	2.993
50	HDR_W7_D13_Bias	648.235	649.202	0.967
50	HDR_W7_D37_Bias	643.226	638.139	-5.087
100	HDR_W5_D8_Bias	648.265	653.254	4.989
100	HDR_W5_D13_Bias	664.325	665.292	0.967
100	HDR_W5_D30_Bias	656.274	669.332	13.058
100	HDR_W5_D32_Bias	652.252	656.243	3.991
100	HDR_W5_D34_Bias	641.194	646.184	4.990
100	HDR_W5_D38_Bias	657.290	661.269	3.979
100	HDR_W5_D41_Bias	667.319	670.330	3.011
100	HDR_W6_D1_Bias	648.265	656.249	7.984
100	HDR_W6_D8_Bias	663.321	669.314	5.993
100	HDR_W6_D18_Bias	656.274	658.251	1.977
100	HDR_W6_D22_Bias	638.212	637.158	-1.054
100	HDR_W6_D24_Bias	637.190	639.173	1.983
100	HDR_W6_D30_Bias	649.257	650.200	0.943
100	HDR_W6_D32_Bias	643.214	651.222	8.008
100	HDR_W6_D39_Bias	639.198	646.208	7.010
100	HDR_W7_D4_Bias	644.207	640.171	-4.036
100	HDR_W7_D9_Bias	655.264	664.288	9.024
100	HDR_W7_D17_Bias	630.143	630.106	-0.037
100	HDR_W7_D18_Bias	647.213	649.214	2.001
100	HDR_W7_D25_Bias	653.274	657.265	3.991
100	HDR_W7_D34_Bias	657.290	660.295	3.005
100	HDR_W7_D35_Bias	649.233	646.190	-3.043
	Max	673.374	674.335	15.054
	Average	649.293	651.799	2.506
	Min	630.143	630.106	-5.087
	Std Dev	10.027	10.922	4.079



	26.1__Current Limit with 47K				
Test Site	Dallas				
Tester	ETS-364				
Test Number	EF5069				
Max Limit	750	mA			
Min Limit	500	mA			
krad(Si)	3	10	30	50	100
LL	500.000	500.000	500.000	500.000	500.000
Min	632.156	636.142	643.159	638.139	630.106
Average	646.419	649.606	653.024	650.620	653.509
Max	659.255	661.251	674.335	664.306	670.330
UL	750.000	750.000	750.000	750.000	750.000

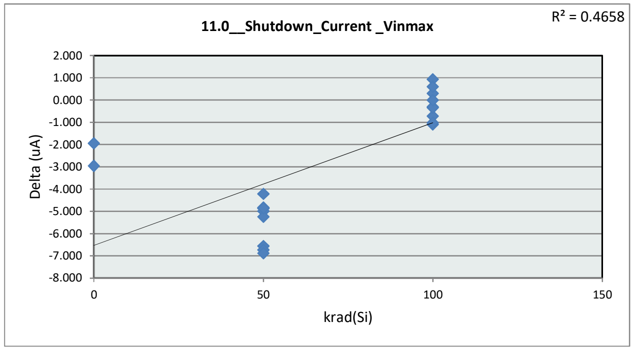


B LDR TID Report Data

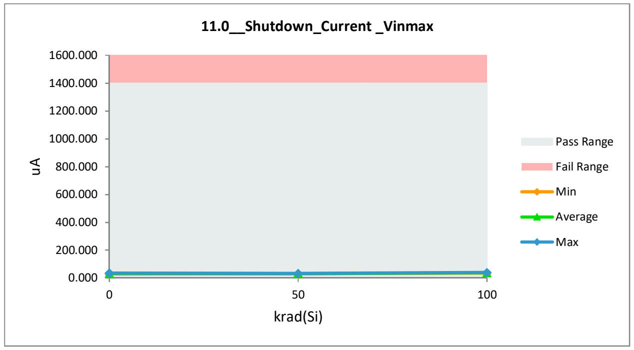
This appendix contains the LDR TID report data.

LDR Report
TPS7H1101-SP

		11.0__Shutdown_Current _Vinm		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		uA	uA	
Max Limit		1400	1400	
Min Limit		0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	32.218	29.262	-2.956
50	LDR_Bias_50K_Q1_3	36.353	32.139	-4.214
50	LDR_Bias_50K_Q2_65	38.133	31.571	-6.562
50	LDR_Bias_50K_Q3_30	38.034	31.304	-6.730
50	LDR_Bias_50K_Q4_76	37.598	30.717	-6.881
50	LDR_Bias_50K_Q5_46	36.273	31.443	-4.830
50	LDR_UnBias_50K_Q1_4	36.817	31.953	-4.864
50	LDR_UnBias_50K_Q2_66	37.513	32.522	-4.991
50	LDR_UnBias_50K_Q3_31	37.086	31.841	-5.245
50	LDR_UnBias_50K_Q4_77	37.859	33.008	-4.851
50	LDR_UnBias_50K_Q5_47	34.909	30.051	-4.858
0	LDR_100K_Correlation_Q5_72	37.406	35.463	-1.943
100	LDR_Bias_100K_Q1_5	36.962	36.242	-0.720
100	LDR_Bias_100K_Q3_28	36.405	37.337	0.932
100	LDR_Bias_100K_Q5_45	36.343	36.034	-0.309
100	LDR_Bias_100K_Q2_67	37.933	38.230	0.297
100	LDR_Bias_100K_Q2_68	37.443	37.103	-0.340
100	LDR_UnBias_100K_Q1_6	38.415	37.321	-1.094
100	LDR_UnBias_100K_Q3_29	39.250	38.223	-1.027
100	LDR_UnBias_100K_Q5_69	36.287	35.953	-0.334
100	LDR_UnBias_100K_Q4_78	38.211	38.808	0.597
100	LDR_UnBias_100K_Q4_79	37.930	37.920	-0.010
	Max	39.250	38.808	0.932
	Average	37.063	34.293	-2.770
	Min	32.218	29.262	-6.881
	Std Dev	1.444	3.111	2.656

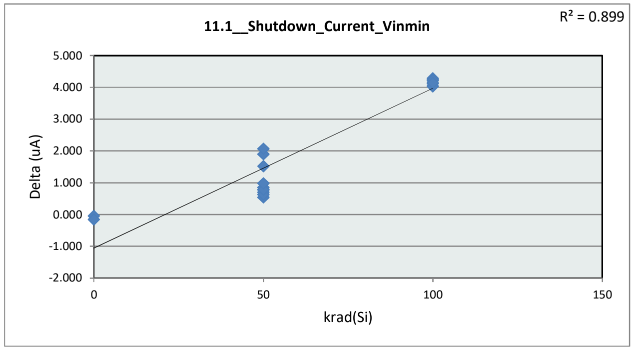


	11.0__Shutdown_Current _Vinmax		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1400	uA	
Min Limit	0.0005	uA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	29.262	30.051	35.953
Average	32.363	31.655	37.317
Max	35.463	33.008	38.808
UL	1400.000	1400.000	1400.000

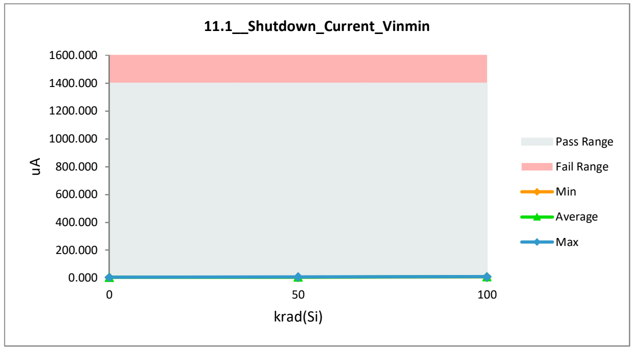


LDR Report
TPS7H1101-SP

		11.1__Shutdown_Current_Vinmi		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1400	1400	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	4.553	4.505	-0.048
50	LDR_Bias_50K_Q1_3	4.588	5.368	0.780
50	LDR_Bias_50K_Q2_65	4.842	5.541	0.699
50	LDR_Bias_50K_Q3_30	4.737	5.279	0.542
50	LDR_Bias_50K_Q4_76	4.574	5.203	0.629
50	LDR_Bias_50K_Q5_46	4.762	5.610	0.848
50	LDR_UnBias_50K_Q1_4	4.839	5.619	0.780
50	LDR_UnBias_50K_Q2_66	4.655	6.552	1.897
50	LDR_UnBias_50K_Q3_31	4.672	5.656	0.984
50	LDR_UnBias_50K_Q4_77	4.792	6.862	2.070
50	LDR_UnBias_50K_Q5_47	4.166	5.685	1.519
0	LDR_100K_Correlation_Q5_72	4.872	4.721	-0.151
100	LDR_Bias_100K_Q1_5	4.751	8.977	4.226
100	LDR_Bias_100K_Q3_28	4.589	8.633	4.044
100	LDR_Bias_100K_Q5_45	4.836	8.954	4.118
100	LDR_Bias_100K_Q2_67	4.866	9.073	4.207
100	LDR_Bias_100K_Q2_68	4.787	9.027	4.240
100	LDR_UnBias_100K_Q1_6	4.776	8.898	4.122
100	LDR_UnBias_100K_Q3_29	4.697	8.725	4.028
100	LDR_UnBias_100K_Q5_69	4.546	8.832	4.286
100	LDR_UnBias_100K_Q4_78	5.030	9.262	4.232
100	LDR_UnBias_100K_Q4_79	4.551	8.688	4.137
	Max	5.030	9.262	4.286
	Average	4.704	7.076	2.372
	Min	4.166	4.505	-0.151
	Std Dev	0.176	1.780	1.745

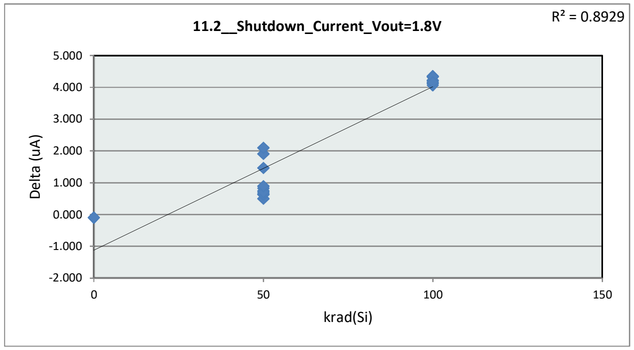


	11.1__Shutdown_Current_Vinmin		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1400	uA	
Min Limit	0.0005	uA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	4.505	5.203	8.633
Average	4.613	5.738	8.907
Max	4.721	6.862	9.262
UL	1400.000	1400.000	1400.000

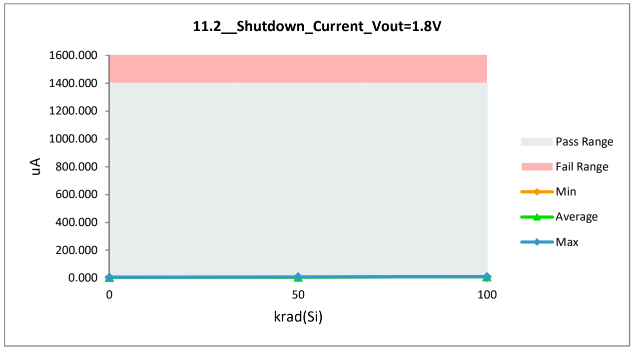


LDR Report
TPS7H1101-SP

		11.2__Shutdown_Current_Vout=		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		uA	uA	
Max Limit		1400	1400	
Min Limit		0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	4.819	4.718	-0.101
50	LDR_Bias_50K_Q1_3	4.873	5.617	0.744
50	LDR_Bias_50K_Q2_65	5.139	5.790	0.651
50	LDR_Bias_50K_Q3_30	4.987	5.485	0.498
50	LDR_Bias_50K_Q4_76	4.843	5.474	0.631
50	LDR_Bias_50K_Q5_46	5.041	5.864	0.823
50	LDR_UnBias_50K_Q1_4	5.150	5.856	0.706
50	LDR_UnBias_50K_Q2_66	4.947	6.850	1.903
50	LDR_UnBias_50K_Q3_31	4.969	5.857	0.888
50	LDR_UnBias_50K_Q4_77	5.068	7.164	2.096
50	LDR_UnBias_50K_Q5_47	4.481	5.947	1.466
0	LDR_100K_Correlation_Q5_72	5.121	5.025	-0.096
100	LDR_Bias_100K_Q1_5	4.958	9.307	4.349
100	LDR_Bias_100K_Q3_28	4.853	8.967	4.114
100	LDR_Bias_100K_Q5_45	5.113	9.243	4.130
100	LDR_Bias_100K_Q2_67	5.147	9.344	4.197
100	LDR_Bias_100K_Q2_68	4.993	9.321	4.328
100	LDR_UnBias_100K_Q1_6	4.989	9.212	4.223
100	LDR_UnBias_100K_Q3_29	4.949	9.016	4.067
100	LDR_UnBias_100K_Q5_69	4.831	9.164	4.333
100	LDR_UnBias_100K_Q4_78	5.228	9.568	4.340
100	LDR_UnBias_100K_Q4_79	4.826	8.983	4.157
	Max	5.228	9.568	4.349
	Average	4.969	7.353	2.384
	Min	4.481	4.718	-0.101
	Std Dev	0.163	1.809	1.789



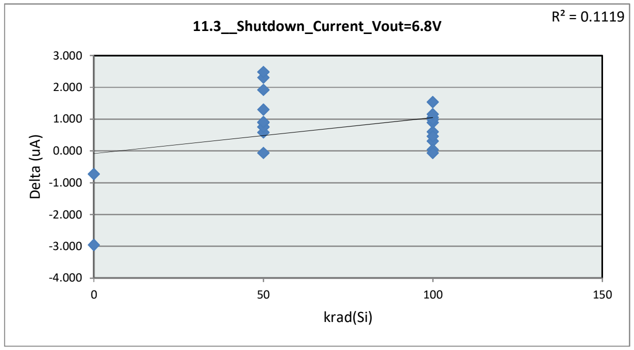
	11.2__Shutdown_Current_Vout=1.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1400	uA	
Min Limit	0.0005	uA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	4.718	5.474	8.967
Average	4.872	5.990	9.213
Max	5.025	7.164	9.568
UL	1400.000	1400.000	1400.000



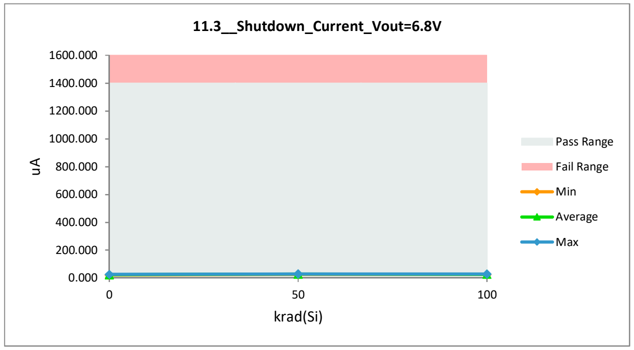
LDR Report
TPS7H1101-SP

	11.3__Shutdown_Current_Vout=	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	uA	uA
Max Limit	1400	1400
Min Limit	0.0005	0.0005

krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	24.203	21.246	-2.957
50	LDR_Bias_50K_Q1_3	26.438	27.329	0.891
50	LDR_Bias_50K_Q2_65	26.653	27.404	0.751
50	LDR_Bias_50K_Q3_30	27.131	27.066	-0.065
50	LDR_Bias_50K_Q4_76	26.119	26.703	0.584
50	LDR_Bias_50K_Q5_46	25.735	27.033	1.298
50	LDR_UnBias_50K_Q1_4	26.986	27.740	0.754
50	LDR_UnBias_50K_Q2_66	26.267	28.576	2.309
50	LDR_UnBias_50K_Q3_31	26.751	27.661	0.910
50	LDR_UnBias_50K_Q4_77	26.622	29.108	2.486
50	LDR_UnBias_50K_Q5_47	24.054	25.976	1.922
0	LDR_100K_Correlation_Q5_72	26.052	25.326	-0.726
100	LDR_Bias_100K_Q1_5	26.668	26.979	0.311
100	LDR_Bias_100K_Q3_28	26.261	26.861	0.600
100	LDR_Bias_100K_Q5_45	25.931	26.392	0.461
100	LDR_Bias_100K_Q2_67	26.656	27.552	0.896
100	LDR_Bias_100K_Q2_68	26.184	27.239	1.055
100	LDR_UnBias_100K_Q1_6	27.124	27.160	0.036
100	LDR_UnBias_100K_Q3_29	27.391	27.329	-0.062
100	LDR_UnBias_100K_Q5_69	25.030	26.018	0.988
100	LDR_UnBias_100K_Q4_78	26.943	28.097	1.154
100	LDR_UnBias_100K_Q4_79	25.510	27.043	1.533
	Max	27.391	29.108	2.486
	Average	26.214	26.902	0.688
	Min	24.054	21.246	-2.957
	Std Dev	0.879	1.513	1.115



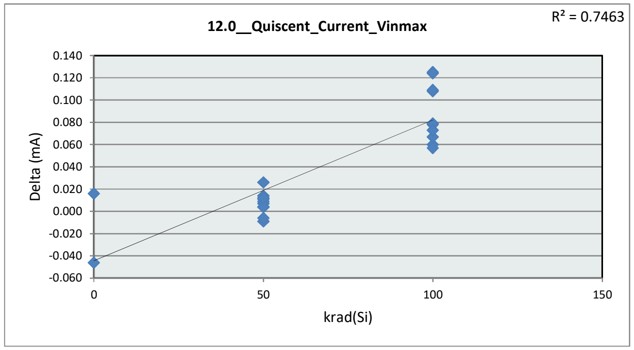
	11.3__Shutdown_Current_Vout=6.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1400	uA	
Min Limit	0.0005	uA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	21.246	25.976	26.018
Average	23.286	27.460	27.067
Max	25.326	29.108	28.097
UL	1400.000	1400.000	1400.000



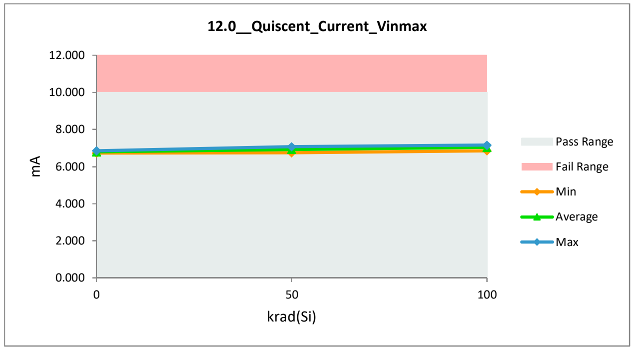
LDR Report
TPS7H1101-SP

	12.0__Quiscent_Current_Vinmax	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	mA	mA
Max Limit	10	10
Min Limit	0.0005	0.0005

krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	6.779	6.733	-0.046
50	LDR_Bias_50K_Q1_3	6.972	6.976	0.004
50	LDR_Bias_50K_Q2_65	7.066	7.075	0.009
50	LDR_Bias_50K_Q3_30	6.895	6.902	0.007
50	LDR_Bias_50K_Q4_76	6.924	6.938	0.014
50	LDR_Bias_50K_Q5_46	6.797	6.808	0.011
50	LDR_UnBias_50K_Q1_4	6.942	6.933	-0.009
50	LDR_UnBias_50K_Q2_66	7.043	7.069	0.026
50	LDR_UnBias_50K_Q3_31	6.939	6.943	0.004
50	LDR_UnBias_50K_Q4_77	6.846	6.858	0.012
50	LDR_UnBias_50K_Q5_47	6.761	6.755	-0.006
0	LDR_100K_Correlation_Q5_72	6.836	6.852	0.016
100	LDR_Bias_100K_Q1_5	7.000	7.125	0.125
100	LDR_Bias_100K_Q3_28	6.989	7.049	0.060
100	LDR_Bias_100K_Q5_45	6.818	6.926	0.108
100	LDR_Bias_100K_Q2_67	7.102	7.159	0.057
100	LDR_Bias_100K_Q2_68	6.998	7.122	0.124
100	LDR_UnBias_100K_Q1_6	7.046	7.124	0.078
100	LDR_UnBias_100K_Q3_29	7.036	7.103	0.067
100	LDR_UnBias_100K_Q5_69	6.778	6.857	0.079
100	LDR_UnBias_100K_Q4_78	6.852	6.925	0.073
100	LDR_UnBias_100K_Q4_79	6.841	6.950	0.109
	Max	7.102	7.159	0.125
	Average	6.921	6.963	0.042
	Min	6.761	6.733	-0.046
	Std Dev	0.106	0.125	0.048

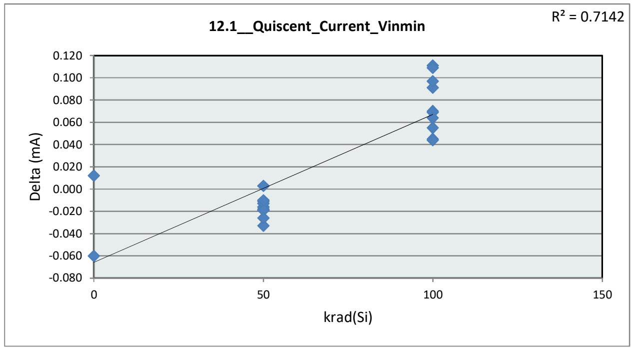


	12.0__Quiscent_Current_Vinmax		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	10	mA	
Min Limit	0.0005	mA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	6.733	6.755	6.857
Average	6.793	6.926	7.034
Max	6.852	7.075	7.159
UL	10.000	10.000	10.000

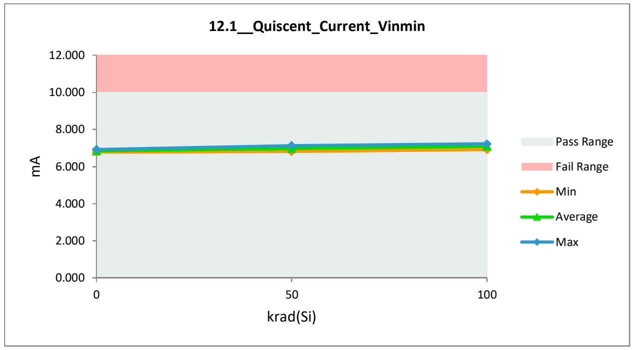


LDR Report
TPS7H1101-SP

		12.1__Quiscent_Current_Vinmin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	6.848	6.788	-0.060
50	LDR_Bias_50K_Q1_3	7.048	7.030	-0.018
50	LDR_Bias_50K_Q2_65	7.145	7.129	-0.016
50	LDR_Bias_50K_Q3_30	6.978	6.959	-0.019
50	LDR_Bias_50K_Q4_76	7.005	6.994	-0.011
50	LDR_Bias_50K_Q5_46	6.876	6.863	-0.013
50	LDR_UnBias_50K_Q1_4	7.019	6.986	-0.033
50	LDR_UnBias_50K_Q2_66	7.121	7.124	0.003
50	LDR_UnBias_50K_Q3_31	7.020	7.001	-0.019
50	LDR_UnBias_50K_Q4_77	6.929	6.919	-0.010
50	LDR_UnBias_50K_Q5_47	6.835	6.809	-0.026
0	LDR_100K_Correlation_Q5_72	6.915	6.927	0.012
100	LDR_Bias_100K_Q1_5	7.074	7.185	0.111
100	LDR_Bias_100K_Q3_28	7.069	7.114	0.045
100	LDR_Bias_100K_Q5_45	6.898	6.989	0.091
100	LDR_Bias_100K_Q2_67	7.179	7.223	0.044
100	LDR_Bias_100K_Q2_68	7.077	7.186	0.109
100	LDR_UnBias_100K_Q1_6	7.122	7.192	0.070
100	LDR_UnBias_100K_Q3_29	7.116	7.171	0.055
100	LDR_UnBias_100K_Q5_69	6.855	6.924	0.069
100	LDR_UnBias_100K_Q4_78	6.933	6.997	0.064
100	LDR_UnBias_100K_Q4_79	6.922	7.019	0.097
	Max	7.179	7.223	0.111
	Average	6.999	7.024	0.025
	Min	6.835	6.788	-0.060
	Std Dev	0.106	0.127	0.052



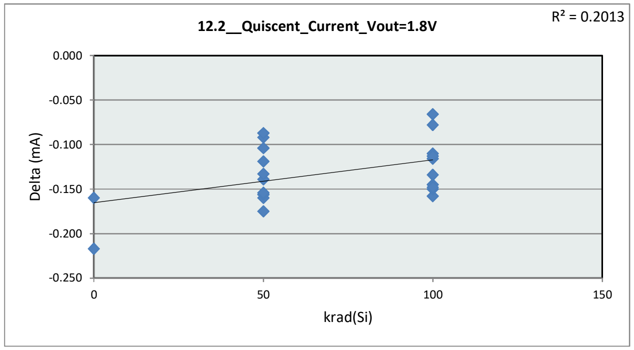
	12.1__Quiscent_Current_Vinmin		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	10	mA	
Min Limit	0.0005	mA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	6.788	6.809	6.924
Average	6.858	6.981	7.100
Max	6.927	7.129	7.223
UL	10.000	10.000	10.000



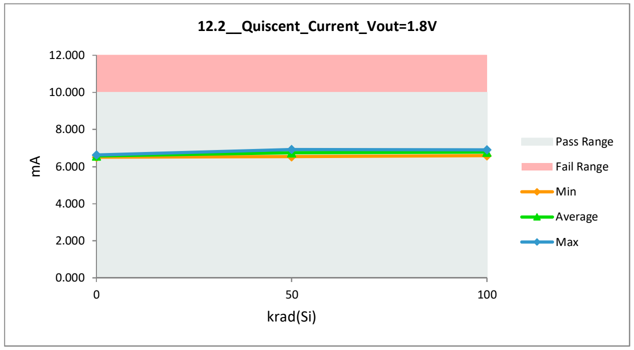
LDR Report
TPS7H1101-SP

	12.2__Quiscent_Current_Vout=1	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	mA	mA
Max Limit	10	10
Min Limit	0.0005	0.0005

krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	6.730	6.513	-0.217
50	LDR_Bias_50K_Q1_3	6.928	6.824	-0.104
50	LDR_Bias_50K_Q2_65	7.014	6.922	-0.092
50	LDR_Bias_50K_Q3_30	6.856	6.717	-0.139
50	LDR_Bias_50K_Q4_76	6.884	6.765	-0.119
50	LDR_Bias_50K_Q5_46	6.751	6.591	-0.160
50	LDR_UnBias_50K_Q1_4	6.901	6.745	-0.156
50	LDR_UnBias_50K_Q2_66	6.997	6.910	-0.087
50	LDR_UnBias_50K_Q3_31	6.898	6.765	-0.133
50	LDR_UnBias_50K_Q4_77	6.807	6.653	-0.154
50	LDR_UnBias_50K_Q5_47	6.706	6.531	-0.175
0	LDR_100K_Correlation_Q5_72	6.791	6.631	-0.160
100	LDR_Bias_100K_Q1_5	6.947	6.881	-0.066
100	LDR_Bias_100K_Q3_28	6.950	6.792	-0.158
100	LDR_Bias_100K_Q5_45	6.775	6.665	-0.110
100	LDR_Bias_100K_Q2_67	7.056	6.911	-0.145
100	LDR_Bias_100K_Q2_68	6.954	6.876	-0.078
100	LDR_UnBias_100K_Q1_6	6.998	6.882	-0.116
100	LDR_UnBias_100K_Q3_29	6.991	6.857	-0.134
100	LDR_UnBias_100K_Q5_69	6.735	6.585	-0.150
100	LDR_UnBias_100K_Q4_78	6.812	6.664	-0.148
100	LDR_UnBias_100K_Q4_79	6.806	6.693	-0.113
	Max	7.056	6.922	-0.066
	Average	6.877	6.744	-0.132
	Min	6.706	6.513	-0.217
	Std Dev	0.105	0.129	0.035

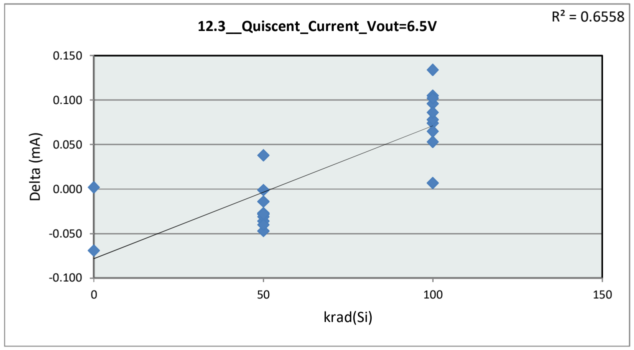


	12.2__Quiscent_Current_Vout=1.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	10	mA	
Min Limit	0.0005	mA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	6.513	6.531	6.585
Average	6.572	6.742	6.781
Max	6.631	6.922	6.911
UL	10.000	10.000	10.000

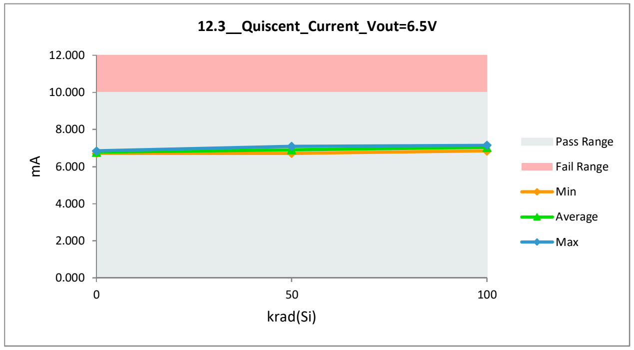


LDR Report
TPS7H1101-SP

		12.3__Quiscent_Current_Vout=6		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	10	10	
	Min Limit	0.0005	0.0005	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	6.783	6.714	-0.069
50	LDR_Bias_50K_Q1_3	6.978	6.950	-0.028
50	LDR_Bias_50K_Q2_65	7.068	7.067	-0.001
50	LDR_Bias_50K_Q3_30	6.910	6.874	-0.036
50	LDR_Bias_50K_Q4_76	6.935	6.888	-0.047
50	LDR_Bias_50K_Q5_46	6.808	6.781	-0.027
50	LDR_UnBias_50K_Q1_4	6.949	6.918	-0.031
50	LDR_UnBias_50K_Q2_66	7.053	7.091	0.038
50	LDR_UnBias_50K_Q3_31	6.950	6.936	-0.014
50	LDR_UnBias_50K_Q4_77	6.862	6.834	-0.028
50	LDR_UnBias_50K_Q5_47	6.759	6.719	-0.040
0	LDR_100K_Correlation_Q5_72	6.846	6.848	0.002
100	LDR_Bias_100K_Q1_5	6.995	7.129	0.134
100	LDR_Bias_100K_Q3_28	7.003	7.056	0.053
100	LDR_Bias_100K_Q5_45	6.829	6.934	0.105
100	LDR_Bias_100K_Q2_67	7.111	7.118	0.007
100	LDR_Bias_100K_Q2_68	7.008	7.082	0.074
100	LDR_UnBias_100K_Q1_6	7.055	7.151	0.096
100	LDR_UnBias_100K_Q3_29	7.048	7.126	0.078
100	LDR_UnBias_100K_Q5_69	6.782	6.847	0.065
100	LDR_UnBias_100K_Q4_78	6.866	6.952	0.086
100	LDR_UnBias_100K_Q4_79	6.857	6.959	0.102
	Max	7.111	7.151	0.134
	Average	6.930	6.953	0.024
	Min	6.759	6.714	-0.069
	Std Dev	0.106	0.134	0.061

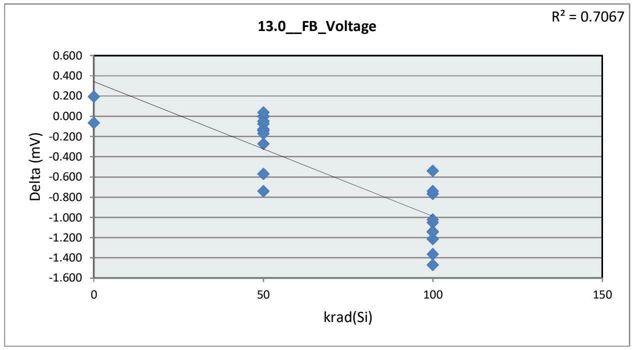


	12.3__Quiscent_Current_Vout=6.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	10	mA	
Min Limit	0.0005	mA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	6.714	6.719	6.847
Average	6.781	6.906	7.035
Max	6.848	7.091	7.151
UL	10.000	10.000	10.000

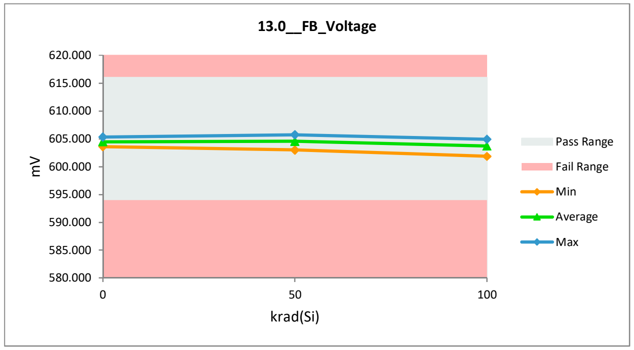


LDR Report
TPS7H1101-SP

		13.0__FB_Voltage		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		mV	mV	
Max Limit		616	616	
Min Limit		594	594	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	605.140	605.334	0.194
50	LDR_Bias_50K_Q1_3	604.250	604.122	-0.128
50	LDR_Bias_50K_Q2_65	605.523	605.447	-0.076
50	LDR_Bias_50K_Q3_30	605.040	604.767	-0.273
50	LDR_Bias_50K_Q4_76	604.305	604.163	-0.142
50	LDR_Bias_50K_Q5_46	604.191	604.188	-0.003
50	LDR_UnBias_50K_Q1_4	603.041	602.991	-0.050
50	LDR_UnBias_50K_Q2_66	605.479	604.908	-0.571
50	LDR_UnBias_50K_Q3_31	604.972	604.801	-0.171
50	LDR_UnBias_50K_Q4_77	605.094	604.354	-0.740
50	LDR_UnBias_50K_Q5_47	605.692	605.730	0.038
0	LDR_100K_Correlation_Q5_72	603.670	603.605	-0.065
100	LDR_Bias_100K_Q1_5	604.596	603.457	-1.139
100	LDR_Bias_100K_Q3_28	604.760	603.710	-1.050
100	LDR_Bias_100K_Q5_45	605.253	604.040	-1.213
100	LDR_Bias_100K_Q2_67	604.679	603.658	-1.021
100	LDR_Bias_100K_Q2_68	604.782	603.313	-1.469
100	LDR_UnBias_100K_Q1_6	605.209	604.442	-0.767
100	LDR_UnBias_100K_Q3_29	605.452	604.912	-0.540
100	LDR_UnBias_100K_Q5_69	602.982	601.838	-1.144
100	LDR_UnBias_100K_Q4_78	604.835	604.094	-0.741
100	LDR_UnBias_100K_Q4_79	604.881	603.517	-1.364
	Max	605.692	605.730	0.194
	Average	604.719	604.154	-0.565
	Min	602.982	601.838	-1.469
	Std Dev	0.736	0.891	0.521

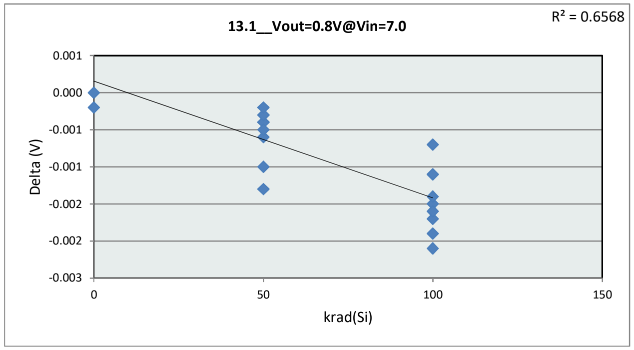


	13.0__FB_Voltage		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	616	mV	
Min Limit	594	mV	
krad(Si)	0	50	100
LL	594.000	594.000	594.000
Min	603.605	602.991	601.838
Average	604.470	604.547	603.698
Max	605.334	605.730	604.912
UL	616.000	616.000	616.000

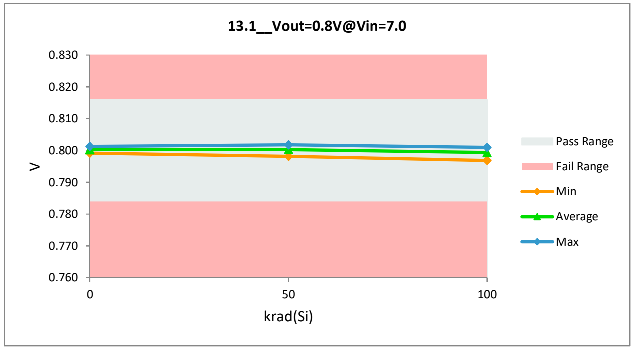


LDR Report
TPS7H1101-SP

		13.1__Vout=0.8V@Vin=7.0		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.801	0.801	0.000
50	LDR_Bias_50K_Q1_3	0.800	0.800	0.000
50	LDR_Bias_50K_Q2_65	0.802	0.802	0.000
50	LDR_Bias_50K_Q3_30	0.801	0.801	-0.001
50	LDR_Bias_50K_Q4_76	0.800	0.800	0.000
50	LDR_Bias_50K_Q5_46	0.800	0.800	0.000
50	LDR_UnBias_50K_Q1_4	0.799	0.798	0.000
50	LDR_UnBias_50K_Q2_66	0.802	0.801	-0.001
50	LDR_UnBias_50K_Q3_31	0.801	0.801	-0.001
50	LDR_UnBias_50K_Q4_77	0.801	0.800	-0.001
50	LDR_UnBias_50K_Q5_47	0.802	0.802	0.000
0	LDR_100K_Correlation_Q5_72	0.799	0.799	0.000
100	LDR_Bias_100K_Q1_5	0.801	0.799	-0.002
100	LDR_Bias_100K_Q3_28	0.801	0.799	-0.002
100	LDR_Bias_100K_Q5_45	0.802	0.800	-0.002
100	LDR_Bias_100K_Q2_67	0.801	0.799	-0.001
100	LDR_Bias_100K_Q2_68	0.801	0.799	-0.002
100	LDR_UnBias_100K_Q1_6	0.801	0.800	-0.001
100	LDR_UnBias_100K_Q3_29	0.802	0.801	-0.001
100	LDR_UnBias_100K_Q5_69	0.799	0.797	-0.002
100	LDR_UnBias_100K_Q4_78	0.801	0.800	-0.001
100	LDR_UnBias_100K_Q4_79	0.801	0.799	-0.002
	Max	0.802	0.802	0.000
	Average	0.801	0.800	-0.001
	Min	0.799	0.797	-0.002
	Std Dev	0.001	0.001	0.001

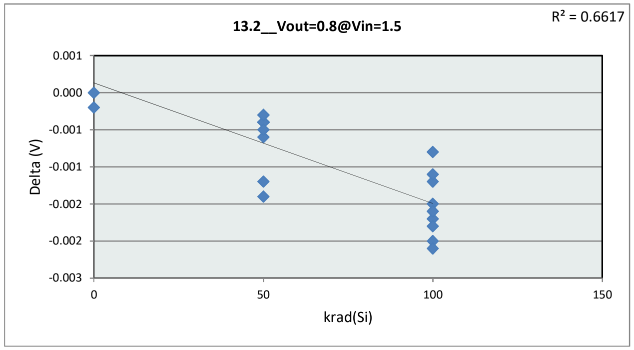


	13.1__Vout=0.8V@Vin=7.0		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.816	V	
Min Limit	0.784	V	
krad(Si)	0	50	100
LL	0.784	0.784	0.784
Min	0.799	0.798	0.797
Average	0.800	0.800	0.799
Max	0.801	0.802	0.801
UL	0.816	0.816	0.816

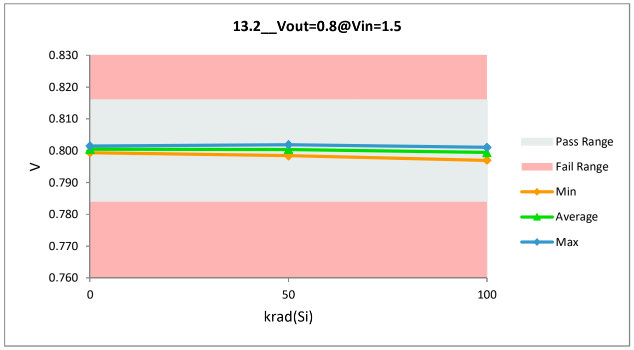


LDR Report
TPS7H1101-SP

		13.2__Vout=0.8@Vin=1.5		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.802	0.802	0.000
50	LDR_Bias_50K_Q1_3	0.800	0.800	0.000
50	LDR_Bias_50K_Q2_65	0.802	0.802	0.000
50	LDR_Bias_50K_Q3_30	0.801	0.801	-0.001
50	LDR_Bias_50K_Q4_76	0.800	0.800	0.000
50	LDR_Bias_50K_Q5_46	0.800	0.800	0.000
50	LDR_UnBias_50K_Q1_4	0.799	0.798	0.000
50	LDR_UnBias_50K_Q2_66	0.802	0.801	-0.001
50	LDR_UnBias_50K_Q3_31	0.801	0.801	0.000
50	LDR_UnBias_50K_Q4_77	0.802	0.800	-0.001
50	LDR_UnBias_50K_Q5_47	0.802	0.802	0.000
0	LDR_100K_Correlation_Q5_72	0.800	0.799	0.000
100	LDR_Bias_100K_Q1_5	0.801	0.799	-0.002
100	LDR_Bias_100K_Q3_28	0.801	0.799	-0.002
100	LDR_Bias_100K_Q5_45	0.802	0.800	-0.002
100	LDR_Bias_100K_Q2_67	0.801	0.799	-0.002
100	LDR_Bias_100K_Q2_68	0.801	0.799	-0.002
100	LDR_UnBias_100K_Q1_6	0.802	0.800	-0.001
100	LDR_UnBias_100K_Q3_29	0.802	0.801	-0.001
100	LDR_UnBias_100K_Q5_69	0.799	0.797	-0.002
100	LDR_UnBias_100K_Q4_78	0.801	0.800	-0.001
100	LDR_UnBias_100K_Q4_79	0.801	0.799	-0.002
	Max	0.802	0.802	0.000
	Average	0.801	0.800	-0.001
	Min	0.799	0.797	-0.002
	Std Dev	0.001	0.001	0.001

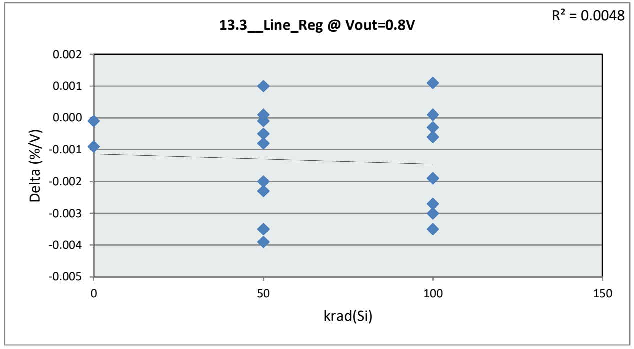


	13.2__Vout=0.8@Vin=1.5		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.816	V	
Min Limit	0.784	V	
krad(Si)	0	50	100
LL	0.784	0.784	0.784
Min	0.799	0.798	0.797
Average	0.800	0.800	0.799
Max	0.802	0.802	0.801
UL	0.816	0.816	0.816

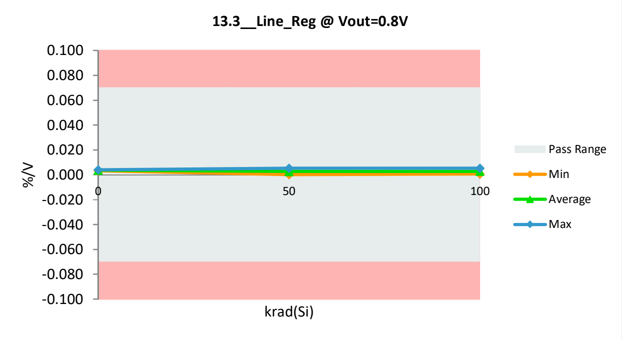


LDR Report
TPS7H1101-SP

		13.3__Line_Reg @ Vout=0.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.004	0.003	-0.001
50	LDR_Bias_50K_Q1_3	0.004	0.004	0.000
50	LDR_Bias_50K_Q2_65	0.004	0.002	-0.002
50	LDR_Bias_50K_Q3_30	0.004	0.004	0.000
50	LDR_Bias_50K_Q4_76	0.004	0.005	0.001
50	LDR_Bias_50K_Q5_46	0.004	0.000	-0.004
50	LDR_UnBias_50K_Q1_4	0.004	0.004	-0.001
50	LDR_UnBias_50K_Q2_66	0.004	0.000	-0.003
50	LDR_UnBias_50K_Q3_31	0.004	0.004	-0.001
50	LDR_UnBias_50K_Q4_77	0.004	0.002	-0.002
50	LDR_UnBias_50K_Q5_47	0.004	0.001	-0.003
0	LDR_100K_Correlation_Q5_72	0.004	0.004	0.000
100	LDR_Bias_100K_Q1_5	0.004	0.001	-0.003
100	LDR_Bias_100K_Q3_28	0.004	0.004	0.000
100	LDR_Bias_100K_Q5_45	0.004	0.004	-0.001
100	LDR_Bias_100K_Q2_67	0.004	0.001	-0.003
100	LDR_Bias_100K_Q2_68	0.004	0.005	0.001
100	LDR_UnBias_100K_Q1_6	0.004	0.002	-0.002
100	LDR_UnBias_100K_Q3_29	0.004	0.002	-0.002
100	LDR_UnBias_100K_Q5_69	0.004	0.004	-0.001
100	LDR_UnBias_100K_Q4_78	0.004	0.004	0.000
100	LDR_UnBias_100K_Q4_79	0.004	0.001	-0.003
	Max	0.004	0.005	0.001
	Average	0.004	0.003	-0.001
	Min	0.004	0.000	-0.004
	Std Dev	0.000	0.002	0.002

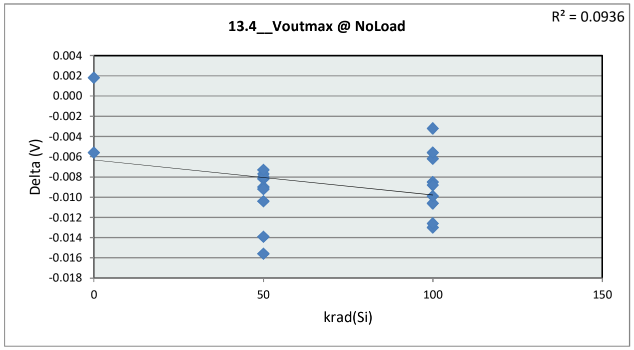


	13.3__Line_Reg @ Vout=0.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.07	%/V	
Min Limit	-0.07	%/V	
krad(Si)	0	50	100
LL	-0.070	-0.070	-0.070
Min	0.003	0.000	0.001
Average	0.004	0.003	0.003
Max	0.004	0.005	0.005
UL	0.070	0.070	0.070

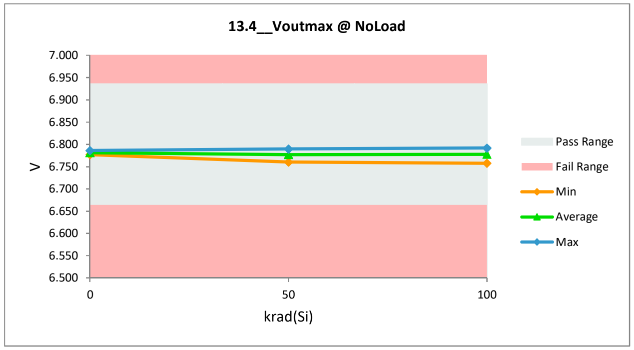


LDR Report
TPS7H1101-SP

		13.4__Voutmax @ NoLoad		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		6.936	6.936	
Min Limit		6.664	6.664	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	6.792	6.786	-0.006
50	LDR_Bias_50K_Q1_3	6.782	6.773	-0.009
50	LDR_Bias_50K_Q2_65	6.795	6.787	-0.008
50	LDR_Bias_50K_Q3_30	6.791	6.780	-0.010
50	LDR_Bias_50K_Q4_76	6.783	6.774	-0.009
50	LDR_Bias_50K_Q5_46	6.780	6.772	-0.008
50	LDR_UnBias_50K_Q1_4	6.768	6.760	-0.008
50	LDR_UnBias_50K_Q2_66	6.794	6.781	-0.014
50	LDR_UnBias_50K_Q3_31	6.790	6.780	-0.009
50	LDR_UnBias_50K_Q4_77	6.791	6.775	-0.016
50	LDR_UnBias_50K_Q5_47	6.797	6.790	-0.007
0	LDR_100K_Correlation_Q5_72	6.775	6.777	0.002
100	LDR_Bias_100K_Q1_5	6.785	6.774	-0.011
100	LDR_Bias_100K_Q3_28	6.787	6.778	-0.009
100	LDR_Bias_100K_Q5_45	6.792	6.782	-0.011
100	LDR_Bias_100K_Q2_67	6.786	6.777	-0.009
100	LDR_Bias_100K_Q2_68	6.788	6.775	-0.013
100	LDR_UnBias_100K_Q1_6	6.792	6.786	-0.006
100	LDR_UnBias_100K_Q3_29	6.795	6.792	-0.003
100	LDR_UnBias_100K_Q5_69	6.767	6.758	-0.010
100	LDR_UnBias_100K_Q4_78	6.789	6.783	-0.006
100	LDR_UnBias_100K_Q4_79	6.788	6.776	-0.013
	Max	6.797	6.792	0.002
	Average	6.787	6.778	-0.009
	Min	6.767	6.758	-0.016
	Std Dev	0.008	0.008	0.004

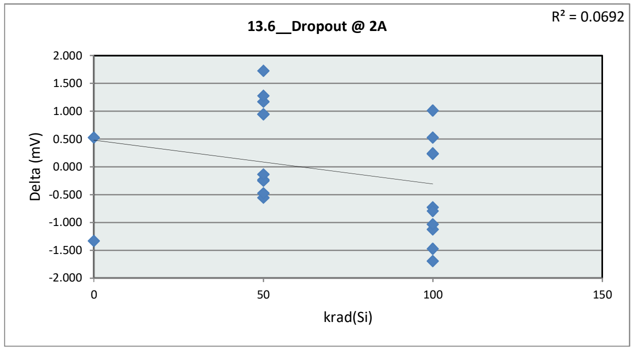


	13.4__Voutmax @ NoLoad		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	6.936	V	
Min Limit	6.664	V	
krad(Si)	0	50	100
LL	6.664	6.664	6.664
Min	6.777	6.760	6.758
Average	6.781	6.777	6.778
Max	6.786	6.790	6.792
UL	6.936	6.936	6.936

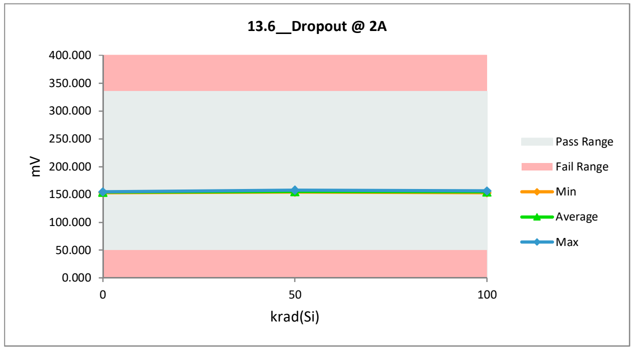


LDR Report
TPS7H1101-SP

		13.6__Dropout @ 2A		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	335	335	
	Min Limit	50	50	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	154.135	154.658	0.523
50	LDR_Bias_50K_Q1_3	154.628	155.569	0.941
50	LDR_Bias_50K_Q2_65	156.522	157.692	1.170
50	LDR_Bias_50K_Q3_30	155.141	156.417	1.276
50	LDR_Bias_50K_Q4_76	154.277	156.003	1.726
50	LDR_Bias_50K_Q5_46	153.836	154.782	0.946
50	LDR_UnBias_50K_Q1_4	154.809	154.576	-0.233
50	LDR_UnBias_50K_Q2_66	154.781	154.529	-0.252
50	LDR_UnBias_50K_Q3_31	154.933	154.377	-0.556
50	LDR_UnBias_50K_Q4_77	155.044	154.567	-0.477
50	LDR_UnBias_50K_Q5_47	155.297	155.163	-0.134
0	LDR_100K_Correlation_Q5_72	154.746	153.416	-1.330
100	LDR_Bias_100K_Q1_5	156.800	156.074	-0.726
100	LDR_Bias_100K_Q3_28	154.663	155.189	0.526
100	LDR_Bias_100K_Q5_45	152.854	153.086	0.232
100	LDR_Bias_100K_Q2_67	154.728	154.971	0.243
100	LDR_Bias_100K_Q2_68	155.292	156.302	1.010
100	LDR_UnBias_100K_Q1_6	155.142	154.348	-0.794
100	LDR_UnBias_100K_Q3_29	155.343	153.870	-1.473
100	LDR_UnBias_100K_Q5_69	155.191	154.065	-1.126
100	LDR_UnBias_100K_Q4_78	155.607	153.914	-1.693
100	LDR_UnBias_100K_Q4_79	154.519	153.489	-1.030
	Max	156.800	157.692	1.726
	Average	154.922	154.866	-0.056
	Min	152.854	153.086	-1.693
	Std Dev	0.820	1.122	0.984

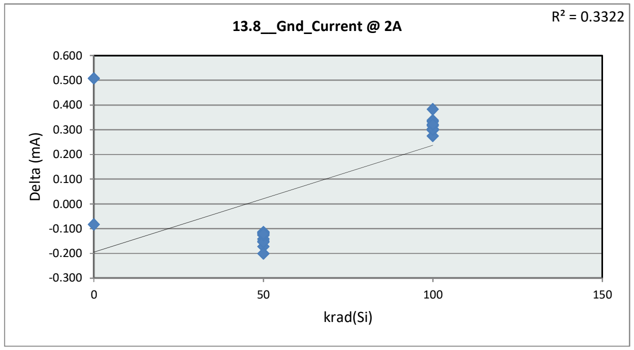


	13.6__Dropout @ 2A		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	335	mV	
Min Limit	50	mV	
krad(Si)	0	50	100
LL	50.000	50.000	50.000
Min	153.416	154.377	153.086
Average	154.037	155.368	154.531
Max	154.658	157.692	156.302
UL	335.000	335.000	335.000

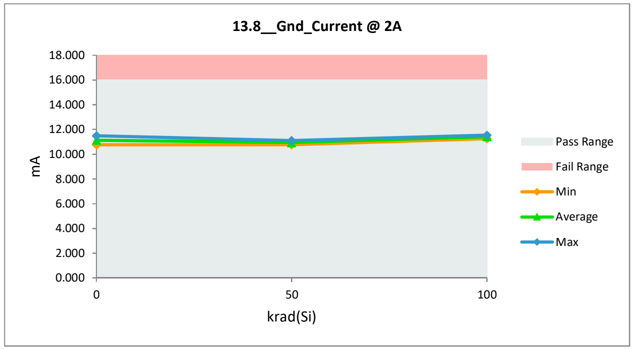


LDR Report
TPS7H1101-SP

krad(Si)	Serial #	Pre	Post	Delta
		13.8__Gnd_Current @ 2A		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	16	16	
	Min Limit	0.0005	0.0005	
0	LDR_50K_Correlation_Q5_73	10.843	10.760	-0.083
50	LDR_Bias_50K_Q1_3	11.127	10.985	-0.142
50	LDR_Bias_50K_Q2_65	11.205	11.055	-0.150
50	LDR_Bias_50K_Q3_30	11.018	10.905	-0.113
50	LDR_Bias_50K_Q4_76	11.063	10.945	-0.118
50	LDR_Bias_50K_Q5_46	11.006	10.834	-0.172
50	LDR_UnBias_50K_Q1_4	11.121	10.967	-0.154
50	LDR_UnBias_50K_Q2_66	11.222	11.106	-0.116
50	LDR_UnBias_50K_Q3_31	11.069	10.943	-0.126
50	LDR_UnBias_50K_Q4_77	11.002	10.881	-0.121
50	LDR_UnBias_50K_Q5_47	10.971	10.770	-0.201
0	LDR_100K_Correlation_Q5_72	10.992	11.500	0.508
100	LDR_Bias_100K_Q1_5	11.153	11.536	0.383
100	LDR_Bias_100K_Q3_28	11.185	11.483	0.298
100	LDR_Bias_100K_Q5_45	10.989	11.327	0.338
100	LDR_Bias_100K_Q2_67	11.244	11.519	0.275
100	LDR_Bias_100K_Q2_68	11.208	11.541	0.333
100	LDR_UnBias_100K_Q1_6	11.172	11.488	0.316
100	LDR_UnBias_100K_Q3_29	11.169	11.472	0.303
100	LDR_UnBias_100K_Q5_69	10.943	11.262	0.319
100	LDR_UnBias_100K_Q4_78	10.984	11.285	0.301
100	LDR_UnBias_100K_Q4_79	11.012	11.334	0.322
	Max	11.244	11.541	0.508
	Average	11.077	11.177	0.100
	Min	10.843	10.760	-0.201
	Std Dev	0.109	0.281	0.246

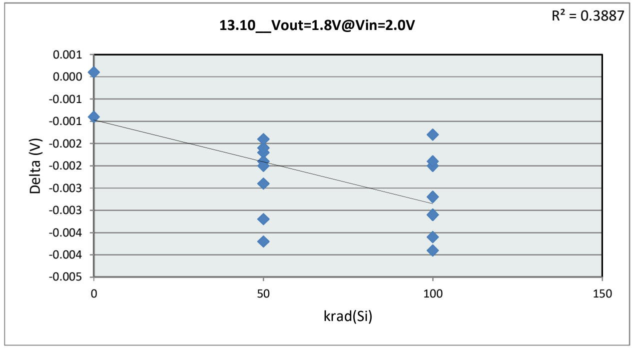


	0	50	100
	13.8__Gnd_Current @ 2A		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	16	mA	
Min Limit	0.0005	mA	
krad(Si)	0	50	100
LL	0.001	0.001	0.001
Min	10.760	10.770	11.262
Average	11.130	10.939	11.425
Max	11.500	11.106	11.541
UL	16.000	16.000	16.000

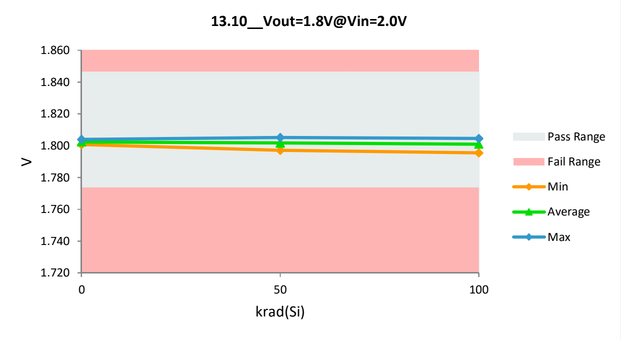


LDR Report
TPS7H1101-SP

		13.10__Vout=1.8V@Vin=2.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.805	1.804	-0.001
50	LDR_Bias_50K_Q1_3	1.802	1.801	-0.002
50	LDR_Bias_50K_Q2_65	1.806	1.804	-0.002
50	LDR_Bias_50K_Q3_30	1.805	1.802	-0.002
50	LDR_Bias_50K_Q4_76	1.803	1.801	-0.002
50	LDR_Bias_50K_Q5_46	1.802	1.801	-0.002
50	LDR_UnBias_50K_Q1_4	1.799	1.797	-0.002
50	LDR_UnBias_50K_Q2_66	1.806	1.803	-0.003
50	LDR_UnBias_50K_Q3_31	1.804	1.803	-0.002
50	LDR_UnBias_50K_Q4_77	1.805	1.801	-0.004
50	LDR_UnBias_50K_Q5_47	1.806	1.805	-0.001
0	LDR_100K_Correlation_Q5_72	1.801	1.801	0.000
100	LDR_Bias_100K_Q1_5	1.803	1.800	-0.003
100	LDR_Bias_100K_Q3_28	1.804	1.801	-0.003
100	LDR_Bias_100K_Q5_45	1.805	1.802	-0.003
100	LDR_Bias_100K_Q2_67	1.804	1.801	-0.003
100	LDR_Bias_100K_Q2_68	1.804	1.800	-0.004
100	LDR_UnBias_100K_Q1_6	1.805	1.803	-0.002
100	LDR_UnBias_100K_Q3_29	1.806	1.805	-0.001
100	LDR_UnBias_100K_Q5_69	1.799	1.796	-0.003
100	LDR_UnBias_100K_Q4_78	1.804	1.802	-0.002
100	LDR_UnBias_100K_Q4_79	1.804	1.801	-0.004
	Max	1.806	1.805	0.000
	Average	1.804	1.801	-0.002
	Min	1.799	1.796	-0.004
	Std Dev	0.002	0.002	0.001

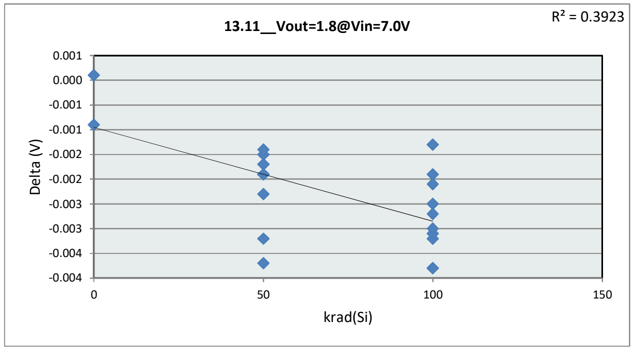


	13.10__Vout=1.8V@Vin=2.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.8462	V	
Min Limit	1.7738	V	
krad(Si)	0	50	100
LL	1.774	1.774	1.774
Min	1.801	1.797	1.796
Average	1.802	1.802	1.801
Max	1.804	1.805	1.805
UL	1.846	1.846	1.846

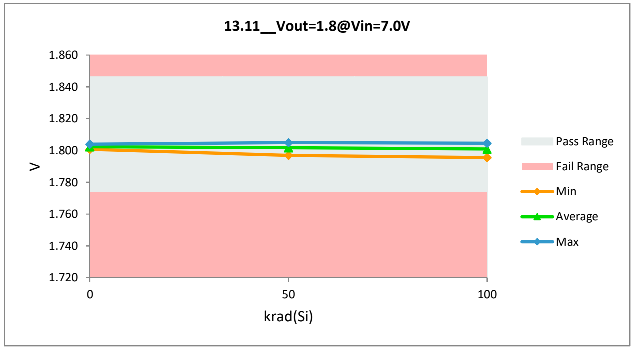


LDR Report
TPS7H1101-SP

		13.11__Vout=1.8@Vin=7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.805	1.804	-0.001
50	LDR_Bias_50K_Q1_3	1.802	1.801	-0.002
50	LDR_Bias_50K_Q2_65	1.806	1.804	-0.002
50	LDR_Bias_50K_Q3_30	1.805	1.802	-0.002
50	LDR_Bias_50K_Q4_76	1.803	1.801	-0.002
50	LDR_Bias_50K_Q5_46	1.802	1.800	-0.002
50	LDR_UnBias_50K_Q1_4	1.799	1.797	-0.002
50	LDR_UnBias_50K_Q2_66	1.806	1.803	-0.003
50	LDR_UnBias_50K_Q3_31	1.804	1.803	-0.002
50	LDR_UnBias_50K_Q4_77	1.805	1.801	-0.004
50	LDR_UnBias_50K_Q5_47	1.806	1.805	-0.001
0	LDR_100K_Correlation_Q5_72	1.801	1.801	0.000
100	LDR_Bias_100K_Q1_5	1.803	1.800	-0.003
100	LDR_Bias_100K_Q3_28	1.804	1.801	-0.002
100	LDR_Bias_100K_Q5_45	1.805	1.802	-0.003
100	LDR_Bias_100K_Q2_67	1.803	1.801	-0.003
100	LDR_Bias_100K_Q2_68	1.804	1.800	-0.004
100	LDR_UnBias_100K_Q1_6	1.805	1.803	-0.002
100	LDR_UnBias_100K_Q3_29	1.806	1.804	-0.001
100	LDR_UnBias_100K_Q5_69	1.798	1.796	-0.003
100	LDR_UnBias_100K_Q4_78	1.804	1.802	-0.002
100	LDR_UnBias_100K_Q4_79	1.804	1.800	-0.004
	Max	1.806	1.805	0.000
	Average	1.804	1.801	-0.002
	Min	1.798	1.796	-0.004
	Std Dev	0.002	0.002	0.001

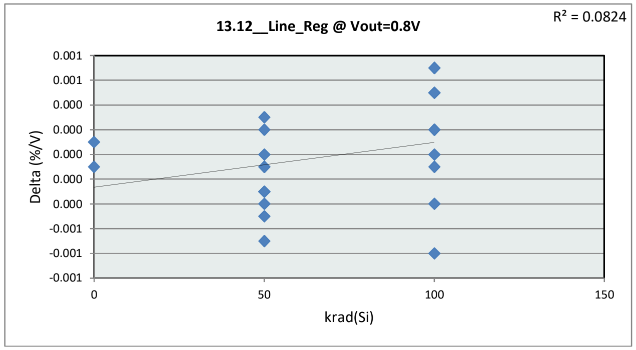


	13.11__Vout=1.8@Vin=7.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.8462	V	
Min Limit	1.7738	V	
krad(Si)	0	50	100
LL	1.774	1.774	1.774
Min	1.801	1.797	1.796
Average	1.802	1.802	1.801
Max	1.804	1.805	1.805
UL	1.846	1.846	1.846

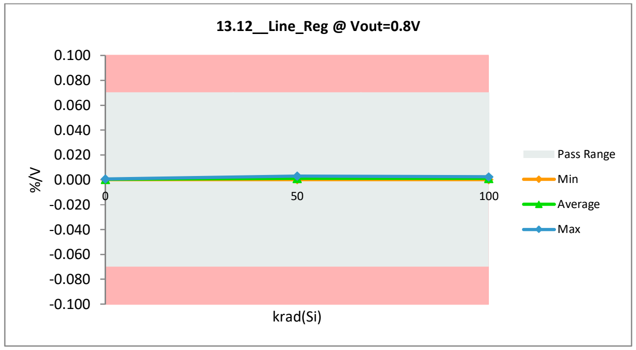


LDR Report
TPS7H1101-SP

		13.12__Line_Reg @ Vout=0.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.001	0.001	0.000
50	LDR_Bias_50K_Q1_3	0.000	0.001	0.000
50	LDR_Bias_50K_Q2_65	0.002	0.001	0.000
50	LDR_Bias_50K_Q3_30	0.000	0.001	0.000
50	LDR_Bias_50K_Q4_76	0.001	0.001	0.000
50	LDR_Bias_50K_Q5_46	0.003	0.003	0.000
50	LDR_UnBias_50K_Q1_4	0.001	0.000	0.000
50	LDR_UnBias_50K_Q2_66	0.002	0.002	0.000
50	LDR_UnBias_50K_Q3_31	0.001	0.000	-0.001
50	LDR_UnBias_50K_Q4_77	0.001	0.001	0.000
50	LDR_UnBias_50K_Q5_47	0.002	0.002	0.000
0	LDR_100K_Correlation_Q5_72	0.000	0.000	0.000
100	LDR_Bias_100K_Q1_5	0.001	0.002	0.001
100	LDR_Bias_100K_Q3_28	0.001	0.000	-0.001
100	LDR_Bias_100K_Q5_45	0.001	0.000	0.000
100	LDR_Bias_100K_Q2_67	0.002	0.002	0.001
100	LDR_Bias_100K_Q2_68	0.000	0.001	0.000
100	LDR_UnBias_100K_Q1_6	0.000	0.001	0.001
100	LDR_UnBias_100K_Q3_29	0.001	0.001	0.000
100	LDR_UnBias_100K_Q5_69	0.000	0.000	0.000
100	LDR_UnBias_100K_Q4_78	0.001	0.001	0.000
100	LDR_UnBias_100K_Q4_79	0.001	0.001	0.001
	Max	0.003	0.003	0.001
	Average	0.001	0.001	0.000
	Min	0.000	0.000	-0.001
	Std Dev	0.001	0.001	0.000

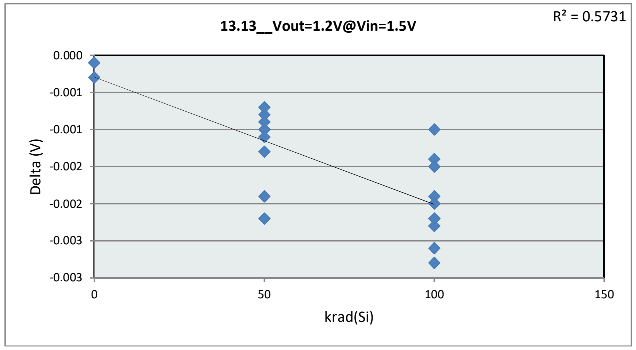


	13.12__Line_Reg @ Vout=0.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.07	%/V	
Min Limit	-0.07	%/V	
krad(Si)	0	50	100
LL	-0.070	-0.070	-0.070
Min	0.000	0.000	0.000
Average	0.000	0.001	0.001
Max	0.001	0.003	0.002
UL	0.070	0.070	0.070

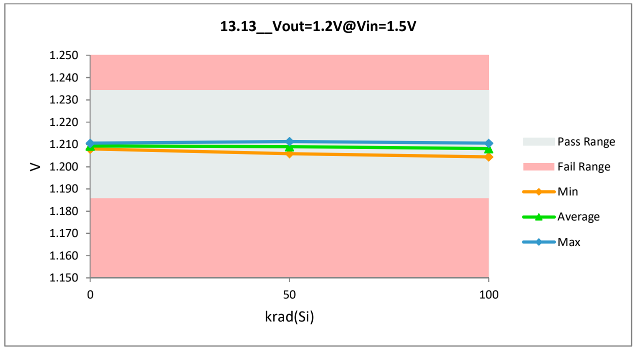


LDR Report
TPS7H1101-SP

		13.13__Vout=1.2V@Vin=1.5V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.211	1.211	0.000
50	LDR_Bias_50K_Q1_3	1.209	1.208	-0.001
50	LDR_Bias_50K_Q2_65	1.212	1.211	-0.001
50	LDR_Bias_50K_Q3_30	1.211	1.209	-0.001
50	LDR_Bias_50K_Q4_76	1.209	1.208	-0.001
50	LDR_Bias_50K_Q5_46	1.209	1.208	-0.001
50	LDR_UnBias_50K_Q1_4	1.207	1.206	-0.001
50	LDR_UnBias_50K_Q2_66	1.212	1.210	-0.002
50	LDR_UnBias_50K_Q3_31	1.211	1.209	-0.001
50	LDR_UnBias_50K_Q4_77	1.211	1.209	-0.002
50	LDR_UnBias_50K_Q5_47	1.212	1.211	-0.001
0	LDR_100K_Correlation_Q5_72	1.208	1.208	0.000
100	LDR_Bias_100K_Q1_5	1.210	1.208	-0.002
100	LDR_Bias_100K_Q3_28	1.210	1.208	-0.002
100	LDR_Bias_100K_Q5_45	1.211	1.209	-0.002
100	LDR_Bias_100K_Q2_67	1.210	1.208	-0.002
100	LDR_Bias_100K_Q2_68	1.210	1.207	-0.003
100	LDR_UnBias_100K_Q1_6	1.211	1.210	-0.001
100	LDR_UnBias_100K_Q3_29	1.212	1.211	-0.001
100	LDR_UnBias_100K_Q5_69	1.207	1.204	-0.002
100	LDR_UnBias_100K_Q4_78	1.210	1.209	-0.002
100	LDR_UnBias_100K_Q4_79	1.210	1.208	-0.003
	Max	1.212	1.211	0.000
	Average	1.210	1.209	-0.001
	Min	1.207	1.204	-0.003
	Std Dev	0.001	0.002	0.001

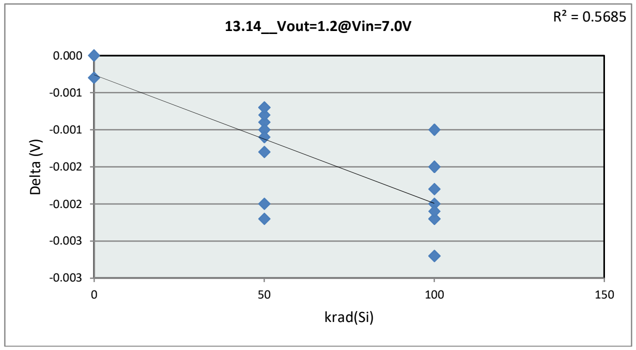


	13.13__Vout=1.2V@Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.2342	V	
Min Limit	1.1858	V	
krad(Si)	0	50	100
LL	1.186	1.186	1.186
Min	1.208	1.206	1.204
Average	1.209	1.209	1.208
Max	1.211	1.211	1.211
UL	1.234	1.234	1.234

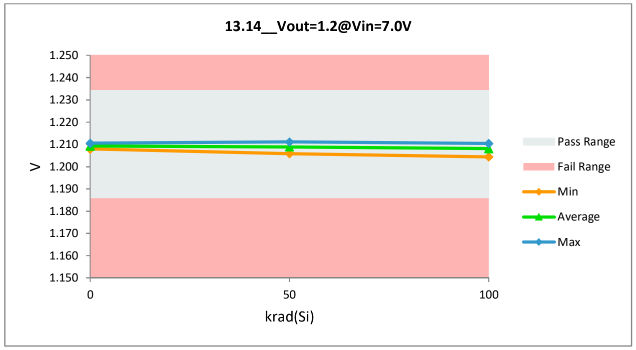


LDR Report
TPS7H1101-SP

		13.14__Vout=1.2@Vin=7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.211	1.211	0.000
50	LDR_Bias_50K_Q1_3	1.209	1.208	-0.001
50	LDR_Bias_50K_Q2_65	1.212	1.211	-0.001
50	LDR_Bias_50K_Q3_30	1.211	1.209	-0.001
50	LDR_Bias_50K_Q4_76	1.209	1.208	-0.001
50	LDR_Bias_50K_Q5_46	1.209	1.208	-0.001
50	LDR_UnBias_50K_Q1_4	1.207	1.206	-0.001
50	LDR_UnBias_50K_Q2_66	1.211	1.209	-0.002
50	LDR_UnBias_50K_Q3_31	1.211	1.209	-0.001
50	LDR_UnBias_50K_Q4_77	1.211	1.209	-0.002
50	LDR_UnBias_50K_Q5_47	1.212	1.211	-0.001
0	LDR_100K_Correlation_Q5_72	1.208	1.208	0.000
100	LDR_Bias_100K_Q1_5	1.210	1.207	-0.002
100	LDR_Bias_100K_Q3_28	1.210	1.208	-0.002
100	LDR_Bias_100K_Q5_45	1.211	1.209	-0.002
100	LDR_Bias_100K_Q2_67	1.210	1.208	-0.002
100	LDR_Bias_100K_Q2_68	1.210	1.207	-0.003
100	LDR_UnBias_100K_Q1_6	1.211	1.209	-0.002
100	LDR_UnBias_100K_Q3_29	1.211	1.210	-0.001
100	LDR_UnBias_100K_Q5_69	1.207	1.204	-0.002
100	LDR_UnBias_100K_Q4_78	1.210	1.209	-0.002
100	LDR_UnBias_100K_Q4_79	1.210	1.208	-0.003
	Max	1.212	1.211	0.000
	Average	1.210	1.209	-0.001
	Min	1.207	1.204	-0.003
	Std Dev	0.001	0.002	0.001

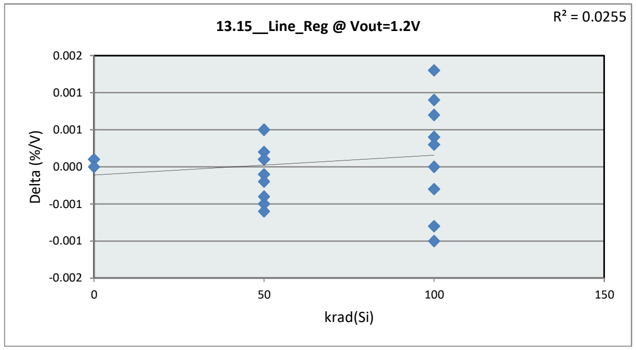


	13.14__Vout=1.2@Vin=7.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.2342	V	
Min Limit	1.1858	V	
krad(Si)	0	50	100
LL	1.186	1.186	1.186
Min	1.208	1.206	1.204
Average	1.209	1.209	1.208
Max	1.211	1.211	1.210
UL	1.234	1.234	1.234

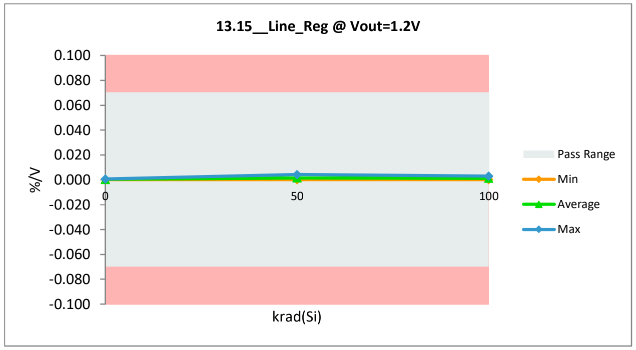


LDR Report
TPS7H1101-SP

		13.15__Line_Reg @ Vout=1.2V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%/V	%/V	
	Max Limit	0.07	0.07	
	Min Limit	-0.07	-0.07	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.001	0.001	0.000
50	LDR_Bias_50K_Q1_3	0.000	0.000	0.000
50	LDR_Bias_50K_Q2_65	0.002	0.002	-0.001
50	LDR_Bias_50K_Q3_30	0.000	0.000	0.000
50	LDR_Bias_50K_Q4_76	0.001	0.001	0.000
50	LDR_Bias_50K_Q5_46	0.004	0.004	0.000
50	LDR_UnBias_50K_Q1_4	0.001	0.000	-0.001
50	LDR_UnBias_50K_Q2_66	0.003	0.003	0.000
50	LDR_UnBias_50K_Q3_31	0.001	0.001	0.000
50	LDR_UnBias_50K_Q4_77	0.002	0.001	0.000
50	LDR_UnBias_50K_Q5_47	0.002	0.003	0.000
0	LDR_100K_Correlation_Q5_72	0.000	0.000	0.000
100	LDR_Bias_100K_Q1_5	0.001	0.002	0.000
100	LDR_Bias_100K_Q3_28	0.001	0.000	-0.001
100	LDR_Bias_100K_Q5_45	0.001	0.000	-0.001
100	LDR_Bias_100K_Q2_67	0.002	0.003	0.001
100	LDR_Bias_100K_Q2_68	0.000	0.002	0.001
100	LDR_UnBias_100K_Q1_6	0.001	0.001	0.000
100	LDR_UnBias_100K_Q3_29	0.001	0.001	0.000
100	LDR_UnBias_100K_Q5_69	0.000	0.000	0.000
100	LDR_UnBias_100K_Q4_78	0.001	0.001	0.000
100	LDR_UnBias_100K_Q4_79	0.001	0.002	0.001
	Max	0.004	0.004	0.001
	Average	0.001	0.001	0.000
	Min	0.000	0.000	-0.001
	Std Dev	0.001	0.001	0.001



	13.15__Line_Reg @ Vout=1.2V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.07	%/V	
Min Limit	-0.07	%/V	
krad(Si)	0	50	100
LL	-0.070	-0.070	-0.070
Min	0.000	0.000	0.000
Average	0.000	0.002	0.001
Max	0.001	0.004	0.003
UL	0.070	0.070	0.070



LDR Report
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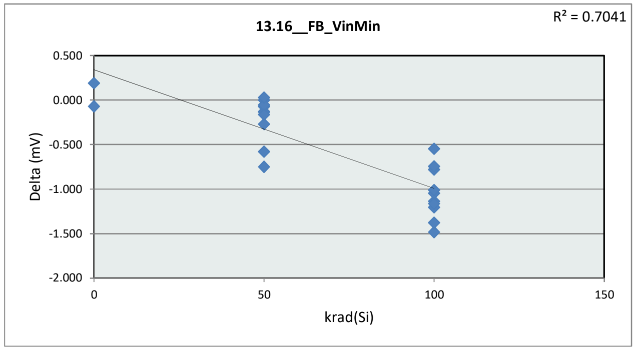
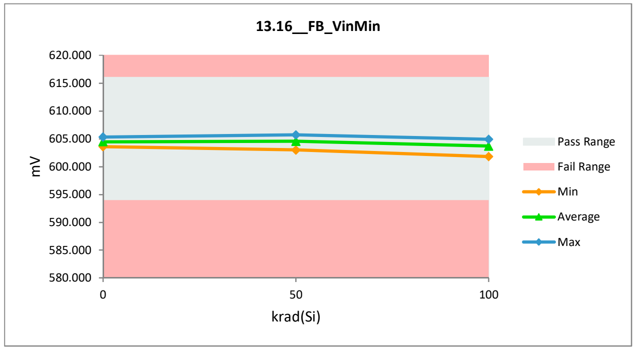
		13.16__FB_VinMin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	605.143	605.333	0.190
50	LDR_Bias_50K_Q1_3	604.252	604.123	-0.129
50	LDR_Bias_50K_Q2_65	605.517	605.444	-0.073
50	LDR_Bias_50K_Q3_30	605.039	604.767	-0.272
50	LDR_Bias_50K_Q4_76	604.305	604.169	-0.136
50	LDR_Bias_50K_Q5_46	604.190	604.188	-0.002
50	LDR_UnBias_50K_Q1_4	603.040	602.985	-0.055
50	LDR_UnBias_50K_Q2_66	605.480	604.900	-0.580
50	LDR_UnBias_50K_Q3_31	604.969	604.806	-0.163
50	LDR_UnBias_50K_Q4_77	605.096	604.346	-0.750
50	LDR_UnBias_50K_Q5_47	605.687	605.716	0.029
0	LDR_100K_Correlation_Q5_72	603.670	603.599	-0.071
100	LDR_Bias_100K_Q1_5	604.591	603.455	-1.136
100	LDR_Bias_100K_Q3_28	604.754	603.706	-1.048
100	LDR_Bias_100K_Q5_45	605.250	604.046	-1.204
100	LDR_Bias_100K_Q2_67	604.670	603.660	-1.010
100	LDR_Bias_100K_Q2_68	604.786	603.302	-1.484
100	LDR_UnBias_100K_Q1_6	605.210	604.429	-0.781
100	LDR_UnBias_100K_Q3_29	605.455	604.908	-0.547
100	LDR_UnBias_100K_Q5_69	602.979	601.816	-1.163
100	LDR_UnBias_100K_Q4_78	604.834	604.089	-0.745
100	LDR_UnBias_100K_Q4_79	604.881	603.504	-1.377
	Max	605.687	605.716	0.190
	Average	604.718	604.150	-0.568
	Min	602.979	601.816	-1.484
	Std Dev	0.736	0.894	0.523



	13.16__FB_VinMin		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	616	mV	
Min Limit	594	mV	
krad(Si)	0	50	100
LL	594.000	594.000	594.000
Min	603.599	602.985	601.816
Average	604.466	604.544	603.692
Max	605.333	605.716	604.908
UL	616.000	616.000	616.000



LDR Report
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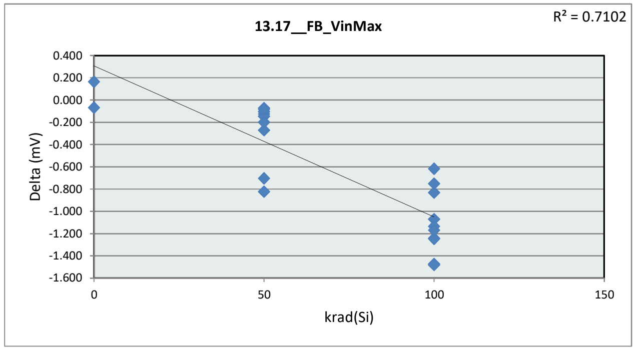
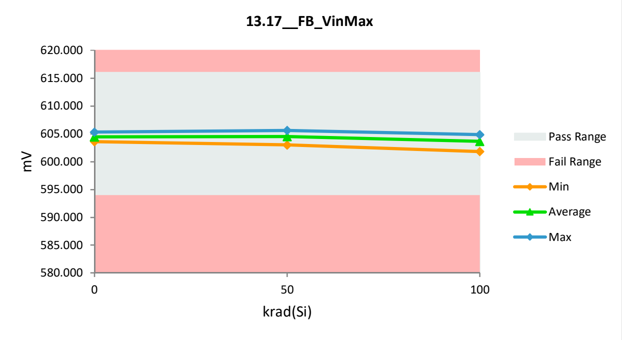
		13.17__FB_VinMax		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	616	616	
	Min Limit	594	594	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	605.142	605.306	0.164
50	LDR_Bias_50K_Q1_3	604.249	604.124	-0.125
50	LDR_Bias_50K_Q2_65	605.517	605.370	-0.147
50	LDR_Bias_50K_Q3_30	605.038	604.768	-0.270
50	LDR_Bias_50K_Q4_76	604.307	604.202	-0.105
50	LDR_Bias_50K_Q5_46	604.186	604.040	-0.146
50	LDR_UnBias_50K_Q1_4	603.043	602.971	-0.072
50	LDR_UnBias_50K_Q2_66	605.478	604.775	-0.703
50	LDR_UnBias_50K_Q3_31	604.974	604.775	-0.199
50	LDR_UnBias_50K_Q4_77	605.095	604.273	-0.822
50	LDR_UnBias_50K_Q5_47	605.688	605.606	-0.082
0	LDR_100K_Correlation_Q5_72	603.666	603.597	-0.069
100	LDR_Bias_100K_Q1_5	604.588	603.346	-1.242
100	LDR_Bias_100K_Q3_28	604.757	603.687	-1.070
100	LDR_Bias_100K_Q5_45	605.251	604.005	-1.246
100	LDR_Bias_100K_Q2_67	604.674	603.539	-1.135
100	LDR_Bias_100K_Q2_68	604.787	603.315	-1.472
100	LDR_UnBias_100K_Q1_6	605.214	604.383	-0.831
100	LDR_UnBias_100K_Q3_29	605.453	604.836	-0.617
100	LDR_UnBias_100K_Q5_69	602.982	601.813	-1.169
100	LDR_UnBias_100K_Q4_78	604.837	604.086	-0.751
100	LDR_UnBias_100K_Q4_79	604.881	603.400	-1.481
	Max	605.688	605.606	0.164
	Average	604.719	604.101	-0.618
	Min	602.982	601.813	-1.481
	Std Dev	0.736	0.881	0.530

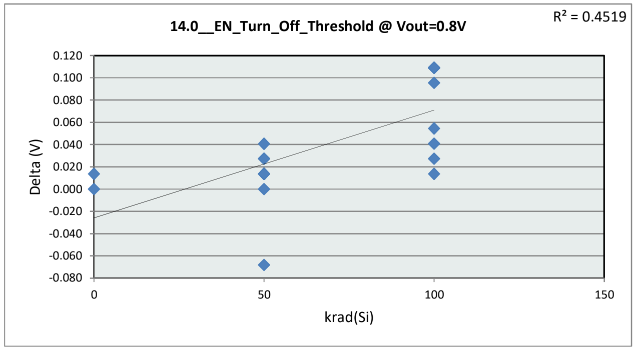


	13.17__FB_VinMax		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	616	mV	
Min Limit	594	mV	
krad(Si)	0	50	100
LL	594.000	594.000	594.000
Min	603.597	602.971	601.813
Average	604.452	604.490	603.641
Max	605.306	605.606	604.836
UL	616.000	616.000	616.000

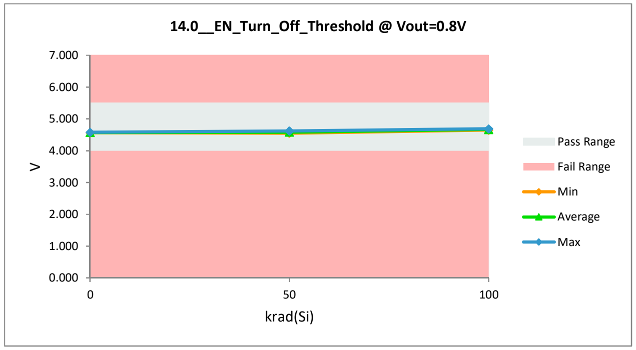


LDR Report
TPS7H1101-SP

krad(Si)	Serial #	Pre	Post	Delta
		14.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	5.5	5.5	
	Min Limit	4	4	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	4.579	4.579	0.000
50	LDR_Bias_50K_Q1_3	4.551	4.565	0.014
50	LDR_Bias_50K_Q2_65	4.551	4.565	0.014
50	LDR_Bias_50K_Q3_30	4.565	4.579	0.014
50	LDR_Bias_50K_Q4_76	4.620	4.551	-0.068
50	LDR_Bias_50K_Q5_46	4.565	4.579	0.014
50	LDR_UnBias_50K_Q1_4	4.579	4.579	0.000
50	LDR_UnBias_50K_Q2_66	4.579	4.606	0.027
50	LDR_UnBias_50K_Q3_31	4.579	4.592	0.014
50	LDR_UnBias_50K_Q4_77	4.579	4.620	0.041
50	LDR_UnBias_50K_Q5_47	4.579	4.606	0.027
0	LDR_100K_Correlation_Q5_72	4.551	4.565	0.014
100	LDR_Bias_100K_Q1_5	4.551	4.661	0.109
100	LDR_Bias_100K_Q3_28	4.579	4.688	0.109
100	LDR_Bias_100K_Q5_45	4.647	4.674	0.027
100	LDR_Bias_100K_Q2_67	4.538	4.647	0.109
100	LDR_Bias_100K_Q2_68	4.633	4.674	0.041
100	LDR_UnBias_100K_Q1_6	4.633	4.647	0.014
100	LDR_UnBias_100K_Q3_29	4.551	4.647	0.095
100	LDR_UnBias_100K_Q5_69	4.565	4.674	0.109
100	LDR_UnBias_100K_Q4_78	4.633	4.688	0.055
100	LDR_UnBias_100K_Q4_79	4.565	4.674	0.109
	Max	4.647	4.688	0.109
	Average	4.581	4.621	0.040
	Min	4.538	4.551	-0.068
	Std Dev	0.032	0.047	0.047

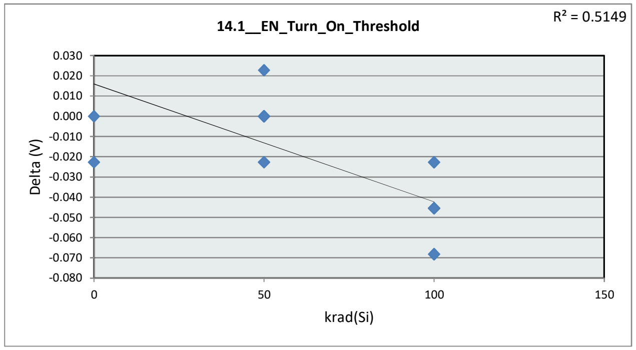


	14.0__EN_Turn_Off_Threshold @ Vout=0.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	5.5	V	
Min Limit	4	V	
krad(Si)	0	50	100
LL	4.000	4.000	4.000
Min	4.565	4.552	4.647
Average	4.572	4.584	4.667
Max	4.579	4.620	4.688
UL	5.500	5.500	5.500

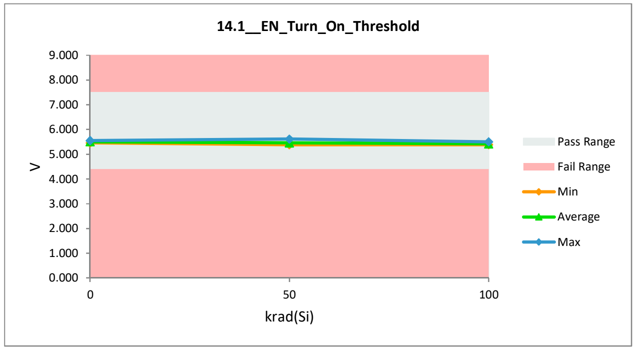


LDR Report
TPS7H1101-SP

		14.1__EN_Turn_On_Threshold		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	7.5	7.5	
	Min Limit	4.4	4.4	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	5.549	5.549	0.000
50	LDR_Bias_50K_Q1_3	5.458	5.458	0.000
50	LDR_Bias_50K_Q2_65	5.481	5.481	0.000
50	LDR_Bias_50K_Q3_30	5.458	5.458	0.000
50	LDR_Bias_50K_Q4_76	5.458	5.436	-0.023
50	LDR_Bias_50K_Q5_46	5.504	5.504	0.000
50	LDR_UnBias_50K_Q1_4	5.390	5.413	0.023
50	LDR_UnBias_50K_Q2_66	5.436	5.436	0.000
50	LDR_UnBias_50K_Q3_31	5.413	5.413	0.000
50	LDR_UnBias_50K_Q4_77	5.390	5.390	0.000
50	LDR_UnBias_50K_Q5_47	5.640	5.617	-0.023
0	LDR_100K_Correlation_Q5_72	5.481	5.458	-0.023
100	LDR_Bias_100K_Q1_5	5.481	5.413	-0.068
100	LDR_Bias_100K_Q3_28	5.436	5.390	-0.046
100	LDR_Bias_100K_Q5_45	5.481	5.436	-0.045
100	LDR_Bias_100K_Q2_67	5.458	5.413	-0.045
100	LDR_Bias_100K_Q2_68	5.481	5.413	-0.068
100	LDR_UnBias_100K_Q1_6	5.436	5.390	-0.046
100	LDR_UnBias_100K_Q3_29	5.436	5.413	-0.023
100	LDR_UnBias_100K_Q5_69	5.549	5.504	-0.046
100	LDR_UnBias_100K_Q4_78	5.413	5.390	-0.023
100	LDR_UnBias_100K_Q4_79	5.481	5.413	-0.068
	Max	5.640	5.617	0.023
	Average	5.469	5.445	-0.024
	Min	5.390	5.390	-0.068
	Std Dev	0.057	0.057	0.027

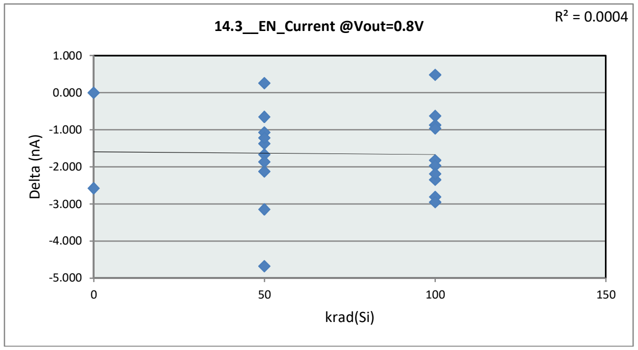


	14.1__EN_Turn_On_Threshold		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	7.5	V	
Min Limit	4.4	V	
krad(Si)	0	50	100
LL	4.400	4.400	4.400
Min	5.458	5.390	5.390
Average	5.504	5.460	5.417
Max	5.549	5.617	5.504
UL	7.500	7.500	7.500

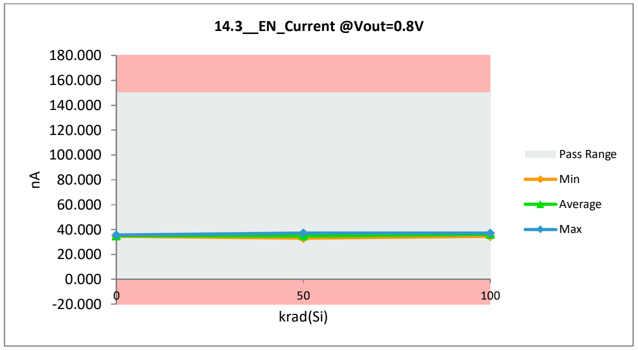


LDR Report
TPS7H1101-SP

		14.3__EN_Current @Vout=0.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	37.036	34.457	-2.579
50	LDR_Bias_50K_Q1_3	37.776	36.403	-1.373
50	LDR_Bias_50K_Q2_65	35.913	34.840	-1.073
50	LDR_Bias_50K_Q3_30	36.899	34.777	-2.122
50	LDR_Bias_50K_Q4_76	37.800	33.120	-4.680
50	LDR_Bias_50K_Q5_46	36.641	33.495	-3.146
50	LDR_UnBias_50K_Q1_4	37.776	37.123	-0.653
50	LDR_UnBias_50K_Q2_66	35.584	33.917	-1.667
50	LDR_UnBias_50K_Q3_31	35.521	34.301	-1.220
50	LDR_UnBias_50K_Q4_77	36.476	34.613	-1.863
50	LDR_UnBias_50K_Q5_47	36.015	36.270	0.255
0	LDR_100K_Correlation_Q5_72	35.670	35.670	0.000
100	LDR_Bias_100K_Q1_5	37.854	35.044	-2.810
100	LDR_Bias_100K_Q3_28	37.847	36.022	-1.825
100	LDR_Bias_100K_Q5_45	37.463	34.513	-2.950
100	LDR_Bias_100K_Q2_67	37.674	36.796	-0.878
100	LDR_Bias_100K_Q2_68	37.651	37.023	-0.628
100	LDR_UnBias_100K_Q1_6	38.543	36.577	-1.966
100	LDR_UnBias_100K_Q3_29	38.019	35.670	-2.349
100	LDR_UnBias_100K_Q5_69	37.510	36.546	-0.964
100	LDR_UnBias_100K_Q4_78	38.653	36.460	-2.193
100	LDR_UnBias_100K_Q4_79	35.936	36.413	0.477
	Max	38.653	37.123	0.477
	Average	37.103	35.457	-1.646
	Min	35.521	33.120	-4.680
	Std Dev	0.981	1.195	1.216



	14.3__EN_Current @Vout=0.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	150	nA	
Min Limit	-0.0001	nA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	34.457	33.120	34.513
Average	35.063	34.886	36.106
Max	35.670	37.123	37.023
UL	150.000	150.000	150.000



LDR Report
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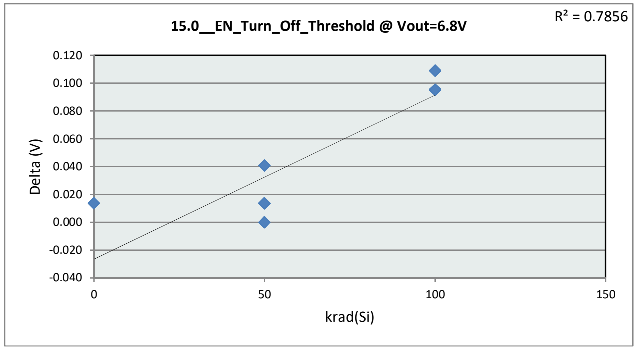
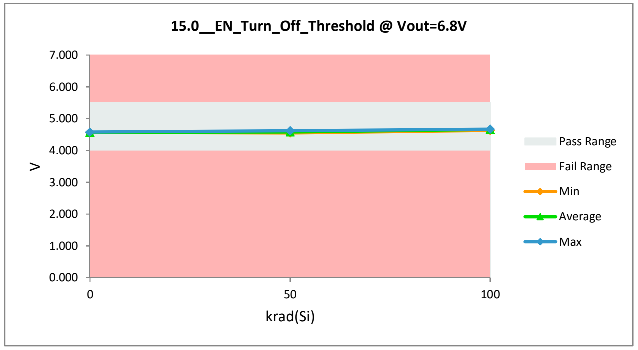
		15.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	5.5	5.5	
	Min Limit	4	4	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	4.565	4.579	0.014
50	LDR_Bias_50K_Q1_3	4.551	4.565	0.014
50	LDR_Bias_50K_Q2_65	4.551	4.565	0.014
50	LDR_Bias_50K_Q3_30	4.565	4.565	0.000
50	LDR_Bias_50K_Q4_76	4.551	4.551	0.000
50	LDR_Bias_50K_Q5_46	4.565	4.579	0.014
50	LDR_UnBias_50K_Q1_4	4.565	4.579	0.014
50	LDR_UnBias_50K_Q2_66	4.565	4.606	0.041
50	LDR_UnBias_50K_Q3_31	4.565	4.579	0.014
50	LDR_UnBias_50K_Q4_77	4.579	4.620	0.041
50	LDR_UnBias_50K_Q5_47	4.592	4.606	0.014
0	LDR_100K_Correlation_Q5_72	4.551	4.565	0.014
100	LDR_Bias_100K_Q1_5	4.551	4.661	0.109
100	LDR_Bias_100K_Q3_28	4.579	4.674	0.095
100	LDR_Bias_100K_Q5_45	4.579	4.674	0.095
100	LDR_Bias_100K_Q2_67	4.538	4.633	0.095
100	LDR_Bias_100K_Q2_68	4.565	4.661	0.095
100	LDR_UnBias_100K_Q1_6	4.551	4.647	0.095
100	LDR_UnBias_100K_Q3_29	4.551	4.647	0.095
100	LDR_UnBias_100K_Q5_69	4.565	4.674	0.109
100	LDR_UnBias_100K_Q4_78	4.579	4.674	0.095
100	LDR_UnBias_100K_Q4_79	4.551	4.661	0.109
	Max	4.592	4.674	0.109
	Average	4.563	4.617	0.054
	Min	4.538	4.551	0.000
	Std Dev	0.013	0.045	0.044



	15.0__EN_Turn_Off_Threshold @ Vout=6.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	5.5	V	
Min Limit	4	V	
krad(Si)	0	50	100
LL	4.000	4.000	4.000
Min	4.565	4.552	4.633
Average	4.572	4.581	4.661
Max	4.579	4.620	4.674
UL	5.500	5.500	5.500



LDR Report
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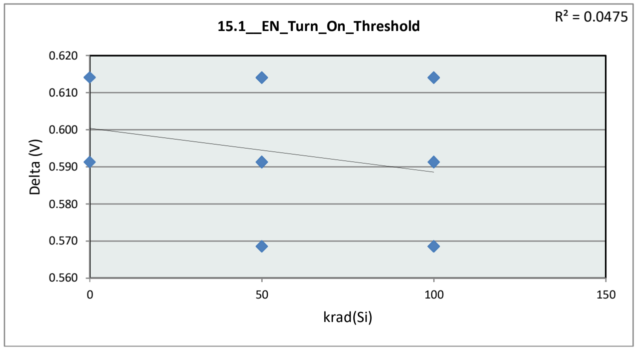
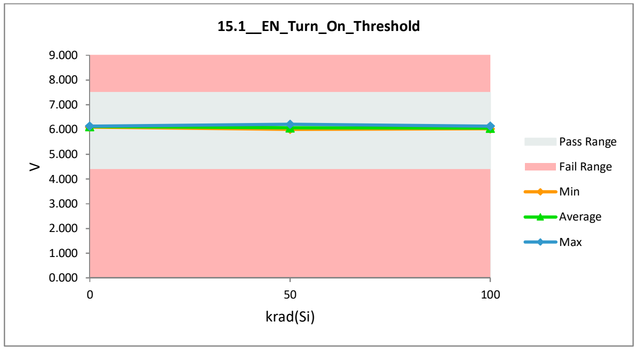
		15.1__EN_Turn_On_Threshold		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		7.5	7.5	
Min Limit		4.4	4.4	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	5.549	6.141	0.591
50	LDR_Bias_50K_Q1_3	5.458	6.072	0.614
50	LDR_Bias_50K_Q2_65	5.481	6.095	0.614
50	LDR_Bias_50K_Q3_30	5.458	6.072	0.614
50	LDR_Bias_50K_Q4_76	5.458	6.049	0.591
50	LDR_Bias_50K_Q5_46	5.504	6.095	0.591
50	LDR_UnBias_50K_Q1_4	5.413	6.004	0.591
50	LDR_UnBias_50K_Q2_66	5.458	6.027	0.569
50	LDR_UnBias_50K_Q3_31	5.413	6.004	0.591
50	LDR_UnBias_50K_Q4_77	5.413	6.004	0.591
50	LDR_UnBias_50K_Q5_47	5.640	6.209	0.569
0	LDR_100K_Correlation_Q5_72	5.481	6.095	0.614
100	LDR_Bias_100K_Q1_5	5.481	6.049	0.569
100	LDR_Bias_100K_Q3_28	5.436	6.049	0.614
100	LDR_Bias_100K_Q5_45	5.481	6.072	0.591
100	LDR_Bias_100K_Q2_67	5.458	6.049	0.591
100	LDR_Bias_100K_Q2_68	5.481	6.049	0.569
100	LDR_UnBias_100K_Q1_6	5.458	6.027	0.569
100	LDR_UnBias_100K_Q3_29	5.436	6.049	0.614
100	LDR_UnBias_100K_Q5_69	5.572	6.141	0.569
100	LDR_UnBias_100K_Q4_78	5.413	6.027	0.614
100	LDR_UnBias_100K_Q4_79	5.481	6.072	0.591
	Max	5.640	6.209	0.614
	Average	5.474	6.066	0.592
	Min	5.413	6.004	0.569
	Std Dev	0.055	0.050	0.018

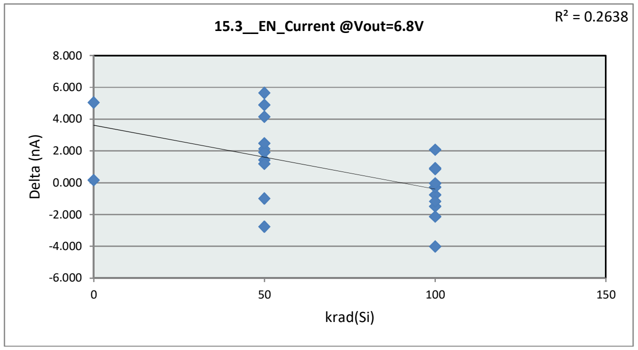


	15.1__EN_Turn_On_Threshold		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	7.5	V	
Min Limit	4.4	V	
krad(Si)	0	50	100
LL	4.400	4.400	4.400
Min	6.095	6.004	6.027
Average	6.118	6.063	6.059
Max	6.141	6.209	6.141
UL	7.500	7.500	7.500

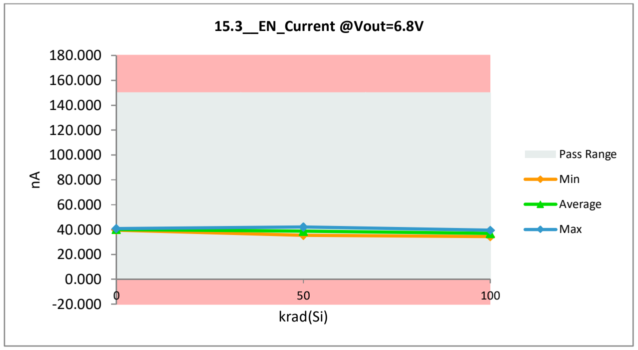


LDR Report
TPS7H1101-SP

		15.3__EN_Current @Vout=6.8V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	150	150	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	39.278	39.446	0.168
50	LDR_Bias_50K_Q1_3	38.207	35.446	-2.761
50	LDR_Bias_50K_Q2_65	36.383	37.815	1.432
50	LDR_Bias_50K_Q3_30	36.422	38.542	2.120
50	LDR_Bias_50K_Q4_76	38.543	37.557	-0.986
50	LDR_Bias_50K_Q5_46	35.756	39.910	4.154
50	LDR_UnBias_50K_Q1_4	36.790	37.979	1.189
50	LDR_UnBias_50K_Q2_66	37.134	42.020	4.886
50	LDR_UnBias_50K_Q3_31	35.631	37.549	1.918
50	LDR_UnBias_50K_Q4_77	35.866	38.338	2.472
50	LDR_UnBias_50K_Q5_47	36.210	41.856	5.646
0	LDR_100K_Correlation_Q5_72	35.694	40.746	5.052
100	LDR_Bias_100K_Q1_5	38.035	36.551	-1.484
100	LDR_Bias_100K_Q3_28	38.082	37.325	-0.757
100	LDR_Bias_100K_Q5_45	35.811	34.642	-1.169
100	LDR_Bias_100K_Q2_67	36.915	37.834	0.919
100	LDR_Bias_100K_Q2_68	38.285	38.006	-0.279
100	LDR_UnBias_100K_Q1_6	38.512	39.367	0.855
100	LDR_UnBias_100K_Q3_29	36.445	34.322	-2.123
100	LDR_UnBias_100K_Q5_69	38.332	34.322	-4.010
100	LDR_UnBias_100K_Q4_78	37.674	37.638	-0.036
100	LDR_UnBias_100K_Q4_79	36.202	38.279	2.077
	Max	39.278	42.020	5.646
	Average	37.100	37.977	0.876
	Min	35.631	34.322	-4.010
	Std Dev	1.142	2.123	2.570

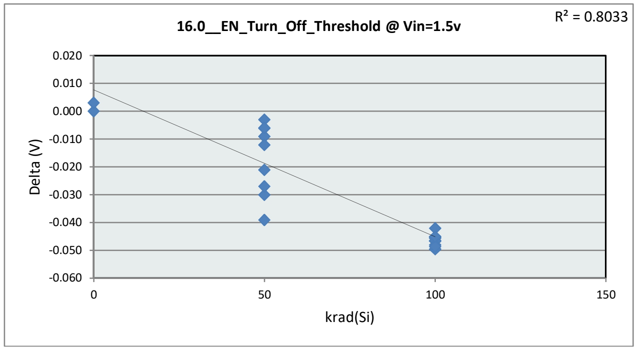


	15.3__EN_Current @Vout=6.8V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	150	nA	
Min Limit	-0.0001	nA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	39.446	35.446	34.322
Average	40.096	38.701	36.829
Max	40.746	42.020	39.367
UL	150.000	150.000	150.000

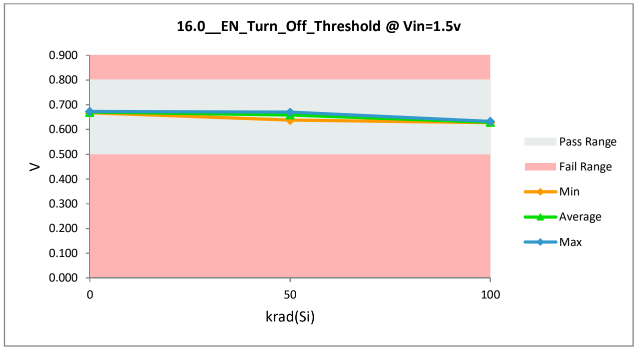


LDR Report
TPS7H1101-SP

		16.0__EN_Turn_Off_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.8	0.8	
	Min Limit	0.5	0.5	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.673	0.673	0.000
50	LDR_Bias_50K_Q1_3	0.676	0.670	-0.006
50	LDR_Bias_50K_Q2_65	0.673	0.670	-0.003
50	LDR_Bias_50K_Q3_30	0.679	0.670	-0.009
50	LDR_Bias_50K_Q4_76	0.676	0.667	-0.009
50	LDR_Bias_50K_Q5_46	0.670	0.664	-0.006
50	LDR_UnBias_50K_Q1_4	0.679	0.667	-0.012
50	LDR_UnBias_50K_Q2_66	0.676	0.646	-0.030
50	LDR_UnBias_50K_Q3_31	0.676	0.655	-0.021
50	LDR_UnBias_50K_Q4_77	0.676	0.637	-0.039
50	LDR_UnBias_50K_Q5_47	0.673	0.646	-0.027
0	LDR_100K_Correlation_Q5_72	0.664	0.667	0.003
100	LDR_Bias_100K_Q1_5	0.679	0.633	-0.047
100	LDR_Bias_100K_Q3_28	0.676	0.630	-0.047
100	LDR_Bias_100K_Q5_45	0.673	0.628	-0.046
100	LDR_Bias_100K_Q2_67	0.676	0.630	-0.047
100	LDR_Bias_100K_Q2_68	0.679	0.630	-0.050
100	LDR_UnBias_100K_Q1_6	0.676	0.628	-0.048
100	LDR_UnBias_100K_Q3_29	0.676	0.631	-0.045
100	LDR_UnBias_100K_Q5_69	0.670	0.628	-0.042
100	LDR_UnBias_100K_Q4_78	0.676	0.628	-0.049
100	LDR_UnBias_100K_Q4_79	0.673	0.628	-0.045
	Max	0.679	0.673	0.003
	Average	0.675	0.647	-0.028
	Min	0.664	0.628	-0.050
	Std Dev	0.004	0.018	0.019

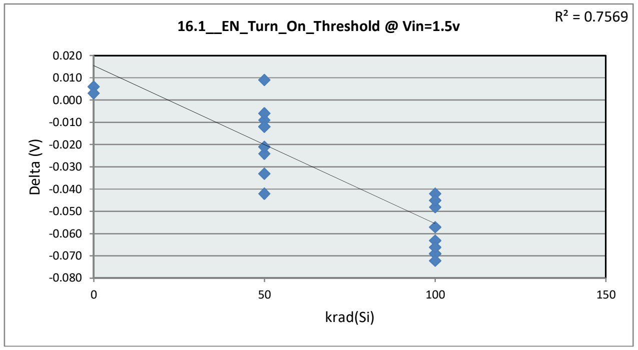


	16.0__EN_Turn_Off_Threshold @ Vin=1.5v		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.8	V	
Min Limit	0.5	V	
krad(Si)	0	50	100
LL	0.500	0.500	0.500
Min	0.667	0.637	0.628
Average	0.670	0.660	0.629
Max	0.673	0.670	0.633
UL	0.800	0.800	0.800

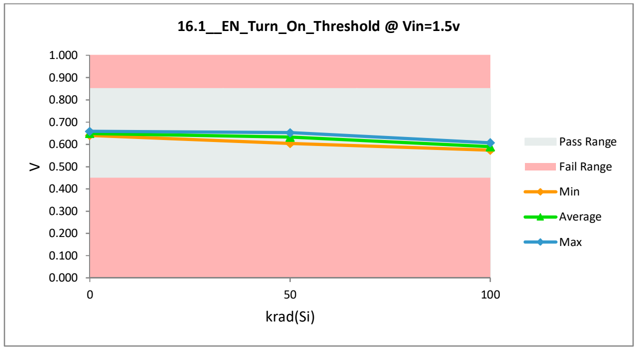


LDR Report
TPS7H1101-SP

		16.1__EN_Turn_On_Threshold @		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.85	0.85	
	Min Limit	0.45	0.45	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.652	0.658	0.006
50	LDR_Bias_50K_Q1_3	0.649	0.640	-0.009
50	LDR_Bias_50K_Q2_65	0.646	0.640	-0.006
50	LDR_Bias_50K_Q3_30	0.643	0.652	0.009
50	LDR_Bias_50K_Q4_76	0.646	0.634	-0.012
50	LDR_Bias_50K_Q5_46	0.643	0.637	-0.006
50	LDR_UnBias_50K_Q1_4	0.646	0.634	-0.012
50	LDR_UnBias_50K_Q2_66	0.646	0.613	-0.033
50	LDR_UnBias_50K_Q3_31	0.646	0.622	-0.024
50	LDR_UnBias_50K_Q4_77	0.646	0.604	-0.042
50	LDR_UnBias_50K_Q5_47	0.664	0.643	-0.021
0	LDR_100K_Correlation_Q5_72	0.637	0.640	0.003
100	LDR_Bias_100K_Q1_5	0.649	0.604	-0.045
100	LDR_Bias_100K_Q3_28	0.646	0.598	-0.048
100	LDR_Bias_100K_Q5_45	0.640	0.583	-0.057
100	LDR_Bias_100K_Q2_67	0.649	0.607	-0.042
100	LDR_Bias_100K_Q2_68	0.646	0.601	-0.045
100	LDR_UnBias_100K_Q1_6	0.649	0.580	-0.069
100	LDR_UnBias_100K_Q3_29	0.649	0.580	-0.069
100	LDR_UnBias_100K_Q5_69	0.649	0.586	-0.063
100	LDR_UnBias_100K_Q4_78	0.646	0.574	-0.072
100	LDR_UnBias_100K_Q4_79	0.643	0.577	-0.066
	Max	0.664	0.658	0.009
	Average	0.647	0.614	-0.033
	Min	0.637	0.574	-0.072
	Std Dev	0.005	0.027	0.027

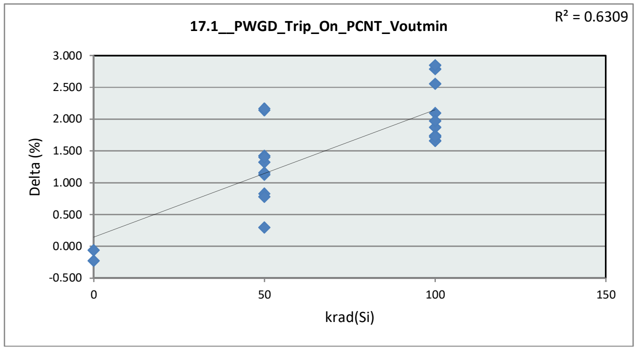


	16.1__EN_Turn_On_Threshold @ Vin=1.5v		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.85	V	
Min Limit	0.45	V	
krad(Si)	0	50	100
LL	0.450	0.450	0.450
Min	0.640	0.604	0.574
Average	0.649	0.632	0.589
Max	0.658	0.652	0.607
UL	0.850	0.850	0.850

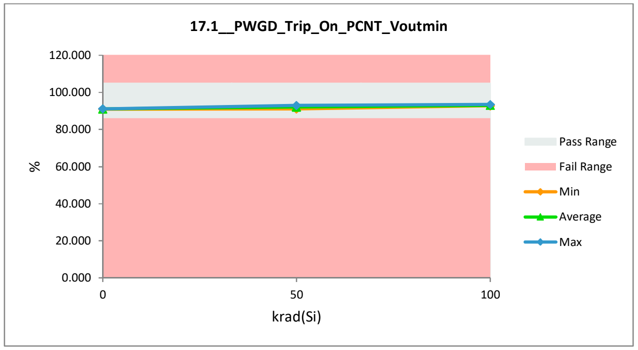


LDR Report
TPS7H1101-SP

		17.1__PWGD_Trip_On_PCNT_Vo		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%	%	
	Max Limit	105	105	
	Min Limit	86	86	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	91.231	91.170	-0.061
50	LDR_Bias_50K_Q1_3	90.923	91.751	0.828
50	LDR_Bias_50K_Q2_65	91.050	91.828	0.778
50	LDR_Bias_50K_Q3_30	90.974	92.397	1.423
50	LDR_Bias_50K_Q4_76	90.798	92.938	2.140
50	LDR_Bias_50K_Q5_46	90.645	91.770	1.125
50	LDR_UnBias_50K_Q1_4	91.108	92.264	1.156
50	LDR_UnBias_50K_Q2_66	90.784	92.108	1.324
50	LDR_UnBias_50K_Q3_31	90.592	92.758	2.166
50	LDR_UnBias_50K_Q4_77	91.404	92.804	1.400
50	LDR_UnBias_50K_Q5_47	90.757	91.053	0.296
0	LDR_100K_Correlation_Q5_72	91.230	91.003	-0.227
100	LDR_Bias_100K_Q1_5	91.427	93.299	1.872
100	LDR_Bias_100K_Q3_28	90.586	93.372	2.786
100	LDR_Bias_100K_Q5_45	90.692	92.789	2.097
100	LDR_Bias_100K_Q2_67	90.625	93.471	2.846
100	LDR_Bias_100K_Q2_68	90.932	92.904	1.972
100	LDR_UnBias_100K_Q1_6	90.709	93.264	2.555
100	LDR_UnBias_100K_Q3_29	91.358	93.017	1.659
100	LDR_UnBias_100K_Q5_69	91.116	92.778	1.662
100	LDR_UnBias_100K_Q4_78	91.229	92.969	1.740
100	LDR_UnBias_100K_Q4_79	91.308	93.029	1.721
	Max	91.427	93.471	2.846
	Average	90.976	92.488	1.512
	Min	90.586	91.003	-0.227
	Std Dev	0.283	0.763	0.830

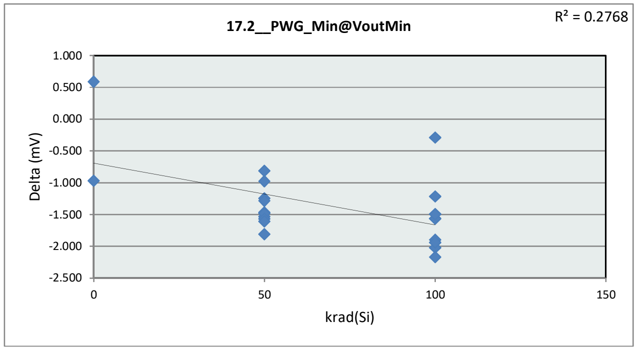


	17.1__PWGD_Trip_On_PCNT_Voutmin		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	105	%	
Min Limit	86	%	
krad(Si)	0	50	100
LL	86.000	86.000	86.000
Min	91.003	91.053	92.778
Average	91.087	92.167	93.089
Max	91.170	92.938	93.471
UL	105.000	105.000	105.000

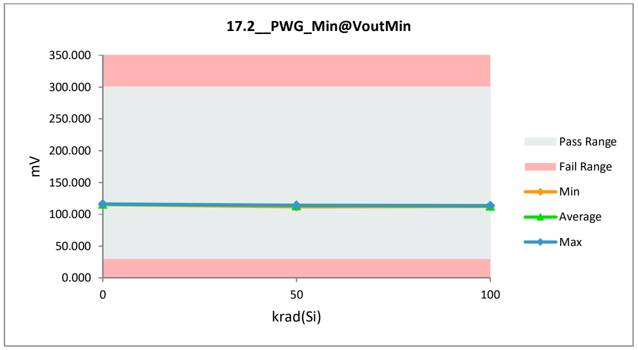


LDR Report
TPS7H1101-SP

		17.2__PWG_Min@VoutMin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	300	300	
	Min Limit	30	30	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	116.196	115.225	-0.971
50	LDR_Bias_50K_Q1_3	114.341	112.873	-1.468
50	LDR_Bias_50K_Q2_65	114.183	112.938	-1.245
50	LDR_Bias_50K_Q3_30	115.446	113.914	-1.532
50	LDR_Bias_50K_Q4_76	114.879	114.067	-0.812
50	LDR_Bias_50K_Q5_46	115.942	114.659	-1.283
50	LDR_UnBias_50K_Q1_4	114.794	113.818	-0.976
50	LDR_UnBias_50K_Q2_66	113.392	111.910	-1.482
50	LDR_UnBias_50K_Q3_31	114.524	112.955	-1.569
50	LDR_UnBias_50K_Q4_77	115.576	113.768	-1.808
50	LDR_UnBias_50K_Q5_47	115.317	113.711	-1.606
0	LDR_100K_Correlation_Q5_72	115.941	116.528	0.587
100	LDR_Bias_100K_Q1_5	113.948	113.657	-0.291
100	LDR_Bias_100K_Q3_28	116.063	114.043	-2.020
100	LDR_Bias_100K_Q5_45	115.973	114.076	-1.897
100	LDR_Bias_100K_Q2_67	114.055	112.493	-1.562
100	LDR_Bias_100K_Q2_68	114.714	113.223	-1.491
100	LDR_UnBias_100K_Q1_6	114.582	113.366	-1.216
100	LDR_UnBias_100K_Q3_29	115.440	113.271	-2.169
100	LDR_UnBias_100K_Q5_69	115.290	113.726	-1.564
100	LDR_UnBias_100K_Q4_78	114.621	112.682	-1.939
100	LDR_UnBias_100K_Q4_79	114.861	113.366	-1.495
	Max	116.196	116.528	0.587
	Average	115.004	113.649	-1.355
	Min	113.392	111.910	-2.169
	Std Dev	0.774	0.971	0.608



	17.2__PWG_Min@VoutMin		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	300	mV	
Min Limit	30	mV	
krad(Si)	0	50	100
LL	30.000	30.000	30.000
Min	115.225	111.910	112.493
Average	115.877	113.461	113.390
Max	116.528	114.659	114.076
UL	300.000	300.000	300.000



LDR Report
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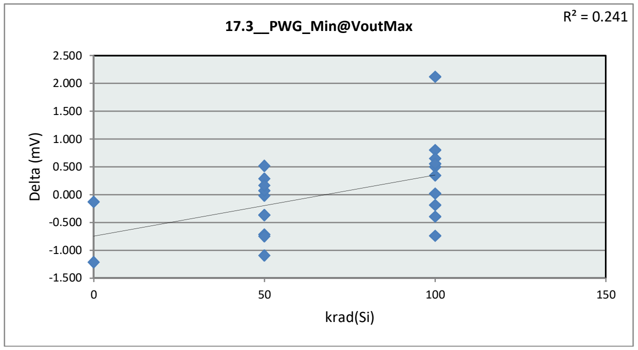
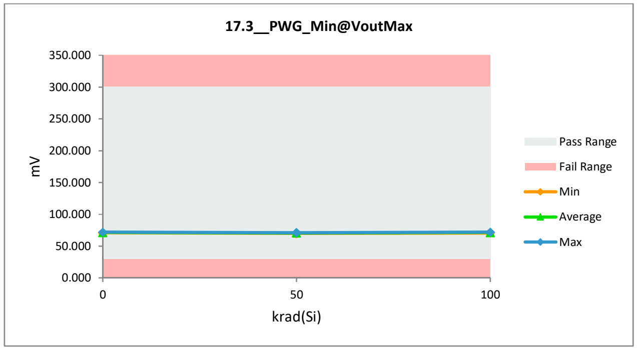
		17.3__PWG_Min@VoutMax		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mV	mV	
	Max Limit	300	300	
	Min Limit	30	30	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	72.222	71.008	-1.214
50	LDR_Bias_50K_Q1_3	70.348	70.636	0.288
50	LDR_Bias_50K_Q2_65	70.188	70.170	-0.018
50	LDR_Bias_50K_Q3_30	71.481	70.762	-0.719
50	LDR_Bias_50K_Q4_76	70.901	70.972	0.071
50	LDR_Bias_50K_Q5_46	71.982	71.234	-0.748
50	LDR_UnBias_50K_Q1_4	70.790	70.956	0.166
50	LDR_UnBias_50K_Q2_66	69.431	69.950	0.519
50	LDR_UnBias_50K_Q3_31	70.516	70.151	-0.365
50	LDR_UnBias_50K_Q4_77	71.613	71.243	-0.370
50	LDR_UnBias_50K_Q5_47	71.316	70.224	-1.092
0	LDR_100K_Correlation_Q5_72	71.944	71.814	-0.130
100	LDR_Bias_100K_Q1_5	69.943	72.061	2.118
100	LDR_Bias_100K_Q3_28	72.077	71.339	-0.738
100	LDR_Bias_100K_Q5_45	71.963	71.568	-0.395
100	LDR_Bias_100K_Q2_67	70.054	70.856	0.802
100	LDR_Bias_100K_Q2_68	70.694	71.194	0.500
100	LDR_UnBias_100K_Q1_6	70.590	71.238	0.648
100	LDR_UnBias_100K_Q3_29	71.465	71.486	0.021
100	LDR_UnBias_100K_Q5_69	71.312	71.126	-0.186
100	LDR_UnBias_100K_Q4_78	70.619	70.963	0.344
100	LDR_UnBias_100K_Q4_79	70.839	71.393	0.554
	Max	72.222	72.061	2.118
	Average	71.013	71.016	0.003
	Min	69.431	69.950	-1.214
	Std Dev	0.779	0.542	0.736

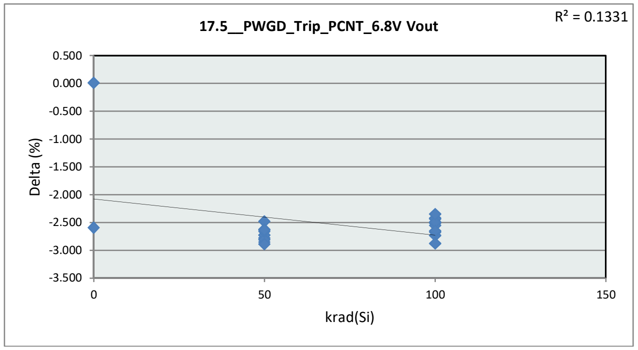


	17.3__PWG_Min@VoutMax		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	300	mV	
Min Limit	30	mV	
krad(Si)	0	50	100
LL	30.000	30.000	30.000
Min	71.008	69.950	70.856
Average	71.411	70.630	71.322
Max	71.814	71.243	72.061
UL	300.000	300.000	300.000

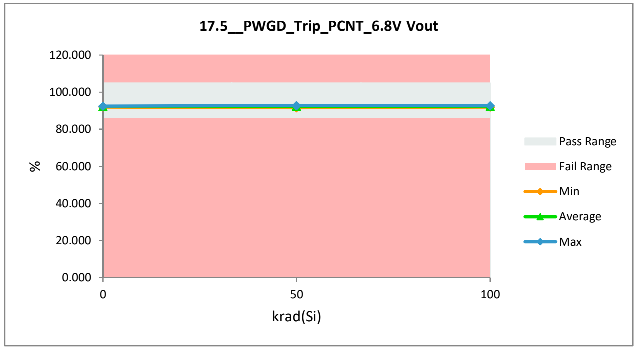


LDR Report
TPS7H1101-SP

		17.5__PWGD_Trip_PCNT_6.8V V		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		%	%	
Max Limit		105	105	
Min Limit		86	86	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	92.052	92.061	0.009
50	LDR_Bias_50K_Q1_3	95.006	92.277	-2.729
50	LDR_Bias_50K_Q2_65	94.380	91.900	-2.480
50	LDR_Bias_50K_Q3_30	95.559	92.780	-2.779
50	LDR_Bias_50K_Q4_76	95.243	92.620	-2.623
50	LDR_Bias_50K_Q5_46	94.944	92.092	-2.852
50	LDR_UnBias_50K_Q1_4	95.405	92.682	-2.723
50	LDR_UnBias_50K_Q2_66	95.132	92.326	-2.806
50	LDR_UnBias_50K_Q3_31	94.316	91.654	-2.662
50	LDR_UnBias_50K_Q4_77	94.787	92.153	-2.634
50	LDR_UnBias_50K_Q5_47	94.794	91.905	-2.889
0	LDR_100K_Correlation_Q5_72	95.088	92.495	-2.593
100	LDR_Bias_100K_Q1_5	95.129	92.618	-2.511
100	LDR_Bias_100K_Q3_28	95.115	92.693	-2.422
100	LDR_Bias_100K_Q5_45	94.714	92.278	-2.436
100	LDR_Bias_100K_Q2_67	95.252	92.517	-2.735
100	LDR_Bias_100K_Q2_68	95.170	92.617	-2.553
100	LDR_UnBias_100K_Q1_6	94.702	92.208	-2.494
100	LDR_UnBias_100K_Q3_29	94.907	92.557	-2.350
100	LDR_UnBias_100K_Q5_69	94.772	91.894	-2.878
100	LDR_UnBias_100K_Q4_78	94.733	92.061	-2.672
100	LDR_UnBias_100K_Q4_79	95.180	92.529	-2.651
	Max	95.559	92.780	0.009
	Average	94.835	92.314	-2.521
	Min	92.052	91.654	-2.889
	Std Dev	0.692	0.318	0.585

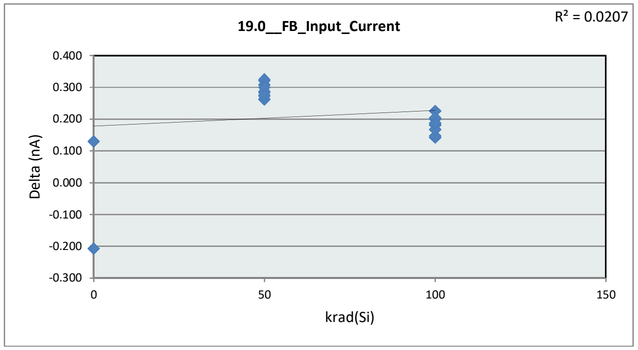


	17.5__PWGD_Trip_PCNT_6.8V Vout		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	105	%	
Min Limit	86	%	
krad(Si)	0	50	100
LL	86.000	86.000	86.000
Min	92.061	91.654	91.894
Average	92.278	92.239	92.397
Max	92.495	92.780	92.693
UL	105.000	105.000	105.000

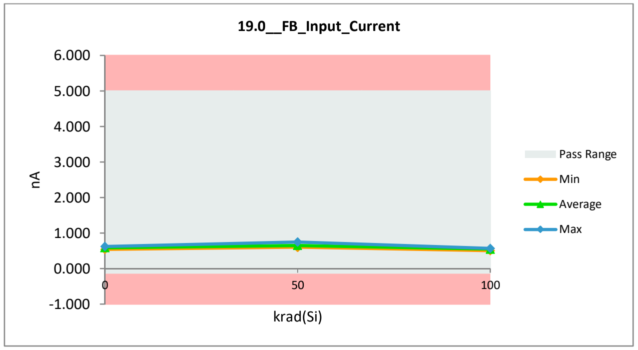


LDR Report
TPS7H1101-SP

		19.0__FB_Input_Current		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	nA	nA	
	Max Limit	5	5	
	Min Limit	-0.15	-0.15	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.832	0.625	-0.207
50	LDR_Bias_50K_Q1_3	0.328	0.649	0.321
50	LDR_Bias_50K_Q2_65	0.381	0.643	0.262
50	LDR_Bias_50K_Q3_30	0.361	0.645	0.284
50	LDR_Bias_50K_Q4_76	0.324	0.649	0.325
50	LDR_Bias_50K_Q5_46	0.337	0.600	0.263
50	LDR_UnBias_50K_Q1_4	0.439	0.747	0.308
50	LDR_UnBias_50K_Q2_66	0.384	0.671	0.287
50	LDR_UnBias_50K_Q3_31	0.356	0.628	0.272
50	LDR_UnBias_50K_Q4_77	0.342	0.642	0.300
50	LDR_UnBias_50K_Q5_47	0.359	0.634	0.275
0	LDR_100K_Correlation_Q5_72	0.415	0.545	0.130
100	LDR_Bias_100K_Q1_5	0.357	0.560	0.203
100	LDR_Bias_100K_Q3_28	0.369	0.511	0.142
100	LDR_Bias_100K_Q5_45	0.346	0.572	0.226
100	LDR_Bias_100K_Q2_67	0.370	0.570	0.200
100	LDR_Bias_100K_Q2_68	0.352	0.556	0.204
100	LDR_UnBias_100K_Q1_6	0.359	0.540	0.181
100	LDR_UnBias_100K_Q3_29	0.378	0.560	0.182
100	LDR_UnBias_100K_Q5_69	0.422	0.569	0.147
100	LDR_UnBias_100K_Q4_78	0.337	0.504	0.167
100	LDR_UnBias_100K_Q4_79	0.334	0.521	0.187
	Max	0.832	0.747	0.325
	Average	0.386	0.597	0.212
	Min	0.324	0.504	-0.207
	Std Dev	0.104	0.061	0.112

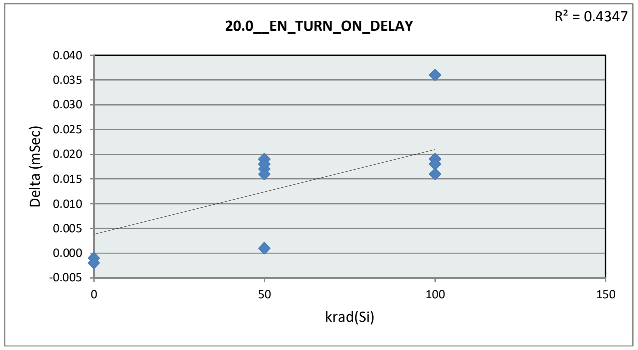


	19.0__FB_Input_Current		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	5	nA	
Min Limit	-0.15	nA	
krad(Si)	0	50	100
LL	-0.150	-0.150	-0.150
Min	0.545	0.600	0.504
Average	0.585	0.651	0.546
Max	0.625	0.747	0.572
UL	5.000	5.000	5.000

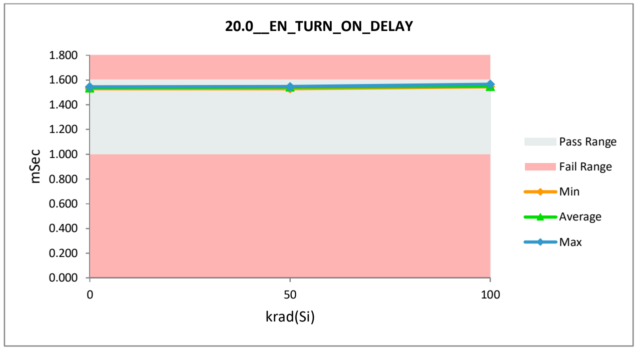


LDR Report
TPS7H1101-SP

		20.0__EN_TURN_ON_DELAY		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mSec	mSec	
	Max Limit	1.6	1.6	
	Min Limit	1	1	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.531	1.530	-0.001
50	LDR_Bias_50K_Q1_3	1.528	1.529	0.001
50	LDR_Bias_50K_Q2_65	1.528	1.529	0.001
50	LDR_Bias_50K_Q3_30	1.529	1.547	0.018
50	LDR_Bias_50K_Q4_76	1.529	1.547	0.018
50	LDR_Bias_50K_Q5_46	1.530	1.547	0.017
50	LDR_UnBias_50K_Q1_4	1.528	1.547	0.019
50	LDR_UnBias_50K_Q2_66	1.528	1.547	0.019
50	LDR_UnBias_50K_Q3_31	1.529	1.547	0.018
50	LDR_UnBias_50K_Q4_77	1.529	1.547	0.018
50	LDR_UnBias_50K_Q5_47	1.531	1.547	0.016
0	LDR_100K_Correlation_Q5_72	1.547	1.545	-0.002
100	LDR_Bias_100K_Q1_5	1.528	1.546	0.018
100	LDR_Bias_100K_Q3_28	1.528	1.546	0.018
100	LDR_Bias_100K_Q5_45	1.531	1.547	0.016
100	LDR_Bias_100K_Q2_67	1.528	1.546	0.018
100	LDR_Bias_100K_Q2_68	1.528	1.546	0.018
100	LDR_UnBias_100K_Q1_6	1.528	1.547	0.019
100	LDR_UnBias_100K_Q3_29	1.528	1.547	0.019
100	LDR_UnBias_100K_Q5_69	1.547	1.566	0.019
100	LDR_UnBias_100K_Q4_78	1.529	1.547	0.018
100	LDR_UnBias_100K_Q4_79	1.530	1.566	0.036
	Max	1.547	1.566	0.036
	Average	1.531	1.546	0.016
	Min	1.528	1.529	-0.002
	Std Dev	0.005	0.009	0.009

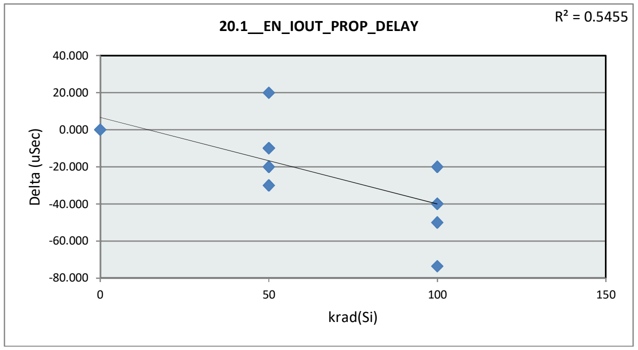


	20.0__EN_TURN_ON_DELAY		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.6	mSec	
Min Limit	1	mSec	
krad(Si)	0	50	100
LL	1.000	1.000	1.000
Min	1.530	1.529	1.546
Average	1.538	1.543	1.550
Max	1.545	1.547	1.566
UL	1.600	1.600	1.600

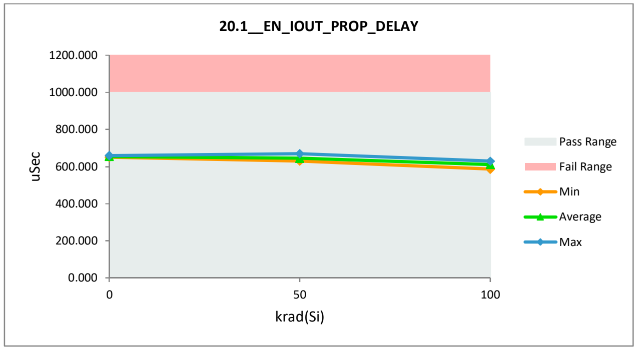


LDR Report
TPS7H1101-SP

		20.1__EN_IOUT_PROP_DELAY		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		uSec	uSec	
Max Limit		1000	1000	
Min Limit		1	1	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	650.000	650.000	0.000
50	LDR_Bias_50K_Q1_3	660.000	630.000	-30.000
50	LDR_Bias_50K_Q2_65	640.000	660.000	20.000
50	LDR_Bias_50K_Q3_30	660.000	630.000	-30.000
50	LDR_Bias_50K_Q4_76	660.000	650.000	-10.000
50	LDR_Bias_50K_Q5_46	670.000	660.000	-10.000
50	LDR_UnBias_50K_Q1_4	650.000	640.000	-10.000
50	LDR_UnBias_50K_Q2_66	660.000	640.000	-20.000
50	LDR_UnBias_50K_Q3_31	650.000	640.000	-10.000
50	LDR_UnBias_50K_Q4_77	650.000	630.000	-20.000
50	LDR_UnBias_50K_Q5_47	690.000	670.000	-20.000
0	LDR_100K_Correlation_Q5_72	660.000	660.000	0.000
100	LDR_Bias_100K_Q1_5	640.000	600.000	-40.000
100	LDR_Bias_100K_Q3_28	660.000	586.370	-73.630
100	LDR_Bias_100K_Q5_45	660.000	620.000	-40.000
100	LDR_Bias_100K_Q2_67	660.000	610.000	-50.000
100	LDR_Bias_100K_Q2_68	660.000	620.000	-40.000
100	LDR_UnBias_100K_Q1_6	660.000	610.000	-50.000
100	LDR_UnBias_100K_Q3_29	630.000	610.000	-20.000
100	LDR_UnBias_100K_Q5_69	650.000	630.000	-20.000
100	LDR_UnBias_100K_Q4_78	650.000	610.000	-40.000
100	LDR_UnBias_100K_Q4_79	660.000	620.000	-40.000
	Max	690.000	670.000	20.000
	Average	655.909	630.744	-25.165
	Min	630.000	586.370	-73.630
	Std Dev	11.816	21.921	20.804

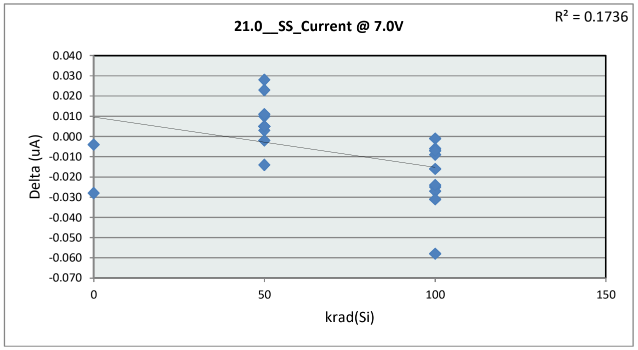


	20.1__EN_IOUT_PROP_DELAY		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1000	uSec	
Min Limit	1	uSec	
krad(Si)	0	50	100
LL	1.000	1.000	1.000
Min	650.000	630.000	586.370
Average	655.000	645.000	611.637
Max	660.000	670.000	630.000
UL	1000.000	1000.000	1000.000

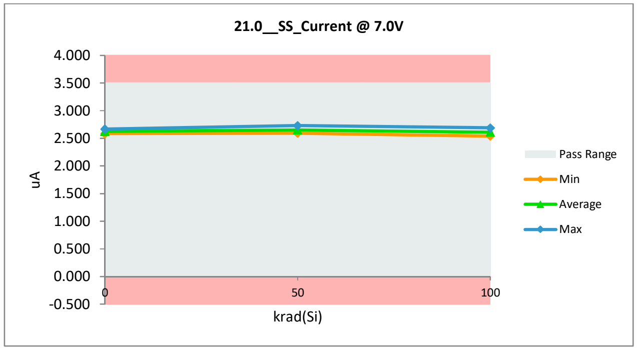


LDR Report
TPS7H1101-SP

		21.0__SS_Current @ 7.0V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	3.5	3.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	2.612	2.584	-0.028
50	LDR_Bias_50K_Q1_3	2.616	2.626	0.010
50	LDR_Bias_50K_Q2_65	2.703	2.731	0.028
50	LDR_Bias_50K_Q3_30	2.660	2.683	0.023
50	LDR_Bias_50K_Q4_76	2.642	2.647	0.005
50	LDR_Bias_50K_Q5_46	2.583	2.594	0.011
50	LDR_UnBias_50K_Q1_4	2.619	2.624	0.005
50	LDR_UnBias_50K_Q2_66	2.666	2.664	-0.002
50	LDR_UnBias_50K_Q3_31	2.712	2.715	0.003
50	LDR_UnBias_50K_Q4_77	2.626	2.612	-0.014
50	LDR_UnBias_50K_Q5_47	2.628	2.633	0.005
0	LDR_100K_Correlation_Q5_72	2.671	2.667	-0.004
100	LDR_Bias_100K_Q1_5	2.582	2.557	-0.025
100	LDR_Bias_100K_Q3_28	2.708	2.681	-0.027
100	LDR_Bias_100K_Q5_45	2.690	2.689	-0.001
100	LDR_Bias_100K_Q2_67	2.656	2.598	-0.058
100	LDR_Bias_100K_Q2_68	2.627	2.618	-0.009
100	LDR_UnBias_100K_Q1_6	2.647	2.623	-0.024
100	LDR_UnBias_100K_Q3_29	2.673	2.642	-0.031
100	LDR_UnBias_100K_Q5_69	2.604	2.588	-0.016
100	LDR_UnBias_100K_Q4_78	2.549	2.543	-0.006
100	LDR_UnBias_100K_Q4_79	2.597	2.590	-0.007
	Max	2.712	2.731	0.028
	Average	2.640	2.632	-0.007
	Min	2.549	2.543	-0.058
	Std Dev	0.044	0.049	0.020

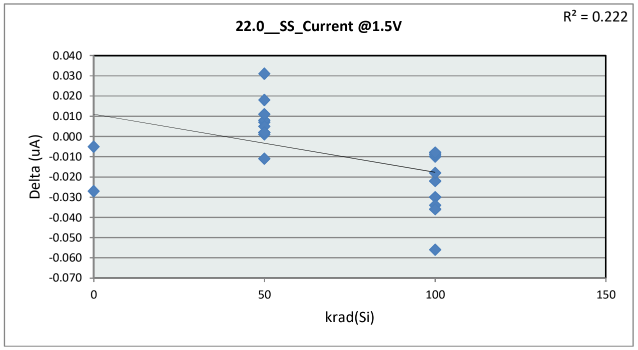


	21.0__SS_Current @ 7.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	3.5	uA	
Min Limit	-0.0001	uA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	2.584	2.594	2.543
Average	2.626	2.653	2.613
Max	2.667	2.731	2.689
UL	3.500	3.500	3.500

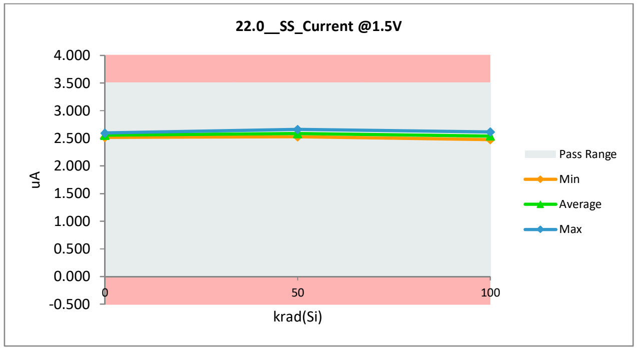


LDR Report
TPS7H1101-SP

		22.0__SS_Current @1.5V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	3.5	3.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	2.544	2.517	-0.027
50	LDR_Bias_50K_Q1_3	2.550	2.557	0.007
50	LDR_Bias_50K_Q2_65	2.631	2.662	0.031
50	LDR_Bias_50K_Q3_30	2.593	2.611	0.018
50	LDR_Bias_50K_Q4_76	2.572	2.580	0.008
50	LDR_Bias_50K_Q5_46	2.518	2.529	0.011
50	LDR_UnBias_50K_Q1_4	2.551	2.556	0.005
50	LDR_UnBias_50K_Q2_66	2.593	2.595	0.002
50	LDR_UnBias_50K_Q3_31	2.645	2.646	0.001
50	LDR_UnBias_50K_Q4_77	2.556	2.545	-0.011
50	LDR_UnBias_50K_Q5_47	2.562	2.564	0.002
0	LDR_100K_Correlation_Q5_72	2.601	2.596	-0.005
100	LDR_Bias_100K_Q1_5	2.513	2.483	-0.030
100	LDR_Bias_100K_Q3_28	2.640	2.606	-0.034
100	LDR_Bias_100K_Q5_45	2.624	2.616	-0.008
100	LDR_Bias_100K_Q2_67	2.583	2.527	-0.056
100	LDR_Bias_100K_Q2_68	2.555	2.545	-0.010
100	LDR_UnBias_100K_Q1_6	2.574	2.552	-0.022
100	LDR_UnBias_100K_Q3_29	2.605	2.569	-0.036
100	LDR_UnBias_100K_Q5_69	2.535	2.517	-0.018
100	LDR_UnBias_100K_Q4_78	2.485	2.476	-0.009
100	LDR_UnBias_100K_Q4_79	2.529	2.521	-0.008
	Max	2.645	2.662	0.031
	Average	2.571	2.562	-0.009
	Min	2.485	2.476	-0.056
	Std Dev	0.043	0.048	0.020

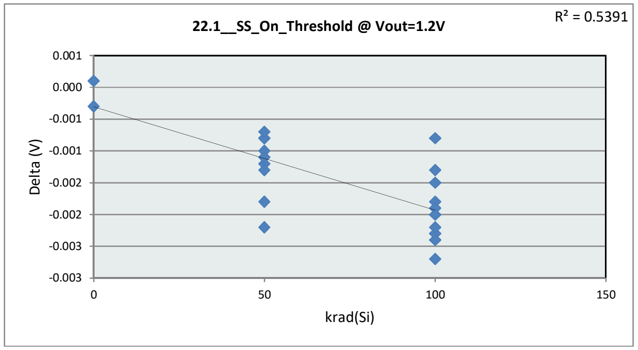


	22.0__SS_Current @1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	3.5	uA	
Min Limit	-0.0001	uA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	2.517	2.529	2.476
Average	2.557	2.585	2.541
Max	2.596	2.662	2.616
UL	3.500	3.500	3.500

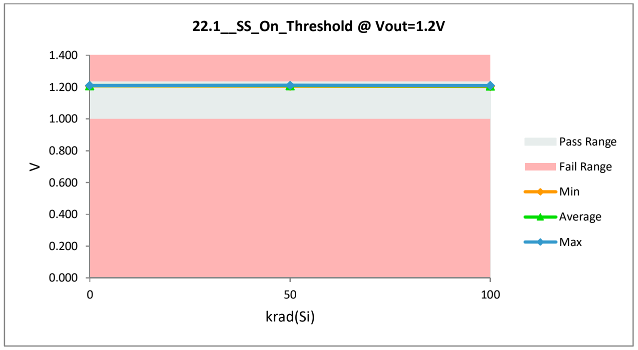


LDR Report
TPS7H1101-SP

		22.1__SS_On_Threshold @ Vout=		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		1.232	1.232	
Min Limit		1	1	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.211	1.211	0.000
50	LDR_Bias_50K_Q1_3	1.209	1.208	-0.001
50	LDR_Bias_50K_Q2_65	1.212	1.211	-0.001
50	LDR_Bias_50K_Q3_30	1.211	1.209	-0.001
50	LDR_Bias_50K_Q4_76	1.209	1.208	-0.001
50	LDR_Bias_50K_Q5_46	1.209	1.208	-0.001
50	LDR_UnBias_50K_Q1_4	1.207	1.206	-0.001
50	LDR_UnBias_50K_Q2_66	1.212	1.210	-0.002
50	LDR_UnBias_50K_Q3_31	1.211	1.209	-0.001
50	LDR_UnBias_50K_Q4_77	1.211	1.209	-0.002
50	LDR_UnBias_50K_Q5_47	1.212	1.211	-0.001
0	LDR_100K_Correlation_Q5_72	1.208	1.208	0.000
100	LDR_Bias_100K_Q1_5	1.210	1.207	-0.002
100	LDR_Bias_100K_Q3_28	1.210	1.208	-0.002
100	LDR_Bias_100K_Q5_45	1.211	1.209	-0.002
100	LDR_Bias_100K_Q2_67	1.210	1.208	-0.002
100	LDR_Bias_100K_Q2_68	1.210	1.207	-0.003
100	LDR_UnBias_100K_Q1_6	1.211	1.210	-0.002
100	LDR_UnBias_100K_Q3_29	1.212	1.211	-0.001
100	LDR_UnBias_100K_Q5_69	1.207	1.204	-0.002
100	LDR_UnBias_100K_Q4_78	1.210	1.209	-0.001
100	LDR_UnBias_100K_Q4_79	1.210	1.208	-0.002
	Max	1.212	1.211	0.000
	Average	1.210	1.209	-0.001
	Min	1.207	1.204	-0.003
	Std Dev	0.001	0.002	0.001



	22.1__SS_On_Threshold @ Vout=1.2V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.232	V	
Min Limit	1	V	
krad(Si)	0	50	100
LL	1.000	1.000	1.000
Min	1.208	1.206	1.205
Average	1.209	1.209	1.208
Max	1.211	1.211	1.211
UL	1.232	1.232	1.232



LDR Report
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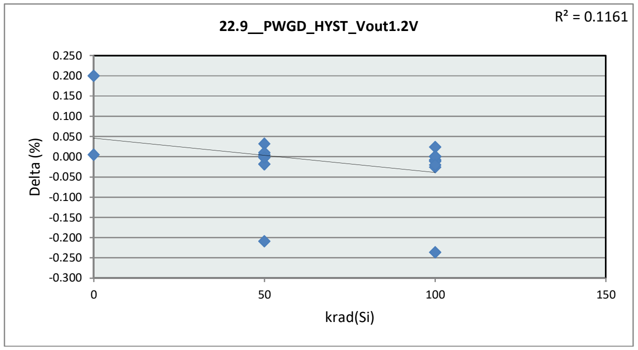
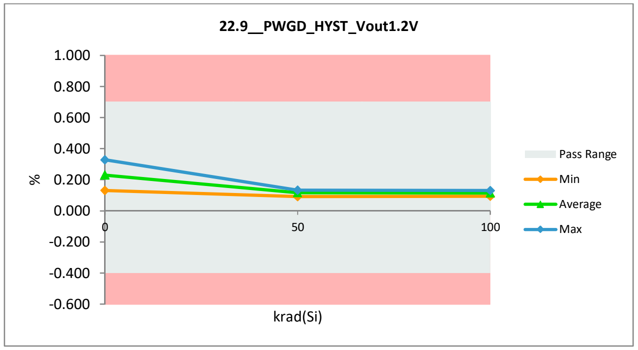
		22.9__PWGD_HYST_Vout1.2V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	%	%	
	Max Limit	0.7	0.7	
	Min Limit	-0.4	-0.4	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.127	0.132	0.005
50	LDR_Bias_50K_Q1_3	0.115	0.117	0.002
50	LDR_Bias_50K_Q2_65	0.099	0.131	0.032
50	LDR_Bias_50K_Q3_30	0.111	0.109	-0.002
50	LDR_Bias_50K_Q4_76	0.100	0.106	0.006
50	LDR_Bias_50K_Q5_46	0.125	0.130	0.005
50	LDR_UnBias_50K_Q1_4	0.126	0.107	-0.019
50	LDR_UnBias_50K_Q2_66	0.110	0.092	-0.018
50	LDR_UnBias_50K_Q3_31	0.123	0.133	0.010
50	LDR_UnBias_50K_Q4_77	0.336	0.127	-0.209
50	LDR_UnBias_50K_Q5_47	0.122	0.120	-0.002
0	LDR_100K_Correlation_Q5_72	0.129	0.329	0.200
100	LDR_Bias_100K_Q1_5	0.115	0.107	-0.008
100	LDR_Bias_100K_Q3_28	0.116	0.116	0.000
100	LDR_Bias_100K_Q5_45	0.133	0.107	-0.026
100	LDR_Bias_100K_Q2_67	0.107	0.131	0.024
100	LDR_Bias_100K_Q2_68	0.118	0.119	0.001
100	LDR_UnBias_100K_Q1_6	0.117	0.117	0.000
100	LDR_UnBias_100K_Q3_29	0.105	0.094	-0.011
100	LDR_UnBias_100K_Q5_69	0.131	0.131	0.000
100	LDR_UnBias_100K_Q4_78	0.130	0.110	-0.020
100	LDR_UnBias_100K_Q4_79	0.348	0.112	-0.236
	Max	0.348	0.329	0.200
	Average	0.138	0.126	-0.012
	Min	0.099	0.092	-0.236
	Std Dev	0.067	0.047	0.082



	22.9__PWGD_HYST_Vout1.2V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.7	%	
Min Limit	-0.4	%	
krad(Si)	0	50	100
LL	-0.400	-0.400	-0.400
Min	0.132	0.092	0.094
Average	0.231	0.117	0.114
Max	0.329	0.133	0.131
UL	0.700	0.700	0.700



LDR Report
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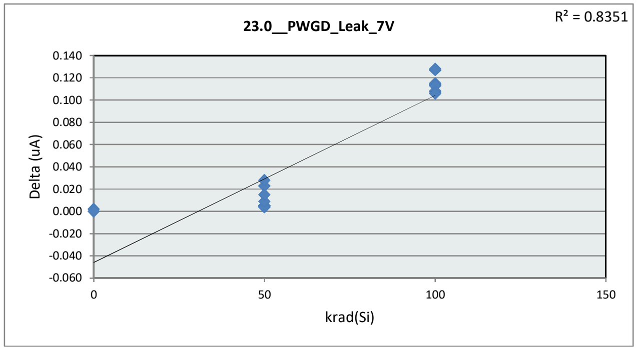
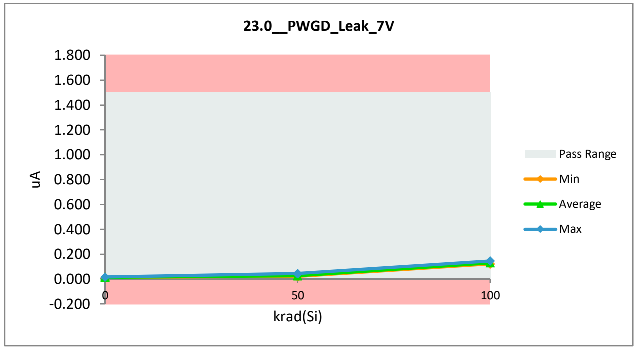
		23.0__PWGD_Leak_7V		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	uA	uA	
	Max Limit	1.5	1.5	
	Min Limit	-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.012	0.014	0.002
50	LDR_Bias_50K_Q1_3	0.016	0.020	0.004
50	LDR_Bias_50K_Q2_65	0.017	0.022	0.005
50	LDR_Bias_50K_Q3_30	0.015	0.020	0.005
50	LDR_Bias_50K_Q4_76	0.015	0.020	0.005
50	LDR_Bias_50K_Q5_46	0.017	0.022	0.005
50	LDR_UnBias_50K_Q1_4	0.017	0.021	0.004
50	LDR_UnBias_50K_Q2_66	0.016	0.039	0.023
50	LDR_UnBias_50K_Q3_31	0.016	0.025	0.009
50	LDR_UnBias_50K_Q4_77	0.016	0.044	0.028
50	LDR_UnBias_50K_Q5_47	0.016	0.031	0.015
0	LDR_100K_Correlation_Q5_72	0.016	0.016	0.000
100	LDR_Bias_100K_Q1_5	0.017	0.144	0.127
100	LDR_Bias_100K_Q3_28	0.015	0.121	0.106
100	LDR_Bias_100K_Q5_45	0.017	0.132	0.115
100	LDR_Bias_100K_Q2_67	0.016	0.130	0.114
100	LDR_Bias_100K_Q2_68	0.016	0.129	0.113
100	LDR_UnBias_100K_Q1_6	0.014	0.127	0.113
100	LDR_UnBias_100K_Q3_29	0.015	0.121	0.106
100	LDR_UnBias_100K_Q5_69	0.017	0.125	0.108
100	LDR_UnBias_100K_Q4_78	0.018	0.146	0.128
100	LDR_UnBias_100K_Q4_79	0.015	0.121	0.106
	Max	0.018	0.146	0.128
	Average	0.016	0.072	0.056
	Min	0.012	0.014	0.000
	Std Dev	0.001	0.054	0.054



	23.0__PWGD_Leak_7V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.5	uA	
Min Limit	-0.0001	uA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	0.014	0.020	0.121
Average	0.015	0.026	0.130
Max	0.016	0.044	0.146
UL	1.500	1.500	1.500



LDR Report
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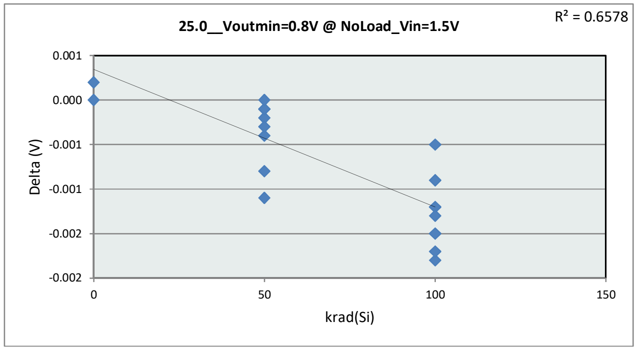
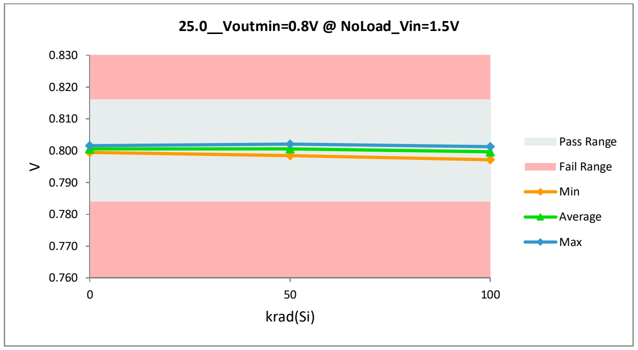
		25.0__Voutmin=0.8V @ NoLoad_		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.801	0.802	0.000
50	LDR_Bias_50K_Q1_3	0.800	0.800	0.000
50	LDR_Bias_50K_Q2_65	0.802	0.802	0.000
50	LDR_Bias_50K_Q3_30	0.801	0.801	0.000
50	LDR_Bias_50K_Q4_76	0.800	0.800	0.000
50	LDR_Bias_50K_Q5_46	0.800	0.800	0.000
50	LDR_UnBias_50K_Q1_4	0.799	0.799	0.000
50	LDR_UnBias_50K_Q2_66	0.802	0.801	-0.001
50	LDR_UnBias_50K_Q3_31	0.801	0.801	0.000
50	LDR_UnBias_50K_Q4_77	0.801	0.800	-0.001
50	LDR_UnBias_50K_Q5_47	0.802	0.802	0.000
0	LDR_100K_Correlation_Q5_72	0.799	0.799	0.000
100	LDR_Bias_100K_Q1_5	0.801	0.799	-0.002
100	LDR_Bias_100K_Q3_28	0.801	0.800	-0.001
100	LDR_Bias_100K_Q5_45	0.802	0.800	-0.001
100	LDR_Bias_100K_Q2_67	0.801	0.800	-0.001
100	LDR_Bias_100K_Q2_68	0.801	0.799	-0.002
100	LDR_UnBias_100K_Q1_6	0.802	0.801	-0.001
100	LDR_UnBias_100K_Q3_29	0.802	0.801	-0.001
100	LDR_UnBias_100K_Q5_69	0.799	0.797	-0.001
100	LDR_UnBias_100K_Q4_78	0.801	0.800	-0.001
100	LDR_UnBias_100K_Q4_79	0.801	0.799	-0.002
	Max	0.802	0.802	0.000
	Average	0.801	0.800	-0.001
	Min	0.799	0.797	-0.002
	Std Dev	0.001	0.001	0.001

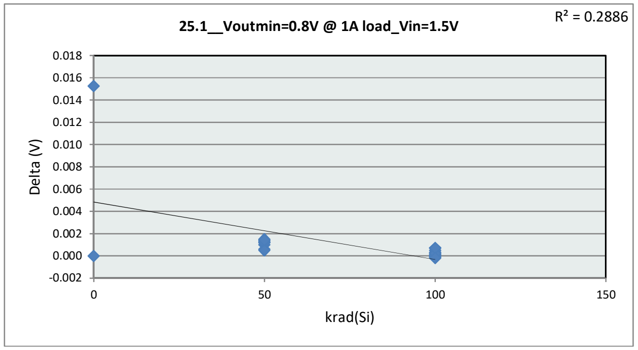


	25.0__Voutmin=0.8V @ NoLoad_Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.816	V	
Min Limit	0.784	V	
krad(Si)	0	50	100
LL	0.784	0.784	0.784
Min	0.800	0.799	0.797
Average	0.801	0.801	0.800
Max	0.802	0.802	0.801
UL	0.816	0.816	0.816

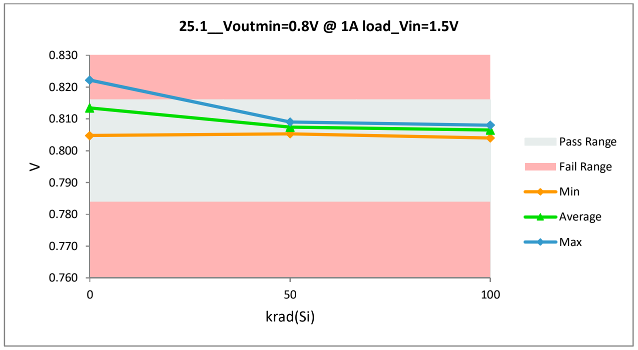


LDR Report
TPS7H1101-SP

		25.1__Voutmin=0.8V @ 1A load_		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	0.816	0.816	
	Min Limit	0.784	0.784	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	0.807	0.822	0.015
50	LDR_Bias_50K_Q1_3	0.806	0.807	0.001
50	LDR_Bias_50K_Q2_65	0.808	0.809	0.001
50	LDR_Bias_50K_Q3_30	0.807	0.808	0.001
50	LDR_Bias_50K_Q4_76	0.806	0.807	0.001
50	LDR_Bias_50K_Q5_46	0.806	0.807	0.001
50	LDR_UnBias_50K_Q1_4	0.804	0.805	0.002
50	LDR_UnBias_50K_Q2_66	0.807	0.808	0.001
50	LDR_UnBias_50K_Q3_31	0.806	0.808	0.001
50	LDR_UnBias_50K_Q4_77	0.807	0.807	0.001
50	LDR_UnBias_50K_Q5_47	0.808	0.809	0.001
0	LDR_100K_Correlation_Q5_72	0.805	0.805	0.000
100	LDR_Bias_100K_Q1_5	0.806	0.806	0.000
100	LDR_Bias_100K_Q3_28	0.806	0.806	0.000
100	LDR_Bias_100K_Q5_45	0.807	0.807	0.000
100	LDR_Bias_100K_Q2_67	0.806	0.807	0.000
100	LDR_Bias_100K_Q2_68	0.806	0.806	0.000
100	LDR_UnBias_100K_Q1_6	0.807	0.807	0.001
100	LDR_UnBias_100K_Q3_29	0.807	0.808	0.001
100	LDR_UnBias_100K_Q5_69	0.804	0.804	0.000
100	LDR_UnBias_100K_Q4_78	0.806	0.807	0.001
100	LDR_UnBias_100K_Q4_79	0.807	0.806	0.000
	Max	0.808	0.822	0.015
	Average	0.806	0.808	0.001
	Min	0.804	0.804	0.000
	Std Dev	0.001	0.003	0.003



	25.1__Voutmin=0.8V @ 1A load_Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	0.816	V	
Min Limit	0.784	V	
krad(Si)	0	50	100
LL	0.784	0.784	0.784
Min	0.805	0.805	0.804
Average	0.813	0.807	0.807
Max	0.822	0.809	0.808
UL	0.816	0.816	0.816



LDR Report
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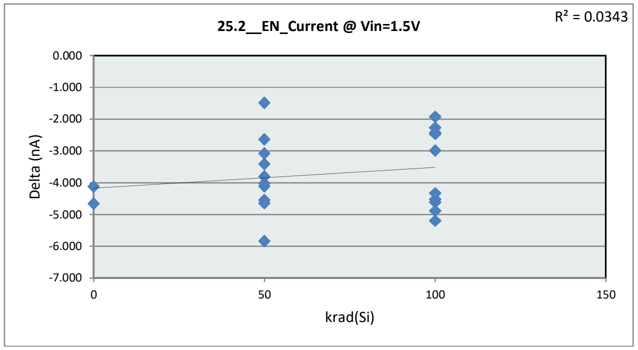
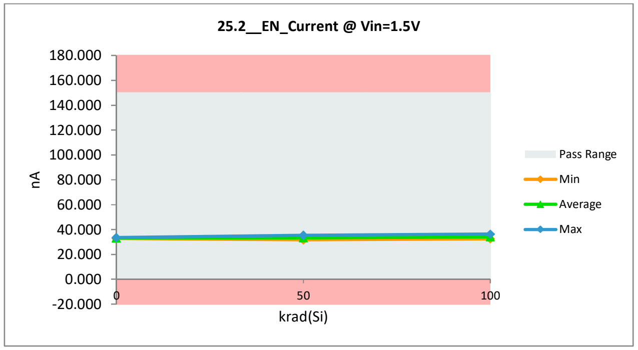
		25.2__EN_Current @ Vin=1.5V		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		nA	nA	
Max Limit		150	150	
Min Limit		-0.0001	-0.0001	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	38.154	33.495	-4.659
50	LDR_Bias_50K_Q1_3	38.332	33.785	-4.547
50	LDR_Bias_50K_Q2_65	35.482	33.996	-1.486
50	LDR_Bias_50K_Q3_30	36.852	33.441	-3.411
50	LDR_Bias_50K_Q4_76	36.054	31.940	-4.114
50	LDR_Bias_50K_Q5_46	37.839	33.198	-4.641
50	LDR_UnBias_50K_Q1_4	39.420	35.395	-4.025
50	LDR_UnBias_50K_Q2_66	37.526	34.887	-2.639
50	LDR_UnBias_50K_Q3_31	35.858	32.057	-3.801
50	LDR_UnBias_50K_Q4_77	37.549	31.713	-5.836
50	LDR_UnBias_50K_Q5_47	36.304	33.230	-3.074
0	LDR_100K_Correlation_Q5_72	36.970	32.848	-4.122
100	LDR_Bias_100K_Q1_5	37.557	34.569	-2.988
100	LDR_Bias_100K_Q3_28	38.395	33.200	-5.195
100	LDR_Bias_100K_Q5_45	37.839	33.231	-4.608
100	LDR_Bias_100K_Q2_67	35.678	33.255	-2.423
100	LDR_Bias_100K_Q2_68	38.183	33.661	-4.522
100	LDR_UnBias_100K_Q1_6	38.238	35.773	-2.465
100	LDR_UnBias_100K_Q3_29	38.277	36.352	-1.925
100	LDR_UnBias_100K_Q5_69	37.502	32.621	-4.881
100	LDR_UnBias_100K_Q4_78	37.933	33.599	-4.334
100	LDR_UnBias_100K_Q4_79	36.844	34.577	-2.267
	Max	39.420	36.352	-1.486
	Average	37.399	33.674	-3.726
	Min	35.482	31.713	-5.836
	Std Dev	1.027	1.197	1.164



	25.2__EN_Current @ Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	150	nA	
Min Limit	-0.0001	nA	
krad(Si)	0	50	100
LL	0.000	0.000	0.000
Min	32.848	31.713	32.621
Average	33.171	33.364	34.084
Max	33.495	35.395	36.352
UL	150.000	150.000	150.000



LDR Report
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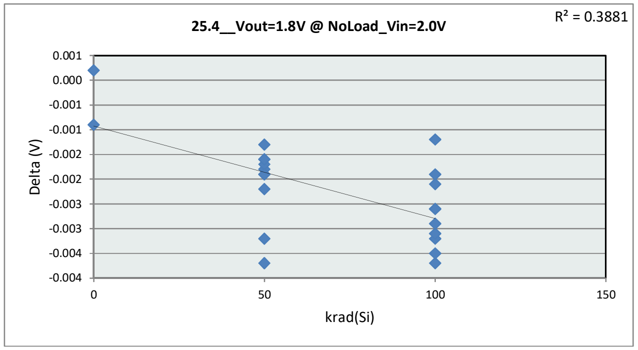
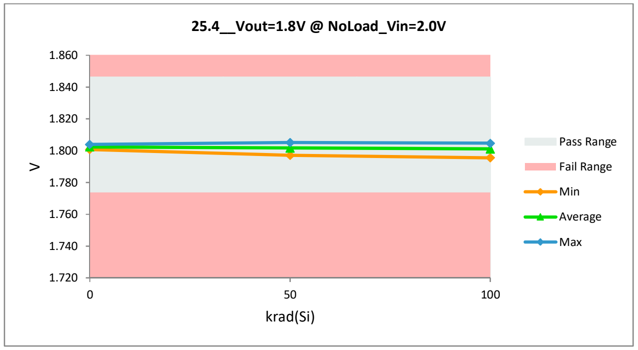
		25.4__Vout=1.8V @ NoLoad_Vin		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.805	1.804	-0.001
50	LDR_Bias_50K_Q1_3	1.802	1.801	-0.002
50	LDR_Bias_50K_Q2_65	1.806	1.804	-0.002
50	LDR_Bias_50K_Q3_30	1.805	1.802	-0.002
50	LDR_Bias_50K_Q4_76	1.803	1.801	-0.002
50	LDR_Bias_50K_Q5_46	1.802	1.801	-0.002
50	LDR_UnBias_50K_Q1_4	1.799	1.797	-0.002
50	LDR_UnBias_50K_Q2_66	1.806	1.803	-0.003
50	LDR_UnBias_50K_Q3_31	1.804	1.803	-0.002
50	LDR_UnBias_50K_Q4_77	1.805	1.801	-0.004
50	LDR_UnBias_50K_Q5_47	1.806	1.805	-0.001
0	LDR_100K_Correlation_Q5_72	1.801	1.801	0.000
100	LDR_Bias_100K_Q1_5	1.803	1.800	-0.003
100	LDR_Bias_100K_Q3_28	1.804	1.801	-0.003
100	LDR_Bias_100K_Q5_45	1.805	1.802	-0.003
100	LDR_Bias_100K_Q2_67	1.804	1.801	-0.003
100	LDR_Bias_100K_Q2_68	1.804	1.800	-0.004
100	LDR_UnBias_100K_Q1_6	1.805	1.803	-0.002
100	LDR_UnBias_100K_Q3_29	1.806	1.805	-0.001
100	LDR_UnBias_100K_Q5_69	1.798	1.796	-0.003
100	LDR_UnBias_100K_Q4_78	1.804	1.802	-0.002
100	LDR_UnBias_100K_Q4_79	1.804	1.801	-0.003
	Max	1.806	1.805	0.000
	Average	1.804	1.801	-0.002
	Min	1.798	1.796	-0.004
	Std Dev	0.002	0.002	0.001

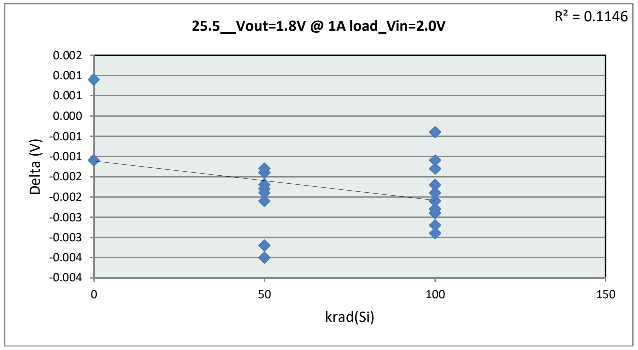


	25.4__Vout=1.8V @ NoLoad_Vin=2.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.8462	V	
Min Limit	1.7738	V	
krad(Si)	0	50	100
LL	1.774	1.774	1.774
Min	1.801	1.797	1.796
Average	1.802	1.802	1.801
Max	1.804	1.805	1.805
UL	1.846	1.846	1.846

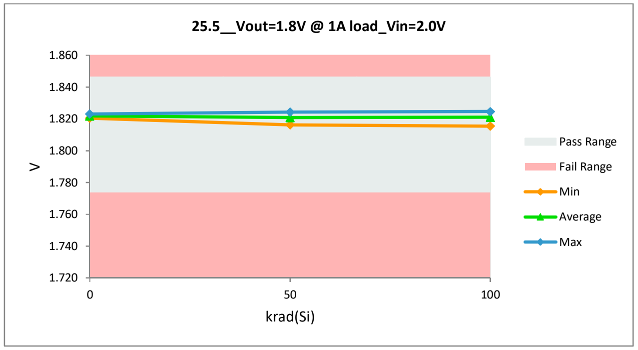


LDR Report
TPS7H1101-SP

		25.5__Vout=1.8V @ 1A load_Vin=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.8462	1.8462	
	Min Limit	1.7738	1.7738	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.824	1.823	-0.001
50	LDR_Bias_50K_Q1_3	1.821	1.820	-0.002
50	LDR_Bias_50K_Q2_65	1.825	1.824	-0.002
50	LDR_Bias_50K_Q3_30	1.824	1.822	-0.002
50	LDR_Bias_50K_Q4_76	1.821	1.820	-0.002
50	LDR_Bias_50K_Q5_46	1.821	1.820	-0.001
50	LDR_UnBias_50K_Q1_4	1.818	1.816	-0.001
50	LDR_UnBias_50K_Q2_66	1.825	1.822	-0.003
50	LDR_UnBias_50K_Q3_31	1.824	1.822	-0.002
50	LDR_UnBias_50K_Q4_77	1.824	1.820	-0.003
50	LDR_UnBias_50K_Q5_47	1.826	1.824	-0.001
0	LDR_100K_Correlation_Q5_72	1.820	1.821	0.001
100	LDR_Bias_100K_Q1_5	1.822	1.820	-0.002
100	LDR_Bias_100K_Q3_28	1.823	1.821	-0.002
100	LDR_Bias_100K_Q5_45	1.824	1.822	-0.002
100	LDR_Bias_100K_Q2_67	1.823	1.821	-0.002
100	LDR_Bias_100K_Q2_68	1.823	1.820	-0.003
100	LDR_UnBias_100K_Q1_6	1.824	1.823	-0.001
100	LDR_UnBias_100K_Q3_29	1.825	1.825	0.000
100	LDR_UnBias_100K_Q5_69	1.818	1.816	-0.002
100	LDR_UnBias_100K_Q4_78	1.823	1.822	-0.001
100	LDR_UnBias_100K_Q4_79	1.823	1.821	-0.003
	Max	1.826	1.825	0.001
	Average	1.823	1.821	-0.002
	Min	1.818	1.816	-0.003
	Std Dev	0.002	0.002	0.001

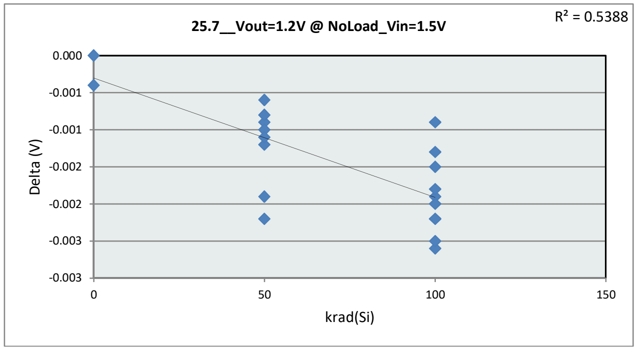


	25.5__Vout=1.8V @ 1A load_Vin=2.0V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.8462	V	
Min Limit	1.7738	V	
krad(Si)	0	50	100
LL	1.774	1.774	1.774
Min	1.821	1.816	1.816
Average	1.822	1.821	1.821
Max	1.823	1.824	1.825
UL	1.846	1.846	1.846

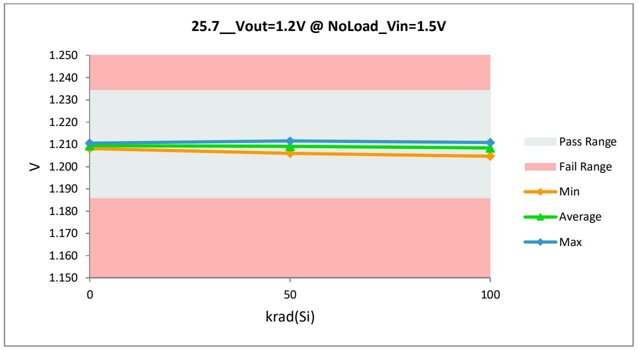


LDR Report
TPS7H1101-SP

		25.7__Vout=1.2V @ NoLoad_Vin=		
Test Site		Dallas	Dallas	
Tester		ETS-364	ETS-364	
Test Number		EF5069	EF5069	
Unit		V	V	
Max Limit		1.2342	1.2342	
Min Limit		1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.211	1.211	0.000
50	LDR_Bias_50K_Q1_3	1.209	1.208	-0.001
50	LDR_Bias_50K_Q2_65	1.212	1.211	-0.001
50	LDR_Bias_50K_Q3_30	1.211	1.210	-0.001
50	LDR_Bias_50K_Q4_76	1.209	1.208	-0.001
50	LDR_Bias_50K_Q5_46	1.209	1.208	-0.001
50	LDR_UnBias_50K_Q1_4	1.207	1.206	-0.001
50	LDR_UnBias_50K_Q2_66	1.212	1.210	-0.002
50	LDR_UnBias_50K_Q3_31	1.211	1.210	-0.001
50	LDR_UnBias_50K_Q4_77	1.211	1.209	-0.002
50	LDR_UnBias_50K_Q5_47	1.212	1.212	-0.001
0	LDR_100K_Correlation_Q5_72	1.208	1.208	0.000
100	LDR_Bias_100K_Q1_5	1.210	1.208	-0.002
100	LDR_Bias_100K_Q3_28	1.210	1.208	-0.002
100	LDR_Bias_100K_Q5_45	1.211	1.209	-0.002
100	LDR_Bias_100K_Q2_67	1.210	1.208	-0.002
100	LDR_Bias_100K_Q2_68	1.210	1.208	-0.003
100	LDR_UnBias_100K_Q1_6	1.211	1.210	-0.002
100	LDR_UnBias_100K_Q3_29	1.212	1.211	-0.001
100	LDR_UnBias_100K_Q5_69	1.207	1.205	-0.002
100	LDR_UnBias_100K_Q4_78	1.210	1.209	-0.001
100	LDR_UnBias_100K_Q4_79	1.211	1.208	-0.003
	Max	1.212	1.212	0.000
	Average	1.210	1.209	-0.001
	Min	1.207	1.205	-0.003
	Std Dev	0.001	0.002	0.001

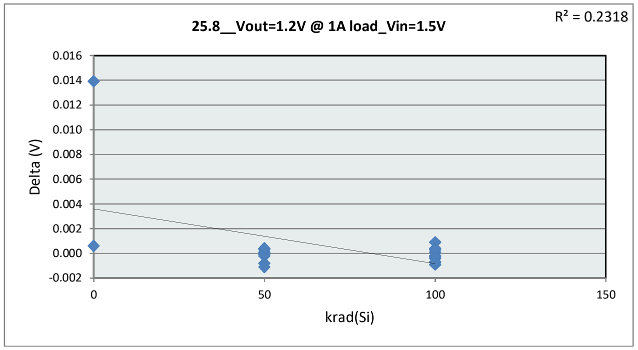


	25.7__Vout=1.2V @ NoLoad_Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.2342	V	
Min Limit	1.1858	V	
krad(Si)	0	50	100
LL	1.186	1.186	1.186
Min	1.208	1.206	1.205
Average	1.209	1.209	1.208
Max	1.211	1.212	1.211
UL	1.234	1.234	1.234

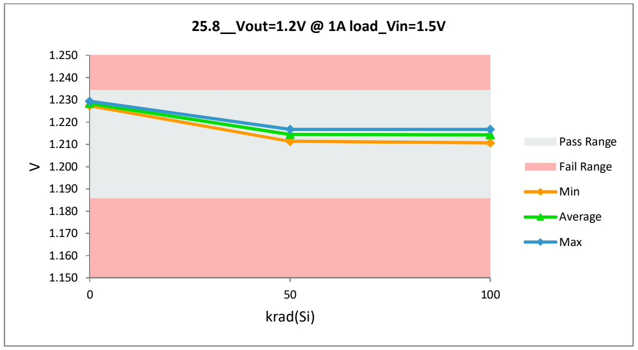


LDR Report
TPS7H1101-SP

		25.8__Vout=1.2V @ 1A load_Vin=		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	V	V	
	Max Limit	1.2342	1.2342	
	Min Limit	1.1858	1.1858	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	1.215	1.229	0.014
50	LDR_Bias_50K_Q1_3	1.213	1.214	0.000
50	LDR_Bias_50K_Q2_65	1.216	1.216	0.000
50	LDR_Bias_50K_Q3_30	1.215	1.215	0.000
50	LDR_Bias_50K_Q4_76	1.214	1.214	0.000
50	LDR_Bias_50K_Q5_46	1.213	1.214	0.000
50	LDR_UnBias_50K_Q1_4	1.211	1.211	0.000
50	LDR_UnBias_50K_Q2_66	1.216	1.215	-0.001
50	LDR_UnBias_50K_Q3_31	1.215	1.215	0.000
50	LDR_UnBias_50K_Q4_77	1.215	1.214	-0.001
50	LDR_UnBias_50K_Q5_47	1.216	1.217	0.000
0	LDR_100K_Correlation_Q5_72	1.227	1.227	0.001
100	LDR_Bias_100K_Q1_5	1.214	1.214	0.000
100	LDR_Bias_100K_Q3_28	1.215	1.214	0.000
100	LDR_Bias_100K_Q5_45	1.215	1.215	0.000
100	LDR_Bias_100K_Q2_67	1.214	1.214	0.000
100	LDR_Bias_100K_Q2_68	1.215	1.214	-0.001
100	LDR_UnBias_100K_Q1_6	1.215	1.216	0.000
100	LDR_UnBias_100K_Q3_29	1.216	1.217	0.001
100	LDR_UnBias_100K_Q5_69	1.211	1.211	0.000
100	LDR_UnBias_100K_Q4_78	1.215	1.215	0.000
100	LDR_UnBias_100K_Q4_79	1.215	1.214	-0.001
	Max	1.227	1.229	0.014
	Average	1.215	1.216	0.001
	Min	1.211	1.211	-0.001
	Std Dev	0.003	0.004	0.003

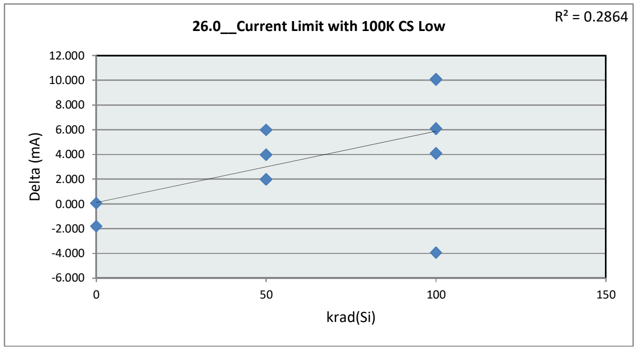


	25.8__Vout=1.2V @ 1A load_Vin=1.5V		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	1.2342	V	
Min Limit	1.1858	V	
krad(Si)	0	50	100
LL	1.186	1.186	1.186
Min	1.227	1.211	1.211
Average	1.228	1.214	1.214
Max	1.229	1.217	1.217
UL	1.234	1.234	1.234

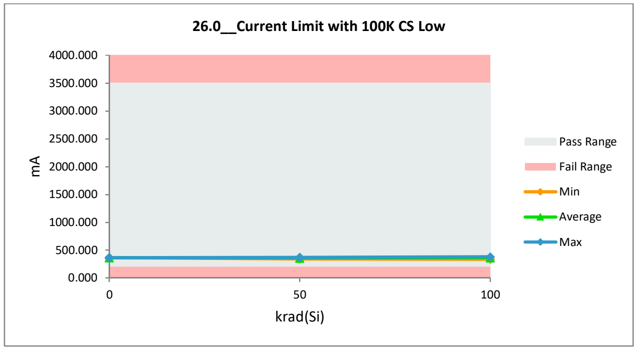


LDR Report
TPS7H1101-SP

		26.0__Current Limit with 100K C		
	Test Site	Dallas	Dallas	
	Tester	ETS-364	ETS-364	
	Test Number	EF5069	EF5069	
	Unit	mA	mA	
	Max Limit	3500	3500	
	Min Limit	200	200	
krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	364.820	363.027	-1.793
50	LDR_Bias_50K_Q1_3	334.959	338.933	3.974
50	LDR_Bias_50K_Q2_65	346.973	350.959	3.986
50	LDR_Bias_50K_Q3_30	352.998	354.978	1.980
50	LDR_Bias_50K_Q4_76	357.005	358.996	1.991
50	LDR_Bias_50K_Q5_46	367.054	369.052	1.998
50	LDR_UnBias_50K_Q1_4	344.979	346.976	1.997
50	LDR_UnBias_50K_Q2_66	348.974	350.971	1.997
50	LDR_UnBias_50K_Q3_31	353.046	357.002	3.956
50	LDR_UnBias_50K_Q4_77	355.028	361.009	5.981
50	LDR_UnBias_50K_Q5_47	363.048	369.028	5.980
0	LDR_100K_Correlation_Q5_72	363.018	363.081	0.063
100	LDR_Bias_100K_Q1_5	340.954	337.011	-3.943
100	LDR_Bias_100K_Q3_28	367.042	373.142	6.100
100	LDR_Bias_100K_Q5_45	365.078	375.130	10.052
100	LDR_Bias_100K_Q2_67	357.029	361.104	4.075
100	LDR_Bias_100K_Q2_68	346.991	357.044	10.053
100	LDR_UnBias_100K_Q1_6	348.962	355.032	6.070
100	LDR_UnBias_100K_Q3_29	369.067	379.161	10.094
100	LDR_UnBias_100K_Q5_69	363.060	369.135	6.075
100	LDR_UnBias_100K_Q4_78	356.993	361.098	4.105
100	LDR_UnBias_100K_Q4_79	354.975	359.086	4.111
	Max	369.067	379.161	10.094
	Average	355.548	359.589	4.041
	Min	334.959	337.011	-3.943
	Std Dev	9.243	10.710	3.543



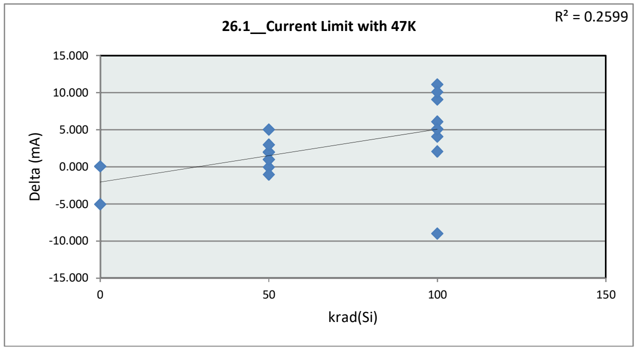
	26.0__Current Limit with 100K CS Low		
Test Site	Dallas		
Tester	ETS-364		
Test Number	EF5069		
Max Limit	3500	mA	
Min Limit	200	mA	
krad(Si)	0	50	100
LL	200.000	200.000	200.000
Min	363.027	338.933	337.011
Average	363.054	355.790	362.694
Max	363.081	369.052	379.161
UL	3500.000	3500.000	3500.000



LDR Report
TPS7H1101-SP

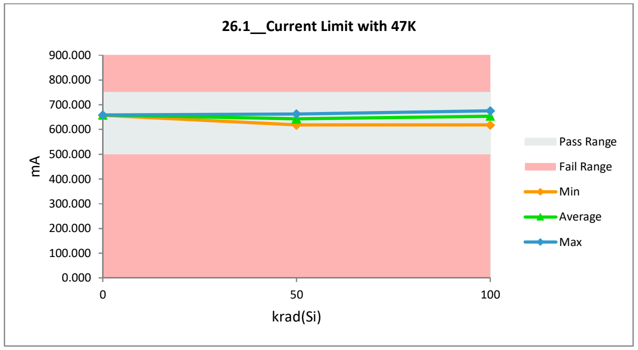
	26.1__Current Limit with 47K	
Test Site	Dallas	Dallas
Tester	ETS-364	ETS-364
Test Number	EF5069	EF5069
Unit	mA	mA
Max Limit	750	750
Min Limit	500	500

krad(Si)	Serial #	Pre	Post	Delta
0	LDR_50K_Correlation_Q5_73	662.272	657.216	-5.056
50	LDR_Bias_50K_Q1_3	617.055	618.045	0.990
50	LDR_Bias_50K_Q2_65	633.129	635.116	1.987
50	LDR_Bias_50K_Q3_30	643.197	643.160	-0.037
50	LDR_Bias_50K_Q4_76	648.207	650.188	1.981
50	LDR_Bias_50K_Q5_46	662.275	663.265	0.990
50	LDR_UnBias_50K_Q1_4	630.132	629.091	-1.041
50	LDR_UnBias_50K_Q2_66	633.147	634.131	0.984
50	LDR_UnBias_50K_Q3_31	642.194	645.166	2.972
50	LDR_UnBias_50K_Q4_77	646.194	651.209	5.015
50	LDR_UnBias_50K_Q5_47	660.286	663.253	2.967
0	LDR_100K_Correlation_Q5_72	659.259	659.314	0.055
100	LDR_Bias_100K_Q1_5	627.099	618.101	-8.998
100	LDR_Bias_100K_Q3_28	664.299	670.385	6.086
100	LDR_Bias_100K_Q5_45	662.275	673.376	11.101
100	LDR_Bias_100K_Q2_67	649.210	651.271	2.061
100	LDR_Bias_100K_Q2_68	636.151	645.246	9.095
100	LDR_UnBias_100K_Q1_6	634.121	640.212	6.091
100	LDR_UnBias_100K_Q3_29	665.302	675.394	10.092
100	LDR_UnBias_100K_Q5_69	656.244	661.344	5.100
100	LDR_UnBias_100K_Q4_78	646.212	650.268	4.056
100	LDR_UnBias_100K_Q4_79	643.197	648.250	5.053
	Max	665.302	675.394	11.101
	Average	646.430	649.227	2.797
	Min	617.055	618.045	-8.998
	Std Dev	13.877	15.971	4.594



	26.1__Current Limit with 47K	
Test Site	Dallas	
Tester	ETS-364	
Test Number	EF5069	
Max Limit	750	mA
Min Limit	500	mA

krad(Si)	0	50	100
LL	500.000	500.000	500.000
Min	657.216	618.045	618.101
Average	658.265	643.262	653.385
Max	659.314	663.265	675.394
UL	750.000	750.000	750.000



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